Radiation Report

TPS7H2201-SEP TID Radiation Report

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Trademarks

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1 Device Information

1.1 Product Description

The TPS7H2201-SEP is a radiation-tolerant single channel eFuse that provides configurable rise time to minimize inrush current and reverse current protection. The device contains a P-channel MOSFET that can operate over an input voltage range of 1.5 V to 7 V and can support a maximum continuous current of 6 A. The switch is controlled by an on and off input (EN), which can directly interface with low-voltage control signals.

The TPS7H2201-SEP is available in a ceramic and plastic package with integrated thermal pad allowing for high power dissipation. The device is characterized for operation over the free-air temperature range of –55°C to +125°C.

1.2 Device Details

Table 1-1 lists the device information used in the TID HDR characterization.

Table 1-1. Device and Exposure Details

TID HDR and LDR Details: Up to 50 krad(Si)	
TI Device Number	TPS7H2201-SEP (TPS7H2201MDAPTSEP)
Package	32 PIN HTSSOP (DAP)
Technology	Linear BiCMOS 7 (LBC7)
Die Lot Number	8288553
A/T Lot Number / Date Code	3531002 / 36A2J3K
Quantity Tested	30 irradiated units
Lot Accept/Reject	All levels tested and passed up to 50 krad(Si)
HDR Radiation Facility	DCLAB - Texas Instruments, Dallas, TX
HDR Dose Level	20 krad(Si), 30 krad(Si) and 50 krad (Si)
HDR Dose Rate	200 rad/s
HDR Radiation Source	Gammacell 220 Excel (GC-220E) Co-60
Irradiation Temperature	Ambient, room temperature

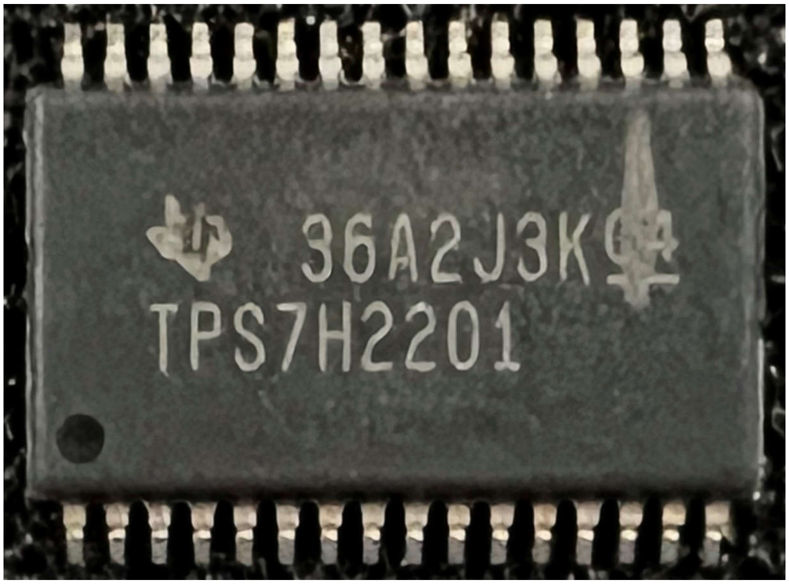


Figure 1-1. Device Used in Exposure

2 Total Dose Test Setup

2.1 Test Overview

The TPS7H2201-SEP was tested according to MIL-STD-883, Test Method 1019.9. For this testing, Condition A was used. For Condition A, the product was irradiated up to target radiation level and then put through full electrical parametric testing on the production Automated Test Equipment (ATE). All devices were fully functional, and passed all electrical parametric tests with the readings within the data-sheet electrical specification limits.

2.2 Test Description and Facilities

The TPS7H2201-SEP HDR exposure was performed on biased and unbiased devices in a Co-60 gamma cell at TI facility in Dallas CLAB (DCLAB), Texas. The unattenuated dose rate of this cell is 200 rads(Si)/s. After exposure, the devices were packed in dry ice (per MIL-STD-883 Method 1019.9 section 3.10) and brought to Junkins lab in TI Dallas for full post-radiation electrical evaluation using Texas Instruments ATE. ATE test limits are set per data sheet electrical limits based on preliminary qualification and characterization data. Post-radiation measurements were taken within 30 minutes of removing the devices from the dry ice container. The devices were allowed to reach room temperature prior to electrical post-radiation measurements.

2.3 Test Setup Details

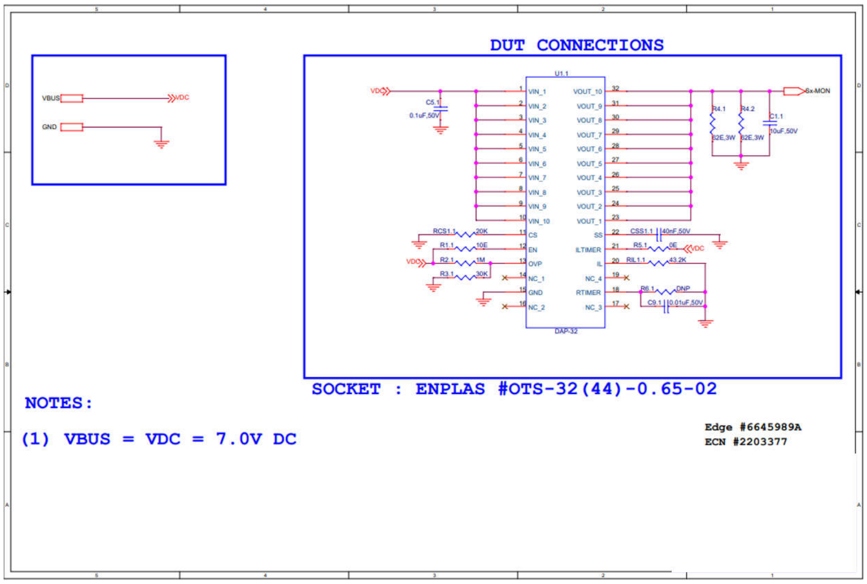
The devices under HDR exposure were tested in both biased and unbiased conditions described as follows.

2.3.1 Unbiased

For the unbiased HDR conditions, the exposure was performed with all pins grounded.

2.3.2 Biased

The TPS7H2201-SEP biased exposure was performed with a 7-V bias on the Vin and Enable pins. Figure 2-1 shows the biased diagram that was used for HDR exposure.



Sequence = VDC. Bulk capacitors added to all PS.

Figure 2-1. Bias Diagram Used in TID Exposure

Table 2-1. Biased Source Configuration

VDC (V)	VDC (mA/device)
7	250

2.4 Test Configuration and Condition

HDR devices were stressed at 20 krad(Si), 30 krad(Si) and 50 krad(Si) for biased and unbiased conditions.

Table 2-2. HDR 20 krad(Si), 30 krad(Si) and 50 krad(Si) Biased Device Information

Total Samples: 15		
Exposure Levels		
20 krad(Si)	30 krad(Si)	50 krad(Si)
6, 7, 8, 9, 10	16, 17, 18, 19, 20	26, 27, 28, 29, 30

Table 2-3. HDR 20 krad(Si), 30 krad(Si) and 50 krad(Si) Unbiased Device Information

Total Samples: 15		
Exposure Levels		
20 krad(Si)	30 krad(Si)	50 krad(Si)
1, 2, 3, 4, 5	11, 12, 13, 14, 15	21, 22, 23, 24, 25

3 TID Characterization Test Results

3.1 TID Characterization Summary Results

The parametric data for the TPS7H2201-SEP passes up to 50-krad(Si) HDR TID irradiation. The drifts of the electrical parameters through HDR were within the data sheet limits.

Overall, the TPS7H2201-SEP showed a strong degree of hardness to HDR TID irradiation up to 50 krad(Si) for both biased and unbiased exposure conditions. The measurements taken post-irradiation for each sample set showed a marginal shift for most parameters at each dose level for both biased and unbiased. The parameters that did show a greater degree of change between pre- and post-irradiation were still within the electrical performance characteristics specified in the data sheet electrical parameters. See Section 3.2 for parameters and associated tests.

See Appendix A for HDR report up to 50 krad(Si).

3.2 TPS7H2201-SEP Specification Compliance Matrix

Parameter	Test Conditions	MIN	TYP	MAX	Unit	SPECID	Test Number
POWER SUPPLIES AND CURRENTS							
VIN_{HUVLO}			1.32		V	VIN_UVLO_Rising	5.0
VIN_{LUVLO}			1.23		V	VIN_UVLO_Falling	5.1
$HYST_{VIN\text{-}UVLO}$			92		mV	VIN_Hysteresis	5.2
I_Q	IOUT = 0 mA, VIN = EN = 5 V, CS resistor of 20 kΩ to GND, IOUT = 0 mA, VIN = EN = 5 V, CS resistor of 20 kΩ to GND		2.4	6.5	mA	IQ_VIN_5V	3.6
I_F	EN = VOUT = GND, measured VOUT current, 1.5 V ≤ VIN ≤ 7 V			250	µA		
I_F	EN = VOUT = GND, measured VOUT current, VIN =1.5 V		3.27		µA	FORWARD_LEAKAGE	4.1, 4.3, 4.5, 4.7, 4.9
I_F	EN = VOUT = GND, measured VOUT current, VIN = 1.8 V		3.35		µA	FORWARD_LEAKAGE_VIN_1p5V	4.1
I_F	EN = VOUT = GND, measured VOUT current, VIN= 3.3 V		3.62		µA	FORWARD_LEAKAGE_VIN_3p3V	4.5
I_F	EN = VOUT = GND, measured VOUT current, VIN = 5 V		4.11		µA		
I_F	EN = VOUT = GND, measured VOUT current, VIN = 7 V		6.82		µA	FORWARD_LEAKAGE_VIN_5V	4.5
I_{SD} VIN	EN = GND, IOUT = 0 mA, measured VIN current, VIN = 5 V		0.4	3	mA	ISD_VIN_5V	4.6
I_{SD} VIN	EN = GND, IOUT = 0 mA, measured VIN current, VIN = 3.3 V		0.3	3	mA	ISD_VIN_3p3V	4.4
I_{SD} VIN	EN = GND, IOUT = 0 mA, measured VIN current, VIN = 1.8 V		0.2	3	mA	ISD_VIN_1p8V	4.2
I_{SD} VIN	EN = GND, IOUT = 0 mA, measured VIN current, VIN = 1.8, 3.3, and 5 V			3.1	mA	ISD_VIN_1p8V	4.2
$V_{RCP\_ENTER\ (3)}$	EN = 7 V, VIN = 1.5 V		TBD		mV	VRCP_ENTER_VIN_1p5V	
$V_{RCP\_ENTER\ (3)}$	EN = 7 V, VIN = 7 V		TBD		mV	VRCP_ENTER_VIN_7V	
$V_{RCP\_EXIT\ (3)}$	EN = 7 V, VIN = 1.5 V		TBD		mV	VRCP_EXIT_VIN_1p5V	
$V_{RCP\_EXIT\ (3)}$	EN = 7 V, VIN = 7 V		TBD		mV	VRCP_EXIT_VIN_7V	
$t_{RCP\ (3)}$	EN = 7 V, VIN = 1.5 V		TBD		µs	tRCP_VIN_1p5V	
$t_{RCP\ (3)}$	EN = 7 V, VIN = 7 V		TBD		µs	tRCP_VIN_7V	
I_{RCP}	EN = 0 V, VIN = 0 to 7 V, VOUT = 0 to 7 V for VOUT > VIN, EN = 0 V, VIN = 0 to 7 V, VOUT = 0 to 7 V for VOUT > VIN		0.45	2.5	mA	IRCP_EN_0V	3.1, 3.3, 3.5, 3.9
I_{RCP}	EN = 7 V, VIN = 0 V, VOUT = 0 to 7 V, EN = 7 V, VIN = 0 V, VOUT = 0 to 7 V		0.45	2.5	mA	IRCP_EN_7V	3.10, 22.16, 3.11, 22.18

Parameter	Test Conditions	MIN	TYP	MAX	Unit	SPECID	Test Number
SOFT START							
I_{SS}	1 V on SS pin, 1 V on SS pin		65	83	µA	SS_I_Charge	6.3, 6.7, 6.11, 6.15, 6.19
SR_{SS}	SS pin floating, COUT = 10 µF, SS pin floating, COUT = 10 µF		295		mV/µs	SS_Slew_Rate	
ENABLE AND UNDERVOLTAGE LOCKOUT (EN/UVLO) INPUT							
V_{IHEN}		0.56	0.61	0.65	V	EN_VTH_RISING	6.0, 6.4, 6.8, 6.12, 6.16
V_{ILEN}		0.47	0.51	0.55	V	EN_VTH_FALLING	6.1, 6.5, 6.9, 6.13, 6.17
$HYST_{EN}$			93	124	mV	EN_HYST	6.2, 6.6, 6.10, 6.14, 6.18
t_{LOW}	RTIMER = GND, IL = 1 A, IVOUT = 2 A	20			µs	EN_LOW_TIME	
VIN_{EN}		75%				VIN_EN_PERCENTAGE	
I_{EN}	EN = VIN = 5 V, EN = VIN = 5 V			12	nA	IEN_VIN_5V	
OVERVOLTAGE PROTECTION (OVP)							
V_{OVPR}		0.52	0.57	0.63	V	OVP_VTH_Rising	7.0, 7.3, 7.6, 7.9, 7.12
V_{OVPF}		0.5	0.55	0.59	V	OVP_VTH_Falling	7.1, 7.4, 7.7, 7.10, 7.13
$HYST_{OVP}$	1.6 V < VIN < 7 V, 1.6 V < VIN < 7 V		20	55	mV	OVP_HYST	7.2, 7.5, 7.8, 7.11, 7.14
I_{OVP}				15	nA	OVP_ILEAK	7.15, 7.16, 7.17, 7.18, 7.19
CURRENT LIMIT AND CURRENT SENSE							
t_{CSEN}	CSS = 120 nF, CSS = 120 nF			5	ms	CS_EN_TIME	13.0, 13.1
Minimum VOUT current for valid CS output		750			mA	MIN_VOUT_CURR_CS	
VOUT current change to CS change delay time	0.5-A rising step, 100 mA/µs, 1.5 V ≤ VIN ≤ 7 V, 0.5-A rising step, 100 mA/µs, 1.5 V ≤ VIN ≤ 7 V		16	74	µs	IOUT_CS_DELAY_RISING	40.1, 40.3, 40.5, 40.7, 40.9
VOUT current change to CS change delay time	0.5-A falling step, 100 mA/µs, 1.5 V ≤ VIN ≤ 7 V, 0.5-A falling step, 100 mA/µs, 1.5 V ≤ VIN ≤ 7 V		16	73	µs	IOUT_CS_DELAY_FALLING	40.0, 40.2, 40.4, 40.6, 40.8
CS pin accuracy	0.75 A ≤ IVOUT ≤ 7.5 A, 0.75 A ≤ IVOUT ≤ 7.5 A	–10%		10%		CS_ACCURACY	9.9, 9.19
CS pin voltage	0.75 A ≤ IVOUT ≤ 7.5 A, no OCP, 0.75 A ≤ IVOUT ≤ 7.5 A, no OCP			VIN – 0.4	V	CS_VOLTAGE	
Current limit setting, I_{IL}	IVOUT ≤ 1 A, IVOUT ≤ 1 A	IVOUT + 0.5			A	CURR_LIMIT_SET_LESS_1A	
Current limit setting, I_{IL}	1 A < IVOUT ≤ 3 A, 1 A < IVOUT ≤ 3 A	IVOUT + 1			A	CURR_LIMIT_SET_GREATER_1A	
Current limit setting, I_{IL}	IVOUT > 3 A, IVOUT > 3 A	IVOUT + 1.5			A	CURR_LIMIT_SET_GREATER_3A	
Programmable current limit accuracy	1.5 V ≤ VIN ≤ 7 V, 1.5 V ≤ VIN ≤ 7 V	–20%		20%		Current_Limit_Accuracy	30.3, 30.7, 30.11, 30.15, 30.19, 30.23, 30.27, 30.31, 30.35, 30.39, 30.43, 30.47, 30.51, 30.55, 30.59
Fast trip off current limit	VIN = 5 V, 10-mΩ short in 10 µs, VIN = 5 V, 10-mΩ short in 10 µs		22		A	FTO_Current_Limit	
Fast trip off off-time	VIN = 5 V, CSS = 2.7 nF, VIN = 5 V, CSS = 2.7 nF		61	158	µs	FTO_OFF_TIME	

Parameter	Test Conditions	MIN	TYP	MAX	Unit	SPECID	Test Number
Internal current limit timer (fast trip off current limit)	VIN = 5 V, IVOUT = 3 A, IL = 6 A, ILTIMER = VIN, 10-mΩ short in 10 µs, VIN = 5 V, IVOUT = 3 A, IL = 6 A, ILTIMER = VIN, 10-mΩ short in 10 µs		15	35	µs	Current_Limit_Timer	
TIMERS							
$I_{ILTIMER}$		0.7	1	1.38	µA	ILTIMER_CHARGE_CURR	12.0, 12.2
$PD_{ILTIMER}$	40 mV on ILTIMER pin, 40 mV on ILTIMER pin		38	153	Ω	ILTIMER_PDR	35.0, 35.2, 35.4, 35.6, 35.8
I_{RTIMER}		0.7	1	1.38	µA	RTIMER_CHARGE_CURR	12.1, 12.3
PD_{RTIMER}	40 mV on RTIMER pin, 40 mV on RTIMER pin		38	153	Ω	RTIMER_PDR	35.1, 35.3, 35.5, 35.7, 35.9
THERMAL SHUTDOWN							
Thermal shutdown	VIN = 5 V, VIN = 5 V		175		°C	Thermal_SHDN	
Thermal shutdown hysteresis	VIN = 5 V, VIN = 5 V		20		°C	Thermal_SHDN_Hyst	
RESISTANCE CHARACTERISTICS							
R_{ON}	VIN = 7 V, IIL = 7.5 A, –55°C		15.9	17	mΩ	RON_VIN_7V_N55_Plastic	
R_{ON}	VIN = 7 V, IIL = 7.5 A, –40°C		16.9		mΩ	RON_VIN_7V_N40_Plastic	
R_{ON}	VIN = 7 V, IIL = 7.5 A, 25°C		19.9	21	mΩ	RON_VIN_7V_25_Plastic	8.4
R_{ON}	VIN = 7 V, IIL = 7.5 A, 85°C		22.9		mΩ	RON_VIN_7V_85_Plastic	
R_{ON}	VIN = 7 V, IIL = 7.5 A, 125°C		25	27	mΩ	RON_VIN_7V_125_Plastic	
R_{ON}	VIN = 5 V, IIL = 7.5 A, –55°C		17	18	mΩ	RON_VIN_5V_N55_Plastic	
R_{ON}	VIN = 5 V, IIL = 7.5 A, –40°C		18		mΩ	RON_VIN_5V_N40_Plastic	
R_{ON}	VIN = 5 V, IIL = 7.5 A, 25°C		21.4	23	mΩ	RON_VIN_5V_25_Plastic	8.3
R_{ON}	VIN = 5 V, IIL = 7.5 A, 85°C		24.8		mΩ	RON_VIN_5V_85_Plastic	
R_{ON}	VIN = 5 V, IIL = 7.5 A, 125°C		27	29	mΩ	RON_VIN_5V_125_Plastic	
R_{ON}	VIN = 3.3 V, IIL = 7.5 A, –55°C		19.2	21	mΩ	RON_VIN_3P3V_N55_Plastic	
R_{ON}	VIN = 3.3 V, IIL = 7.5 A, –40°C		20.4		mΩ	RON_VIN_3P3V_N40_Plastic	
R_{ON}	VIN = 3.3 V, IIL = 7.5 A, 25°C		24.5	26	mΩ	RON_VIN_3P3V_25_Plastic	8.2
R_{ON}	VIN = 3.3 V, IIL = 7.5 A, 85°C		28.5		mΩ	RON_VIN_3P3V_85_Plastic	
R_{ON}	VIN = 3.3 V, IIL = 7.5 A, 125°C		31.2	33	mΩ	RON_VIN_3P3V_125_Plastic	
R_{ON}	VIN = 1.8 V, IIL = 7.5 A, –55°C		27.1	29	mΩ	RON_VIN_1P8V_N55_Plastic	
R_{ON}	VIN = 1.8 V, IIL = 7.5 A, –40°C		28.7		mΩ	RON_VIN_1P8V_N40_Plastic	
R_{ON}	VIN = 1.8 V, IIL = 7.5 A, 25°C		34.9	37	mΩ	RON_VIN_1P8V_25_Plastic	8.1
R_{ON}	VIN = 1.8 V, IIL = 7.5 A, 85°C		41	62	mΩ	RON_VIN_1P8V_85_Plastic	
R_{ON}	VIN = 1.8 V, IIL = 7.5 A, 125°C		44.9	48	mΩ	RON_VIN_1P8V_125_Plastic	
R_{ON}	VIN = 1.5 V, IIL = 7.5 A, –55°C		33	36	mΩ	RON_VIN_1P5V_N55_Plastic	
R_{ON}	VIN = 1.5 V, IIL = 7.5 A, –40°C		35		mΩ	RON_VIN_1P5V_N40_Plastic	
R_{ON}	VIN = 1.5 V, IIL = 7.5 A, 25°C		47.2	46	mΩ	RON_VIN_1P5V_25_Plastic	8.0
R_{ON}	VIN = 1.5 V, IIL = 7.5 A, 85°C		46.2		mΩ	RON_VIN_1P5V_85_Plastic	
R_{ON}	VIN = 1.5 V, IIL = 7.5 A, 125°C		55	59	mΩ	RON_VIN_1P5V_125_Plastic	

4 Applicable and Reference Documents

4.1 Applicable Documents

- Texas Instruments, *TPS7H2201-SEP Radiation Hardened 1.5-V to 7-V, 6-A eFuse*, data sheet.
- Texas Instruments, *Single Event Effects Report of the TPS7H2201-SEP 1.5-V to 7-V, 6-A eFuse*, radiation report.
- Texas Instruments, *TPS7H2201-SEP 1.5-V to 7-V, 6-A eFuse Evaluation Module*, EVM user's guide.

4.2 Reference Documents

Texas Instruments total ionizing dose radiation (total dose) test procedure follows the standards put forth in MIL-STD-883 TM 1019. The document can be found at the DLA website.

5 Revision History

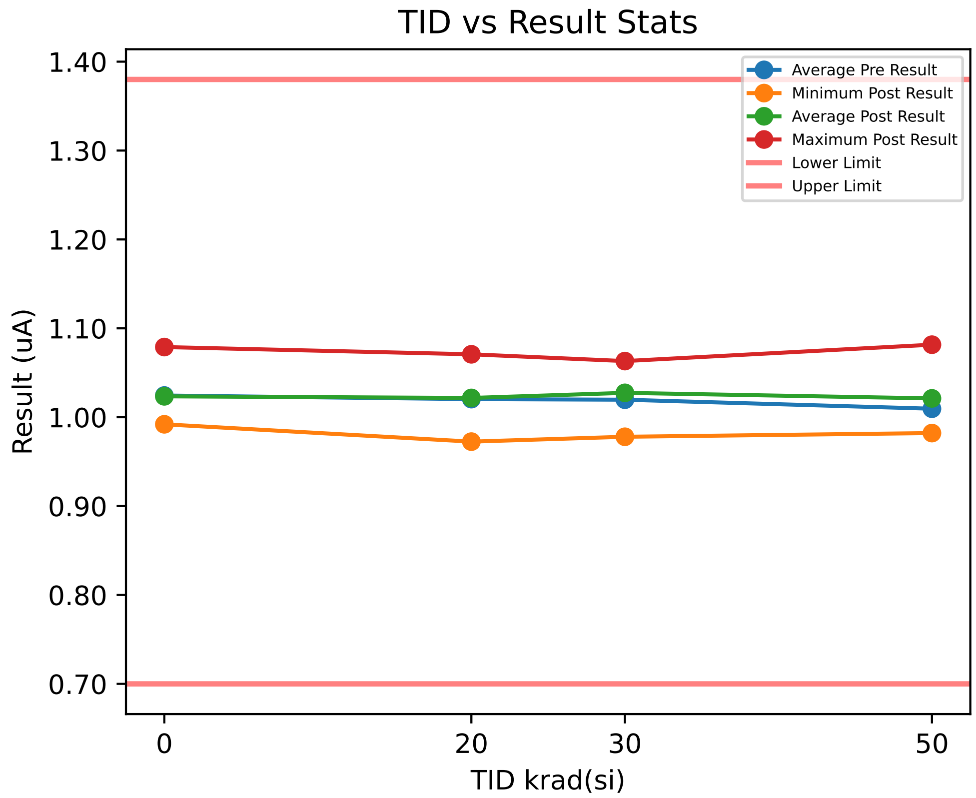
Changes from Revision * (August 2023) to Revision A (September 2023) **Page**

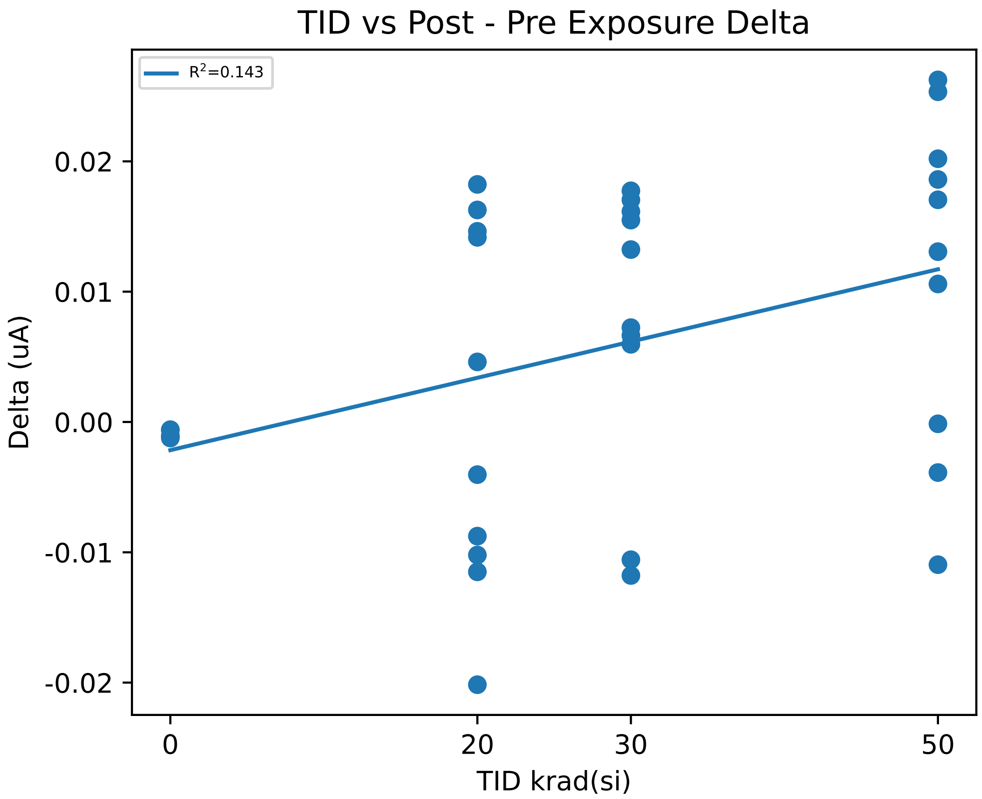
- Updated image in Section 1.2 and part and lot numbers.......... 2
- Added unbiased section.......... 3
- Added unbiased table, update biased and unbiased serial numbers to reflect new data.......... 4
- Updated specification compliance matrix with new plastic limits.......... 5
- Updated data report with new production device data, including 15 biased units, 15 unbiased units, and five correlation units.......... 10

A Appendix: HDR TID Report Data

This appendix contains the HDR TID report data.

Device Test: 12.0 ILTIMER_CHARGE_CURR(ILT_ICharge_Vin1p5V)





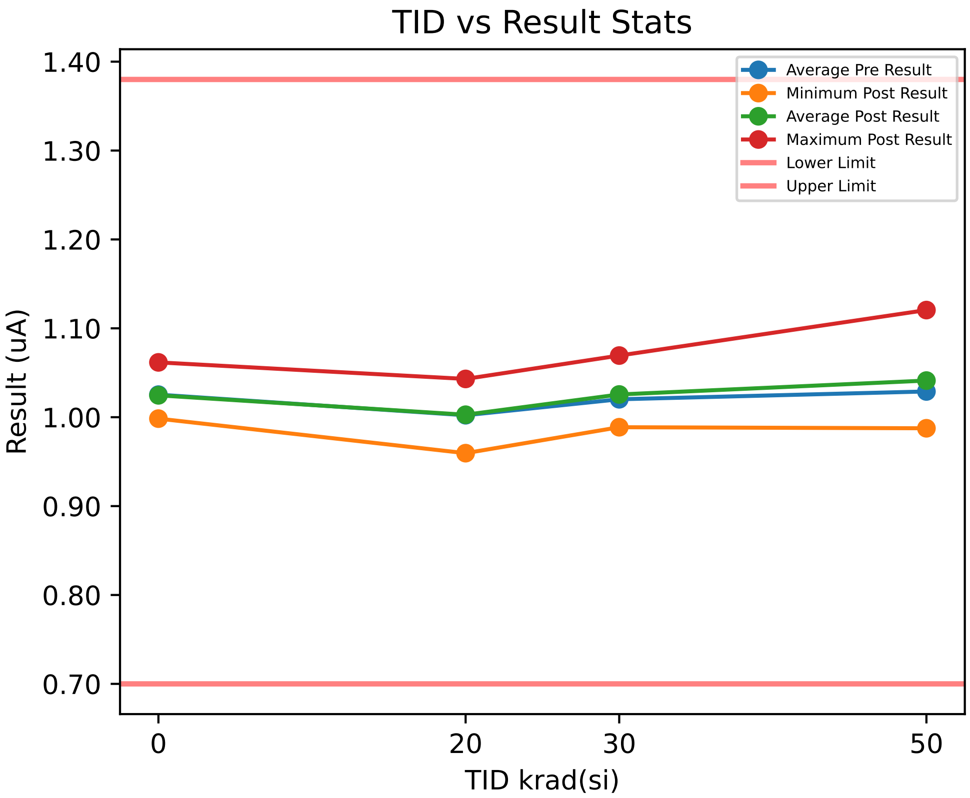
Test Results (Lower Limit = 0.7, Upper Limit = 1.38 (uA))

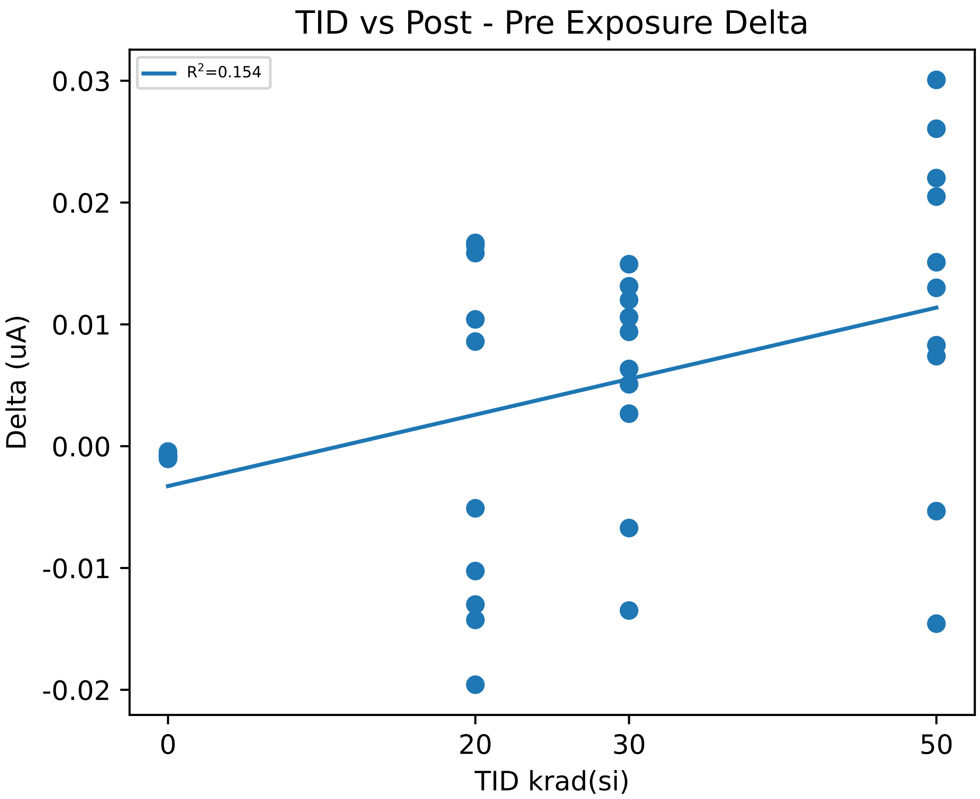
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.9788	0.99343	0.01463
2	20	Unbiased	1.0116	1.0162	0.00461
3	20	Unbiased	1.0369	1.0281	-0.00876
4	20	Unbiased	1.0442	1.0583	0.01417
5	20	Unbiased	1.0288	1.0173	-0.0115
6	20	7V Biased	0.97657	0.97253	-0.00404
7	20	7V Biased	1.0069	1.0251	0.01823
8	20	7V Biased	1.0461	1.0359	-0.01021
9	20	7V Biased	0.98288	0.99915	0.01627
10	20	7V Biased	1.091	1.0708	-0.02016
11	30	Unbiased	0.98857	0.978	-0.01057
12	30	Unbiased	1.0499	1.0632	0.01323
13	30	Unbiased	0.9815	0.98814	0.00664
14	30	Unbiased	1.0383	1.0442	0.00596
15	30	Unbiased	1.0449	1.0332	-0.01178
16	30	7V Biased	0.99961	1.0151	0.01549
17	30	7V Biased	1.03	1.0461	0.01615
18	30	7V Biased	1.0185	1.0356	0.01704
19	30	7V Biased	1.0056	1.0128	0.00724
20	30	7V Biased	1.0401	1.0579	0.01774
21	50	Unbiased	1.071	1.0816	0.01059
22	50	Unbiased	0.99311	0.98216	-0.01095
23	50	Unbiased	1.0192	1.0445	0.02534
24	50	Unbiased	1.0005	1.0191	0.01861
25	50	Unbiased	0.96617	0.98322	0.01705
26	50	7V Biased	0.99499	1.0081	0.01307
27	50	7V Biased	1.0238	1.05	0.02625
28	50	7V Biased	0.9961	0.99596	-0.00014
29	50	7V Biased	1.0128	1.0089	-0.00388
30	50	7V Biased	1.018	1.0382	0.0202
31	0	Correlation	1.0795	1.0789	-0.00059
32	0	Correlation	1.0208	1.0197	-0.00104
33	0	Correlation	1.0264	1.0257	-0.00062
34	0	Correlation	0.99316	0.99203	-0.00113
35	0	Correlation	1.0023	1.0011	-0.00123

Test Statistics (uA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.99316	1.0244	1.0795	0.033617	0.99203	1.0235	1.0789	0.03386	-0.00123	-0.000922	-0.00059	0.00029727
20	0.97657	1.0204	1.091	0.036311	0.97253	1.0217	1.0708	0.029405	-0.02016	0.001324	0.01823	0.013951
30	0.9815	1.0197	1.0499	0.024614	0.978	1.0274	1.0632	0.028456	-0.01178	0.007714	0.01774	0.010895
50	0.96617	1.0096	1.071	0.027446	0.98216	1.0212	1.0816	0.032045	-0.01095	0.011614	0.02625	0.012673

Device Test: 12.1 RTIMER_CHARGE_CURR(RT_ICharge_Vin1p5V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

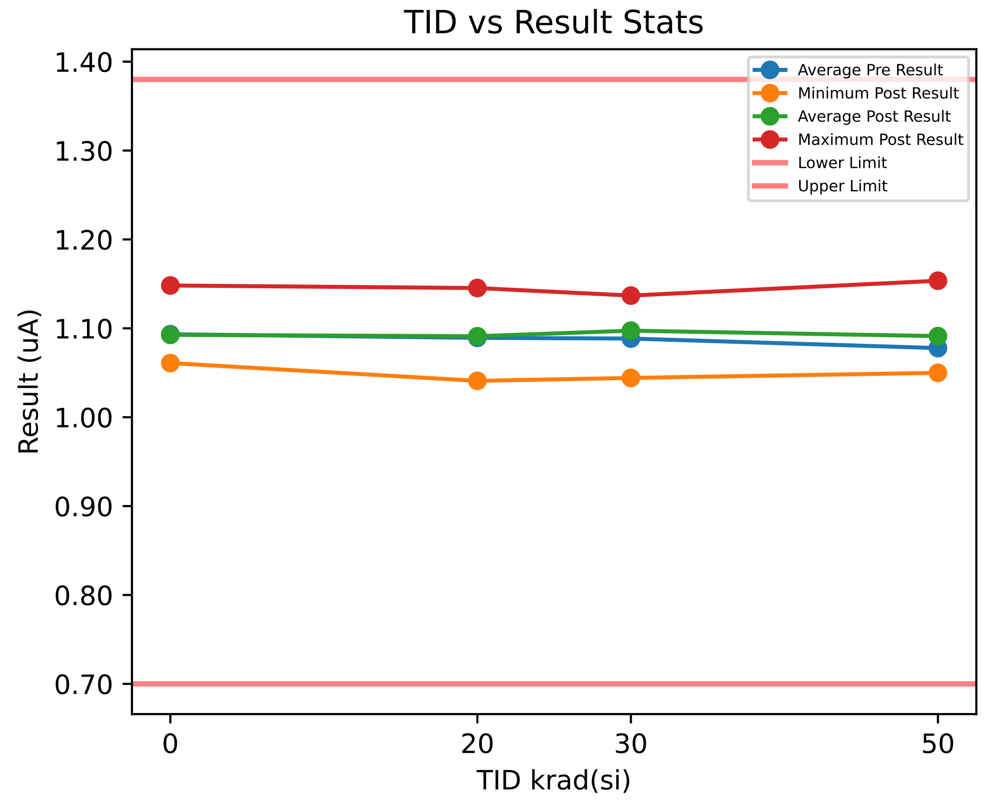
Test Results (Lower Limit = 0.7, Upper Limit = 1.38 (uA))

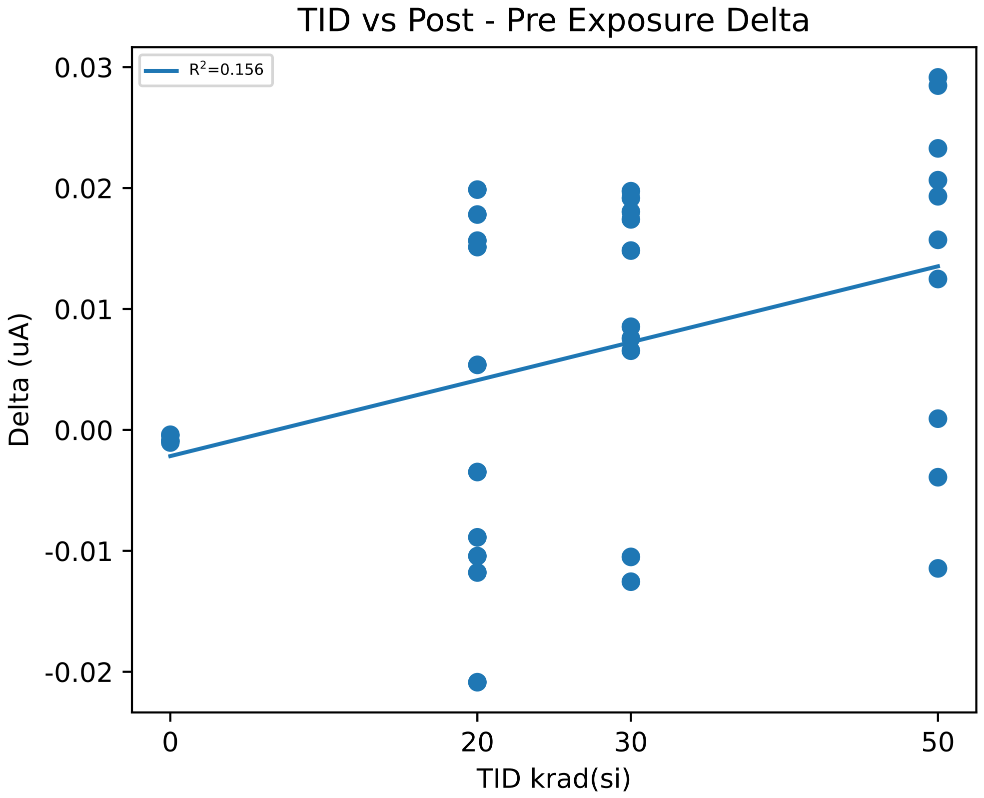
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.95156	0.96803	0.01647
2	20	Unbiased	1.0134	1.022	0.00859
3	20	Unbiased	1.0231	1.0088	-0.01426
4	20	Unbiased	1.0126	1.0284	0.01585
5	20	Unbiased	1.0165	1.0063	-0.01025
6	20	7V Biased	0.96465	0.95955	-0.0051
7	20	7V Biased	0.97366	0.98407	0.01041
8	20	7V Biased	1.0561	1.0431	-0.013
9	20	7V Biased	0.96554	0.98223	0.01669
10	20	7V Biased	1.0451	1.0255	-0.01958
11	30	Unbiased	1.0033	0.9898	-0.01349
12	30	Unbiased	1.0588	1.0694	0.01059
13	30	Unbiased	1.0162	1.0225	0.00634
14	30	Unbiased	1.0228	1.0255	0.00267
15	30	Unbiased	1.0237	1.017	-0.00672
16	30	7V Biased	0.97561	0.98874	0.01313
17	30	7V Biased	1.0498	1.0592	0.00939
18	30	7V Biased	0.9996	1.0116	0.01201
19	30	7V Biased	1.0007	1.0058	0.00508
20	30	7V Biased	1.0513	1.0662	0.01494
21	50	Unbiased	1.1054	1.1205	0.0151
22	50	Unbiased	1.0021	0.98755	-0.01457
23	50	Unbiased	1.0292	1.0553	0.02606
24	50	Unbiased	1.0204	1.0334	0.013
25	50	Unbiased	0.9958	1.0163	0.02049
26	50	7V Biased	1.0003	1.0086	0.00829
27	50	7V Biased	1.037	1.0671	0.03007
28	50	7V Biased	1.0336	1.041	0.00739
29	50	7V Biased	1.0496	1.0443	-0.00533
30	50	7V Biased	1.0162	1.0382	0.02201
31	0	Correlation	1.0625	1.0617	-0.00081
32	0	Correlation	1.0316	1.0308	-0.00084
33	0	Correlation	1.0265	1.0261	-0.00044
34	0	Correlation	1.0071	1.0061	-0.00104
35	0	Correlation	0.99915	0.99841	-0.00074

Test Statistics (uA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.99915	1.0254	1.0625	0.024692	0.99841	1.0246	1.0617	0.024719	-0.00104	-0.000774	-0.00044	0.00021744
20	0.95156	1.0022	1.0561	0.036132	0.95955	1.0028	1.0431	0.028019	-0.01958	0.000582	0.01669	0.014401
30	0.97561	1.0202	1.0588	0.026755	0.98874	1.0256	1.0694	0.029819	-0.01349	0.005394	0.01494	0.0091255
50	0.9958	1.029	1.1054	0.032041	0.98755	1.0412	1.1205	0.036214	-0.01457	0.012251	0.03007	0.013935

Device Test: 12.2 ILTIMER_CHARGE_CURR(ILT_ICharge_Vin7p0V)





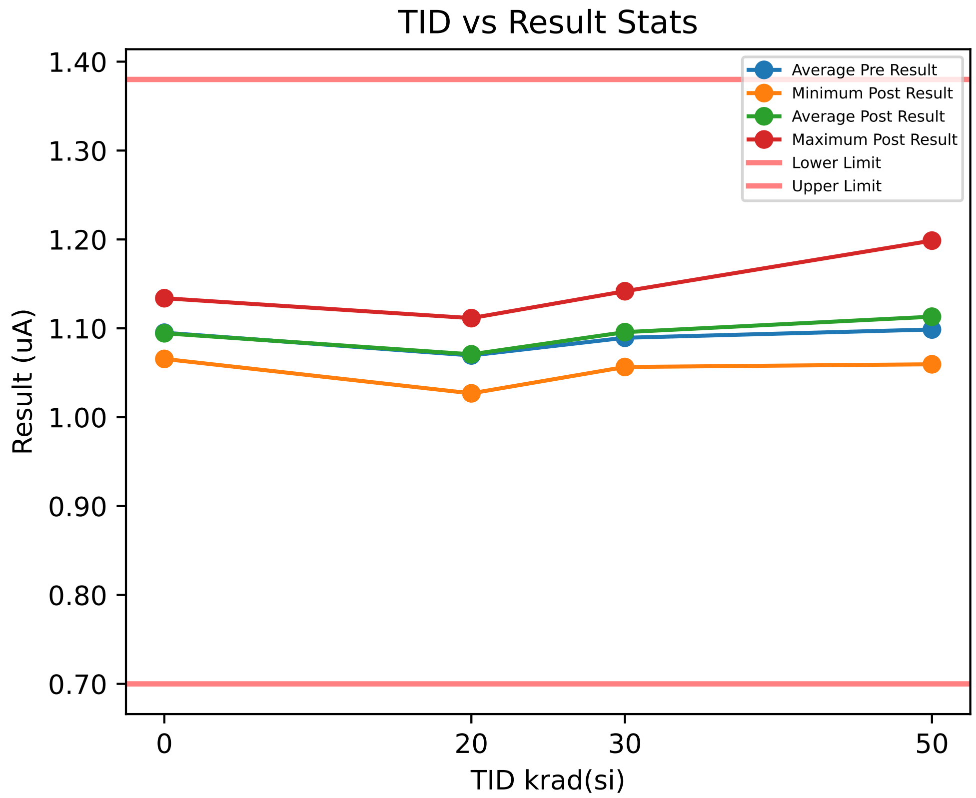
Test Results (Lower Limit = 0.7, Upper Limit = 1.38 (uA))

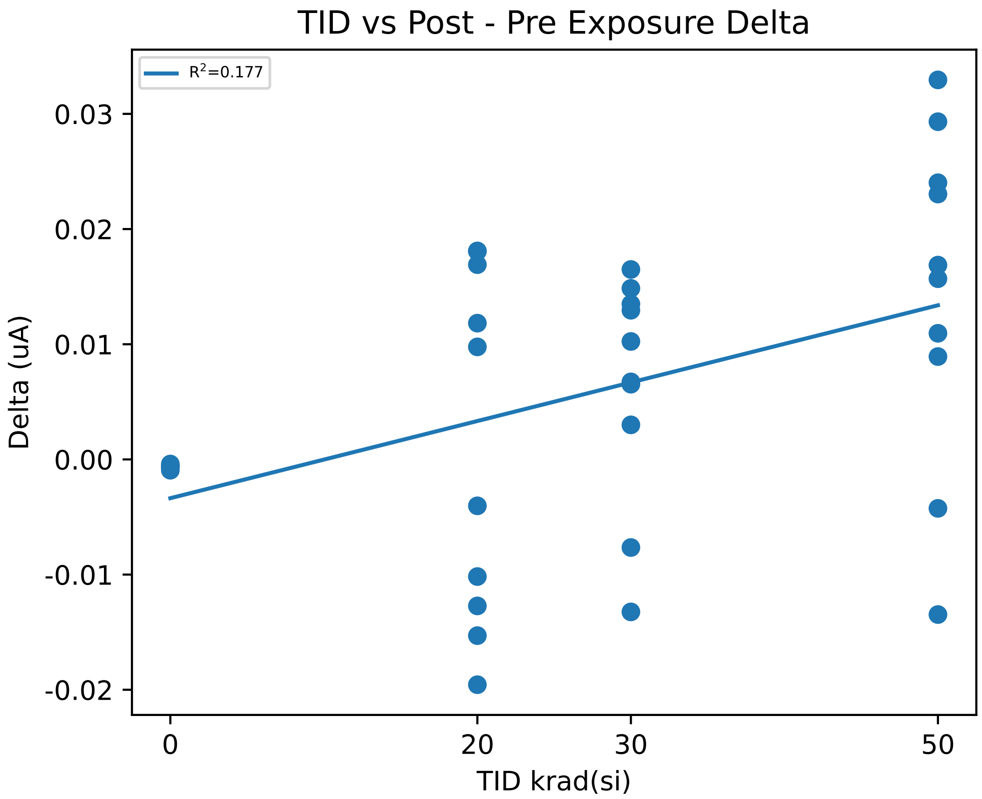
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	1.0455	1.0612	0.01565
2	20	Unbiased	1.0795	1.0849	0.00538
3	20	Unbiased	1.1083	1.0995	-0.00888
4	20	Unbiased	1.1149	1.13	0.01512
5	20	Unbiased	1.0972	1.0855	-0.01179
6	20	7V Biased	1.0444	1.0409	-0.00348
7	20	7V Biased	1.073	1.0929	0.01987
8	20	7V Biased	1.1153	1.1049	-0.01043
9	20	7V Biased	1.0484	1.0662	0.01781
10	20	7V Biased	1.1662	1.1453	-0.02086
11	30	Unbiased	1.0547	1.0442	-0.0105
12	30	Unbiased	1.122	1.1368	0.01483
13	30	Unbiased	1.0466	1.0541	0.00757
14	30	Unbiased	1.1087	1.1152	0.00655
15	30	Unbiased	1.1119	1.0994	-0.01255
16	30	7V Biased	1.0689	1.0863	0.01741
17	30	7V Biased	1.1	1.118	0.01804
18	30	7V Biased	1.0861	1.1052	0.01917
19	30	7V Biased	1.0734	1.0819	0.00853
20	30	7V Biased	1.1127	1.1324	0.01974
21	50	Unbiased	1.1411	1.1536	0.01248
22	50	Unbiased	1.0614	1.0499	-0.01145
23	50	Unbiased	1.0901	1.1186	0.02847
24	50	Unbiased	1.0682	1.0889	0.02065
25	50	Unbiased	1.0311	1.0504	0.01932
26	50	7V Biased	1.0597	1.0754	0.01572
27	50	7V Biased	1.0936	1.1227	0.02915
28	50	7V Biased	1.065	1.0659	0.00093
29	50	7V Biased	1.0818	1.0779	-0.00391
30	50	7V Biased	1.0858	1.1091	0.02328
31	0	Correlation	1.1486	1.1482	-0.00045
32	0	Correlation	1.0909	1.09	-0.00088
33	0	Correlation	1.0947	1.0943	-0.0004
34	0	Correlation	1.062	1.0609	-0.00104
35	0	Correlation	1.0706	1.0697	-0.00091

Test Statistics (uA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.062	1.0934	1.1486	0.033792	1.0609	1.0926	1.1482	0.034016	-0.00104	-0.000736	-0.0004	0.00029074
20	1.0444	1.0893	1.1662	0.038928	1.0409	1.0911	1.1453	0.031315	-0.02086	0.001839	0.01987	0.014737
30	1.0466	1.0885	1.122	0.026488	1.0442	1.0974	1.1368	0.031012	-0.01255	0.008879	0.01974	0.011823
50	1.0311	1.0778	1.1411	0.028909	1.0499	1.0912	1.1536	0.033983	-0.01145	0.013464	0.02915	0.013901

Device Test: 12.3 RTIMER_CHARGE_CURR(RT_ICharge_Vin7p0V)





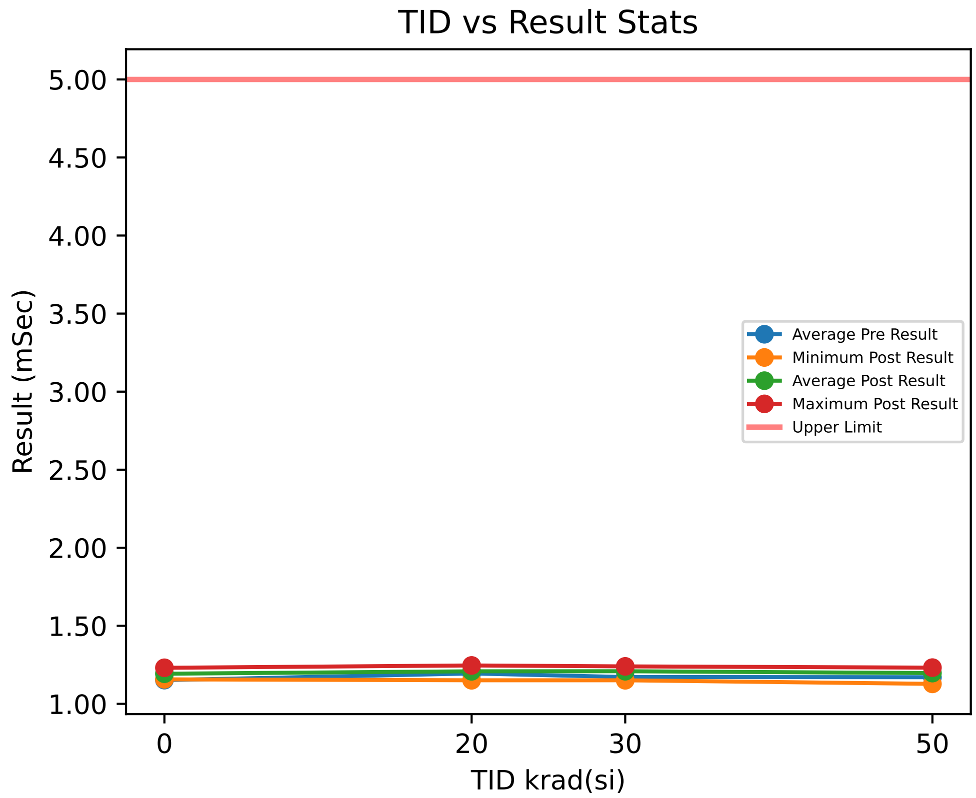
Test Results (Lower Limit = 0.7, Upper Limit = 1.38 (uA))

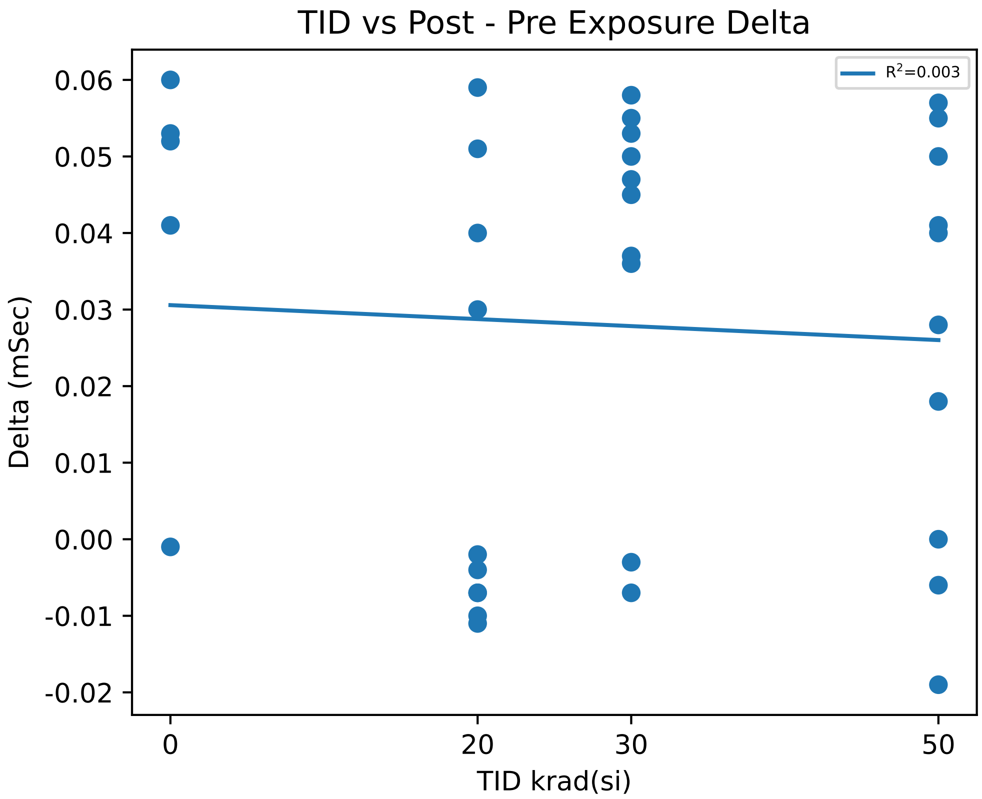
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	1.0151	1.0332	0.01807
2	20	Unbiased	1.0864	1.0962	0.00977
3	20	Unbiased	1.0907	1.0754	-0.0153
4	20	Unbiased	1.0801	1.0971	0.01691
5	20	Unbiased	1.0839	1.0737	-0.01017
6	20	7V Biased	1.0309	1.0269	-0.00403
7	20	7V Biased	1.039	1.0508	0.01183
8	20	7V Biased	1.1242	1.1115	-0.01272
9	20	7V Biased	1.0302	1.0483	0.0181
10	20	7V Biased	1.1143	1.0948	-0.01956
11	30	Unbiased	1.0716	1.0584	-0.01324
12	30	Unbiased	1.1288	1.1418	0.01295
13	30	Unbiased	1.0848	1.0916	0.00673
14	30	Unbiased	1.0924	1.0954	0.003
15	30	Unbiased	1.0911	1.0835	-0.00765
16	30	7V Biased	1.0416	1.0565	0.01485
17	30	7V Biased	1.1238	1.134	0.01024
18	30	7V Biased	1.0663	1.0798	0.01349
19	30	7V Biased	1.0686	1.0752	0.00653
20	30	7V Biased	1.1246	1.1411	0.01649
21	50	Unbiased	1.1818	1.1987	0.01687
22	50	Unbiased	1.073	1.0596	-0.01347
23	50	Unbiased	1.0993	1.1286	0.02932
24	50	Unbiased	1.088	1.1037	0.01569
25	50	Unbiased	1.0607	1.0837	0.02304
26	50	7V Biased	1.0688	1.0798	0.01095
27	50	7V Biased	1.1064	1.1393	0.03295
28	50	7V Biased	1.1052	1.1141	0.00893
29	50	7V Biased	1.1206	1.1164	-0.00425
30	50	7V Biased	1.0832	1.1072	0.02402
31	0	Correlation	1.1345	1.1339	-0.00057
32	0	Correlation	1.1043	1.1037	-0.00062
33	0	Correlation	1.094	1.0936	-0.0004
34	0	Correlation	1.0765	1.0755	-0.00094
35	0	Correlation	1.0663	1.0656	-0.00068

Test Statistics (uA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.0663	1.0951	1.1345	0.026527	1.0656	1.0945	1.1339	0.026616	-0.00094	-0.000642	-0.0004	0.00019652
20	1.0151	1.0695	1.1242	0.03797	1.0269	1.0708	1.1115	0.029516	-0.01956	0.00129	0.0181	0.015118
30	1.0416	1.0894	1.1288	0.028996	1.0565	1.0957	1.1418	0.032351	-0.01324	0.006339	0.01649	0.0098652
50	1.0607	1.0987	1.1818	0.034709	1.0596	1.1131	1.1987	0.038336	-0.01347	0.014405	0.03295	0.01456

Device Test: 13.0 CS_EN_TIME(CS_Delay_Vin1p5V_1A)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

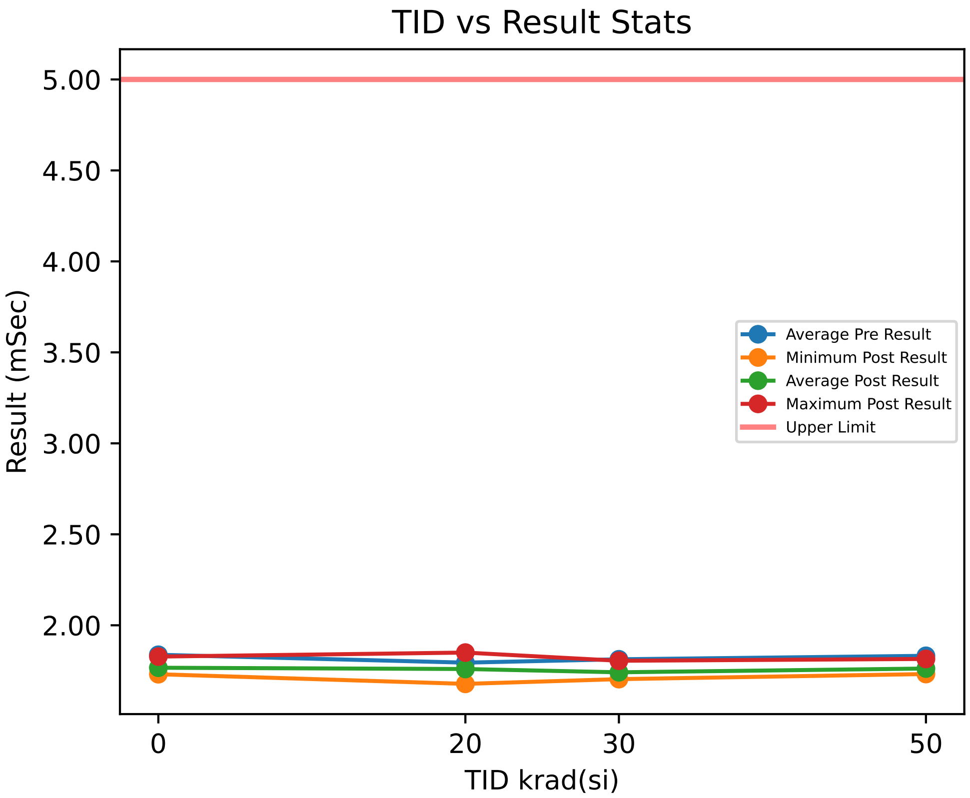
Test Results (Upper Limit = 5.0 (mSec))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	1.186	1.182	-0.004
2	20	Unbiased	1.226	1.219	-0.007
3	20	Unbiased	1.247	1.237	-0.01
4	20	Unbiased	1.257	1.246	-0.011
5	20	Unbiased	1.16	1.158	-0.002
6	20	7V Biased	1.179	1.219	0.04
7	20	7V Biased	1.184	1.235	0.051
8	20	7V Biased	1.179	1.238	0.059
9	20	7V Biased	1.158	1.151	-0.007
10	20	7V Biased	1.17	1.2	0.03
11	30	Unbiased	1.158	1.203	0.045
12	30	Unbiased	1.172	1.23	0.058
13	30	Unbiased	1.196	1.189	-0.007
14	30	Unbiased	1.192	1.228	0.036
15	30	Unbiased	1.179	1.229	0.05
16	30	7V Biased	1.178	1.233	0.055
17	30	7V Biased	1.154	1.151	-0.003
18	30	7V Biased	1.159	1.196	0.037
19	30	7V Biased	1.143	1.19	0.047
20	30	7V Biased	1.187	1.24	0.053
21	50	Unbiased	1.193	1.193	0
22	50	Unbiased	1.166	1.221	0.055
23	50	Unbiased	1.172	1.222	0.05
24	50	Unbiased	1.175	1.232	0.057
25	50	Unbiased	1.171	1.165	-0.006
26	50	7V Biased	1.183	1.201	0.018
27	50	7V Biased	1.157	1.197	0.04
28	50	7V Biased	1.153	1.194	0.041
29	50	7V Biased	1.147	1.128	-0.019
30	50	7V Biased	1.189	1.217	0.028
31	0	Correlation	1.133	1.185	0.052
32	0	Correlation	1.171	1.231	0.06
33	0	Correlation	1.158	1.157	-0.001
34	0	Correlation	1.141	1.182	0.041
35	0	Correlation	1.157	1.21	0.053

Test Statistics (mSec)

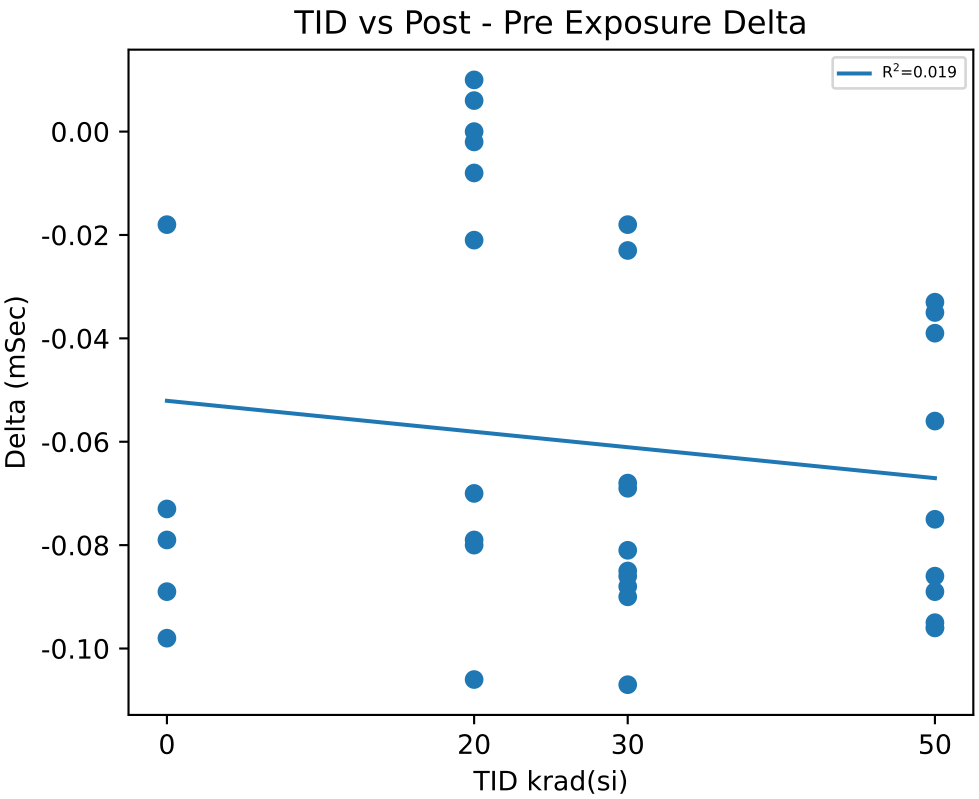
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.133	1.152	1.171	0.015033	1.157	1.193	1.231	0.028346	-0.001	0.041	0.06	0.024444
20	1.158	1.1946	1.257	0.035653	1.151	1.2085	1.246	0.034387	-0.011	0.0139	0.059	0.027867
30	1.143	1.1718	1.196	0.017687	1.151	1.2089	1.24	0.028026	-0.007	0.0371	0.058	0.023312
50	1.147	1.1706	1.193	0.015233	1.128	1.197	1.232	0.031005	-0.019	0.0264	0.057	0.02706

Device Test: 13.1 CS_EN_TIME(CS_Delay_Vin7p0V_1A)



Test Results (Upper Limit = 5.0 (mSec))

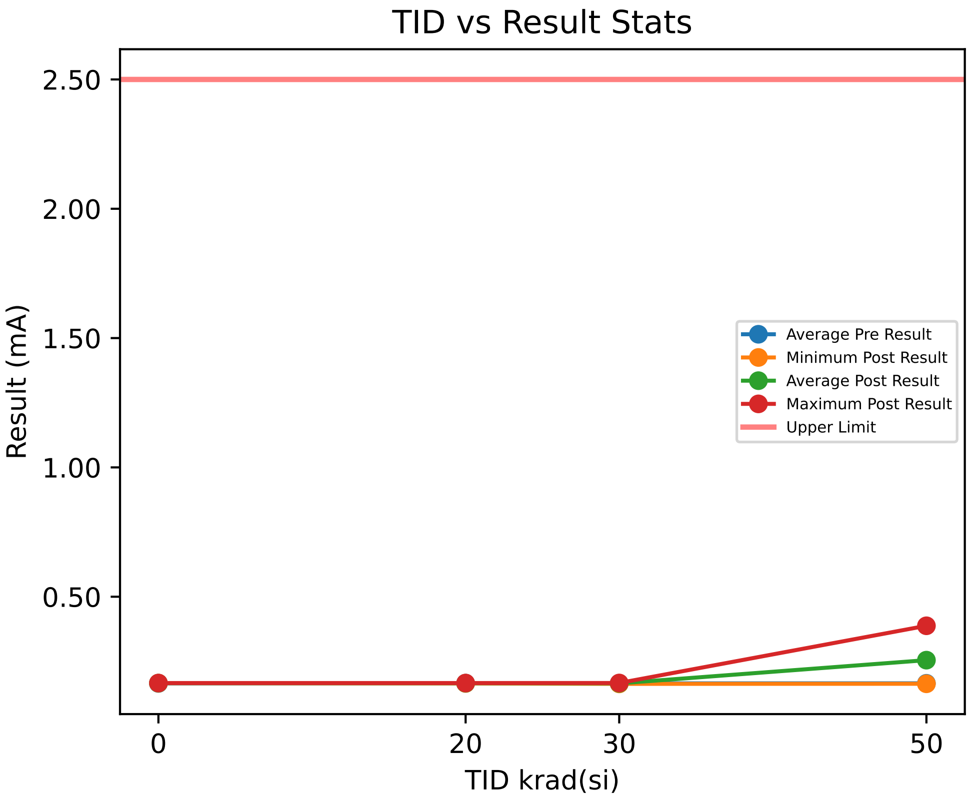
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	1.819	1.825	0.006
2	20	Unbiased	1.678	1.678	0
3	20	Unbiased	1.737	1.735	-0.002
4	20	Unbiased	1.712	1.722	0.01
5	20	Unbiased	1.85	1.842	-0.008
6	20	7V Biased	1.789	1.709	-0.08
7	20	7V Biased	1.814	1.735	-0.079
8	20	7V Biased	1.842	1.736	-0.106
9	20	7V Biased	1.871	1.85	-0.021
10	20	7V Biased	1.835	1.765	-0.07
11	30	Unbiased	1.809	1.721	-0.088
12	30	Unbiased	1.801	1.715	-0.086
13	30	Unbiased	1.823	1.805	-0.018
14	30	Unbiased	1.845	1.764	-0.081
15	30	Unbiased	1.79	1.722	-0.068
16	30	7V Biased	1.828	1.738	-0.09
17	30	7V Biased	1.805	1.782	-0.023
18	30	7V Biased	1.803	1.734	-0.069
19	30	7V Biased	1.816	1.731	-0.085
20	30	7V Biased	1.811	1.704	-0.107
21	50	Unbiased	1.84	1.805	-0.035
22	50	Unbiased	1.854	1.765	-0.089
23	50	Unbiased	1.79	1.734	-0.056
24	50	Unbiased	1.83	1.735	-0.095
25	50	Unbiased	1.848	1.815	-0.033
26	50	7V Biased	1.828	1.732	-0.096
27	50	7V Biased	1.849	1.763	-0.086
28	50	7V Biased	1.836	1.74	-0.096
29	50	7V Biased	1.826	1.787	-0.039
30	50	7V Biased	1.821	1.746	-0.075
31	0	Correlation	1.82	1.731	-0.089
32	0	Correlation	1.855	1.757	-0.098
33	0	Correlation	1.846	1.828	-0.018
34	0	Correlation	1.829	1.756	-0.073
35	0	Correlation	1.84	1.761	-0.079

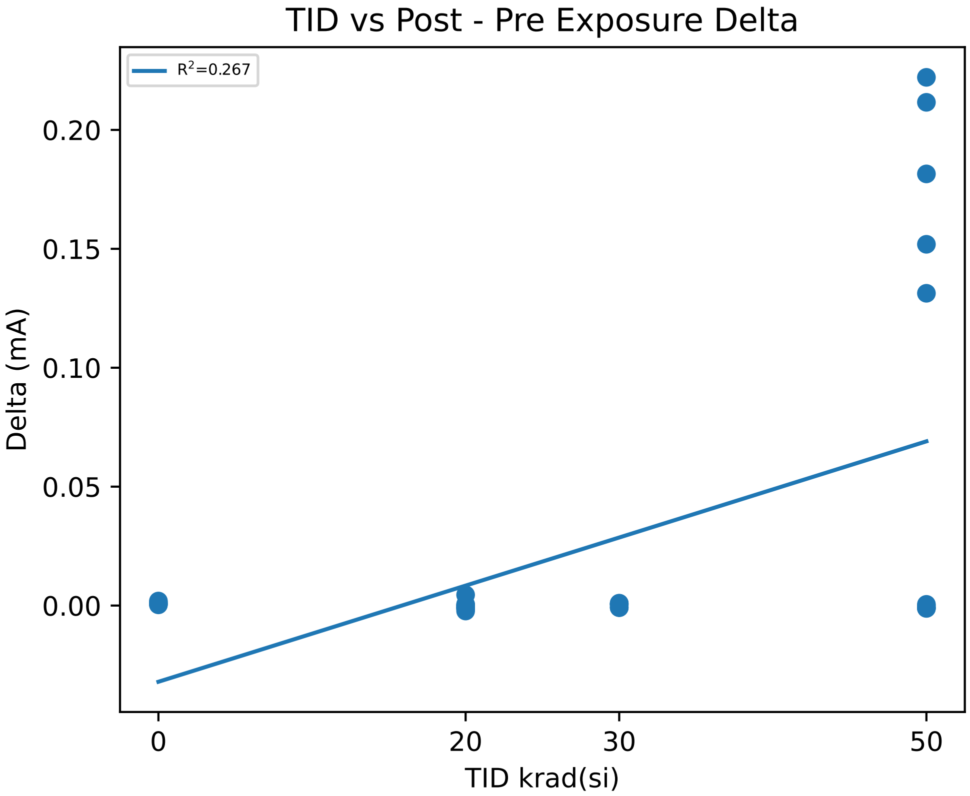


Test Statistics (mSec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.82	1.838	1.855	0.013802	1.731	1.7666	1.828	0.036308	-0.098	-0.0714	-0.018	0.031342
20	1.678	1.7947	1.871	0.06457	1.678	1.7597	1.85	0.059318	-0.106	-0.035	0.01	0.043681
30	1.79	1.8131	1.845	0.015688	1.704	1.7416	1.805	0.032087	-0.107	-0.0715	-0.018	0.029041
50	1.79	1.8322	1.854	0.018408	1.732	1.7622	1.815	0.030633	-0.096	-0.07	-0.033	0.026604

Device Test: 3.1 IRCP_EN_0V(IRCP_1p5V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

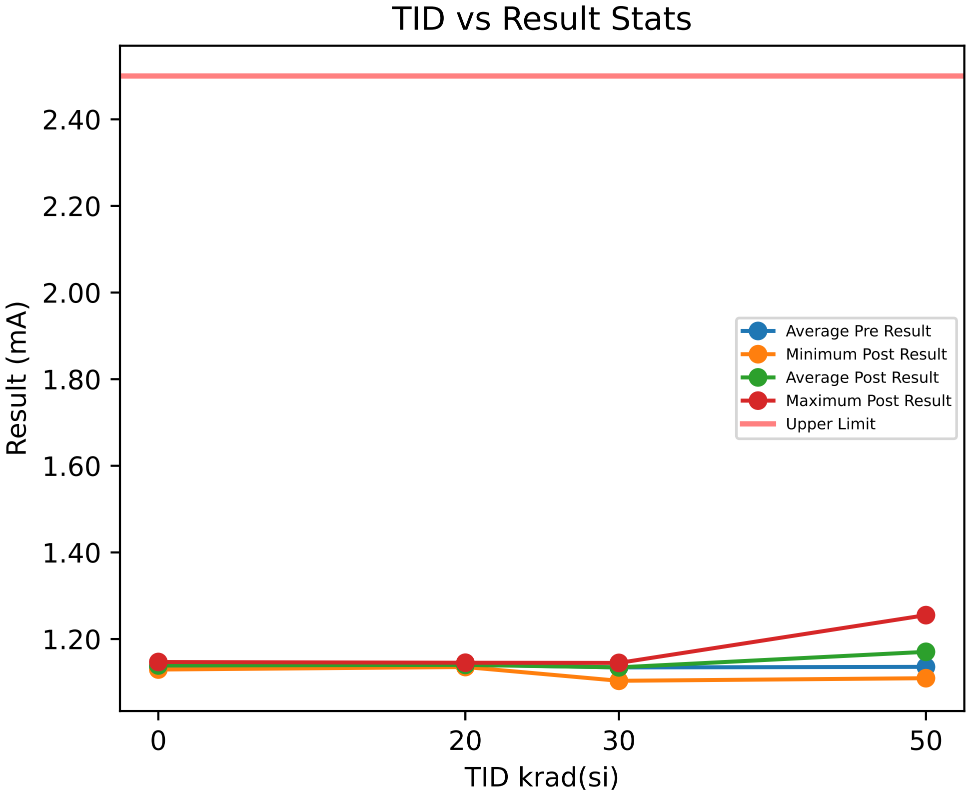
Test Results (Upper Limit = 2.5 (mA))

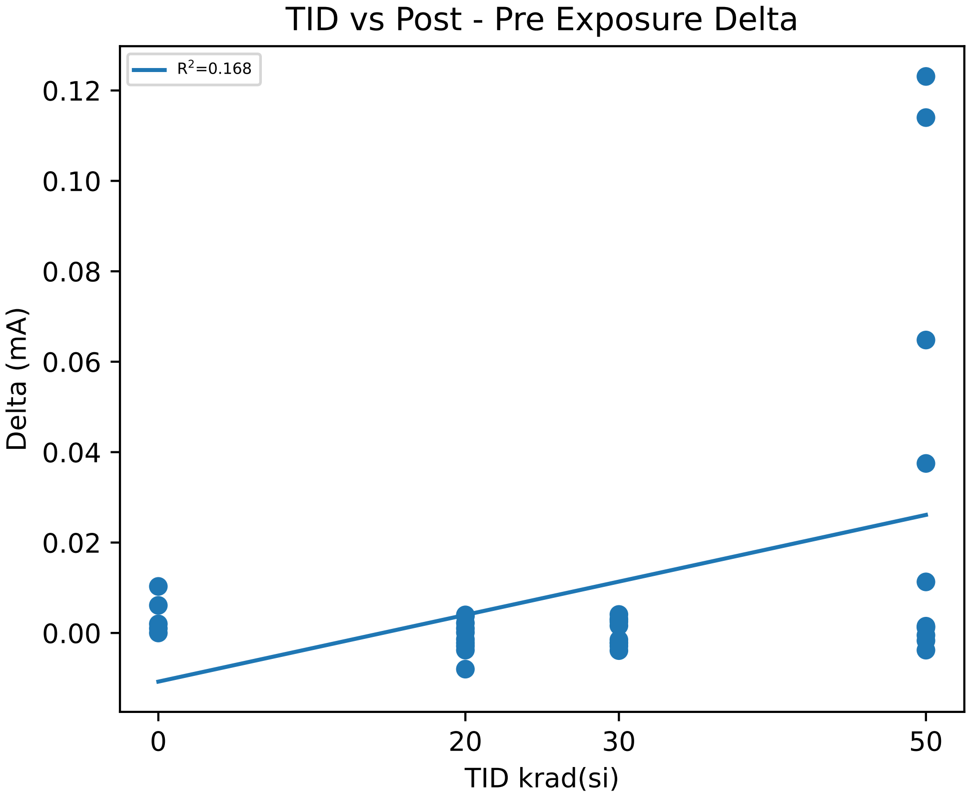
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.1648	0.1647	-0.0001
2	20	Unbiased	0.1674	0.1651	-0.0023
3	20	Unbiased	0.1611	0.1656	0.0045
4	20	Unbiased	0.167	0.1658	-0.0012
5	20	Unbiased	0.1664	0.1655	-0.0009
6	20	7V Biased	0.1657	0.1648	-0.0009
7	20	7V Biased	0.1654	0.1659	0.0005
8	20	7V Biased	0.1659	0.1662	0.0003
9	20	7V Biased	0.1667	0.1653	-0.0014
10	20	7V Biased	0.1659	0.1656	-0.0003
11	30	Unbiased	0.1641	0.1646	0.0005
12	30	Unbiased	0.1631	0.164	0.0009
13	30	Unbiased	0.1638	0.163	-0.0008
14	30	Unbiased	0.1659	0.165	-0.0009
15	30	Unbiased	0.1654	0.1664	0.001
16	30	7V Biased	0.1647	0.1653	0.0006
17	30	7V Biased	0.1653	0.1645	-0.0008
18	30	7V Biased	0.1657	0.1657	0
19	30	7V Biased	0.1655	0.1658	0.0003
20	30	7V Biased	0.1649	0.1657	0.0008
21	50	Unbiased	0.1647	0.1637	-0.001
22	50	Unbiased	0.1644	0.1633	-0.0011
23	50	Unbiased	0.1659	0.1664	0.0005
24	50	Unbiased	0.1653	0.1652	-0.0001
25	50	Unbiased	0.1655	0.1643	-0.0012
26	50	7V Biased	0.1647	0.296	0.1313
27	50	7V Biased	0.1656	0.3175	0.1519
28	50	7V Biased	0.1648	0.3764	0.2116
29	50	7V Biased	0.1655	0.3876	0.2221
30	50	7V Biased	0.165	0.3465	0.1815
31	0	Correlation	0.1643	0.1657	0.0014
32	0	Correlation	0.1653	0.1661	0.0008
33	0	Correlation	0.1654	0.1657	0.0003
34	0	Correlation	0.1643	0.1662	0.0019
35	0	Correlation	0.1649	0.1655	0.0006

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1643	0.16484	0.1654	0.00052726	0.1655	0.16584	0.1662	0.00029665	0.0003	0.001	0.0019	0.0006442
20	0.1611	0.16563	0.1674	0.0017689	0.1647	0.16545	0.1662	0.000479	-0.0023	-0.00018	0.0045	0.0018462
30	0.1631	0.16484	0.1659	0.00091311	0.163	0.165	0.1664	0.0010044	-0.0009	0.00016	0.001	0.00074416
50	0.1644	0.16514	0.1659	0.00048808	0.1633	0.25469	0.3876	0.098412	-0.0012	0.08955	0.2221	0.098415

Device Test: 3.10 IRCP_EN_7V(IRCP_7p0_EN7p0V)





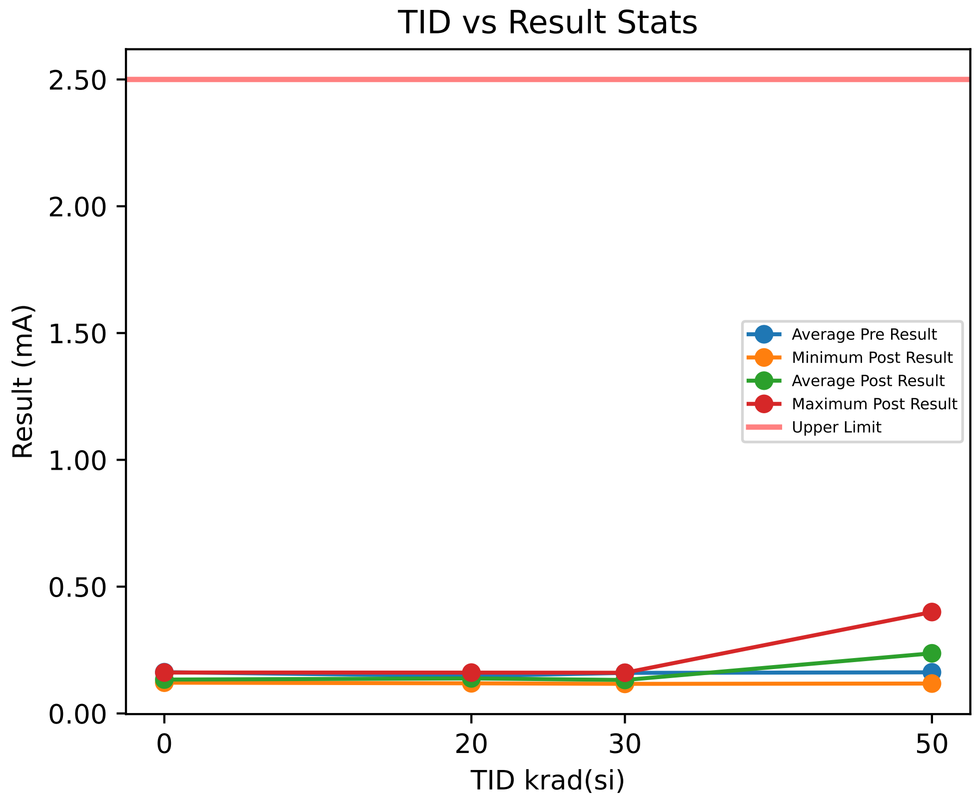
Test Results (Upper Limit = 2.5 (mA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	1.1392	1.1393	0.0001
2	20	Unbiased	1.1392	1.1354	-0.0038
3	20	Unbiased	1.1406	1.1443	0.0037
4	20	Unbiased	1.149	1.141	-0.008
5	20	Unbiased	1.1411	1.1421	0.001
6	20	7V Biased	1.1421	1.1392	-0.0029
7	20	7V Biased	1.1413	1.1453	0.004
8	20	7V Biased	1.14	1.1378	-0.0022
9	20	7V Biased	1.1394	1.1416	0.0022
10	20	7V Biased	1.1384	1.137	-0.0014
11	30	Unbiased	1.1308	1.1339	0.0031
12	30	Unbiased	1.1075	1.1036	-0.0039
13	30	Unbiased	1.1311	1.1336	0.0025
14	30	Unbiased	1.132	1.1299	-0.0021
15	30	Unbiased	1.142	1.1449	0.0029
16	30	7V Biased	1.1363	1.1334	-0.0029
17	30	7V Biased	1.1412	1.1428	0.0016
18	30	7V Biased	1.1423	1.1408	-0.0015
19	30	7V Biased	1.1364	1.1405	0.0041
20	30	7V Biased	1.1451	1.1428	-0.0023
21	50	Unbiased	1.1385	1.14	0.0015
22	50	Unbiased	1.1113	1.1096	-0.0017
23	50	Unbiased	1.1405	1.14	-0.0005
24	50	Unbiased	1.1398	1.136	-0.0038
25	50	Unbiased	1.1416	1.1428	0.0012
26	50	7V Biased	1.1333	1.1446	0.0113
27	50	7V Biased	1.1406	1.1781	0.0375
28	50	7V Biased	1.1408	1.2548	0.114
29	50	7V Biased	1.1321	1.2552	0.1231
30	50	7V Biased	1.1389	1.2037	0.0648
31	0	Correlation	1.1383	1.1444	0.0061
32	0	Correlation	1.1358	1.1358	0
33	0	Correlation	1.1362	1.1382	0.002
34	0	Correlation	1.1286	1.1296	0.001
35	0	Correlation	1.1367	1.147	0.0103

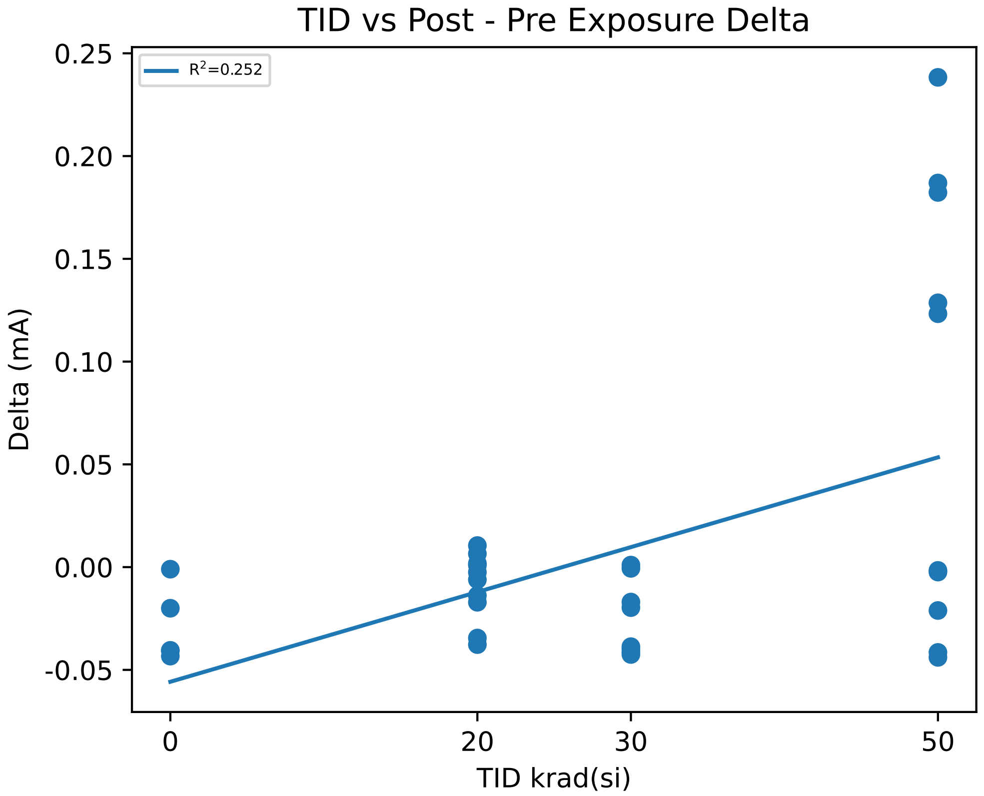
Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.1286	1.1351	1.1383	0.0037666	1.1296	1.139	1.147	0.0069354	0	0.00388	0.0103	0.0042728
20	1.1384	1.141	1.149	0.0030233	1.1354	1.1403	1.1453	0.0031584	-0.008	-0.00073	0.004	0.0037098
30	1.1075	1.1345	1.1451	0.010758	1.1036	1.1346	1.1449	0.012018	-0.0039	0.00015	0.0041	0.0029625
50	1.1113	1.1357	1.1416	0.0091701	1.1096	1.1705	1.2552	0.051249	-0.0038	0.03474	0.1231	0.049256

Device Test: 3.11 IRCP_EN_7V(IRCP_1p5_EN7p0V)



TID vs Result Stats



TID vs Post - Pre Exposure Delta

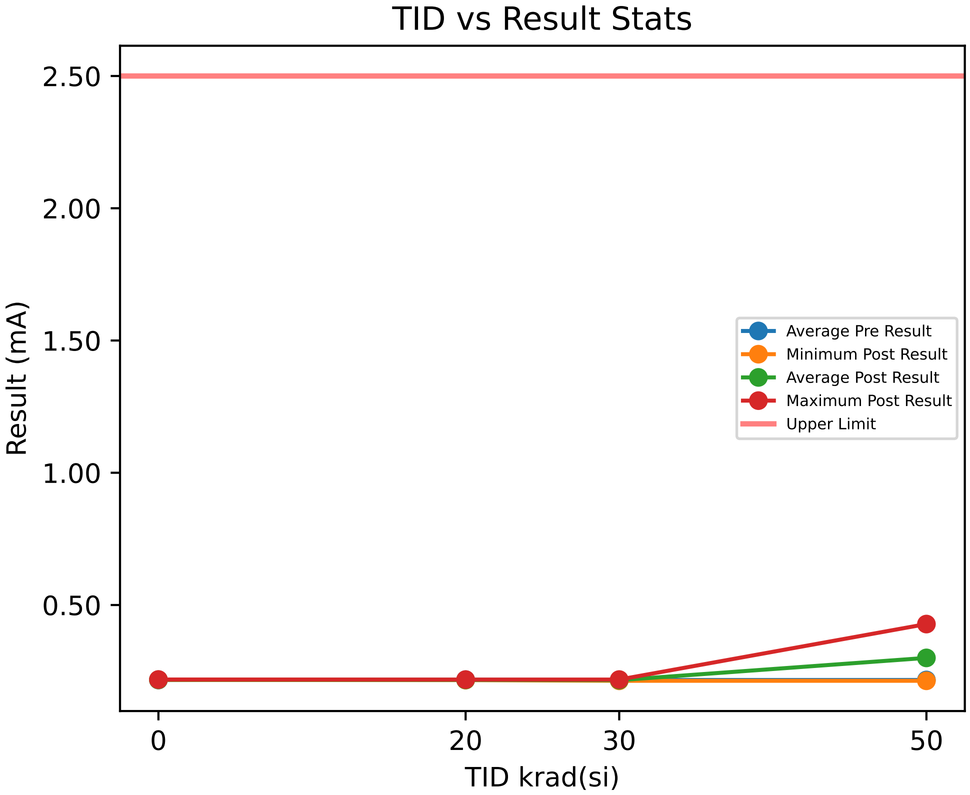
Test Results (Upper Limit = 2.5 (mA))

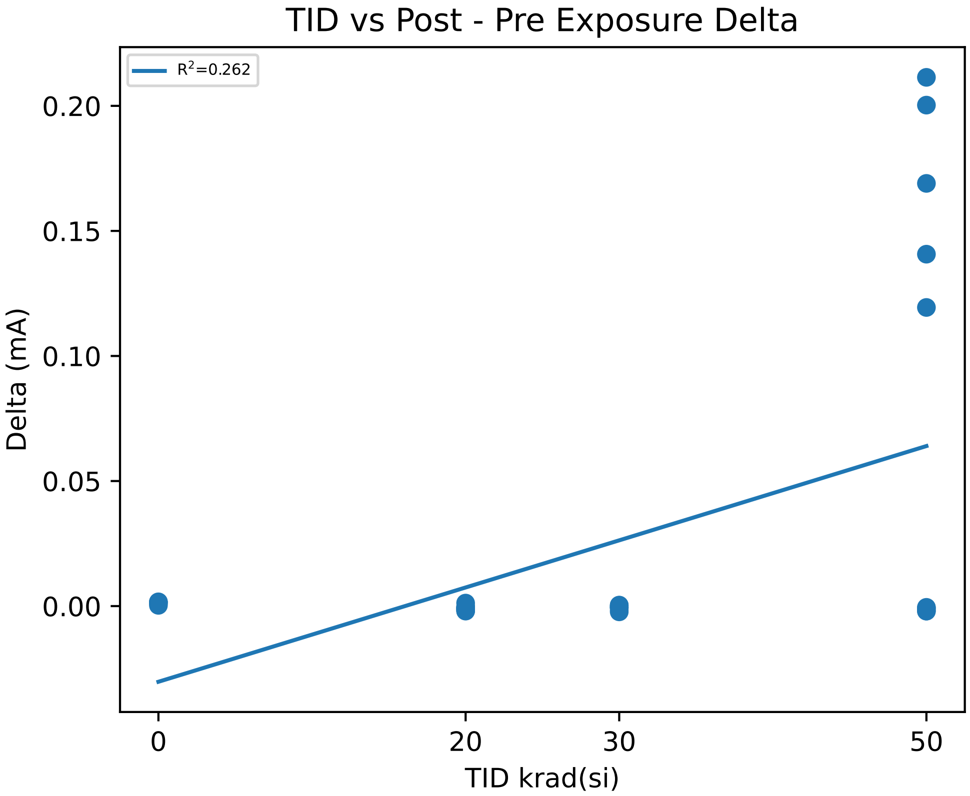
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.1518	0.1583	0.0065
2	20	Unbiased	0.1281	0.1386	0.0105
3	20	Unbiased	0.1244	0.1219	-0.0025
4	20	Unbiased	0.1249	0.1188	-0.0061
5	20	Unbiased	0.1593	0.1602	0.0009
6	20	7V Biased	0.154	0.1402	-0.0138
7	20	7V Biased	0.1559	0.1214	-0.0345
8	20	7V Biased	0.157	0.1193	-0.0377
9	20	7V Biased	0.1592	0.161	0.0018
10	20	7V Biased	0.1583	0.1412	-0.0171
11	30	Unbiased	0.1582	0.1195	-0.0387
12	30	Unbiased	0.1567	0.1166	-0.0401
13	30	Unbiased	0.1586	0.1596	0.001
14	30	Unbiased	0.1587	0.1417	-0.017
15	30	Unbiased	0.1602	0.1207	-0.0395
16	30	7V Biased	0.1601	0.1185	-0.0416
17	30	7V Biased	0.1611	0.1605	-0.0006
18	30	7V Biased	0.1616	0.1419	-0.0197
19	30	7V Biased	0.1618	0.1205	-0.0413
20	30	7V Biased	0.162	0.1195	-0.0425
21	50	Unbiased	0.1613	0.1597	-0.0016
22	50	Unbiased	0.1605	0.1394	-0.0211
23	50	Unbiased	0.1615	0.12	-0.0415
24	50	Unbiased	0.1618	0.1179	-0.0439
25	50	Unbiased	0.1624	0.16	-0.0024
26	50	7V Biased	0.1637	0.2923	0.1286
27	50	7V Biased	0.1625	0.2858	0.1233
28	50	7V Biased	0.1638	0.3461	0.1823
29	50	7V Biased	0.1616	0.3999	0.2383
30	50	7V Biased	0.1624	0.3493	0.1869
31	0	Correlation	0.1619	0.1213	-0.0406
32	0	Correlation	0.1625	0.122	-0.0405
33	0	Correlation	0.1624	0.1614	-0.001
34	0	Correlation	0.1618	0.1418	-0.02
35	0	Correlation	0.1646	0.1213	-0.0433

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1618	0.16264	0.1646	0.0011371	0.1213	0.13356	0.1614	0.017869	-0.0433	-0.02908	-0.001	0.018277
20	0.1244	0.14729	0.1593	0.015036	0.1188	0.13809	0.161	0.017328	-0.0377	-0.0092	0.0105	0.016492
30	0.1567	0.1599	0.162	0.001787	0.1166	0.1319	0.1605	0.017505	-0.0425	-0.028	0.001	0.01747
50	0.1605	0.16215	0.1638	0.0010363	0.1179	0.23704	0.3999	0.10842	-0.0439	0.07489	0.2383	0.10786

Device Test: 3.3 IRCP_EN_0V(IRCP_1p8V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

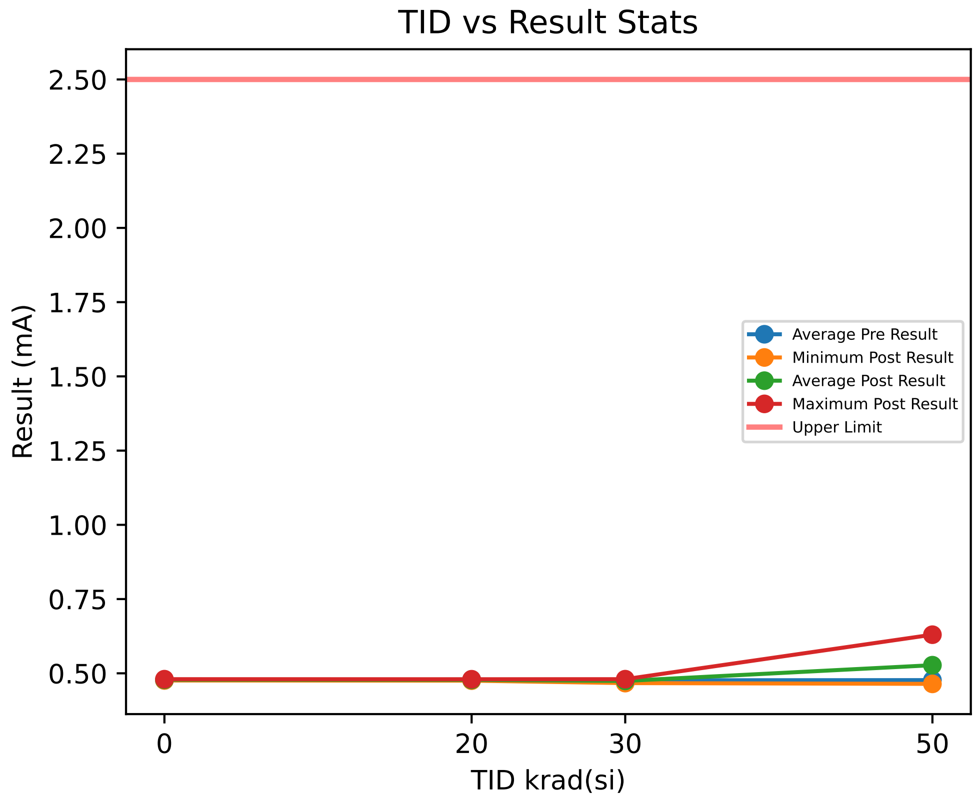
Test Results (Upper Limit = 2.5 (mA))

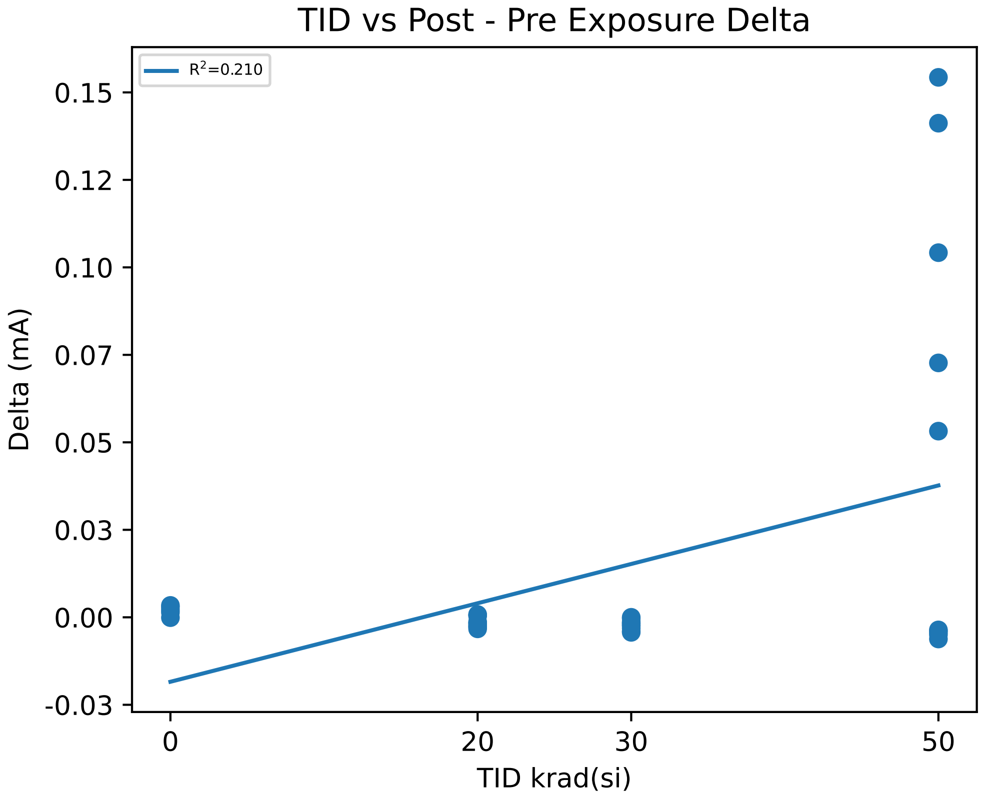
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.2172	0.2163	-0.0009
2	20	Unbiased	0.2181	0.2161	-0.002
3	20	Unbiased	0.2175	0.2168	-0.0007
4	20	Unbiased	0.2188	0.2176	-0.0012
5	20	Unbiased	0.218	0.2164	-0.0016
6	20	7V Biased	0.2175	0.2165	-0.001
7	20	7V Biased	0.2175	0.2174	-0.0001
8	20	7V Biased	0.2169	0.2181	0.0012
9	20	7V Biased	0.2182	0.2163	-0.0019
10	20	7V Biased	0.2166	0.2161	-0.0005
11	30	Unbiased	0.2153	0.2146	-0.0007
12	30	Unbiased	0.2142	0.214	-0.0002
13	30	Unbiased	0.2152	0.2135	-0.0017
14	30	Unbiased	0.2172	0.2166	-0.0006
15	30	Unbiased	0.2176	0.2172	-0.0004
16	30	7V Biased	0.2163	0.2167	0.0004
17	30	7V Biased	0.2174	0.2151	-0.0023
18	30	7V Biased	0.2178	0.217	-0.0008
19	30	7V Biased	0.2165	0.2166	0.0001
20	30	7V Biased	0.2179	0.2182	0.0003
21	50	Unbiased	0.2169	0.2149	-0.002
22	50	Unbiased	0.214	0.2135	-0.0005
23	50	Unbiased	0.2173	0.2166	-0.0007
24	50	Unbiased	0.2178	0.2166	-0.0012
25	50	Unbiased	0.2174	0.2154	-0.002
26	50	7V Biased	0.2159	0.3353	0.1194
27	50	7V Biased	0.2165	0.3572	0.1407
28	50	7V Biased	0.2171	0.4174	0.2003
29	50	7V Biased	0.2166	0.428	0.2114
30	50	7V Biased	0.2169	0.3859	0.169
31	0	Correlation	0.2165	0.2175	0.001
32	0	Correlation	0.2168	0.2184	0.0016
33	0	Correlation	0.2166	0.2169	0.0003
34	0	Correlation	0.2158	0.2173	0.0015
35	0	Correlation	0.2159	0.2176	0.0017

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2158	0.21632	0.2168	0.00044385	0.2169	0.21754	0.2184	0.00055045	0.0003	0.00122	0.0017	0.00058052
20	0.2166	0.21763	0.2188	0.00065668	0.2161	0.21676	0.2181	0.00069952	-0.002	-0.00087	0.0012	0.00094522
30	0.2142	0.21654	0.2179	0.0012738	0.2135	0.21595	0.2182	0.0015451	-0.0023	-0.00059	0.0004	0.00085952
50	0.214	0.21664	0.2178	0.0010669	0.2135	0.30008	0.428	0.093009	-0.002	0.08344	0.2114	0.092983

Device Test: 3.5 IRCP_EN_0V(IRCP_3p3V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

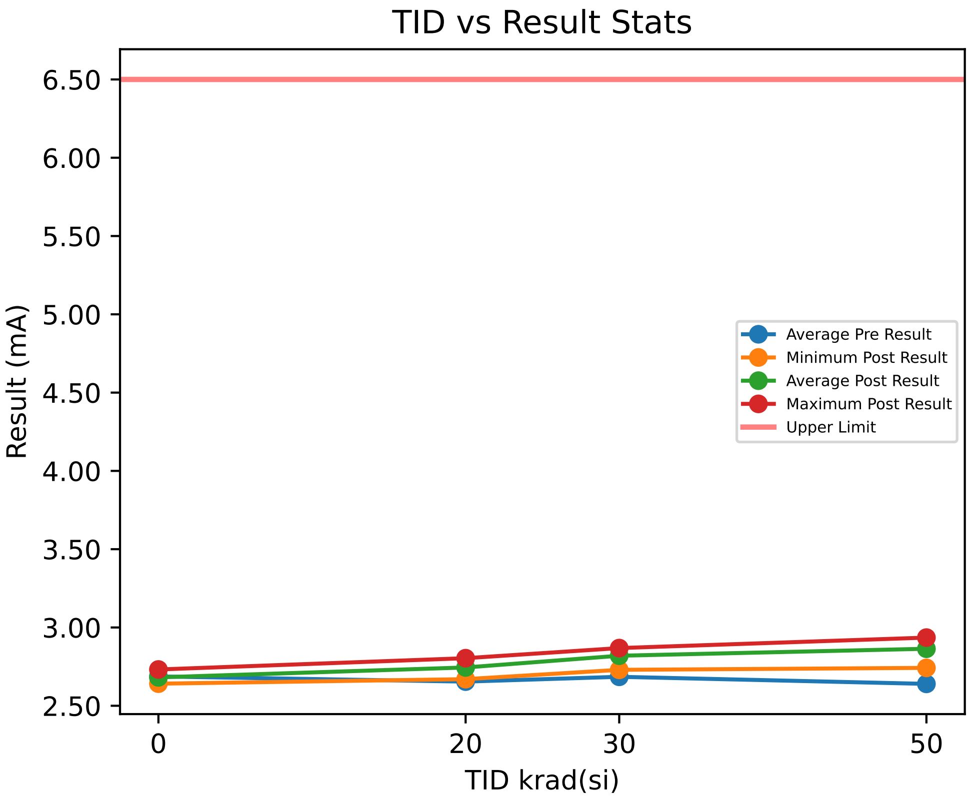
Test Results (Upper Limit = 2.5 (mA))

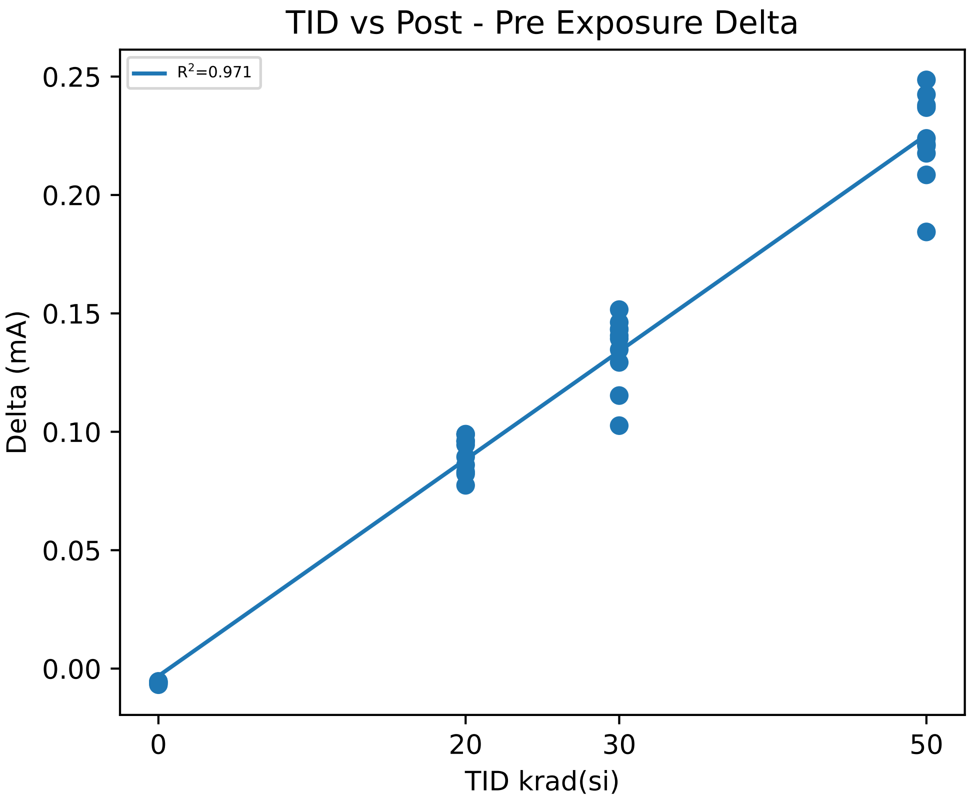
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.4778	0.4752	-0.0026
2	20	Unbiased	0.4794	0.4761	-0.0033
3	20	Unbiased	0.478	0.4787	0.0007
4	20	Unbiased	0.4828	0.48	-0.0028
5	20	Unbiased	0.4798	0.478	-0.0018
6	20	7V Biased	0.4788	0.4772	-0.0016
7	20	7V Biased	0.4792	0.4796	0.0004
8	20	7V Biased	0.4786	0.4794	0.0008
9	20	7V Biased	0.4794	0.4771	-0.0023
10	20	7V Biased	0.4781	0.4768	-0.0013
11	30	Unbiased	0.474	0.4717	-0.0023
12	30	Unbiased	0.467	0.467	0
13	30	Unbiased	0.4746	0.4706	-0.004
14	30	Unbiased	0.4761	0.4737	-0.0024
15	30	Unbiased	0.4799	0.4756	-0.0043
16	30	7V Biased	0.4768	0.4751	-0.0017
17	30	7V Biased	0.4787	0.4756	-0.0031
18	30	7V Biased	0.4792	0.4779	-0.0013
19	30	7V Biased	0.4773	0.4755	-0.0018
20	30	7V Biased	0.4805	0.4802	-0.0003
21	50	Unbiased	0.4775	0.4725	-0.005
22	50	Unbiased	0.4688	0.4644	-0.0044
23	50	Unbiased	0.4783	0.4744	-0.0039
24	50	Unbiased	0.4789	0.4753	-0.0036
25	50	Unbiased	0.4792	0.473	-0.0062
26	50	7V Biased	0.4765	0.5297	0.0532
27	50	7V Biased	0.4787	0.5514	0.0727
28	50	7V Biased	0.4793	0.6205	0.1412
29	50	7V Biased	0.4757	0.63	0.1543
30	50	7V Biased	0.4778	0.582	0.1042
31	0	Correlation	0.477	0.4791	0.0021
32	0	Correlation	0.4768	0.4802	0.0034
33	0	Correlation	0.4772	0.4771	-0.0001
34	0	Correlation	0.4745	0.4759	0.0014
35	0	Correlation	0.4763	0.4792	0.0029

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.4745	0.47636	0.4772	0.0010922	0.4759	0.4783	0.4802	0.0017507	-0.0001	0.00194	0.0034	0.0013722
20	0.4778	0.47919	0.4828	0.0014348	0.4752	0.47781	0.48	0.0015982	-0.0033	-0.00138	0.0008	0.0015098
30	0.467	0.47641	0.4805	0.0039526	0.467	0.47429	0.4802	0.0037613	-0.0043	-0.00212	0	0.0014188
50	0.4688	0.47707	0.4793	0.003133	0.4644	0.52732	0.63	0.065169	-0.0062	0.05025	0.1543	0.064618

Device Test: 3.6 IQ_VIN_5V(IQ_Vin_5p0V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

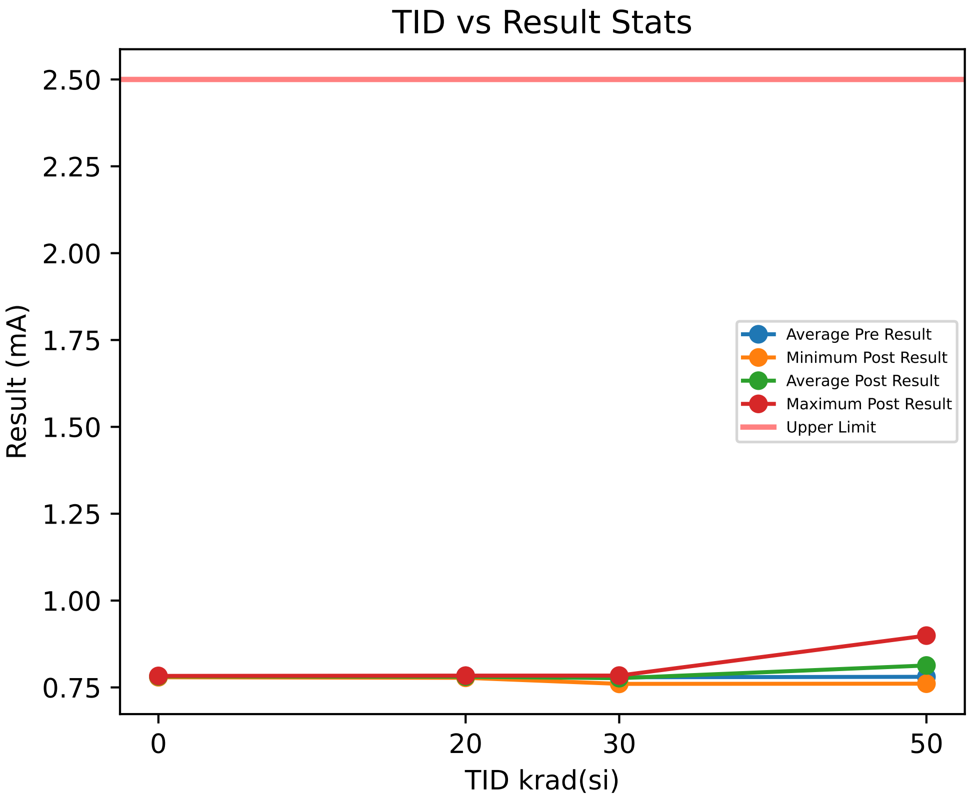
Test Results (Upper Limit = 6.5 (mA))

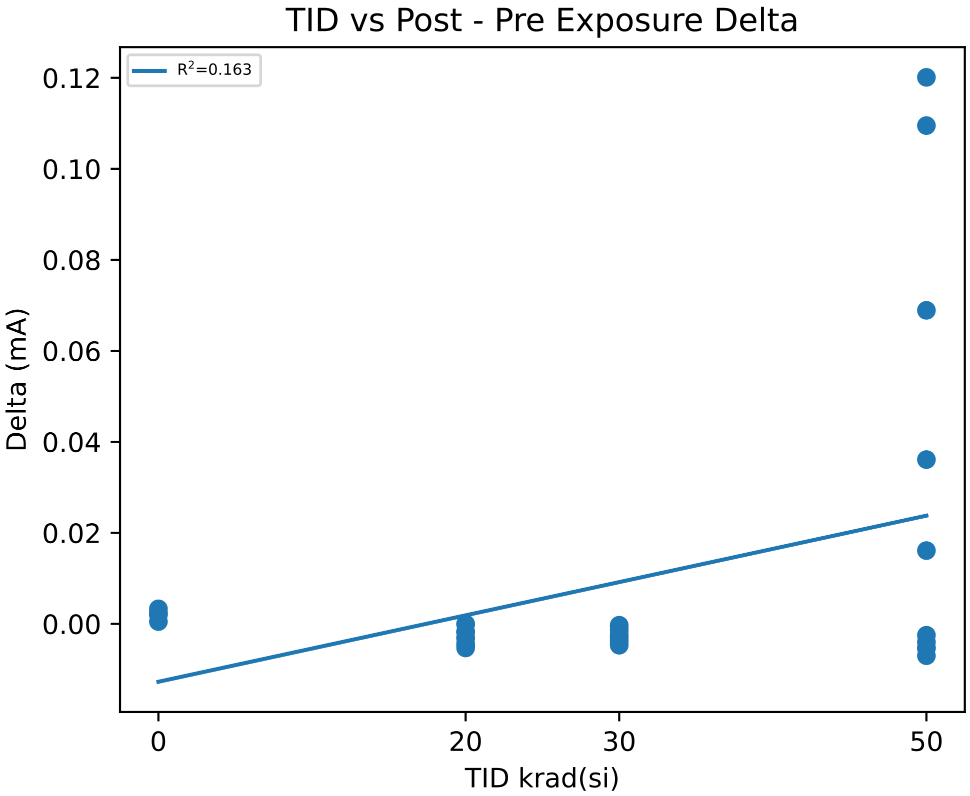
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	2.6567	2.7528	0.0961
2	20	Unbiased	2.7104	2.7964	0.086
3	20	Unbiased	2.6571	2.7531	0.096
4	20	Unbiased	2.7048	2.8038	0.099
5	20	Unbiased	2.6368	2.7199	0.0831
6	20	7V Biased	2.655	2.7495	0.0945
7	20	7V Biased	2.638	2.7274	0.0894
8	20	7V Biased	2.6593	2.7415	0.0822
9	20	7V Biased	2.5711	2.67	0.0989
10	20	7V Biased	2.6538	2.7312	0.0774
11	30	Unbiased	2.7169	2.8603	0.1434
12	30	Unbiased	2.6142	2.7295	0.1153
13	30	Unbiased	2.6789	2.8305	0.1516
14	30	Unbiased	2.6803	2.8196	0.1393
15	30	Unbiased	2.7009	2.8302	0.1293
16	30	7V Biased	2.6523	2.7929	0.1406
17	30	7V Biased	2.6908	2.7934	0.1026
18	30	7V Biased	2.6683	2.803	0.1347
19	30	7V Biased	2.7253	2.8684	0.1431
20	30	7V Biased	2.7215	2.8677	0.1462
21	50	Unbiased	2.6954	2.913	0.2176
22	50	Unbiased	2.5576	2.742	0.1844
23	50	Unbiased	2.651	2.8879	0.2369
24	50	Unbiased	2.6196	2.8682	0.2486
25	50	Unbiased	2.6193	2.8572	0.2379
26	50	7V Biased	2.5906	2.8145	0.2239
27	50	7V Biased	2.6424	2.8631	0.2207
28	50	7V Biased	2.6695	2.878	0.2085
29	50	7V Biased	2.639	2.8814	0.2424
30	50	7V Biased	2.7139	2.9353	0.2214
31	0	Correlation	2.738	2.7317	-0.0063
32	0	Correlation	2.6702	2.6647	-0.0055
33	0	Correlation	2.6602	2.6534	-0.0068
34	0	Correlation	2.6465	2.6411	-0.0054
35	0	Correlation	2.7216	2.7157	-0.0059

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6465	2.6873	2.738	0.04012	2.6411	2.6813	2.7317	0.03998	-0.0068	-0.00598	-0.0054	0.00058052
20	2.5711	2.6543	2.7104	0.038342	2.67	2.7446	2.8038	0.038023	0.0774	0.09026	0.099	0.0077213
30	2.6142	2.6849	2.7253	0.034449	2.7295	2.8196	2.8684	0.042656	0.1026	0.13461	0.1516	0.015114
50	2.5576	2.6398	2.7139	0.04667	2.742	2.8641	2.9353	0.0537	0.1844	0.22423	0.2486	0.018767

Device Test: 3.7 IRCP_EN_0V(IRCP_5p0V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

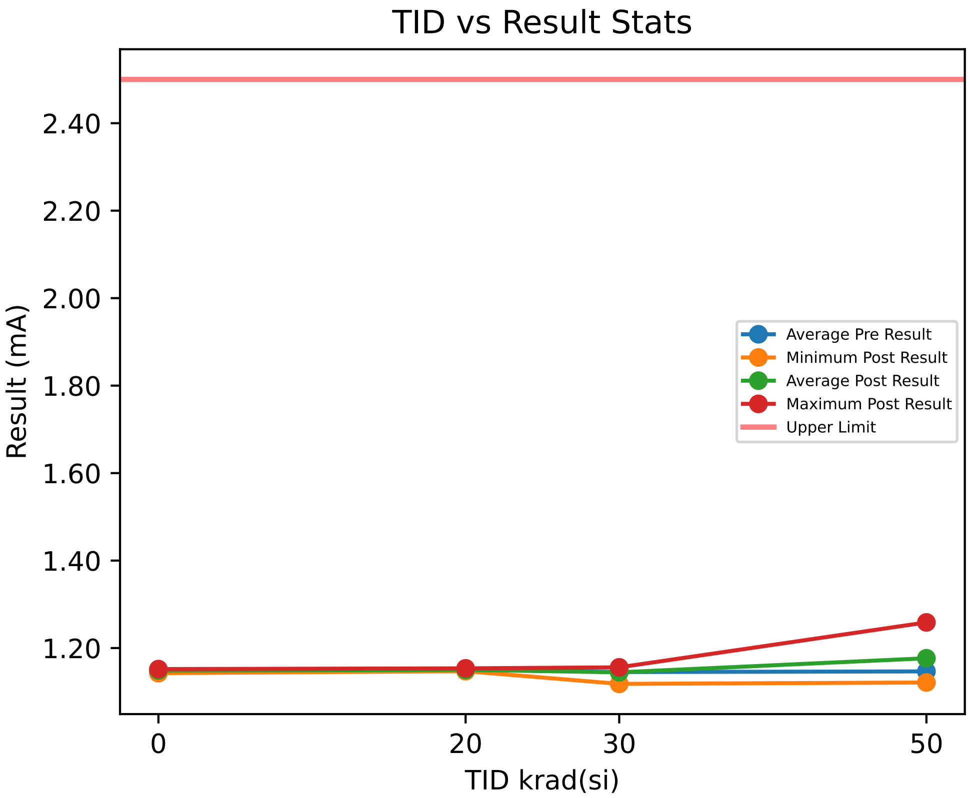
Test Results (Upper Limit = 2.5 (mA))

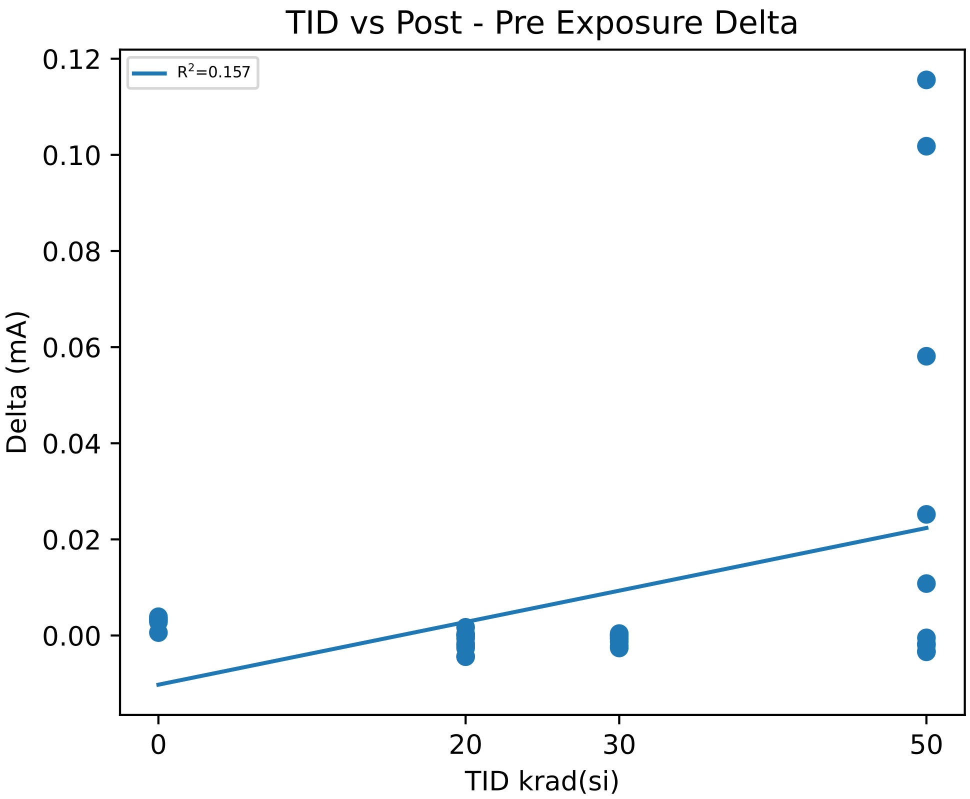
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.7807	0.7776	-0.0031
2	20	Unbiased	0.7837	0.7784	-0.0053
3	20	Unbiased	0.7811	0.7811	0
4	20	Unbiased	0.7882	0.7839	-0.0043
5	20	Unbiased	0.7848	0.78	-0.0048
6	20	7V Biased	0.7833	0.7815	-0.0018
7	20	7V Biased	0.7843	0.7825	-0.0018
8	20	7V Biased	0.7826	0.7825	-0.0001
9	20	7V Biased	0.7837	0.7806	-0.0031
10	20	7V Biased	0.7814	0.7797	-0.0017
11	30	Unbiased	0.7755	0.7741	-0.0014
12	30	Unbiased	0.7649	0.7602	-0.0047
13	30	Unbiased	0.7752	0.7723	-0.0029
14	30	Unbiased	0.7771	0.7736	-0.0035
15	30	Unbiased	0.7841	0.7818	-0.0023
16	30	7V Biased	0.7791	0.7785	-0.0006
17	30	7V Biased	0.7838	0.7796	-0.0042
18	30	7V Biased	0.7857	0.782	-0.0037
19	30	7V Biased	0.7796	0.7793	-0.0003
20	30	7V Biased	0.787	0.7841	-0.0029
21	50	Unbiased	0.7815	0.7763	-0.0052
22	50	Unbiased	0.7677	0.7607	-0.007
23	50	Unbiased	0.7821	0.7781	-0.004
24	50	Unbiased	0.7825	0.78	-0.0025
25	50	Unbiased	0.7828	0.7774	-0.0054
26	50	7V Biased	0.7809	0.797	0.0161
27	50	7V Biased	0.7838	0.8199	0.0361
28	50	7V Biased	0.7832	0.8927	0.1095
29	50	7V Biased	0.779	0.8991	0.1201
30	50	7V Biased	0.7814	0.8503	0.0689
31	0	Correlation	0.7811	0.7831	0.002
32	0	Correlation	0.7793	0.7826	0.0033
33	0	Correlation	0.7813	0.7818	0.0005
34	0	Correlation	0.7771	0.7792	0.0021
35	0	Correlation	0.7795	0.7821	0.0026

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.7771	0.77966	0.7813	0.0016935	0.7792	0.78176	0.7831	0.0015143	0.0005	0.0021	0.0033	0.001032
20	0.7807	0.78338	0.7882	0.0021913	0.7776	0.78078	0.7839	0.0019395	-0.0053	-0.0026	0	0.0018445
30	0.7649	0.7792	0.787	0.0065576	0.7602	0.77655	0.7841	0.0069524	-0.0047	-0.00265	-0.0003	0.0014894
50	0.7677	0.78049	0.7838	0.0046915	0.7607	0.81315	0.8991	0.05068	-0.007	0.03266	0.1201	0.049648

Device Test: 3.9 IRCP_EN_0V(IRCP_7p0V)





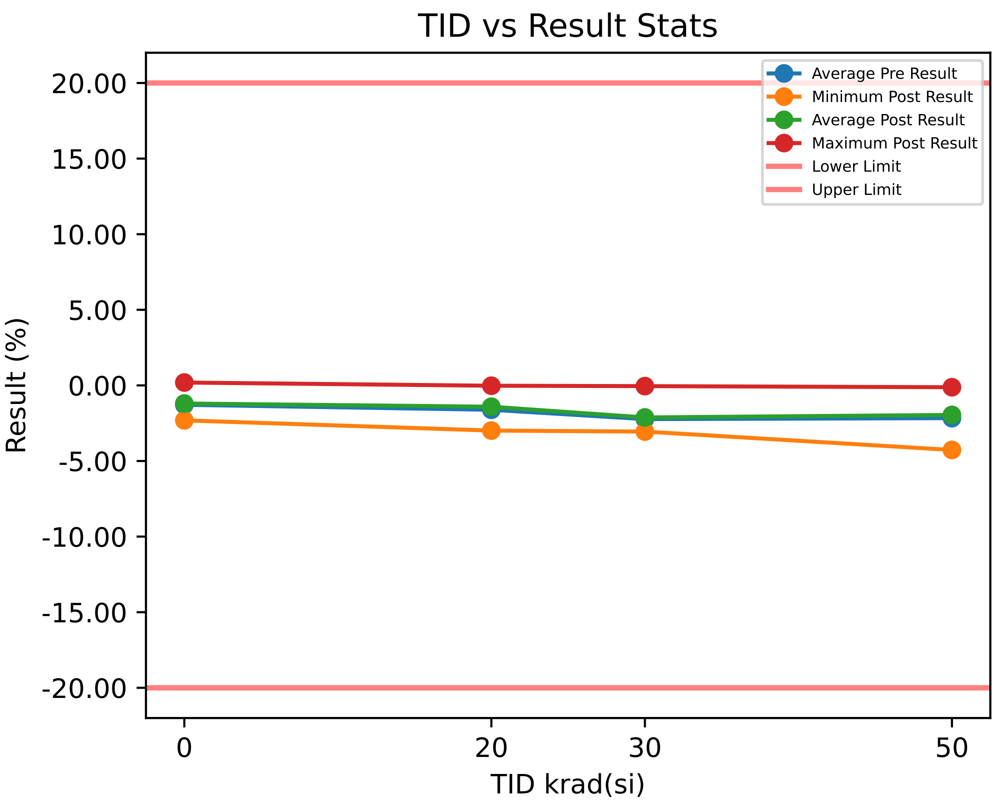
Test Results (Upper Limit = 2.5 (mA))

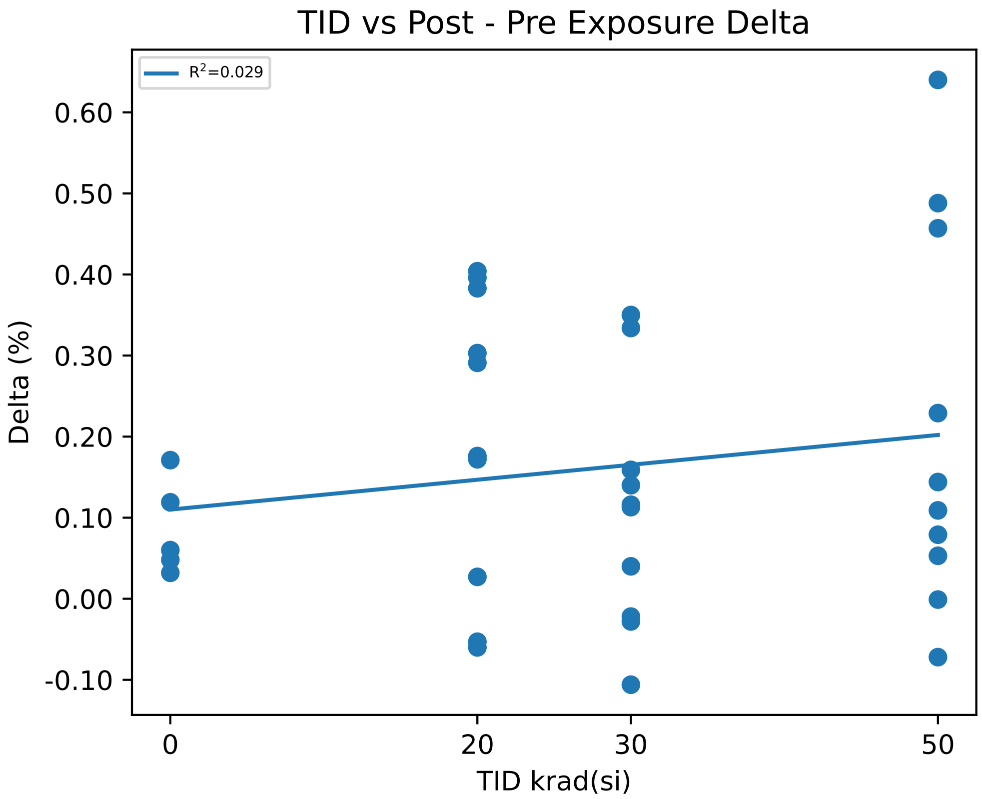
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	1.1492	1.1471	-0.0021
2	20	Unbiased	1.1525	1.1481	-0.0044
3	20	Unbiased	1.1502	1.1503	0.0001
4	20	Unbiased	1.158	1.1536	-0.0044
5	20	Unbiased	1.1514	1.1488	-0.0026
6	20	7V Biased	1.1517	1.1517	0
7	20	7V Biased	1.1517	1.1511	-0.0006
8	20	7V Biased	1.1502	1.1519	0.0017
9	20	7V Biased	1.1508	1.1491	-0.0017
10	20	7V Biased	1.1491	1.1494	0.0003
11	30	Unbiased	1.141	1.141	0
12	30	Unbiased	1.1187	1.1181	-0.0006
13	30	Unbiased	1.1417	1.1391	-0.0026
14	30	Unbiased	1.1427	1.1414	-0.0013
15	30	Unbiased	1.1524	1.1517	-0.0007
16	30	7V Biased	1.147	1.1472	0.0002
17	30	7V Biased	1.1516	1.1494	-0.0022
18	30	7V Biased	1.1532	1.1529	-0.0003
19	30	7V Biased	1.1479	1.1479	0
20	30	7V Biased	1.1555	1.1559	0.0004
21	50	Unbiased	1.1494	1.146	-0.0034
22	50	Unbiased	1.1232	1.1212	-0.002
23	50	Unbiased	1.1493	1.1476	-0.0017
24	50	Unbiased	1.1508	1.1503	-0.0005
25	50	Unbiased	1.1526	1.1493	-0.0033
26	50	7V Biased	1.1441	1.1549	0.0108
27	50	7V Biased	1.1517	1.1769	0.0252
28	50	7V Biased	1.1517	1.2535	0.1018
29	50	7V Biased	1.143	1.2586	0.1156
30	50	7V Biased	1.1501	1.2082	0.0581
31	0	Correlation	1.1491	1.1519	0.0028
32	0	Correlation	1.1462	1.1501	0.0039
33	0	Correlation	1.1471	1.1477	0.0006
34	0	Correlation	1.1394	1.1426	0.0032
35	0	Correlation	1.1472	1.1507	0.0035

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.1394	1.1458	1.1491	0.0037303	1.1426	1.1486	1.1519	0.0036865	0.0006	0.0028	0.0039	0.0012942
20	1.1491	1.1515	1.158	0.0025442	1.1471	1.1501	1.1536	0.0019796	-0.0044	-0.00137	0.0017	0.0020375
30	1.1187	1.1452	1.1555	0.010603	1.1181	1.1445	1.1559	0.010766	-0.0026	-0.00071	0.0004	0.0010214
50	1.1232	1.1466	1.1526	0.008818	1.1212	1.1766	1.2586	0.047599	-0.0034	0.03006	0.1156	0.045762

Device Test: 30.11 Current_Limit_Accuracy(Accuracy_Ilim_2A_1p5V)





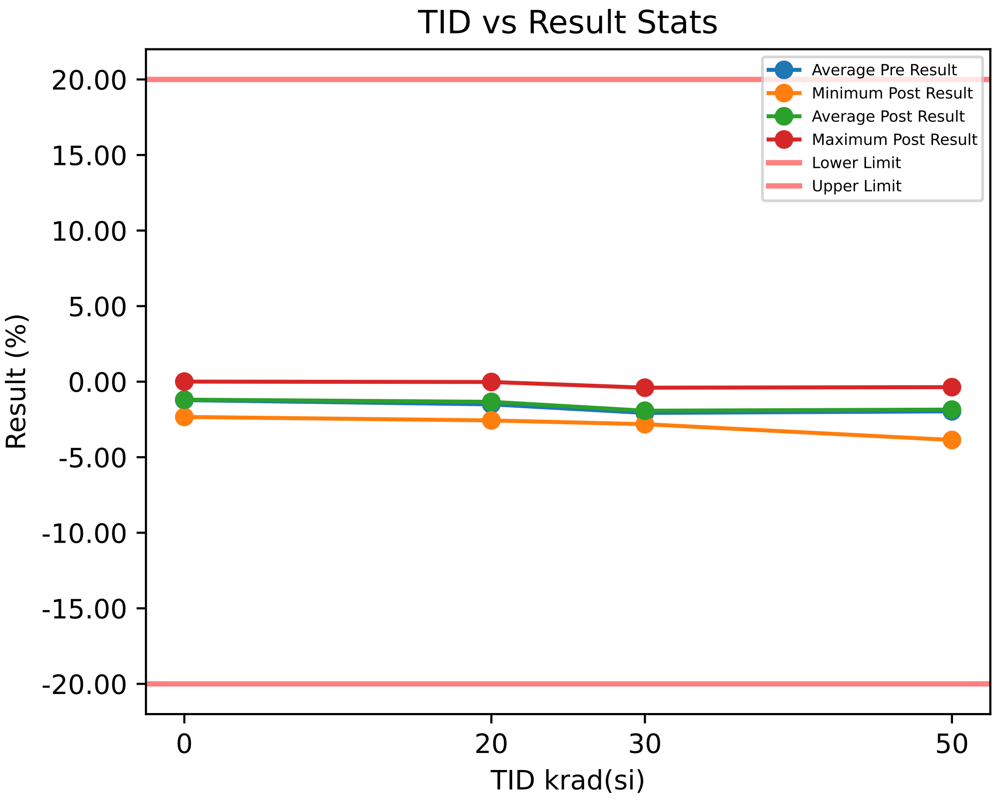
Test Results (Lower Limit = -20.0, Upper Limit = 20.0 (%))

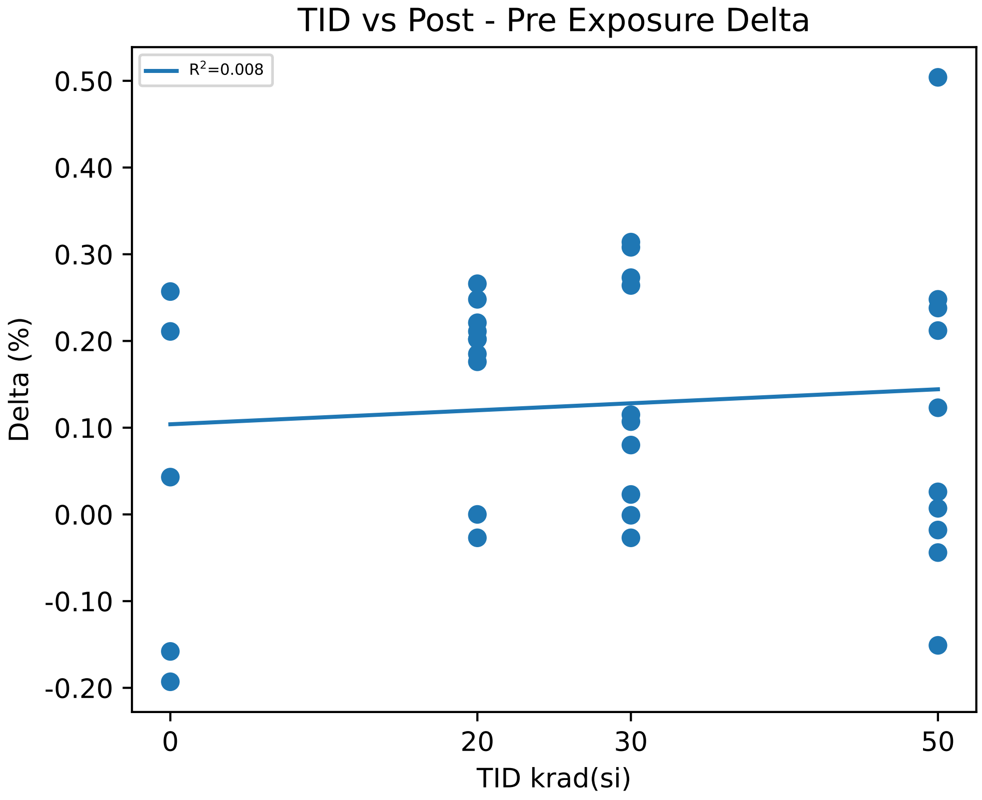
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	-1.791	-1.844	-0.053
2	20	Unbiased	-3.12	-2.724	0.396
3	20	Unbiased	-1.321	-1.018	0.303
4	20	Unbiased	-1.713	-1.422	0.291
5	20	Unbiased	-0.458	-0.075	0.383
6	20	7V Biased	-0.431	-0.491	-0.06
7	20	7V Biased	-2.491	-2.087	0.404
8	20	7V Biased	-0.194	-0.022	0.172
9	20	7V Biased	-1.448	-1.421	0.027
10	20	7V Biased	-3.164	-2.988	0.176
11	30	Unbiased	-3.375	-3.025	0.35
12	30	Unbiased	-3.124	-3.008	0.116
13	30	Unbiased	-2.742	-2.702	0.04
14	30	Unbiased	-3.032	-2.698	0.334
15	30	Unbiased	-0.827	-0.714	0.113
16	30	7V Biased	-0.207	-0.048	0.159
17	30	7V Biased	-2.728	-2.834	-0.106
18	30	7V Biased	-3.032	-3.054	-0.022
19	30	7V Biased	-0.524	-0.384	0.14
20	30	7V Biased	-2.702	-2.73	-0.028
21	50	Unbiased	-3.111	-3.032	0.079
22	50	Unbiased	-3.389	-3.16	0.229
23	50	Unbiased	-0.854	-0.397	0.457
24	50	Unbiased	-1.699	-1.7	-0.001
25	50	Unbiased	-3.164	-2.676	0.488
26	50	7V Biased	-4.379	-4.27	0.109
27	50	7V Biased	-0.365	-0.437	-0.072
28	50	7V Biased	-1.791	-1.647	0.144
29	50	7V Biased	-2.148	-2.095	0.053
30	50	7V Biased	-0.761	-0.121	0.64
31	0	Correlation	-2.148	-2.1	0.048
32	0	Correlation	-0.51	-0.391	0.119
33	0	Correlation	0.018	0.189	0.171
34	0	Correlation	-1.408	-1.376	0.032
35	0	Correlation	-2.372	-2.312	0.06

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-2.372	-1.284	0.018	1.0296	-2.312	-1.198	0.189	1.0795	0.032	0.086	0.171	0.057771
20	-3.164	-1.6131	-0.194	1.0722	-2.988	-1.4092	-0.022	1.0312	-0.06	0.2039	0.404	0.18109
30	-3.375	-2.2293	-0.207	1.2065	-3.054	-2.1197	-0.048	1.2165	-0.106	0.1096	0.35	0.14875
50	-4.379	-2.1661	-0.365	1.3157	-4.27	-1.9535	-0.121	1.3649	-0.072	0.2126	0.64	0.23662

Device Test: 30.15 Current_Limit_Accuracy(Accuracy_Ilim_3A_1p5V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

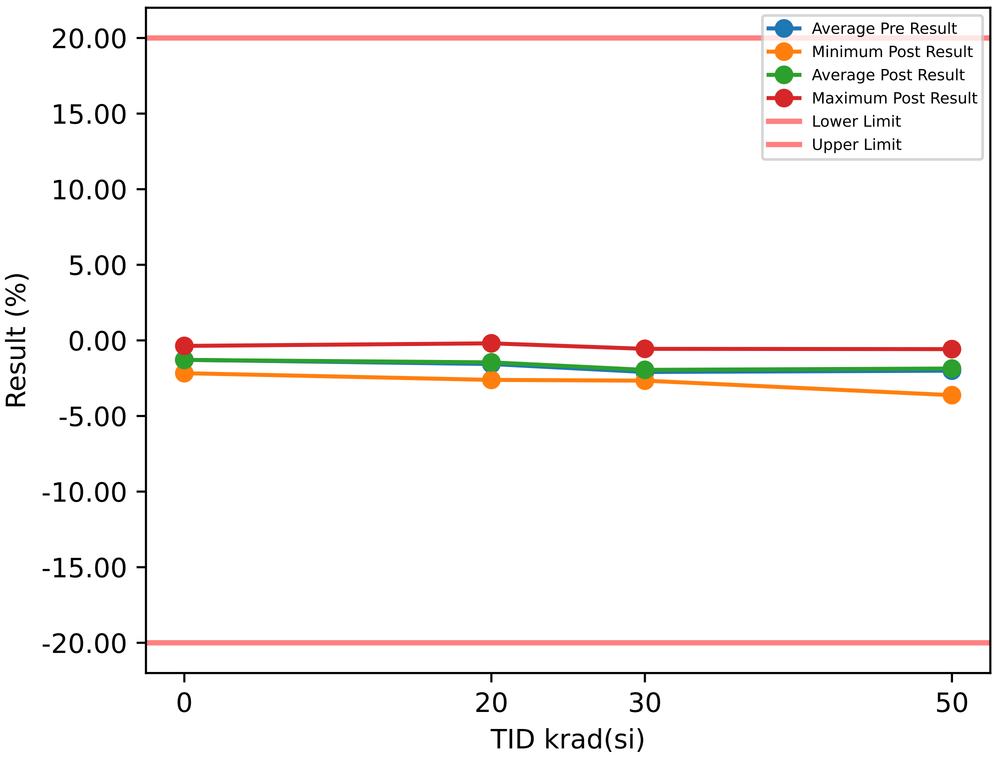
Test Results (Lower Limit = -20.0, Upper Limit = 20.0 (%))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	-1.685	-1.712	-0.027
2	20	Unbiased	-2.786	-2.565	0.221
3	20	Unbiased	-1.235	-1.033	0.202
4	20	Unbiased	-1.502	-1.502	0
5	20	Unbiased	-0.427	-0.251	0.176
6	20	7V Biased	-0.656	-0.39	0.266
7	20	7V Biased	-2.372	-2.124	0.248
8	20	7V Biased	-0.207	-0.022	0.185
9	20	7V Biased	-1.527	-1.325	0.202
10	20	7V Biased	-2.627	-2.416	0.211
11	30	Unbiased	-2.812	-2.732	0.08
12	30	Unbiased	-2.838	-2.815	0.023
13	30	Unbiased	-2.68	-2.416	0.264
14	30	Unbiased	-2.821	-2.513	0.308
15	30	Unbiased	-0.717	-0.602	0.115
16	30	7V Biased	-0.409	-0.41	-0.001
17	30	7V Biased	-2.407	-2.434	-0.027
18	30	7V Biased	-2.83	-2.557	0.273
19	30	7V Biased	-0.506	-0.399	0.107
20	30	7V Biased	-2.662	-2.348	0.314
21	50	Unbiased	-2.777	-2.821	-0.044
22	50	Unbiased	-2.997	-3.015	-0.018
23	50	Unbiased	-0.576	-0.364	0.212
24	50	Unbiased	-1.527	-1.678	-0.151
25	50	Unbiased	-2.83	-2.592	0.238
26	50	7V Biased	-3.886	-3.86	0.026
27	50	7V Biased	-0.612	-0.364	0.248
28	50	7V Biased	-1.712	-1.705	0.007
29	50	7V Biased	-1.835	-1.712	0.123
30	50	7V Biased	-0.885	-0.381	0.504
31	0	Correlation	-1.897	-1.64	0.257
32	0	Correlation	-0.497	-0.454	0.043
33	0	Correlation	-0.207	0.004	0.211
34	0	Correlation	-1.333	-1.526	-0.193
35	0	Correlation	-2.178	-2.336	-0.158

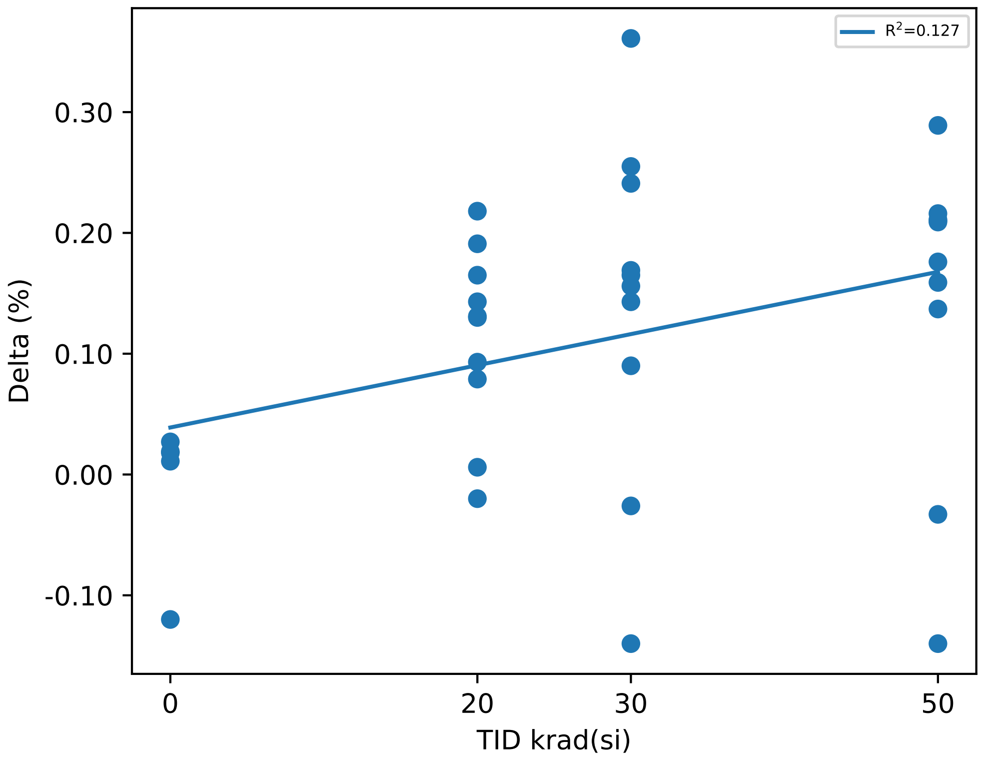
Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-2.178	-1.2224	-0.207	0.85699	-2.336	-1.1904	0.004	0.94816	-0.193	0.032	0.257	0.20586
20	-2.786	-1.5024	-0.207	0.90215	-2.565	-1.334	-0.022	0.90415	-0.027	0.1684	0.266	0.099763
30	-2.838	-2.0682	-0.409	1.0622	-2.815	-1.9226	-0.399	1.0133	-0.027	0.1456	0.314	0.13251
50	-3.886	-1.9637	-0.576	1.1236	-3.86	-1.8492	-0.364	1.2263	-0.151	0.1145	0.504	0.19059

Device Test: 30.19 Current_Limit_Accuracy(Accuracy_Ilim_4A_1p5V)



TID vs Result Stats



TID vs Post - Pre Exposure Delta

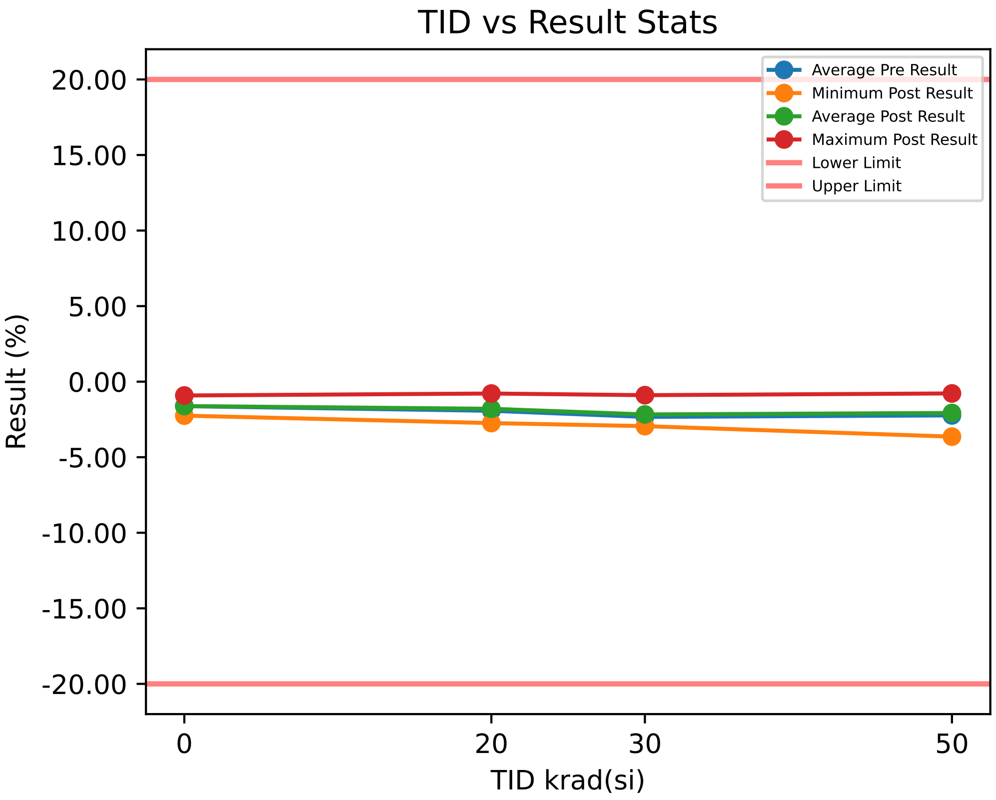
Test Results (Lower Limit = -20.0, Upper Limit = 20.0 (%))

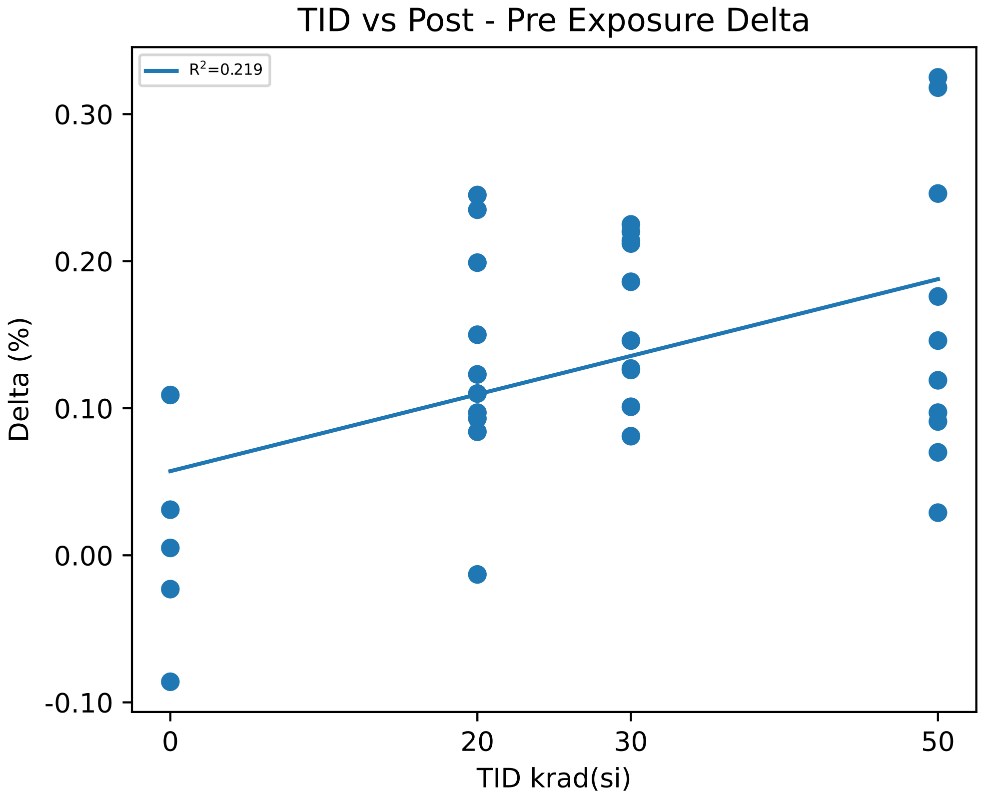
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	-1.666	-1.573	0.093
2	20	Unbiased	-2.691	-2.612	0.079
3	20	Unbiased	-1.357	-1.192	0.165
4	20	Unbiased	-1.542	-1.562	-0.02
5	20	Unbiased	-0.735	-0.517	0.218
6	20	7V Biased	-0.873	-0.742	0.131
7	20	7V Biased	-2.326	-2.196	0.13
8	20	7V Biased	-0.385	-0.194	0.191
9	20	7V Biased	-1.553	-1.547	0.006
10	20	7V Biased	-2.517	-2.374	0.143
11	30	Unbiased	-2.854	-2.493	0.361
12	30	Unbiased	-2.893	-2.652	0.241
13	30	Unbiased	-2.827	-2.662	0.165
14	30	Unbiased	-2.497	-2.341	0.156
15	30	Unbiased	-1.071	-0.816	0.255
16	30	7V Biased	-0.418	-0.558	-0.14
17	30	7V Biased	-2.491	-2.517	-0.026
18	30	7V Biased	-2.636	-2.546	0.09
19	30	7V Biased	-0.702	-0.559	0.143
20	30	7V Biased	-2.51	-2.341	0.169
21	50	Unbiased	-2.854	-2.643	0.211
22	50	Unbiased	-3.012	-2.836	0.176
23	50	Unbiased	-0.715	-0.578	0.137
24	50	Unbiased	-1.534	-1.674	-0.14
25	50	Unbiased	-2.636	-2.477	0.159
26	50	7V Biased	-3.831	-3.622	0.209
27	50	7V Biased	-0.926	-0.71	0.216
28	50	7V Biased	-1.864	-1.654	0.21
29	50	7V Biased	-1.679	-1.712	-0.033
30	50	7V Biased	-0.992	-0.703	0.289
31	0	Correlation	-1.692	-1.681	0.011
32	0	Correlation	-0.603	-0.723	-0.12
33	0	Correlation	-0.392	-0.365	0.027
34	0	Correlation	-1.547	-1.528	0.019
35	0	Correlation	-2.187	-2.169	0.018

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-2.187	-1.2842	-0.392	0.76001	-2.169	-1.2932	-0.365	0.73472	-0.12	-0.009	0.027	0.06231
20	-2.691	-1.5645	-0.385	0.77227	-2.612	-1.4509	-0.194	0.8037	-0.02	0.1136	0.218	0.076024
30	-2.893	-2.0899	-0.418	0.96224	-2.662	-1.9485	-0.558	0.90894	-0.14	0.1414	0.361	0.14237
50	-3.831	-2.0043	-0.715	1.0365	-3.622	-1.8609	-0.578	1.0249	-0.14	0.1434	0.289	0.1302

Device Test: 30.23 Current_Limit_Accuracy(Accuracy_Ilim_6A_1p5V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

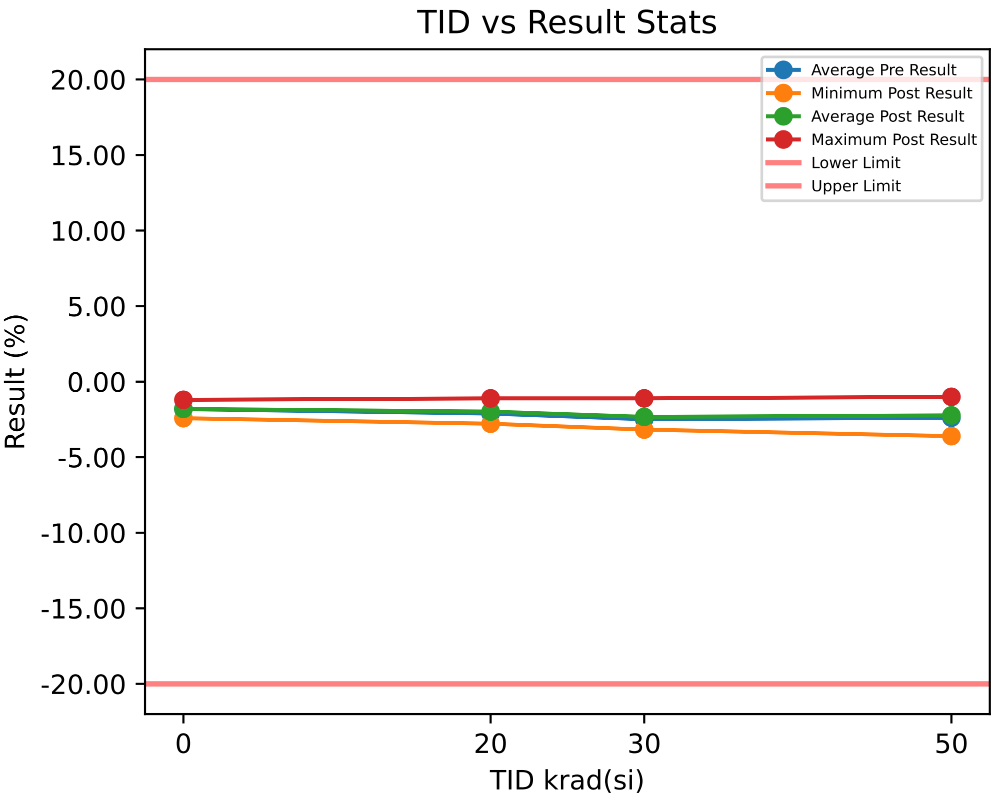
Test Results (Lower Limit = -20.0, Upper Limit = 20.0 (%))

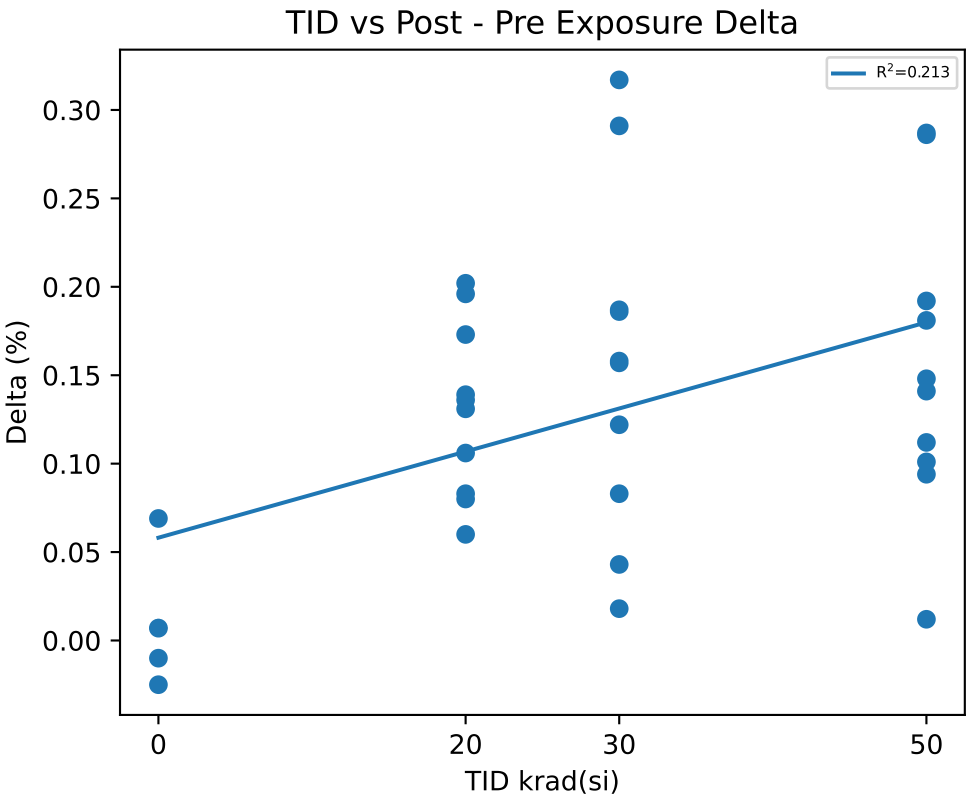
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	-1.786	-1.799	-0.013
2	20	Unbiased	-2.851	-2.741	0.11
3	20	Unbiased	-1.853	-1.756	0.097
4	20	Unbiased	-1.987	-1.903	0.084
5	20	Unbiased	-1.351	-1.152	0.199
6	20	7V Biased	-1.324	-1.231	0.093
7	20	7V Biased	-2.653	-2.408	0.245
8	20	7V Biased	-1.02	-0.785	0.235
9	20	7V Biased	-1.914	-1.764	0.15
10	20	7V Biased	-2.543	-2.42	0.123
11	30	Unbiased	-2.851	-2.637	0.214
12	30	Unbiased	-2.895	-2.749	0.146
13	30	Unbiased	-3.164	-2.944	0.22
14	30	Unbiased	-2.649	-2.437	0.212
15	30	Unbiased	-1.452	-1.325	0.127
16	30	7V Biased	-0.998	-0.917	0.081
17	30	7V Biased	-2.772	-2.671	0.101
18	30	7V Biased	-2.759	-2.534	0.225
19	30	7V Biased	-1.02	-0.894	0.126
20	30	7V Biased	-2.768	-2.582	0.186
21	50	Unbiased	-2.948	-2.772	0.176
22	50	Unbiased	-3.058	-2.988	0.07
23	50	Unbiased	-1.025	-0.779	0.246
24	50	Unbiased	-1.901	-1.872	0.029
25	50	Unbiased	-2.886	-2.561	0.325
26	50	7V Biased	-3.758	-3.639	0.119
27	50	7V Biased	-1.214	-1.123	0.091
28	50	7V Biased	-2.107	-1.961	0.146
29	50	7V Biased	-1.989	-1.892	0.097
30	50	7V Biased	-1.447	-1.129	0.318
31	0	Correlation	-1.883	-1.906	-0.023
32	0	Correlation	-1.029	-1.115	-0.086
33	0	Correlation	-0.946	-0.915	0.031
34	0	Correlation	-1.892	-1.887	0.005
35	0	Correlation	-2.358	-2.249	0.109

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-2.358	-1.6216	-0.946	0.6106	-2.249	-1.6144	-0.915	0.57022	-0.086	0.0072	0.109	0.071646
20	-2.851	-1.9282	-1.02	0.60621	-2.741	-1.7959	-0.785	0.61708	-0.013	0.1323	0.245	0.078053
30	-3.164	-2.3328	-0.998	0.83136	-2.944	-2.169	-0.894	0.79506	0.081	0.1638	0.225	0.053892
50	-3.758	-2.2333	-1.025	0.89721	-3.639	-2.0716	-0.779	0.91713	0.029	0.1617	0.325	0.10311

Device Test: 30.27 Current_Limit_Accuracy(Accuracy_Ilim_7A_1p5V)





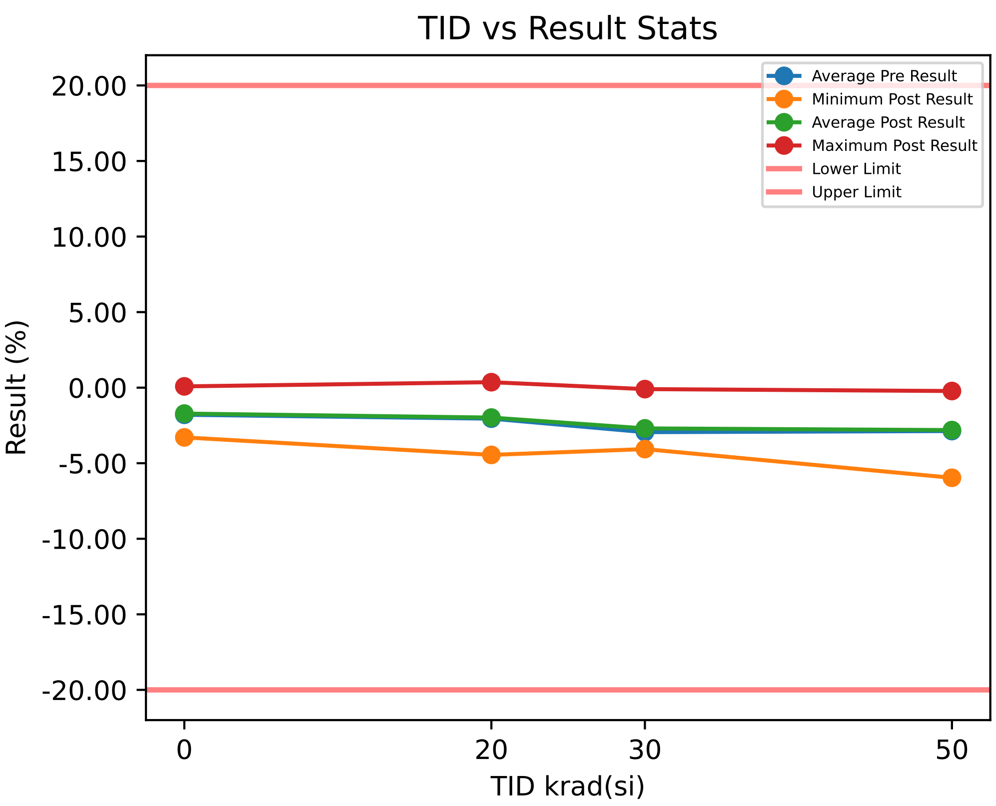
Test Results (Lower Limit = -20.0, Upper Limit = 20.0 (%))

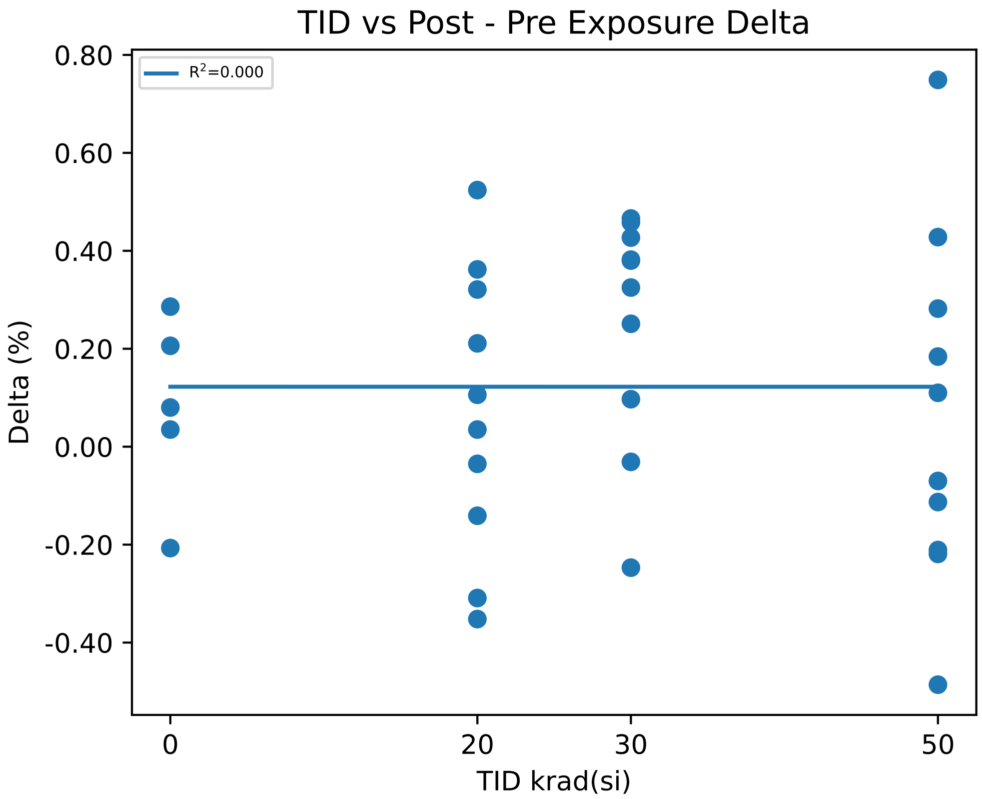
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	-1.949	-1.866	0.083
2	20	Unbiased	-2.957	-2.784	0.173
3	20	Unbiased	-1.997	-1.917	0.08
4	20	Unbiased	-2.231	-2.035	0.196
5	20	Unbiased	-1.572	-1.436	0.136
6	20	7V Biased	-1.56	-1.5	0.06
7	20	7V Biased	-2.767	-2.661	0.106
8	20	7V Biased	-1.308	-1.106	0.202
9	20	7V Biased	-2.175	-2.036	0.139
10	20	7V Biased	-2.601	-2.47	0.131
11	30	Unbiased	-2.982	-2.691	0.291
12	30	Unbiased	-3.031	-2.948	0.083
13	30	Unbiased	-3.329	-3.171	0.158
14	30	Unbiased	-2.703	-2.516	0.187
15	30	Unbiased	-1.677	-1.555	0.122
16	30	7V Biased	-1.217	-1.174	0.043
17	30	7V Biased	-2.899	-2.881	0.018
18	30	7V Biased	-2.865	-2.708	0.157
19	30	7V Biased	-1.292	-1.106	0.186
20	30	7V Biased	-2.877	-2.56	0.317
21	50	Unbiased	-3.069	-2.877	0.192
22	50	Unbiased	-3.239	-3.138	0.101
23	50	Unbiased	-1.153	-1.005	0.148
24	50	Unbiased	-2.058	-2.046	0.012
25	50	Unbiased	-2.971	-2.684	0.287
26	50	7V Biased	-3.718	-3.606	0.112
27	50	7V Biased	-1.519	-1.378	0.141
28	50	7V Biased	-2.318	-2.137	0.181
29	50	7V Biased	-2.13	-2.036	0.094
30	50	7V Biased	-1.692	-1.406	0.286
31	0	Correlation	-2.036	-2.046	-0.01
32	0	Correlation	-1.285	-1.31	-0.025
33	0	Correlation	-1.209	-1.202	0.007
34	0	Correlation	-2.051	-2.044	0.007
35	0	Correlation	-2.488	-2.419	0.069

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-2.488	-1.8138	-1.209	0.549	-2.419	-1.8042	-1.202	0.5246	-0.025	0.0096	0.069	0.035788
20	-2.957	-2.1117	-1.308	0.54598	-2.784	-1.9811	-1.106	0.54402	0.06	0.1306	0.202	0.04909
30	-3.329	-2.4872	-1.217	0.77877	-3.171	-2.331	-1.106	0.75929	0.018	0.1562	0.317	0.096787
50	-3.718	-2.3867	-1.153	0.83279	-3.606	-2.2313	-1.005	0.83853	0.012	0.1554	0.287	0.08551

Device Test: 30.3 Current_Limit_Accuracy(Accuracy_Ilim_750mA_1p5V)





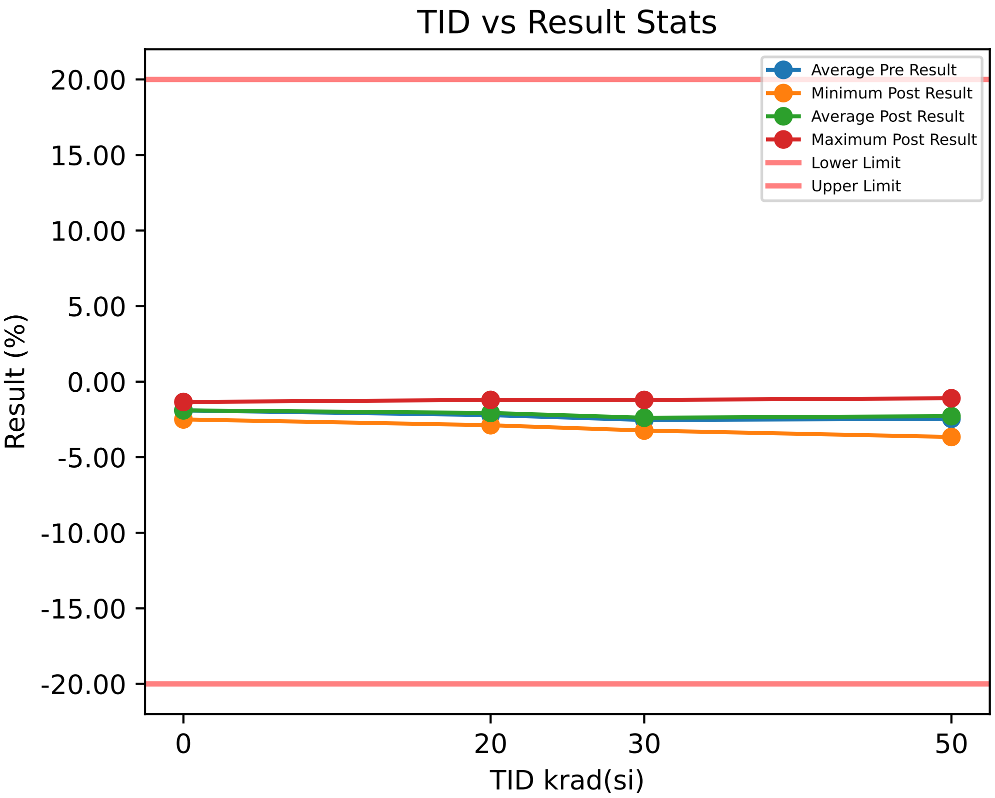
Test Results (Lower Limit = -20.0, Upper Limit = 20.0 (%))

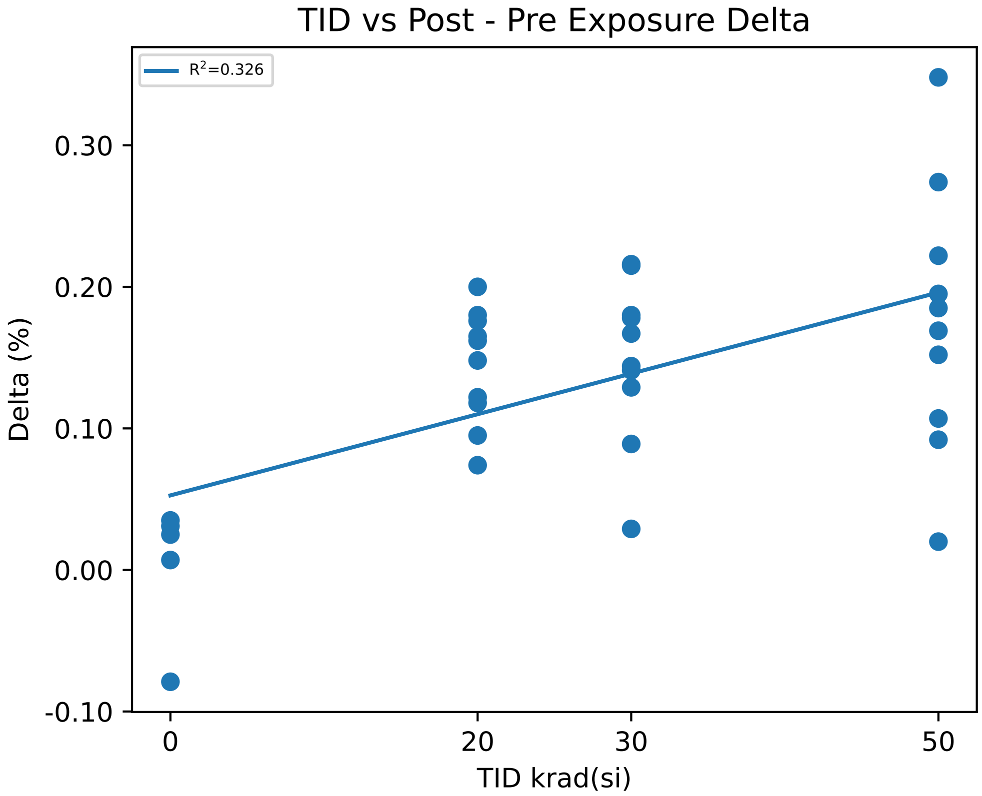
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	-2.837	-2.626	0.211
2	20	Unbiased	-3.921	-4.062	-0.141
3	20	Unbiased	-1.53	-1.882	-0.352
4	20	Unbiased	-1.858	-1.823	0.035
5	20	Unbiased	-0.232	-0.126	0.106
6	20	7V Biased	-0.76	-0.398	0.362
7	20	7V Biased	-3.013	-2.692	0.321
8	20	7V Biased	-0.162	0.362	0.524
9	20	7V Biased	-2.063	-2.098	-0.035
10	20	7V Biased	-4.14	-4.449	-0.309
11	30	Unbiased	-4.492	-4.065	0.427
12	30	Unbiased	-3.893	-3.796	0.097
13	30	Unbiased	-3.647	-3.189	0.458
14	30	Unbiased	-3.893	-3.427	0.466
15	30	Unbiased	-0.901	-0.65	0.251
16	30	7V Biased	-0.478	-0.096	0.382
17	30	7V Biased	-3.189	-3.436	-0.247
18	30	7V Biased	-4.281	-3.956	0.325
19	30	7V Biased	-0.901	-0.932	-0.031
20	30	7V Biased	-3.788	-3.408	0.38
21	50	Unbiased	-4.14	-4.21	-0.07
22	50	Unbiased	-4.774	-4.59	0.184
23	50	Unbiased	-1.007	-0.579	0.428
24	50	Unbiased	-2.344	-2.457	-0.113
25	50	Unbiased	-4.105	-3.823	0.282
26	50	7V Biased	-5.478	-5.964	-0.486
27	50	7V Biased	-0.584	-0.474	0.11
28	50	7V Biased	-2.661	-2.88	-0.219
29	50	7V Biased	-2.661	-2.872	-0.211
30	50	7V Biased	-0.971	-0.222	0.749
31	0	Correlation	-2.908	-3.115	-0.207
32	0	Correlation	-0.901	-0.695	0.206
33	0	Correlation	0.05	0.085	0.035
34	0	Correlation	-1.64	-1.56	0.08
35	0	Correlation	-3.577	-3.291	0.286

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-3.577	-1.7952	0.05	1.4698	-3.291	-1.7152	0.085	1.4789	-0.207	0.08	0.286	0.18888
20	-4.14	-2.0516	-0.162	1.4243	-4.449	-1.9794	0.362	1.5926	-0.352	0.0722	0.524	0.28944
30	-4.492	-2.9463	-0.478	1.5521	-4.065	-2.6955	-0.096	1.5115	-0.247	0.2508	0.466	0.23818
50	-5.478	-2.8725	-0.584	1.7072	-5.964	-2.8071	-0.222	1.9255	-0.486	0.0654	0.749	0.36105

Device Test: 30.31 Current_Limit_Accuracy(Accuracy_Ilim_7p5A_1p5V)





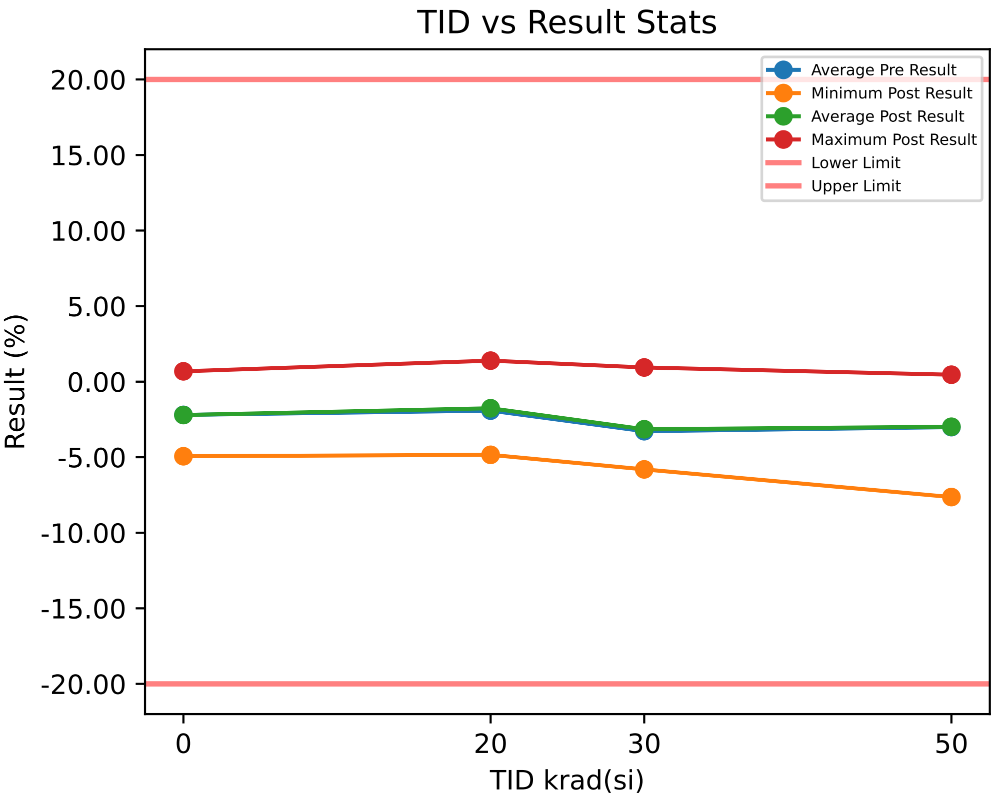
Test Results (Lower Limit = -20.0, Upper Limit = 20.0 (%))

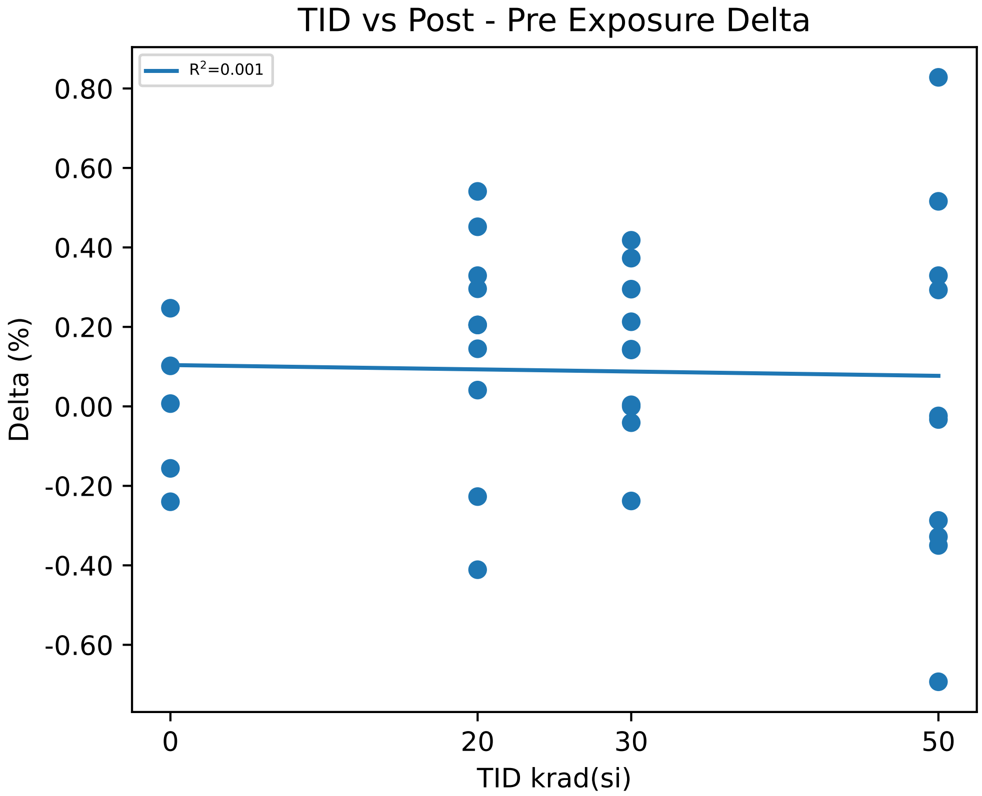
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	-2.014	-1.94	0.074
2	20	Unbiased	-3.044	-2.882	0.162
3	20	Unbiased	-2.183	-2.003	0.18
4	20	Unbiased	-2.329	-2.181	0.148
5	20	Unbiased	-1.753	-1.588	0.165
6	20	7V Biased	-1.697	-1.575	0.122
7	20	7V Biased	-2.897	-2.697	0.2
8	20	7V Biased	-1.384	-1.208	0.176
9	20	7V Biased	-2.2	-2.105	0.095
10	20	7V Biased	-2.644	-2.526	0.118
11	30	Unbiased	-2.986	-2.771	0.215
12	30	Unbiased	-3.074	-2.945	0.129
13	30	Unbiased	-3.415	-3.235	0.18
14	30	Unbiased	-2.714	-2.536	0.178
15	30	Unbiased	-1.722	-1.633	0.089
16	30	7V Biased	-1.359	-1.215	0.144
17	30	7V Biased	-3	-2.971	0.029
18	30	7V Biased	-2.862	-2.695	0.167
19	30	7V Biased	-1.352	-1.211	0.141
20	30	7V Biased	-2.897	-2.681	0.216
21	50	Unbiased	-3.059	-2.89	0.169
22	50	Unbiased	-3.306	-3.121	0.185
23	50	Unbiased	-1.25	-1.098	0.152
24	50	Unbiased	-2.141	-2.121	0.02
25	50	Unbiased	-2.971	-2.697	0.274
26	50	7V Biased	-3.767	-3.66	0.107
27	50	7V Biased	-1.69	-1.468	0.222
28	50	7V Biased	-2.383	-2.188	0.195
29	50	7V Biased	-2.183	-2.091	0.092
30	50	7V Biased	-1.838	-1.49	0.348
31	0	Correlation	-2.098	-2.063	0.035
32	0	Correlation	-1.426	-1.395	0.031
33	0	Correlation	-1.352	-1.345	0.007
34	0	Correlation	-2.116	-2.195	-0.079
35	0	Correlation	-2.524	-2.499	0.025

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-2.524	-1.9032	-1.352	0.50004	-2.499	-1.8994	-1.345	0.50878	-0.079	0.0038	0.035	0.04751
20	-3.044	-2.2145	-1.384	0.53369	-2.882	-2.0705	-1.208	0.5287	0.074	0.144	0.2	0.040412
30	-3.415	-2.5381	-1.352	0.75996	-3.235	-2.3893	-1.211	0.74889	0.029	0.1488	0.216	0.057213
50	-3.767	-2.4588	-1.25	0.79388	-3.66	-2.2824	-1.098	0.81019	0.02	0.1764	0.348	0.093406

Device Test: 30.35 Current_Limit_Accuracy(Accuracy_Ilim_750mA_7V)





Test Results (Lower Limit = -20.0, Upper Limit = 20.0 (%))

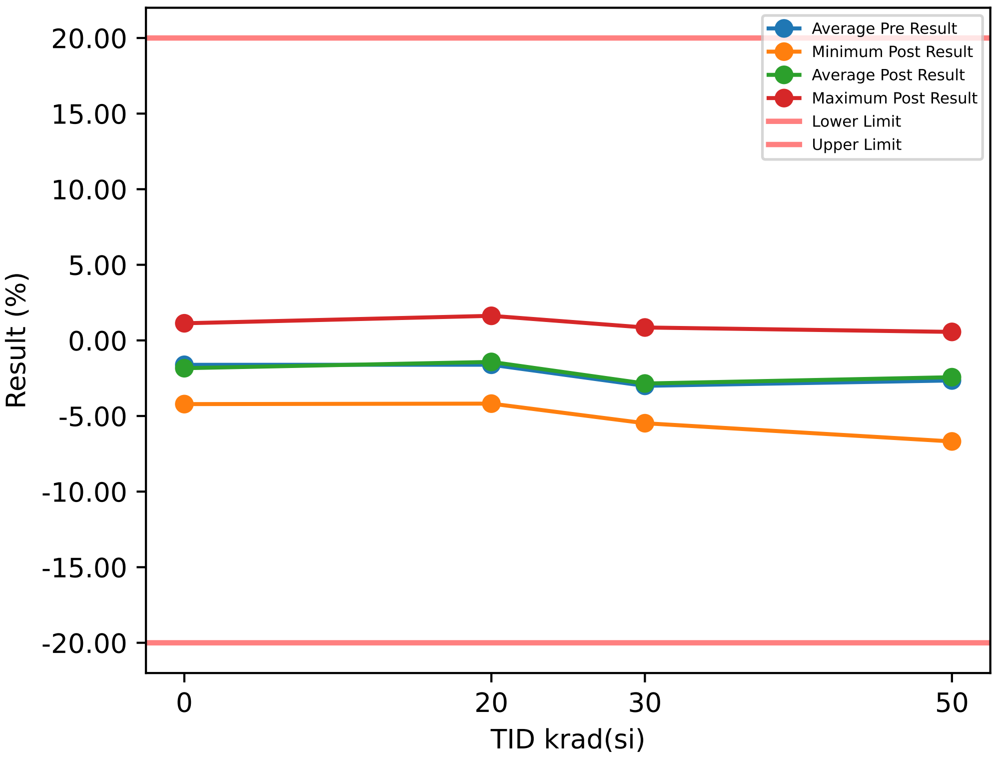
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	-2.191	-2.15	0.041
2	20	Unbiased	-3.609	-4.02	-0.411
3	20	Unbiased	-0.952	-0.747	0.205
4	20	Unbiased	-2.514	-2.309	0.205
5	20	Unbiased	-0.179	0.15	0.329
6	20	7V Biased	0.15	0.295	0.145
7	20	7V Biased	-5.108	-4.567	0.541
8	20	7V Biased	1.095	1.391	0.296
9	20	7V Biased	-1.247	-0.795	0.452
10	20	7V Biased	-4.615	-4.842	-0.227
11	30	Unbiased	-4.574	-4.156	0.418
12	30	Unbiased	-5.395	-5.022	0.373
13	30	Unbiased	-3.917	-3.917	0
14	30	Unbiased	-3.876	-3.732	0.144
15	30	Unbiased	-0.097	0.116	0.213
16	30	7V Biased	1.177	0.939	-0.238
17	30	7V Biased	-5.765	-5.806	-0.041
18	30	7V Biased	-5.642	-5.5	0.142
19	30	7V Biased	-0.384	-0.089	0.295
20	30	7V Biased	-4.327	-4.323	0.004
21	50	Unbiased	-4.985	-5.272	-0.287
22	50	Unbiased	-4.615	-4.965	-0.35
23	50	Unbiased	-1.041	-0.213	0.828
24	50	Unbiased	-2.438	-3.131	-0.693
25	50	Unbiased	-5.19	-4.861	0.329
26	50	7V Biased	-7.613	-7.637	-0.024
27	50	7V Biased	0.478	0.445	-0.033
28	50	7V Biased	-3.383	-3.09	0.293
29	50	7V Biased	-1.247	-1.575	-0.328
30	50	7V Biased	-0.056	0.46	0.516
31	0	Correlation	-4.533	-4.526	0.007
32	0	Correlation	0.478	0.322	-0.156
33	0	Correlation	0.437	0.684	0.247
34	0	Correlation	-2.684	-2.582	0.102
35	0	Correlation	-4.697	-4.937	-0.24

Test Statistics (%)

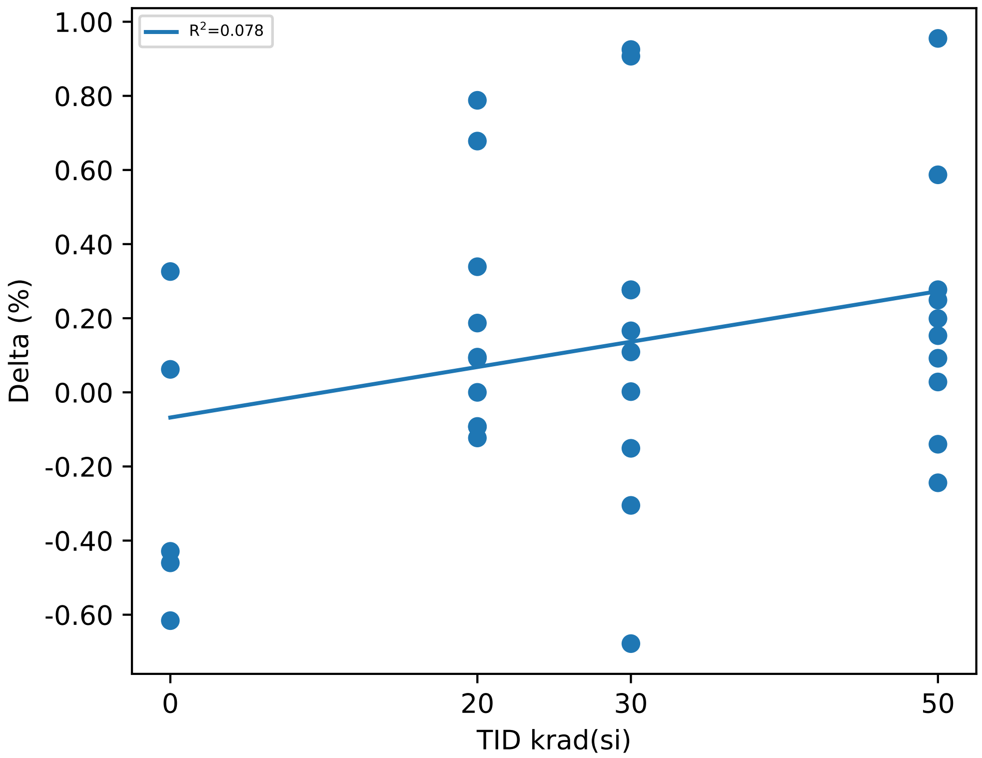
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-4.697	-2.1998	0.478	2.5514	-4.937	-2.2078	0.684	2.6327	-0.24	-0.008	0.247	0.19563
20	-5.108	-1.917	1.095	2.0683	-4.842	-1.7594	1.391	2.1781	-0.411	0.1576	0.541	0.29282
30	-5.765	-3.28	1.177	2.5417	-5.806	-3.149	0.939	2.4978	-0.238	0.131	0.418	0.20382
50	-7.613	-3.009	0.478	2.5983	-7.637	-2.9839	0.46	2.7416	-0.693	0.0251	0.828	0.46356

Device Test: 30.39 Current_Limit_Accuracy(Accuracy_Ilim_1A_7V)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



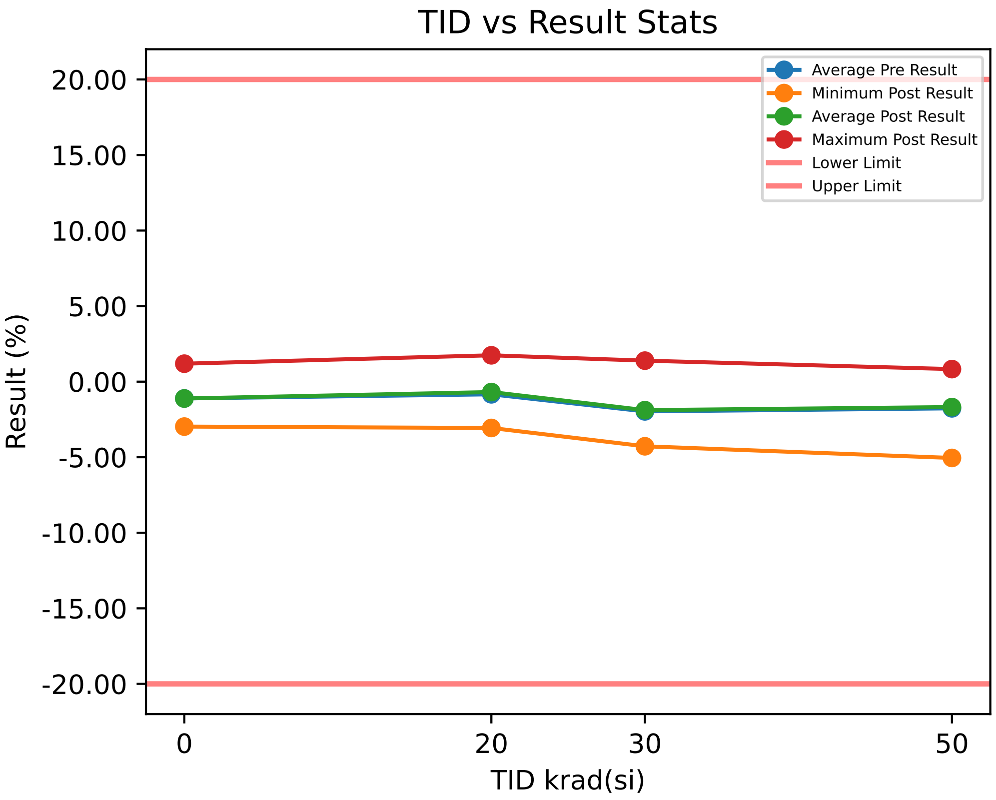
Test Results (Lower Limit = -20.0, Upper Limit = 20.0 (%))

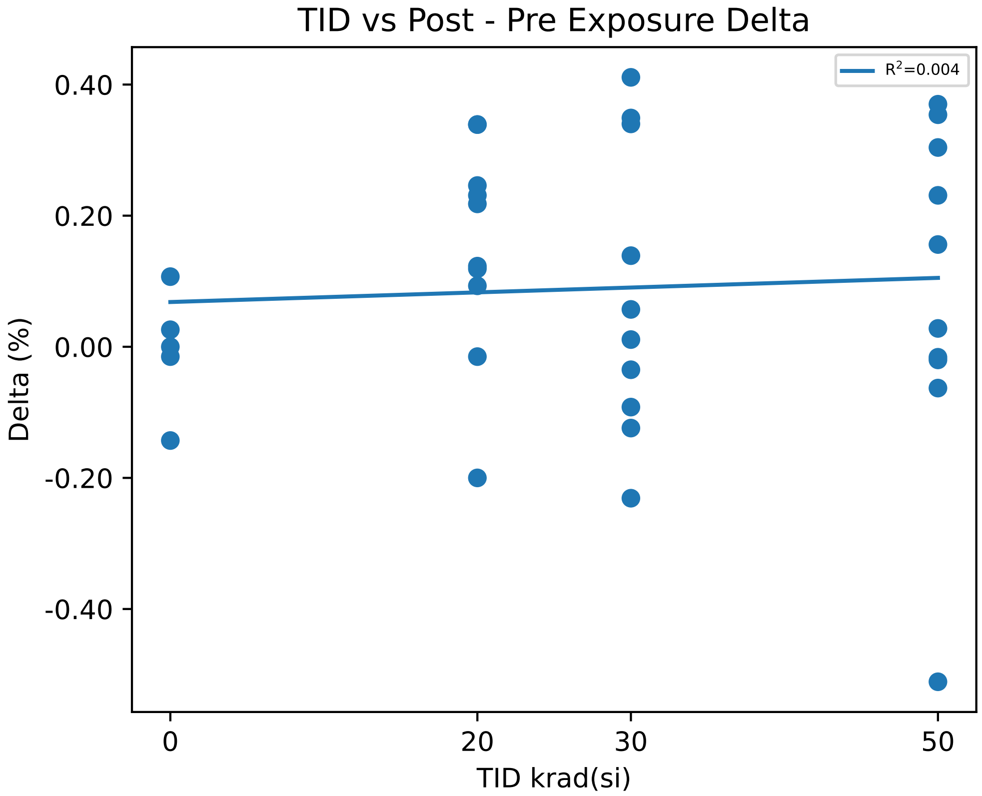
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	-1.997	-2.12	-0.123
2	20	Unbiased	-3.384	-2.706	0.678
3	20	Unbiased	-0.855	-0.947	-0.092
4	20	Unbiased	-2.29	-1.951	0.339
5	20	Unbiased	0.283	0.19	-0.093
6	20	7V Biased	0.313	0.408	0.095
7	20	7V Biased	-4.369	-4.182	0.187
8	20	7V Biased	0.837	1.625	0.788
9	20	7V Biased	-0.95	-0.95	0
10	20	7V Biased	-3.691	-3.599	0.092
11	30	Unbiased	-4.184	-4.182	0.002
12	30	Unbiased	-4.954	-4.788	0.166
13	30	Unbiased	-4.061	-3.784	0.277
14	30	Unbiased	-3.815	-2.89	0.925
15	30	Unbiased	0.159	0.008	-0.151
16	30	7V Biased	0.745	0.854	0.109
17	30	7V Biased	-4.8	-5.478	-0.678
18	30	7V Biased	-5.108	-4.832	0.276
19	30	7V Biased	0.313	0.008	-0.305
20	30	7V Biased	-4.338	-3.431	0.907
21	50	Unbiased	-4.369	-4.277	0.092
22	50	Unbiased	-4.215	-4.062	0.153
23	50	Unbiased	-0.364	-0.115	0.249
24	50	Unbiased	-2.274	-2.414	-0.14
25	50	Unbiased	-5.078	-4.123	0.955
26	50	7V Biased	-6.71	-6.682	0.028
27	50	7V Biased	0.714	0.47	-0.244
28	50	7V Biased	-3.014	-2.815	0.199
29	50	7V Biased	-1.165	-0.888	0.277
30	50	7V Biased	-0.025	0.562	0.587
31	0	Correlation	-3.661	-4.09	-0.429
32	0	Correlation	0.806	1.132	0.326
33	0	Correlation	0.837	0.221	-0.616
34	0	Correlation	-2.305	-2.243	0.062
35	0	Correlation	-3.753	-4.213	-0.46

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-3.753	-1.6152	0.837	2.2971	-4.213	-1.8386	1.132	2.4462	-0.616	-0.2234	0.326	0.39865
20	-4.369	-1.6103	0.837	1.825	-4.182	-1.4232	1.625	1.8395	-0.123	0.1871	0.788	0.32149
30	-5.108	-3.0043	0.745	2.3913	-5.478	-2.8515	0.854	2.3005	-0.678	0.1528	0.925	0.49583
50	-6.71	-2.65	0.714	2.4426	-6.682	-2.4344	0.562	2.4099	-0.244	0.2156	0.955	0.34671

Device Test: 30.43 Current_Limit_Accuracy(Accuracy_Ilim_2A_7V)





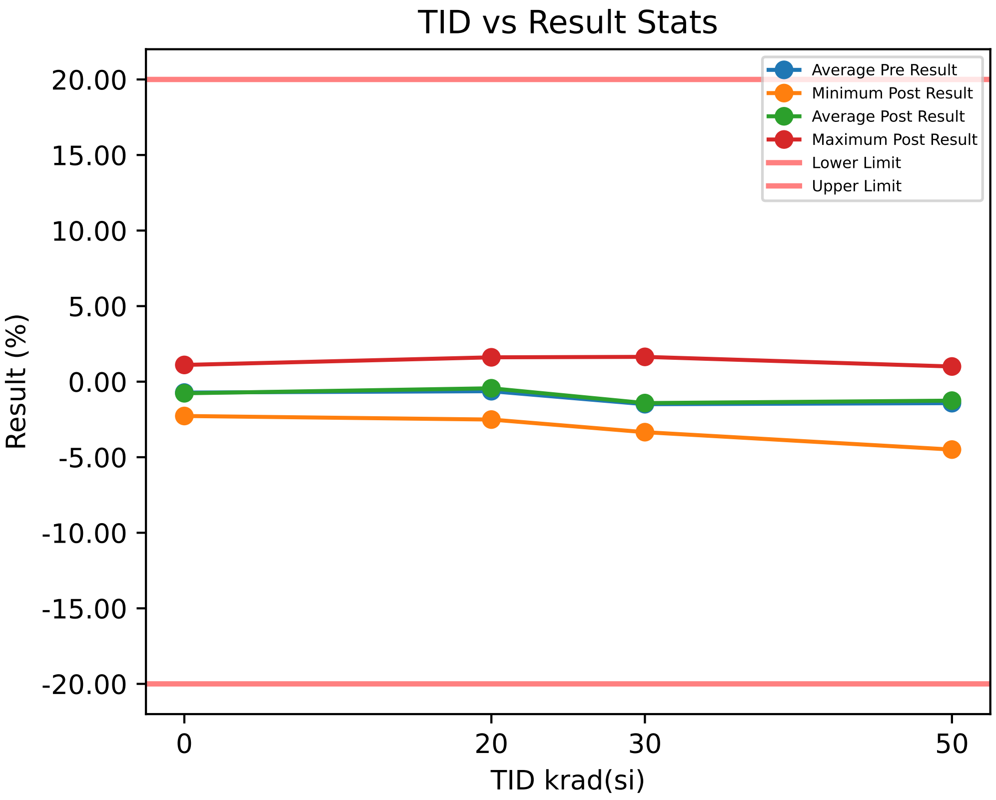
Test Results (Lower Limit = -20.0, Upper Limit = 20.0 (%))

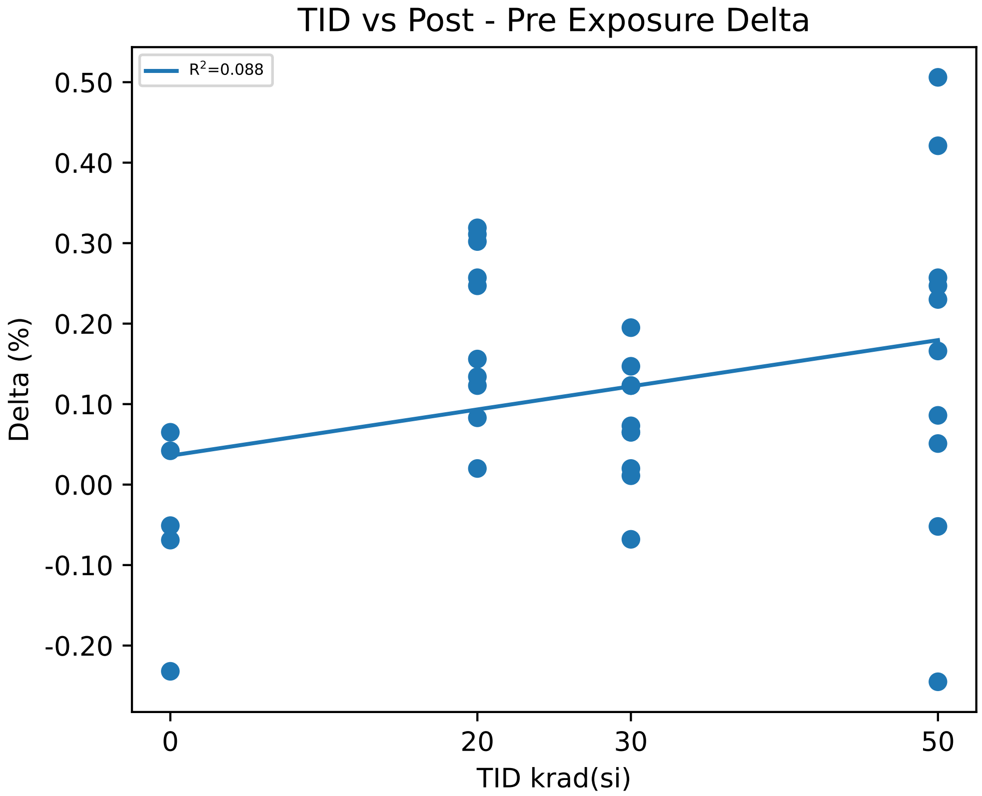
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	-0.935	-1.135	-0.2
2	20	Unbiased	-2.49	-2.244	0.246
3	20	Unbiased	-0.185	-0.092	0.093
4	20	Unbiased	-1.446	-1.215	0.231
5	20	Unbiased	0.436	0.775	0.339
6	20	7V Biased	0.836	1.054	0.218
7	20	7V Biased	-3.184	-3.065	0.119
8	20	7V Biased	1.406	1.745	0.339
9	20	7V Biased	-0.334	-0.211	0.123
10	20	7V Biased	-2.475	-2.49	-0.015
11	30	Unbiased	-2.706	-2.357	0.349
12	30	Unbiased	-3.476	-3.465	0.011
13	30	Unbiased	-2.537	-2.398	0.139
14	30	Unbiased	-2.491	-2.151	0.34
15	30	Unbiased	0.082	0.493	0.411
16	30	7V Biased	1.483	1.391	-0.092
17	30	7V Biased	-4.046	-4.277	-0.231
18	30	7V Biased	-3.615	-3.739	-0.124
19	30	7V Biased	0.482	0.539	0.057
20	30	7V Biased	-2.845	-2.88	-0.035
21	50	Unbiased	-3.492	-3.138	0.354
22	50	Unbiased	-3.153	-3.169	-0.016
23	50	Unbiased	0.066	0.37	0.304
24	50	Unbiased	-1.32	-1.831	-0.511
25	50	Unbiased	-3.754	-3.523	0.231
26	50	7V Biased	-4.986	-5.049	-0.063
27	50	7V Biased	0.852	0.832	-0.02
28	50	7V Biased	-1.813	-1.785	0.028
29	50	7V Biased	-0.535	-0.165	0.37
30	50	7V Biased	0.482	0.638	0.156
31	0	Correlation	-2.783	-2.757	0.026
32	0	Correlation	1.083	1.19	0.107
33	0	Correlation	0.759	0.744	-0.015
34	0	Correlation	-1.782	-1.782	0
35	0	Correlation	-2.83	-2.973	-0.143

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-2.83	-1.1106	1.083	1.9047	-2.973	-1.1156	1.19	1.9597	-0.143	-0.005	0.107	0.09038
20	-3.184	-0.8371	1.406	1.5432	-3.065	-0.6878	1.745	1.615	-0.2	0.1493	0.339	0.1655
30	-4.046	-1.9669	1.483	1.9244	-4.277	-1.8844	1.391	1.9851	-0.231	0.0825	0.411	0.22095
50	-4.986	-1.7653	0.852	2.0056	-5.049	-1.682	0.832	2.0359	-0.511	0.0833	0.37	0.26446

Device Test: 30.47 Current_Limit_Accuracy(Accuracy_Ilim_3A_7V)





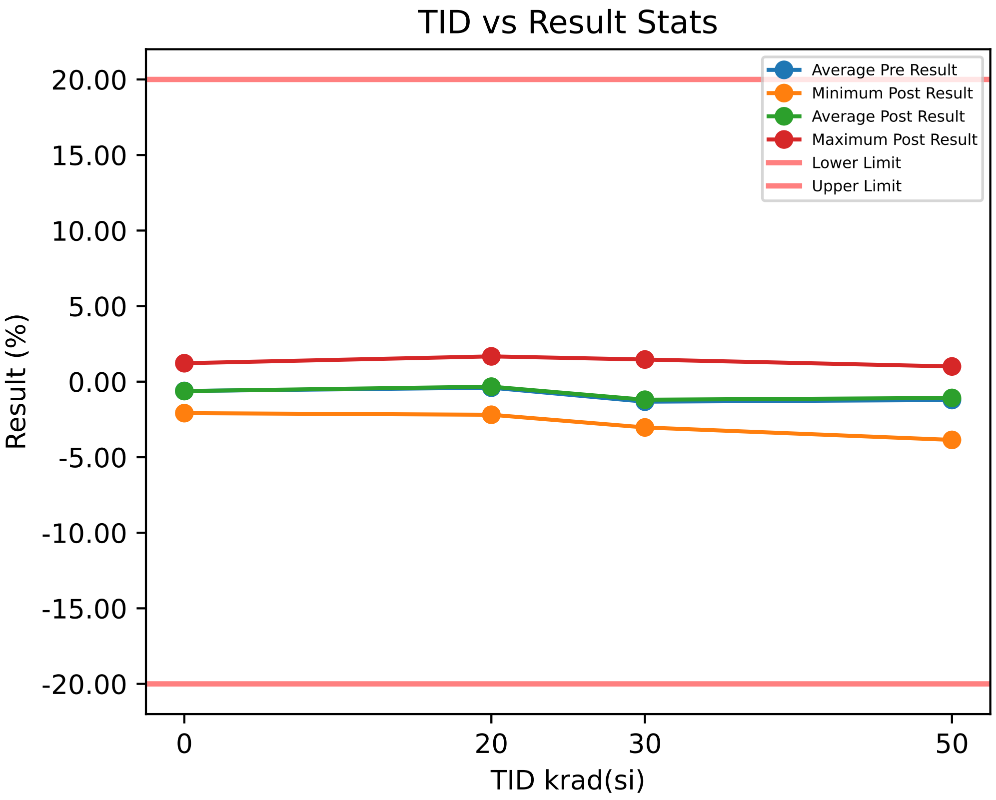
Test Results (Lower Limit = -20.0, Upper Limit = 20.0 (%))

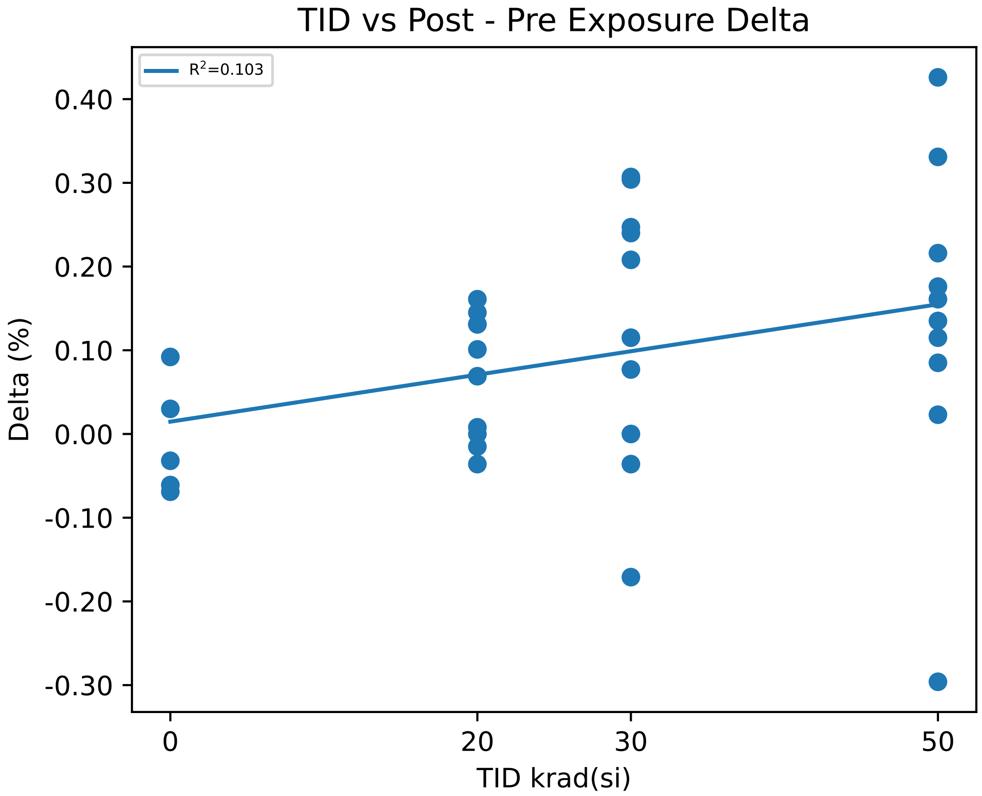
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	-0.766	-0.632	0.134
2	20	Unbiased	-2.09	-1.967	0.123
3	20	Unbiased	-0.115	-0.095	0.02
4	20	Unbiased	-1.298	-0.979	0.319
5	20	Unbiased	0.713	0.97	0.257
6	20	7V Biased	0.867	1.023	0.156
7	20	7V Biased	-2.819	-2.508	0.311
8	20	7V Biased	1.309	1.611	0.302
9	20	7V Biased	-0.201	0.046	0.247
10	20	7V Biased	-1.926	-1.843	0.083
11	30	Unbiased	-2.172	-2.025	0.147
12	30	Unbiased	-2.778	-2.767	0.011
13	30	Unbiased	-2.08	-2.06	0.02
14	30	Unbiased	-1.864	-1.741	0.123
15	30	Unbiased	0.559	0.491	-0.068
16	30	7V Biased	1.576	1.641	0.065
17	30	7V Biased	-3.466	-3.343	0.123
18	30	7V Biased	-3.127	-2.932	0.195
19	30	7V Biased	0.744	0.809	0.065
20	30	7V Biased	-2.316	-2.243	0.073
21	50	Unbiased	-2.778	-2.727	0.051
22	50	Unbiased	-2.717	-2.47	0.247
23	50	Unbiased	0.333	0.563	0.23
24	50	Unbiased	-1.279	-1.524	-0.245
25	50	Unbiased	-3.117	-2.696	0.421
26	50	7V Biased	-4.442	-4.494	-0.052
27	50	7V Biased	0.918	1.004	0.086
28	50	7V Biased	-1.464	-1.298	0.166
29	50	7V Biased	-0.17	0.087	0.257
30	50	7V Biased	0.487	0.993	0.506
31	0	Correlation	-2.121	-2.19	-0.069
32	0	Correlation	1.339	1.107	-0.232
33	0	Correlation	0.939	0.888	-0.051
34	0	Correlation	-1.423	-1.381	0.042
35	0	Correlation	-2.337	-2.272	0.065

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-2.337	-0.7206	1.339	1.7366	-2.272	-0.7696	1.107	1.6521	-0.232	-0.049	0.065	0.11744
20	-2.819	-0.6326	1.309	1.3873	-2.508	-0.4374	1.611	1.3982	0.02	0.1952	0.319	0.10563
30	-3.466	-1.4924	1.576	1.7785	-3.343	-1.417	1.641	1.7431	-0.068	0.0754	0.195	0.075986
50	-4.442	-1.4229	0.918	1.8043	-4.494	-1.2562	1.004	1.8722	-0.245	0.1667	0.506	0.22001

Device Test: 30.51 Current_Limit_Accuracy(Accuracy_Ilim_4A_7V)





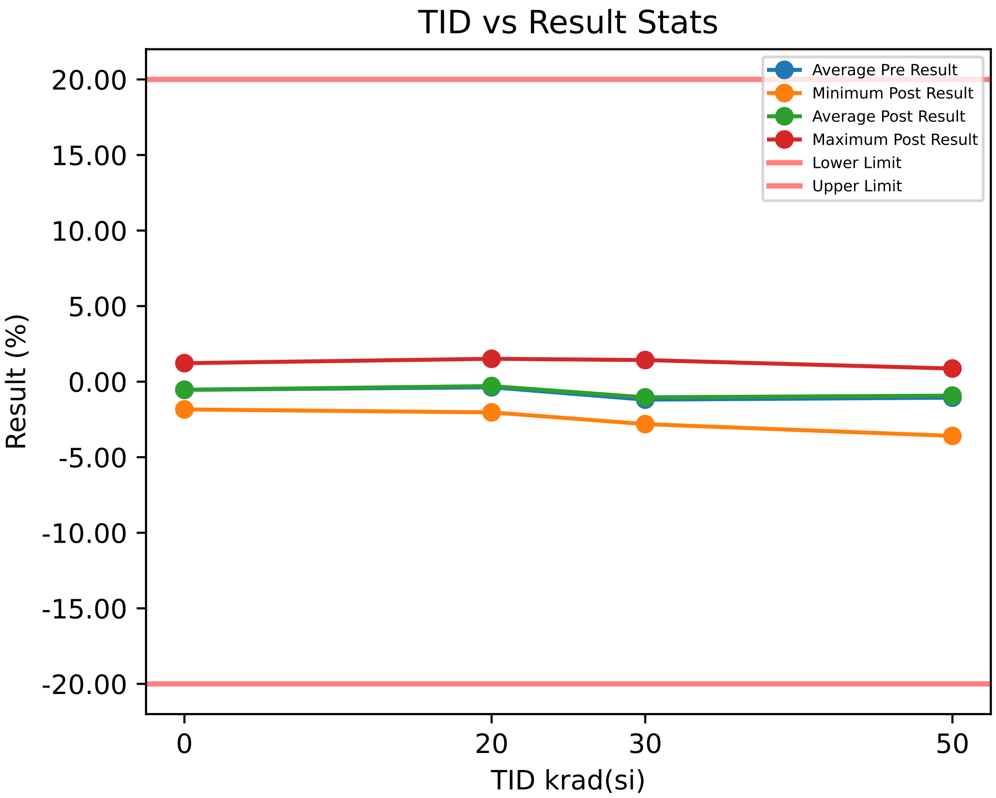
Test Results (Lower Limit = -20.0, Upper Limit = 20.0 (%))

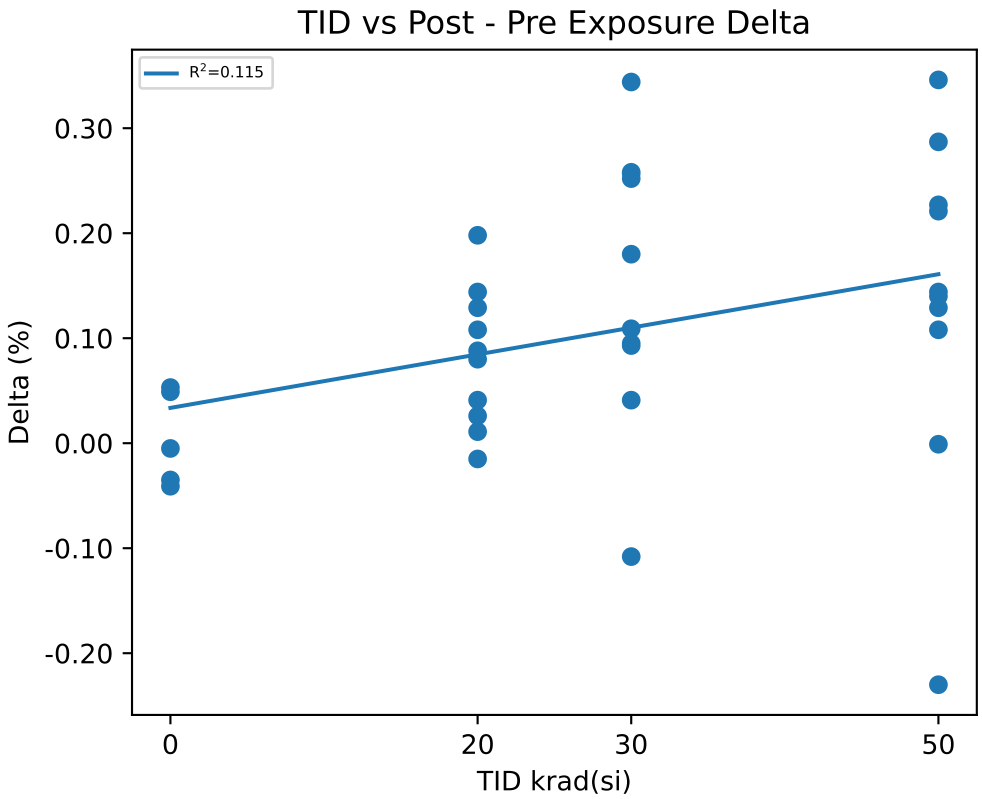
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	-0.458	-0.458	0
2	20	Unbiased	-1.751	-1.766	-0.015
3	20	Unbiased	-0.127	0.004	0.131
4	20	Unbiased	-0.931	-0.923	0.008
5	20	Unbiased	0.805	0.936	0.131
6	20	7V Biased	0.967	0.931	-0.036
7	20	7V Biased	-2.352	-2.191	0.161
8	20	7V Biased	1.529	1.674	0.145
9	20	7V Biased	-0.011	0.058	0.069
10	20	7V Biased	-1.667	-1.566	0.101
11	30	Unbiased	-1.905	-1.598	0.307
12	30	Unbiased	-2.583	-2.619	-0.036
13	30	Unbiased	-1.89	-1.775	0.115
14	30	Unbiased	-1.582	-1.342	0.24
15	30	Unbiased	0.32	0.528	0.208
16	30	7V Biased	1.637	1.466	-0.171
17	30	7V Biased	-3.107	-3.03	0.077
18	30	7V Biased	-2.791	-2.544	0.247
19	30	7V Biased	0.836	0.836	0
20	30	7V Biased	-2.183	-1.879	0.304
21	50	Unbiased	-2.575	-2.414	0.161
22	50	Unbiased	-2.275	-2.252	0.023
23	50	Unbiased	0.366	0.697	0.331
24	50	Unbiased	-0.943	-1.239	-0.296
25	50	Unbiased	-2.791	-2.575	0.216
26	50	7V Biased	-4.031	-3.855	0.176
27	50	7V Biased	0.921	1.006	0.085
28	50	7V Biased	-1.297	-1.162	0.135
29	50	7V Biased	-0.049	0.066	0.115
30	50	7V Biased	0.536	0.962	0.426
31	0	Correlation	-1.875	-1.944	-0.069
32	0	Correlation	1.252	1.22	-0.032
33	0	Correlation	0.906	0.998	0.092
34	0	Correlation	-1.243	-1.304	-0.061
35	0	Correlation	-2.113	-2.083	0.03

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-2.113	-0.6146	1.252	1.5831	-2.083	-0.6226	1.22	1.6097	-0.069	-0.008	0.092	0.068099
20	-2.352	-0.3996	1.529	1.2821	-2.191	-0.3301	1.674	1.2863	-0.036	0.0695	0.161	0.074171
30	-3.107	-1.3248	1.637	1.6504	-3.03	-1.1957	1.466	1.5768	-0.171	0.1291	0.307	0.1604
50	-4.031	-1.2138	0.921	1.6652	-3.855	-1.0766	1.006	1.7034	-0.296	0.1372	0.426	0.1924

Device Test: 30.55 Current_Limit_Accuracy(Accuracy_Ilim_6A_7V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

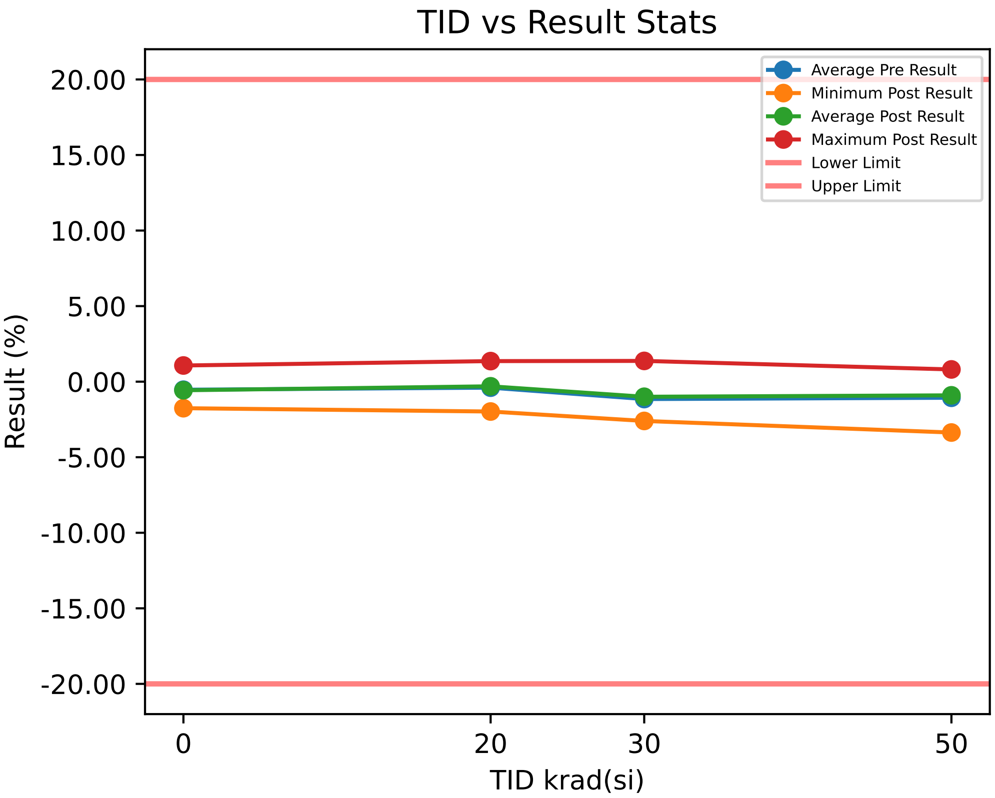
Test Results (Lower Limit = -20.0, Upper Limit = 20.0 (%))

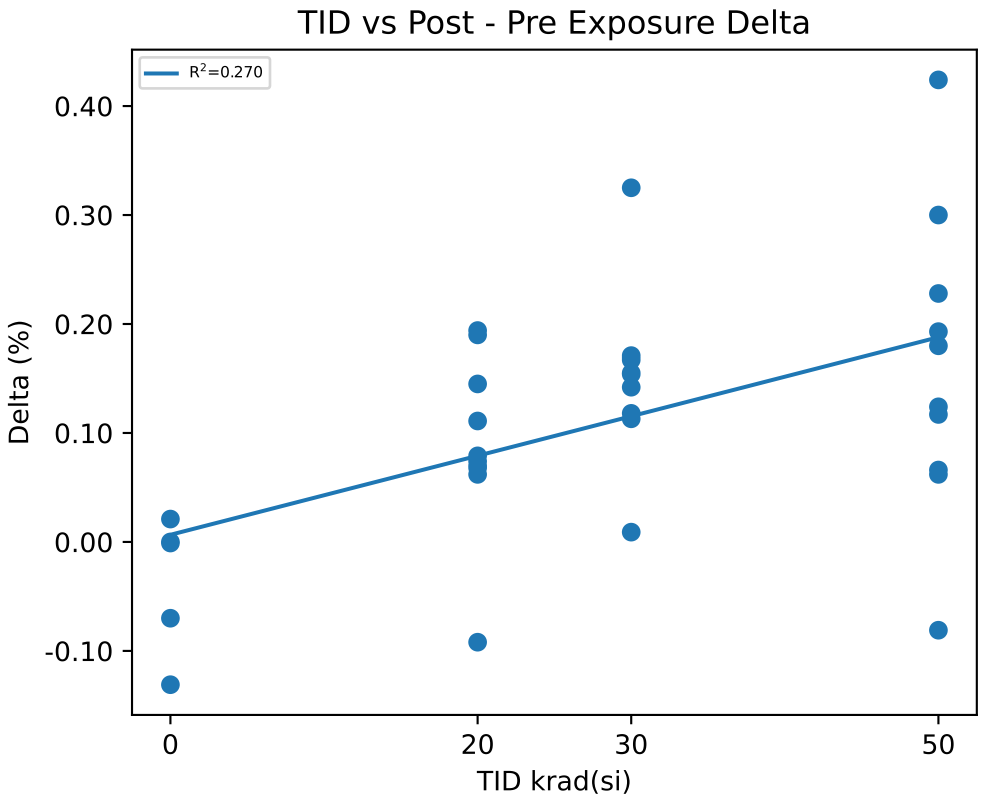
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	-0.462	-0.421	0.041
2	20	Unbiased	-1.617	-1.488	0.129
3	20	Unbiased	-0.01	0.016	0.026
4	20	Unbiased	-0.857	-0.846	0.011
5	20	Unbiased	0.59	0.734	0.144
6	20	7V Biased	0.867	0.947	0.08
7	20	7V Biased	-2.141	-2.033	0.108
8	20	7V Biased	1.314	1.512	0.198
9	20	7V Biased	-0.021	-0.036	-0.015
10	20	7V Biased	-1.392	-1.304	0.088
11	30	Unbiased	-1.623	-1.365	0.258
12	30	Unbiased	-2.249	-2.208	0.041
13	30	Unbiased	-1.859	-1.515	0.344
14	30	Unbiased	-1.412	-1.319	0.093
15	30	Unbiased	0.272	0.524	0.252
16	30	7V Biased	1.335	1.43	0.095
17	30	7V Biased	-2.701	-2.809	-0.108
18	30	7V Biased	-2.47	-2.29	0.18
19	30	7V Biased	0.775	0.884	0.109
20	30	7V Biased	-1.972	-1.715	0.257
21	50	Unbiased	-2.147	-1.926	0.221
22	50	Unbiased	-2.059	-1.93	0.129
23	50	Unbiased	0.308	0.535	0.227
24	50	Unbiased	-0.863	-1.093	-0.23
25	50	Unbiased	-2.485	-2.198	0.287
26	50	7V Biased	-3.589	-3.59	-0.001
27	50	7V Biased	0.724	0.868	0.144
28	50	7V Biased	-1.022	-0.882	0.14
29	50	7V Biased	0.138	0.246	0.108
30	50	7V Biased	0.395	0.741	0.346
31	0	Correlation	-1.654	-1.601	0.053
32	0	Correlation	1.175	1.224	0.049
33	0	Correlation	0.852	0.811	-0.041
34	0	Correlation	-1.248	-1.283	-0.035
35	0	Correlation	-1.833	-1.838	-0.005

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-1.833	-0.5416	1.175	1.4399	-1.838	-0.5374	1.224	1.4404	-0.041	0.0042	0.053	0.044869
20	-2.141	-0.3729	1.314	1.1314	-2.033	-0.2919	1.512	1.1456	-0.015	0.081	0.198	0.066234
30	-2.701	-1.1904	1.335	1.442	-2.809	-1.0383	1.43	1.4594	-0.108	0.1521	0.344	0.13267
50	-3.589	-1.06	0.724	1.4626	-3.59	-0.9229	0.868	1.5003	-0.23	0.1371	0.346	0.16194

Device Test: 30.59 Current_Limit_Accuracy(Accuracy_Ilim_7A_7V)





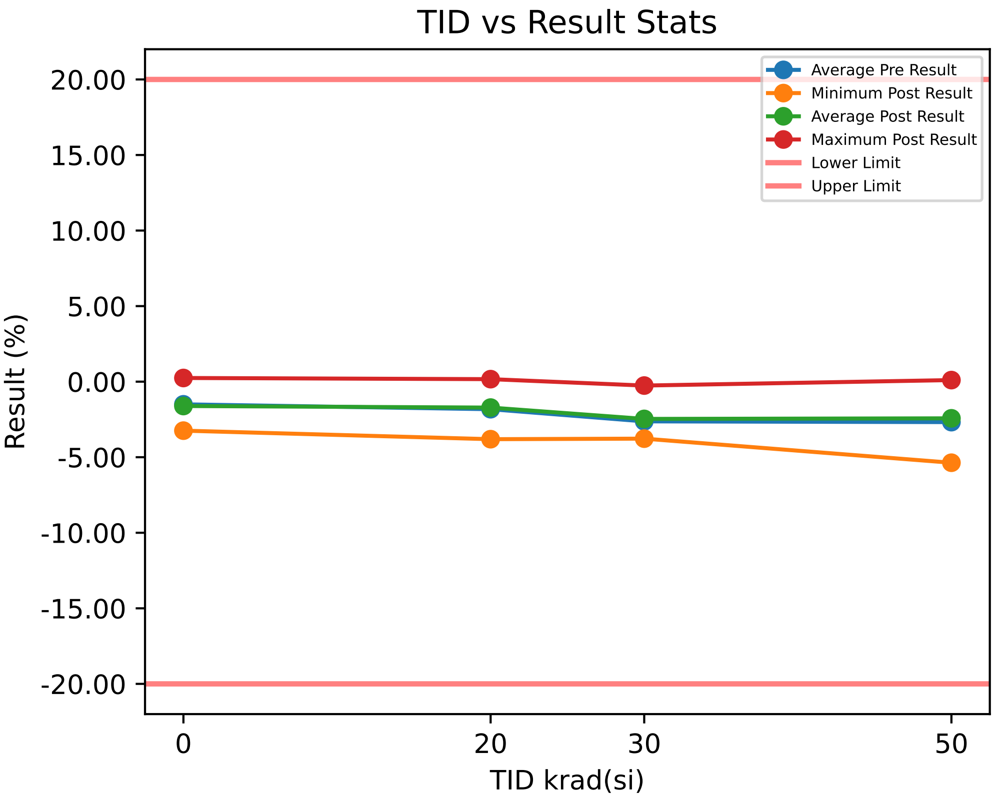
Test Results (Lower Limit = -20.0, Upper Limit = 20.0 (%))

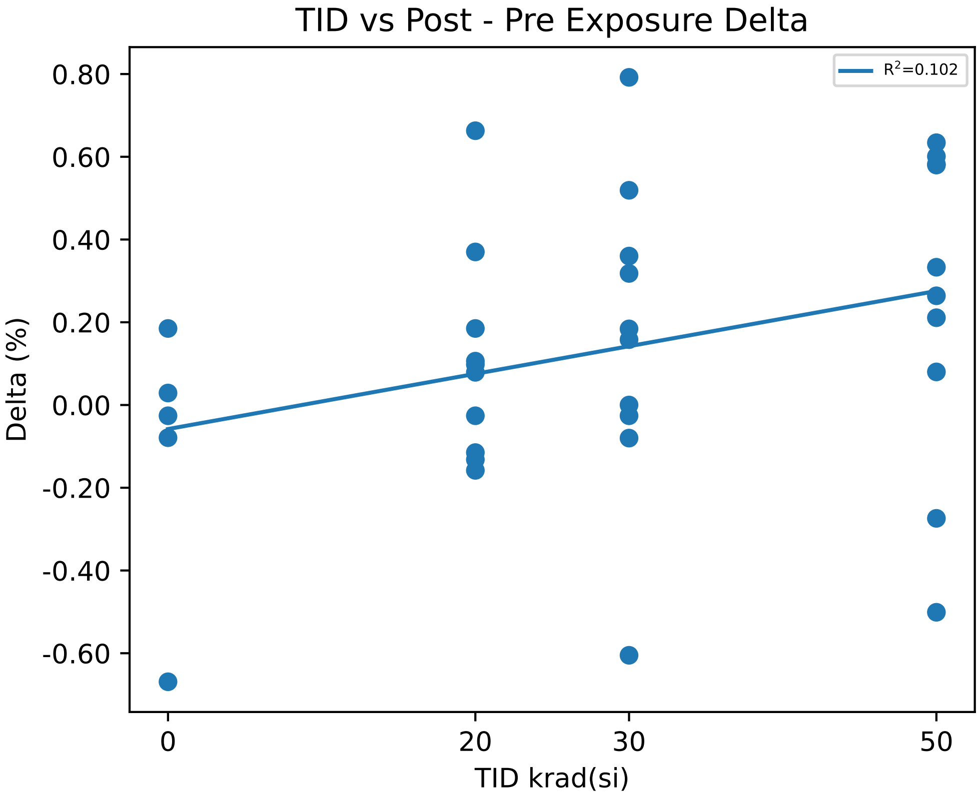
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	-0.378	-0.47	-0.092
2	20	Unbiased	-1.596	-1.402	0.194
3	20	Unbiased	-0.097	-0.018	0.079
4	20	Unbiased	-0.926	-0.864	0.062
5	20	Unbiased	0.427	0.617	0.19
6	20	7V Biased	0.841	0.909	0.068
7	20	7V Biased	-2.121	-1.976	0.145
8	20	7V Biased	1.29	1.36	0.07
9	20	7V Biased	-0.096	-0.022	0.074
10	20	7V Biased	-1.315	-1.204	0.111
11	30	Unbiased	-1.606	-1.281	0.325
12	30	Unbiased	-2.244	-2.102	0.142
13	30	Unbiased	-1.755	-1.588	0.167
14	30	Unbiased	-1.381	-1.226	0.155
15	30	Unbiased	0.256	0.427	0.171
16	30	7V Biased	1.255	1.373	0.118
17	30	7V Biased	-2.609	-2.6	0.009
18	30	7V Biased	-2.314	-2.16	0.154
19	30	7V Biased	0.727	0.84	0.113
20	30	7V Biased	-1.839	-1.67	0.169
21	50	Unbiased	-2.077	-1.953	0.124
22	50	Unbiased	-1.949	-1.887	0.062
23	50	Unbiased	0.3	0.528	0.228
24	50	Unbiased	-0.963	-1.044	-0.081
25	50	Unbiased	-2.429	-2.129	0.3
26	50	7V Biased	-3.432	-3.366	0.066
27	50	7V Biased	0.617	0.81	0.193
28	50	7V Biased	-1.038	-0.921	0.117
29	50	7V Biased	0.071	0.251	0.18
30	50	7V Biased	0.243	0.667	0.424
31	0	Correlation	-1.593	-1.572	0.021
32	0	Correlation	1.07	1.07	0
33	0	Correlation	0.801	0.731	-0.07
34	0	Correlation	-1.192	-1.323	-0.131
35	0	Correlation	-1.755	-1.756	-0.001

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-1.755	-0.5338	1.07	1.3602	-1.756	-0.57	1.07	1.3564	-0.131	-0.0362	0.021	0.063148
20	-2.121	-0.3971	1.29	1.094	-1.976	-0.307	1.36	1.0751	-0.092	0.0901	0.194	0.081275
30	-2.609	-1.151	1.255	1.3771	-2.6	-0.9987	1.373	1.3783	0.009	0.1523	0.325	0.07749
50	-3.432	-1.0657	0.617	1.3733	-3.366	-0.9044	0.81	1.4314	-0.081	0.1613	0.424	0.13947

Device Test: 30.7 Current_Limit_Accuracy(Accuracy_Ilim_1A_1p5V)





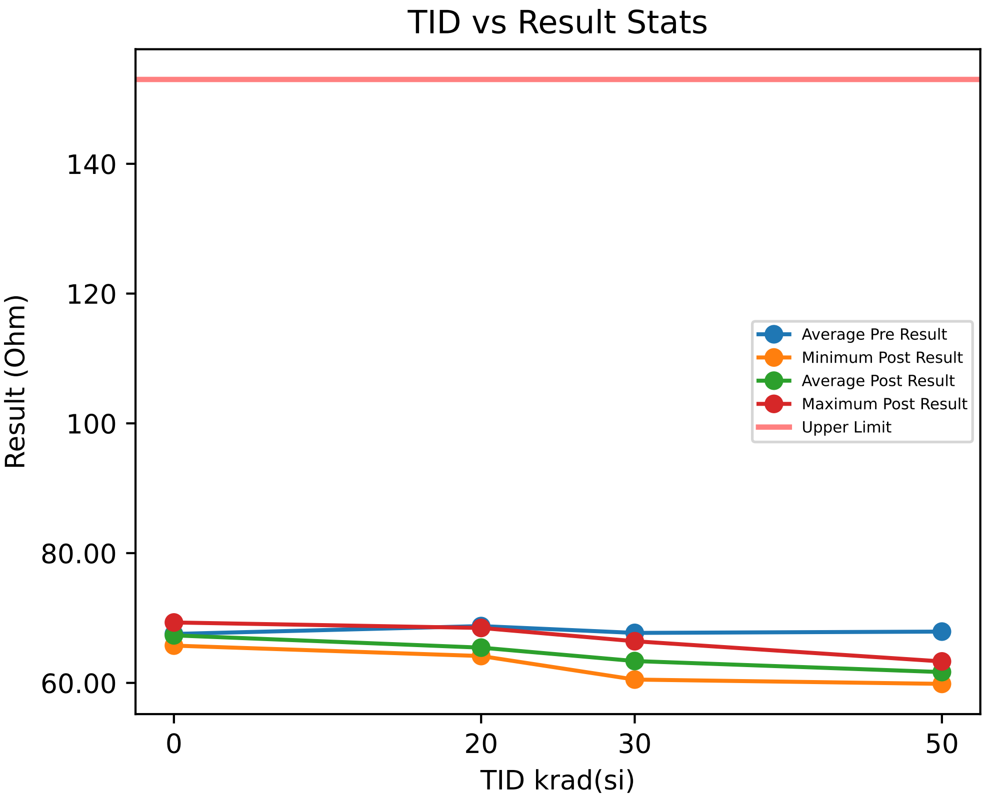
Test Results (Lower Limit = -20.0, Upper Limit = 20.0 (%))

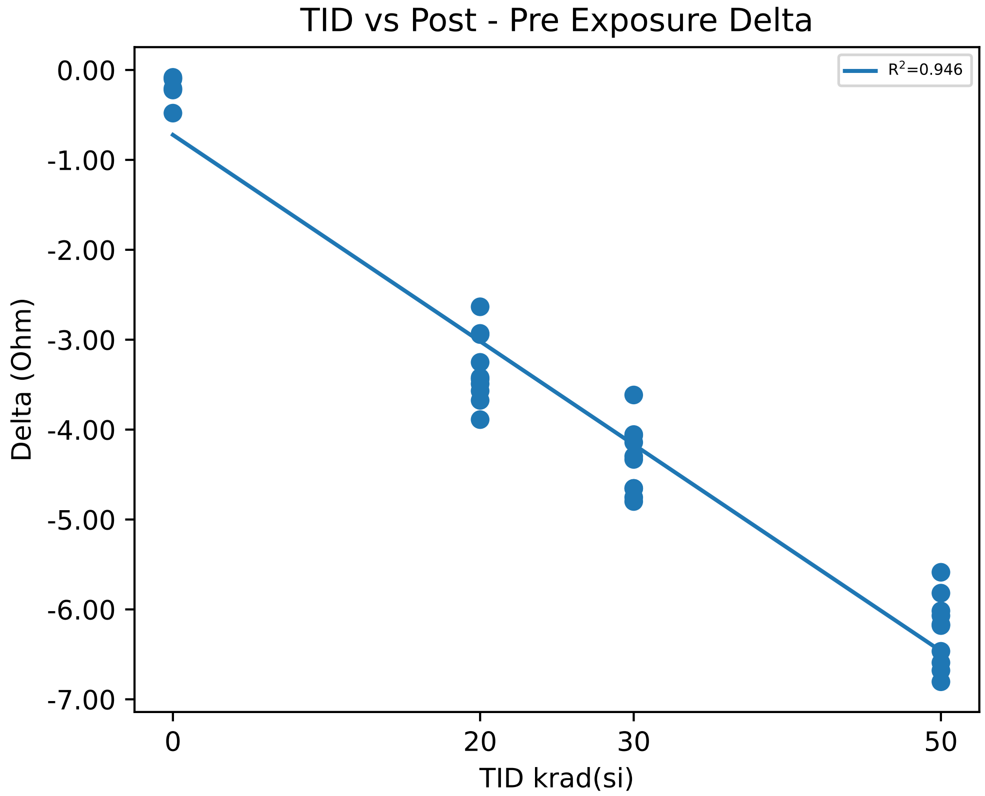
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	-2.477	-2.635	-0.158
2	20	Unbiased	-3.252	-3.278	-0.026
3	20	Unbiased	-1.077	-0.971	0.106
4	20	Unbiased	-2.054	-1.684	0.37
5	20	Unbiased	0.084	-0.048	-0.132
6	20	7V Biased	-0.655	-0.557	0.098
7	20	7V Biased	-2.635	-2.556	0.079
8	20	7V Biased	-0.497	0.166	0.663
9	20	7V Biased	-1.975	-1.79	0.185
10	20	7V Biased	-3.692	-3.807	-0.115
11	30	Unbiased	-4.563	-3.771	0.792
12	30	Unbiased	-3.876	-3.692	0.184
13	30	Unbiased	-3.269	-3.111	0.158
14	30	Unbiased	-3.665	-3.146	0.519
15	30	Unbiased	-0.576	-0.258	0.318
16	30	7V Biased	0.137	-0.468	-0.605
17	30	7V Biased	-3.216	-3.216	0
18	30	7V Biased	-3.612	-3.252	0.36
19	30	7V Biased	-0.549	-0.575	-0.026
20	30	7V Biased	-3.084	-3.164	-0.08
21	50	Unbiased	-3.929	-3.718	0.211
22	50	Unbiased	-4.325	-3.992	0.333
23	50	Unbiased	-1.104	-0.522	0.582
24	50	Unbiased	-1.896	-2.397	-0.501
25	50	Unbiased	-3.876	-3.296	0.58
26	50	7V Biased	-5.091	-5.365	-0.274
27	50	7V Biased	-0.576	-0.496	0.08
28	50	7V Biased	-2.635	-2.001	0.634
29	50	7V Biased	-2.847	-2.583	0.264
30	50	7V Biased	-0.497	0.104	0.601
31	0	Correlation	-2.503	-2.582	-0.079
32	0	Correlation	-0.629	-0.6	0.029
33	0	Correlation	0.058	0.243	0.185
34	0	Correlation	-1.209	-1.878	-0.669
35	0	Correlation	-3.216	-3.242	-0.026

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-3.216	-1.4998	0.058	1.3436	-3.242	-1.6118	0.243	1.426	-0.669	-0.112	0.185	0.32666
20	-3.692	-1.823	0.084	1.2479	-3.807	-1.716	0.166	1.3577	-0.158	0.107	0.663	0.25377
30	-4.563	-2.6273	0.137	1.6495	-3.771	-2.4653	-0.258	1.4219	-0.605	0.162	0.792	0.37959
50	-5.091	-2.6776	-0.497	1.6272	-5.365	-2.4266	0.104	1.7472	-0.501	0.251	0.634	0.38957

Device Test: 35.0 ILTIMER_PDR(ILT_PDresistance_10mA_Vin1p5V)





Test Results (Upper Limit = 153.0 (Ohm))

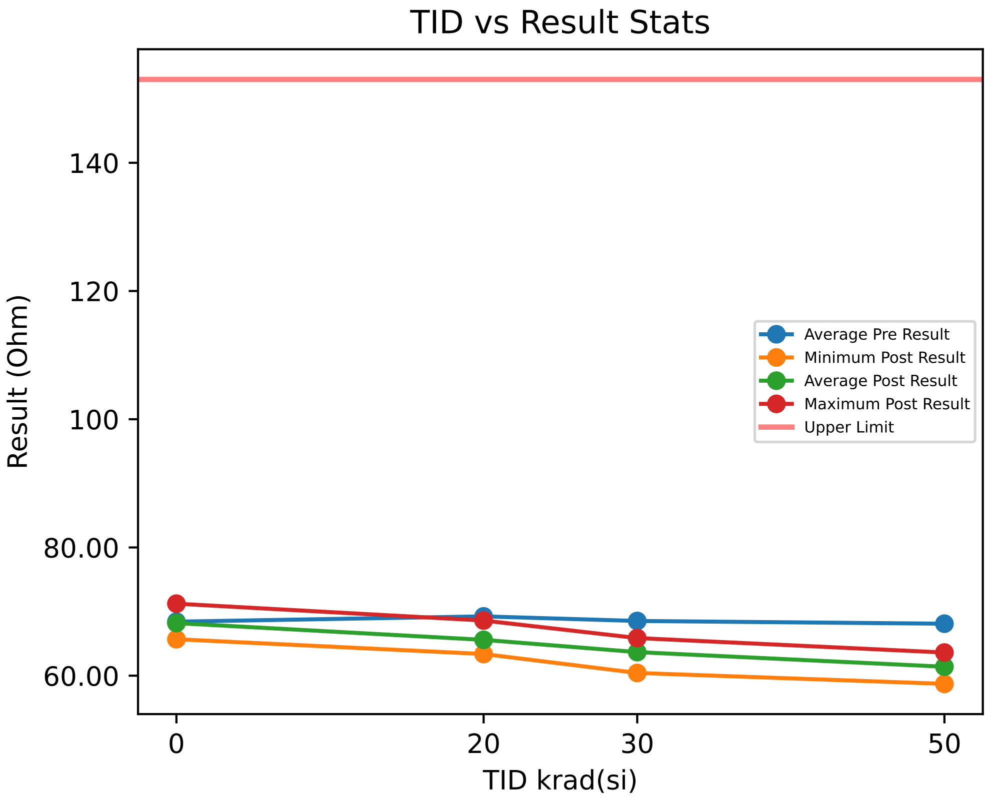
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	66.775	64.141	-2.634
2	20	Unbiased	67.168	64.238	-2.93
3	20	Unbiased	71.892	68.471	-3.421
4	20	Unbiased	67.763	64.82	-2.943
5	20	Unbiased	68.482	65.23	-3.252
6	20	7V Biased	68.174	64.604	-3.57
7	20	7V Biased	69.275	65.834	-3.441
8	20	7V Biased	69.533	65.858	-3.675
9	20	7V Biased	68.431	64.94	-3.491
10	20	7V Biased	70.087	66.198	-3.889
11	30	Unbiased	68.3	64.158	-4.142
12	30	Unbiased	64.129	60.514	-3.615
13	30	Unbiased	68.169	63.837	-4.332
14	30	Unbiased	65.642	61.58	-4.062
15	30	Unbiased	67.558	63.503	-4.055
16	30	7V Biased	67.339	63.041	-4.298
17	30	7V Biased	68.649	63.995	-4.654
18	30	7V Biased	67.268	62.514	-4.754
19	30	7V Biased	71.223	66.423	-4.8
20	30	7V Biased	68.774	64.12	-4.654
21	50	Unbiased	66.871	61.052	-5.819
22	50	Unbiased	67.2	61.02	-6.18
23	50	Unbiased	68.087	61.92	-6.167
24	50	Unbiased	69.365	62.685	-6.68
25	50	Unbiased	70.115	63.31	-6.805
26	50	7V Biased	66.801	60.731	-6.07
27	50	7V Biased	67.534	61.517	-6.017
28	50	7V Biased	69.554	62.962	-6.592
29	50	7V Biased	65.437	59.85	-5.587
30	50	7V Biased	68.104	61.638	-6.466
31	0	Correlation	66.505	66.404	-0.101
32	0	Correlation	68.545	68.322	-0.223
33	0	Correlation	67.045	66.84	-0.205
34	0	Correlation	66.227	65.747	-0.48
35	0	Correlation	69.394	69.312	-0.082

Test Statistics (Ohm)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	66.227	67.543	69.394	1.3682	65.747	67.325	69.312	1.4591	-0.48	-0.2182	-0.082	0.15892
20	66.775	68.758	71.892	1.5067	64.141	65.433	68.471	1.2737	-3.889	-3.3246	-2.634	0.38523
30	64.129	67.705	71.223	1.8965	60.514	63.368	66.423	1.6101	-4.8	-4.3366	-3.615	0.38082
50	65.437	67.907	70.115	1.4461	59.85	61.669	63.31	1.0788	-6.805	-6.2383	-5.587	0.39143

Device Test: 35.1 RTIMER_PDR(RT_PDresistance_10mA_Vin1p5V)

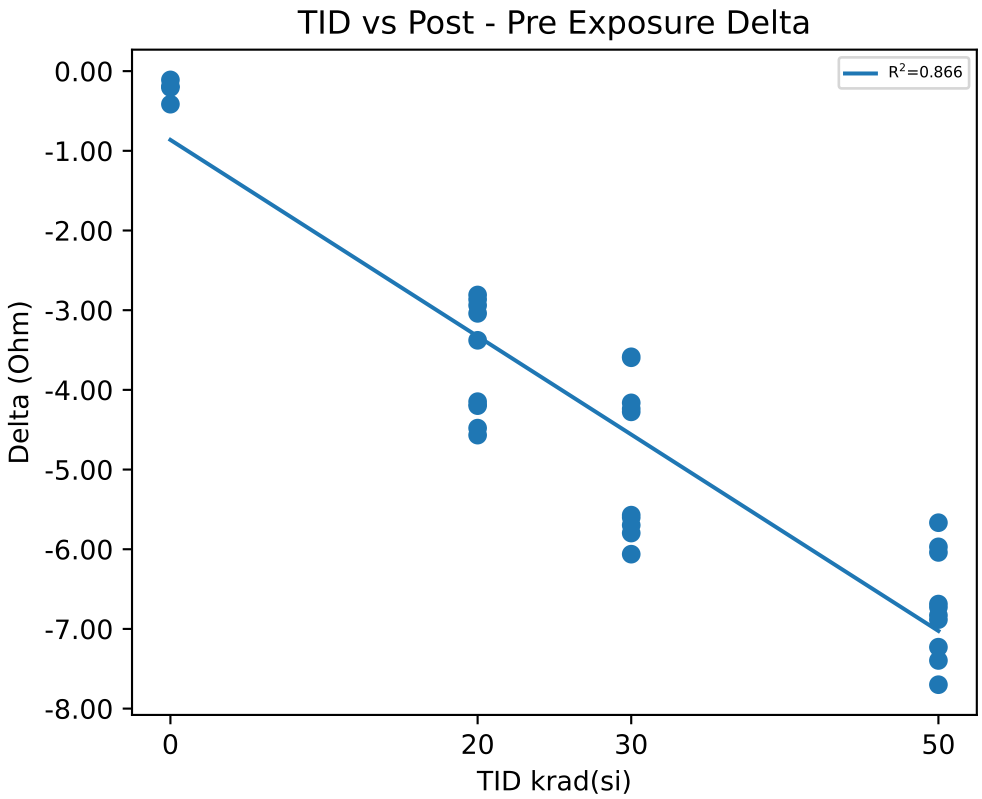
TID vs Result Stats



Test Results (Upper Limit = 153.0 (Ohm))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	68.774	65.965	-2.809
2	20	Unbiased	68.31	65.446	-2.864
3	20	Unbiased	71.979	68.601	-3.378
4	20	Unbiased	69.358	66.419	-2.939
5	20	Unbiased	67.905	64.865	-3.04
6	20	7V Biased	69.341	65.143	-4.198
7	20	7V Biased	69.027	64.839	-4.188
8	20	7V Biased	69.745	65.177	-4.568
9	20	7V Biased	67.523	63.375	-4.148
10	20	7V Biased	70.537	66.057	-4.48
11	30	Unbiased	70.144	65.868	-4.276
12	30	Unbiased	64.01	60.425	-3.585
13	30	Unbiased	69.087	64.85	-4.237
14	30	Unbiased	65.328	61.731	-3.597
15	30	Unbiased	67.88	63.717	-4.163
16	30	7V Biased	67.66	62.059	-5.601
17	30	7V Biased	70.696	64.998	-5.698
18	30	7V Biased	68.165	62.593	-5.572
19	30	7V Biased	71.118	65.321	-5.797
20	30	7V Biased	71.253	65.191	-6.062
21	50	Unbiased	68.894	62.854	-6.04
22	50	Unbiased	66.89	61.223	-5.667
23	50	Unbiased	67.374	61.404	-5.97
24	50	Unbiased	69.024	62.336	-6.688
25	50	Unbiased	70.336	63.61	-6.726
26	50	7V Biased	66.676	59.846	-6.83
27	50	7V Biased	67.301	60.072	-7.229
28	50	7V Biased	69.823	62.123	-7.7
29	50	7V Biased	65.605	58.722	-6.883
30	50	7V Biased	69.16	61.764	-7.396
31	0	Correlation	69.054	68.849	-0.205
32	0	Correlation	68.831	68.416	-0.415
33	0	Correlation	67.01	66.818	-0.192
34	0	Correlation	65.796	65.686	-0.11
35	0	Correlation	71.426	71.229	-0.197

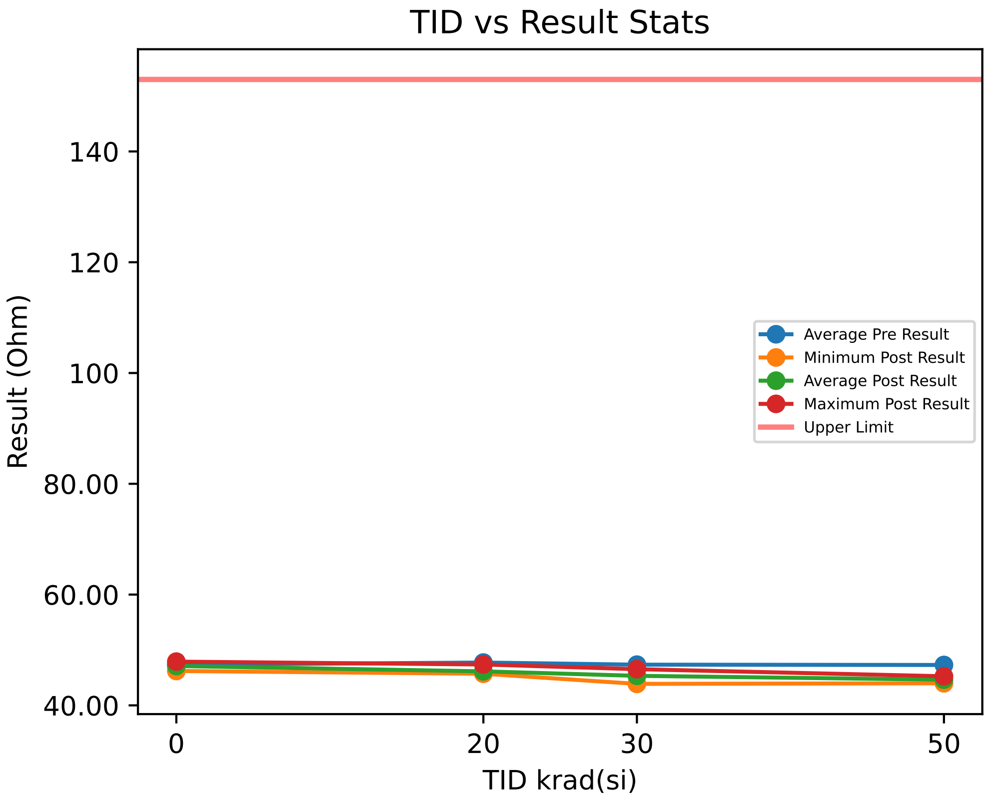
TID vs Post - Pre Exposure Delta

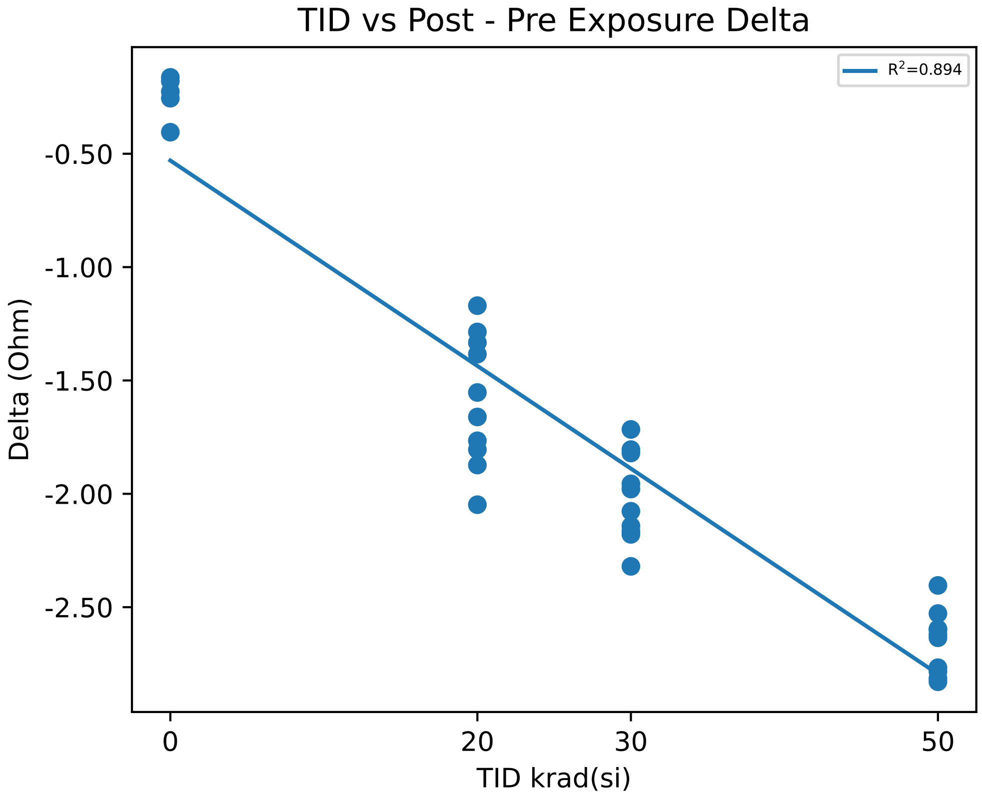


Test Statistics (Ohm)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	65.796	68.423	71.426	2.1494	65.686	68.2	71.229	2.1138	-0.415	-0.2238	-0.11	0.11357
20	67.523	69.25	71.979	1.3047	63.375	65.589	68.601	1.354	-4.568	-3.6612	-2.809	0.71839
30	64.01	68.534	71.253	2.443	60.425	63.675	65.868	1.8581	-6.062	-4.8588	-3.585	0.97279
50	65.605	68.108	70.336	1.5441	58.722	61.395	63.61	1.4874	-7.7	-6.7129	-5.667	0.654

Device Test: 35.2 ILTIMER_PDR(ILT_PDresistance_10mA_Vin1p8V)





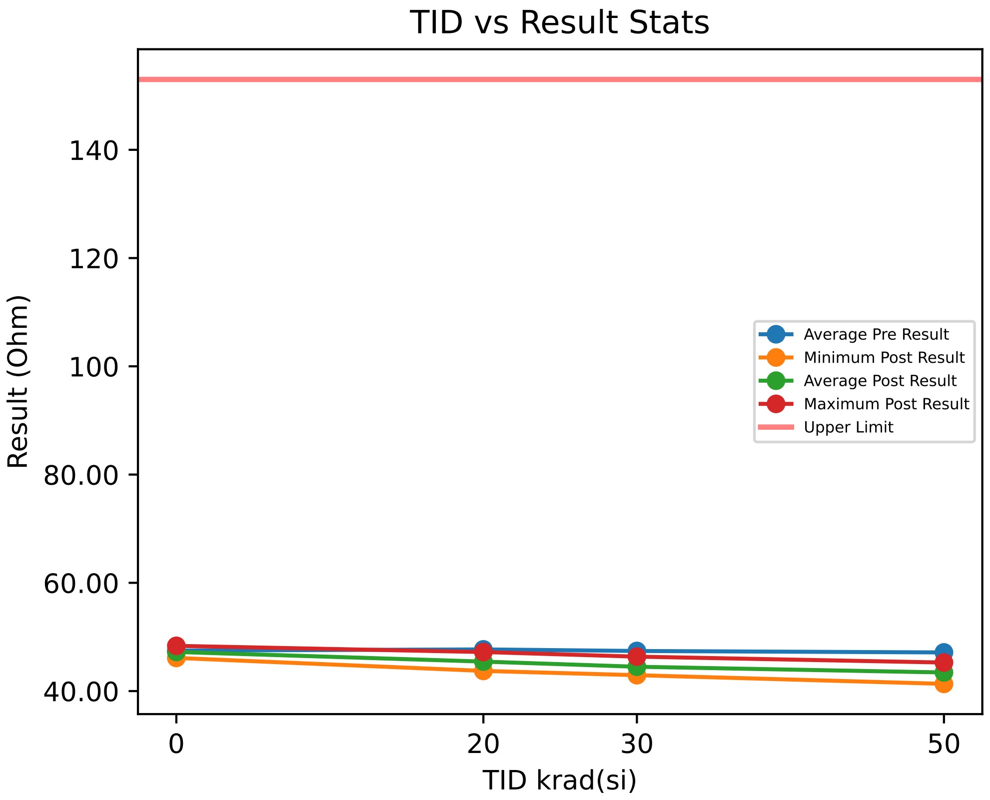
Test Results (Upper Limit = 153.0 (Ohm))

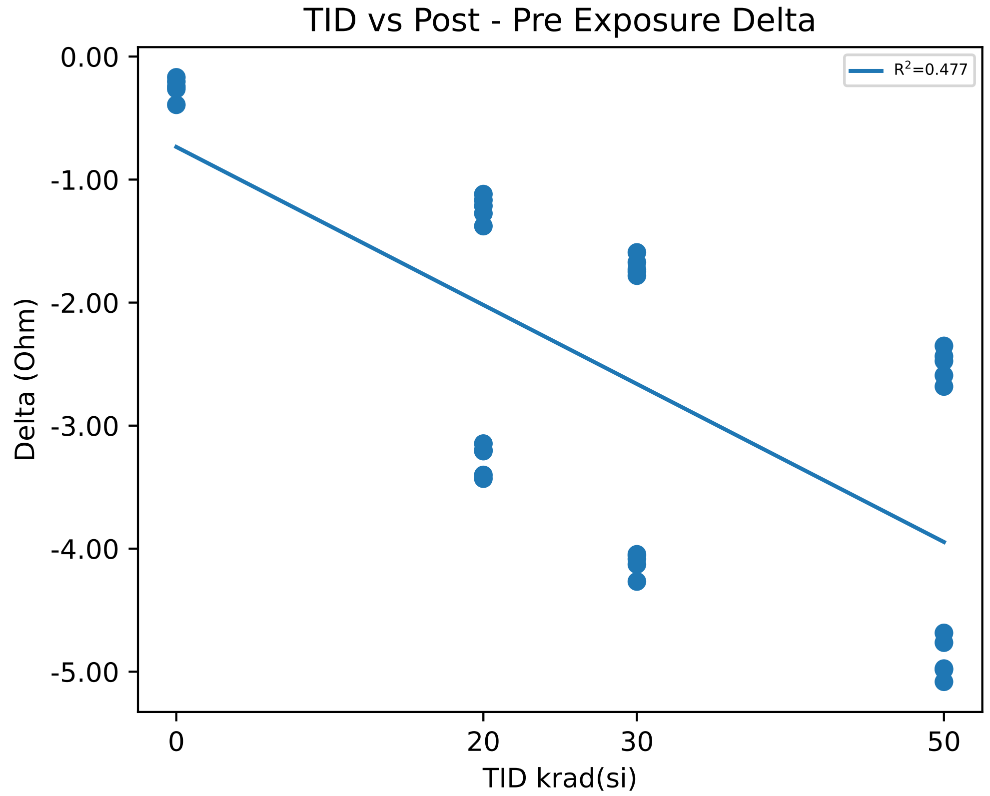
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	46.904	45.734	-1.17
2	20	Unbiased	47.111	45.778	-1.333
3	20	Unbiased	48.763	47.379	-1.384
4	20	Unbiased	47.195	45.909	-1.286
5	20	Unbiased	47.519	45.966	-1.553
6	20	7V Biased	47.58	45.707	-1.873
7	20	7V Biased	47.646	45.985	-1.661
8	20	7V Biased	48.079	46.274	-1.805
9	20	7V Biased	47.492	45.726	-1.766
10	20	7V Biased	48.987	46.939	-2.048
11	30	Unbiased	47.69	45.87	-1.82
12	30	Unbiased	45.595	43.879	-1.716
13	30	Unbiased	47.526	45.57	-1.956
14	30	Unbiased	46.777	44.798	-1.979
15	30	Unbiased	47.374	45.569	-1.805
16	30	7V Biased	47.157	45.08	-2.077
17	30	7V Biased	47.581	45.416	-2.165
18	30	7V Biased	47.212	44.892	-2.32
19	30	7V Biased	48.673	46.531	-2.142
20	30	7V Biased	47.874	45.695	-2.179
21	50	Unbiased	47.072	44.472	-2.6
22	50	Unbiased	46.818	44.051	-2.767
23	50	Unbiased	47.368	44.772	-2.596
24	50	Unbiased	47.788	45.004	-2.784
25	50	Unbiased	48.078	45.249	-2.829
26	50	7V Biased	46.701	44.081	-2.62
27	50	7V Biased	47.274	44.746	-2.528
28	50	7V Biased	47.731	45.096	-2.635
29	50	7V Biased	46.389	43.985	-2.404
30	50	7V Biased	47.693	44.879	-2.814
31	0	Correlation	47.122	46.959	-0.163
32	0	Correlation	47.757	47.502	-0.255
33	0	Correlation	47.186	46.96	-0.226
34	0	Correlation	46.61	46.205	-0.405
35	0	Correlation	48.074	47.894	-0.18

Test Statistics (Ohm)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	46.61	47.35	48.074	0.57365	46.205	47.104	47.894	0.63884	-0.405	-0.2458	-0.163	0.096186
20	46.904	47.728	48.987	0.68729	45.707	46.14	47.379	0.5729	-2.048	-1.5879	-1.17	0.28881
30	45.595	47.346	48.673	0.79512	43.879	45.33	46.531	0.71741	-2.32	-2.0159	-1.716	0.19399
50	46.389	47.291	48.078	0.54377	43.985	44.633	45.249	0.46108	-2.829	-2.6577	-2.404	0.13821

Device Test: 35.3 RTIMER_PDR(RT_PDresistance_10mA_Vin1p8V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

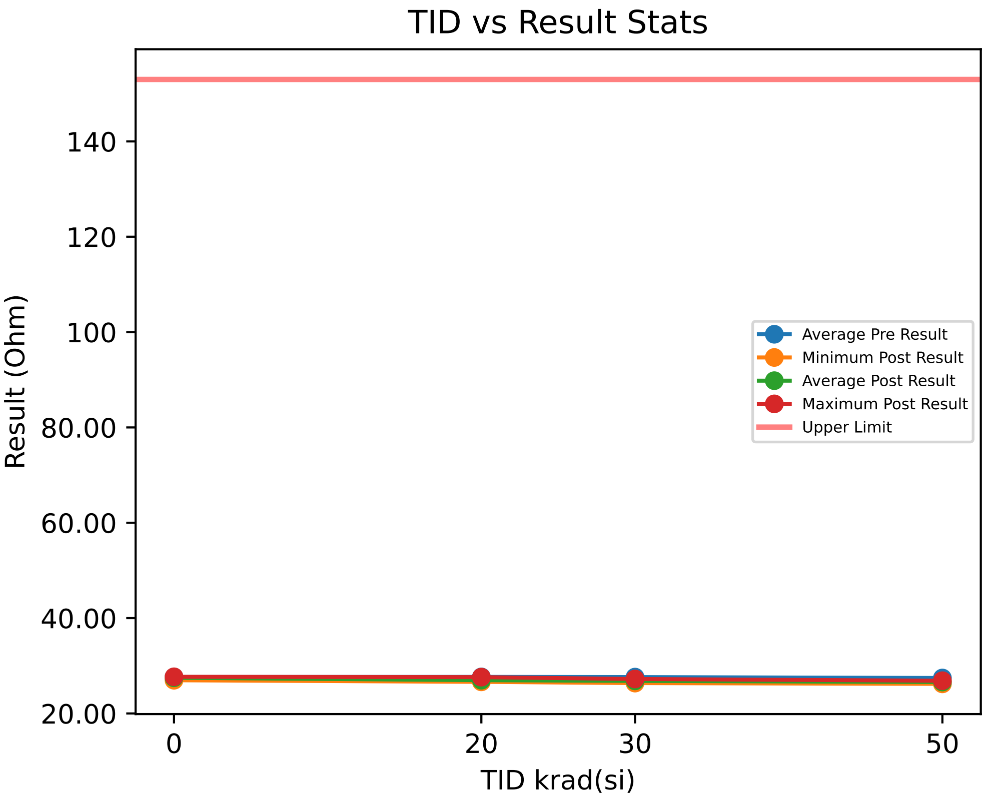
Test Results (Upper Limit = 153.0 (Ohm))

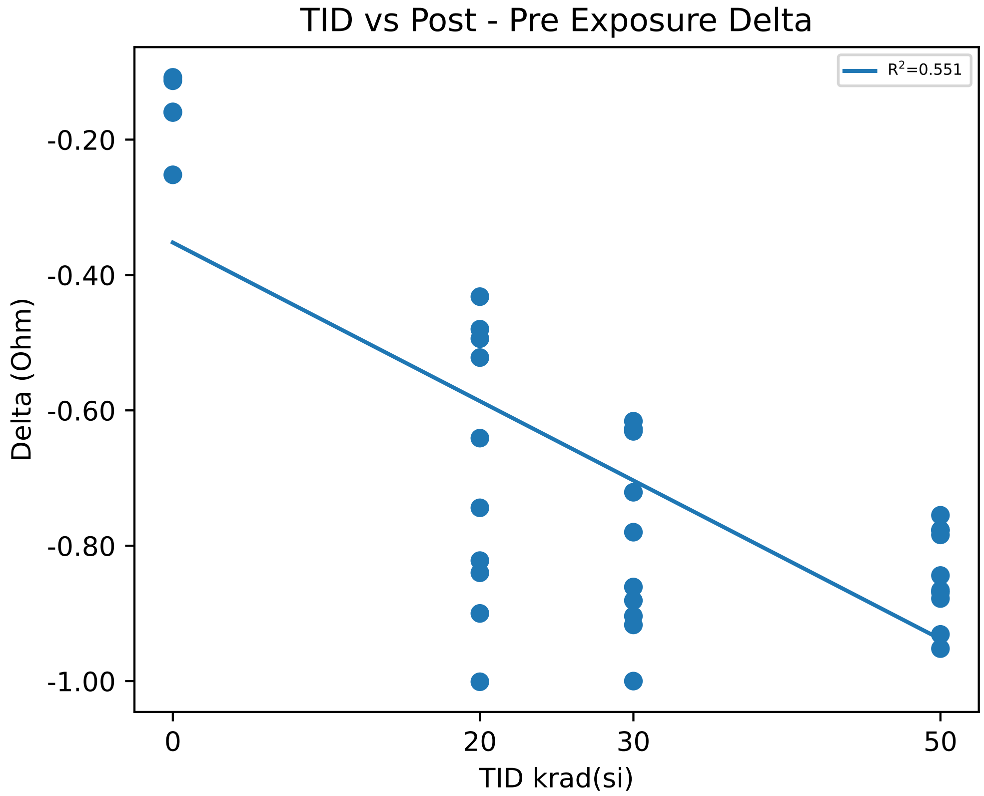
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	47.549	46.431	-1.118
2	20	Unbiased	47.373	46.159	-1.214
3	20	Unbiased	48.487	47.212	-1.275
4	20	Unbiased	47.546	46.379	-1.167
5	20	Unbiased	47.016	45.638	-1.378
6	20	7V Biased	47.858	44.651	-3.207
7	20	7V Biased	47.323	44.177	-3.146
8	20	7V Biased	47.97	44.539	-3.431
9	20	7V Biased	46.925	43.726	-3.199
10	20	7V Biased	48.953	45.552	-3.401
11	30	Unbiased	48.092	46.361	-1.731
12	30	Unbiased	45.381	43.708	-1.673
13	30	Unbiased	47.711	45.962	-1.749
14	30	Unbiased	46.299	44.707	-1.592
15	30	Unbiased	47.258	45.477	-1.781
16	30	7V Biased	47.018	42.934	-4.084
17	30	7V Biased	48.129	44.072	-4.057
18	30	7V Biased	47.31	43.264	-4.046
19	30	7V Biased	48.402	44.274	-4.128
20	30	7V Biased	48.464	44.197	-4.267
21	50	Unbiased	47.632	45.196	-2.436
22	50	Unbiased	46.577	44.225	-2.352
23	50	Unbiased	46.8	44.325	-2.475
24	50	Unbiased	47.434	44.752	-2.682
25	50	Unbiased	47.865	45.273	-2.592
26	50	7V Biased	46.471	41.786	-4.685
27	50	7V Biased	47.002	42.027	-4.975
28	50	7V Biased	47.704	42.622	-5.082
29	50	7V Biased	46.095	41.331	-4.764
30	50	7V Biased	47.82	42.837	-4.983
31	0	Correlation	47.921	47.679	-0.242
32	0	Correlation	47.631	47.239	-0.392
33	0	Correlation	46.939	46.736	-0.203
34	0	Correlation	46.292	46.123	-0.169
35	0	Correlation	48.618	48.355	-0.263

Test Statistics (Ohm)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	46.292	47.48	48.618	0.89671	46.123	47.226	48.355	0.85684	-0.392	-0.2538	-0.169	0.085286
20	46.925	47.7	48.953	0.63695	43.726	45.446	47.212	1.1323	-3.431	-2.2536	-1.118	1.0841
30	45.381	47.406	48.464	0.9835	42.934	44.496	46.361	1.1319	-4.267	-2.9108	-1.592	1.2732
50	46.095	47.14	47.865	0.63472	41.331	43.437	45.273	1.4824	-5.082	-3.7026	-2.352	1.2677

Device Test: 35.4 ILTIMER_PDR(ILT_PDresistance_10mA_Vin3p3V)





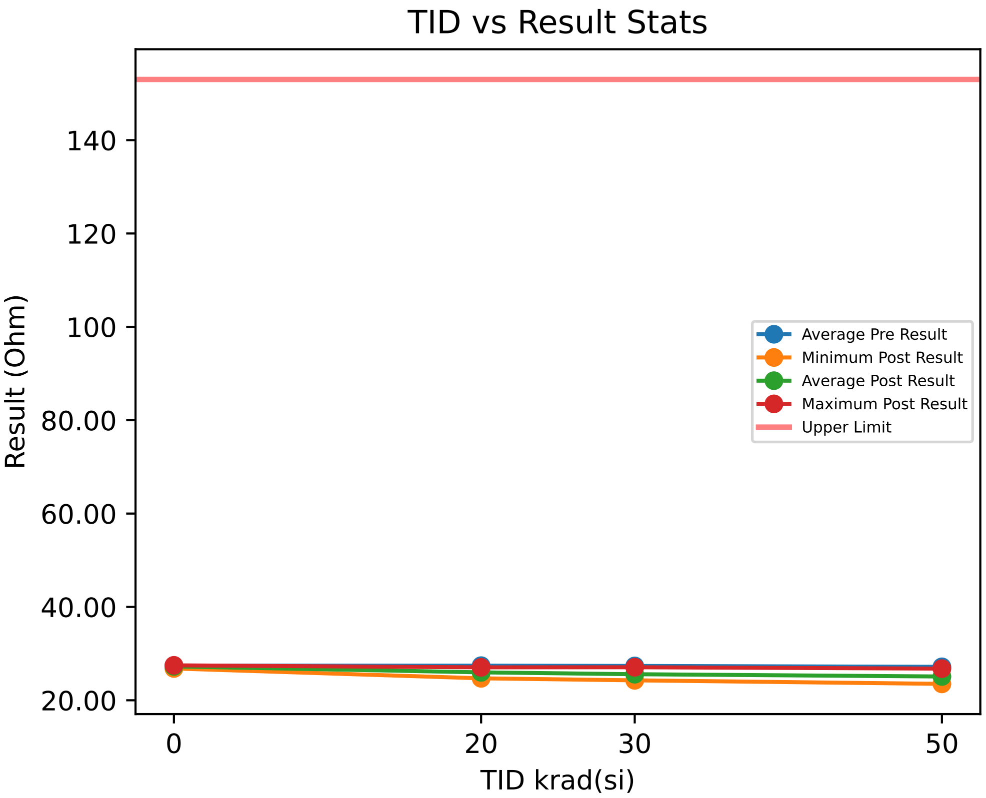
Test Results (Upper Limit = 153.0 (Ohm))

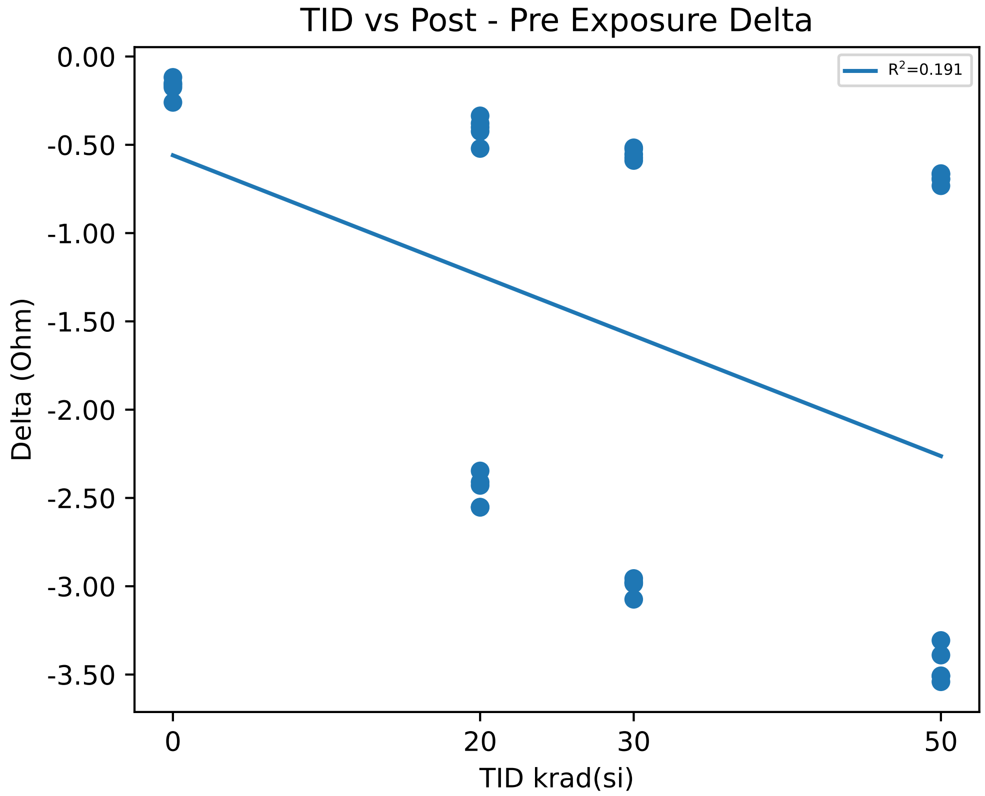
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	27.38	26.948	-0.432
2	20	Unbiased	27.496	26.974	-0.522
3	20	Unbiased	27.806	27.312	-0.494
4	20	Unbiased	27.42	26.94	-0.48
5	20	Unbiased	27.509	26.868	-0.641
6	20	7V Biased	27.635	26.735	-0.9
7	20	7V Biased	27.371	26.627	-0.744
8	20	7V Biased	27.894	27.072	-0.822
9	20	7V Biased	27.522	26.682	-0.84
10	20	7V Biased	28.614	27.613	-1.001
11	30	Unbiased	27.84	27.224	-0.616
12	30	Unbiased	26.997	26.366	-0.631
13	30	Unbiased	27.624	26.903	-0.721
14	30	Unbiased	27.635	26.855	-0.78
15	30	Unbiased	27.811	27.184	-0.627
16	30	7V Biased	27.593	26.712	-0.881
17	30	7V Biased	27.544	26.627	-0.917
18	30	7V Biased	27.604	26.604	-1
19	30	7V Biased	27.82	26.959	-0.861
20	30	7V Biased	27.773	26.869	-0.904
21	50	Unbiased	27.546	26.677	-0.869
22	50	Unbiased	27.155	26.203	-0.952
23	50	Unbiased	27.425	26.641	-0.784
24	50	Unbiased	27.511	26.667	-0.844
25	50	Unbiased	27.499	26.633	-0.866
26	50	7V Biased	27.162	26.284	-0.878
27	50	7V Biased	27.642	26.865	-0.777
28	50	7V Biased	27.313	26.536	-0.777
29	50	7V Biased	27.299	26.544	-0.755
30	50	7V Biased	27.794	26.863	-0.931
31	0	Correlation	27.685	27.577	-0.108
32	0	Correlation	27.845	27.685	-0.16
33	0	Correlation	27.718	27.559	-0.159
34	0	Correlation	27.216	26.964	-0.252
35	0	Correlation	27.735	27.622	-0.113

Test Statistics (Ohm)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	27.216	27.64	27.845	0.2444	26.964	27.481	27.685	0.29329	-0.252	-0.1584	-0.108	0.057804
20	27.371	27.665	28.614	0.37636	26.627	26.977	27.613	0.29962	-1.001	-0.6876	-0.432	0.20092
30	26.997	27.624	27.84	0.24569	26.366	26.83	27.224	0.26377	-1	-0.7938	-0.616	0.1388
50	27.155	27.435	27.794	0.20557	26.203	26.591	26.865	0.21513	-0.952	-0.8433	-0.755	0.068307

Device Test: 35.5 RTIMER_PDR(RT_PDresistance_10mA_Vin3p3V)





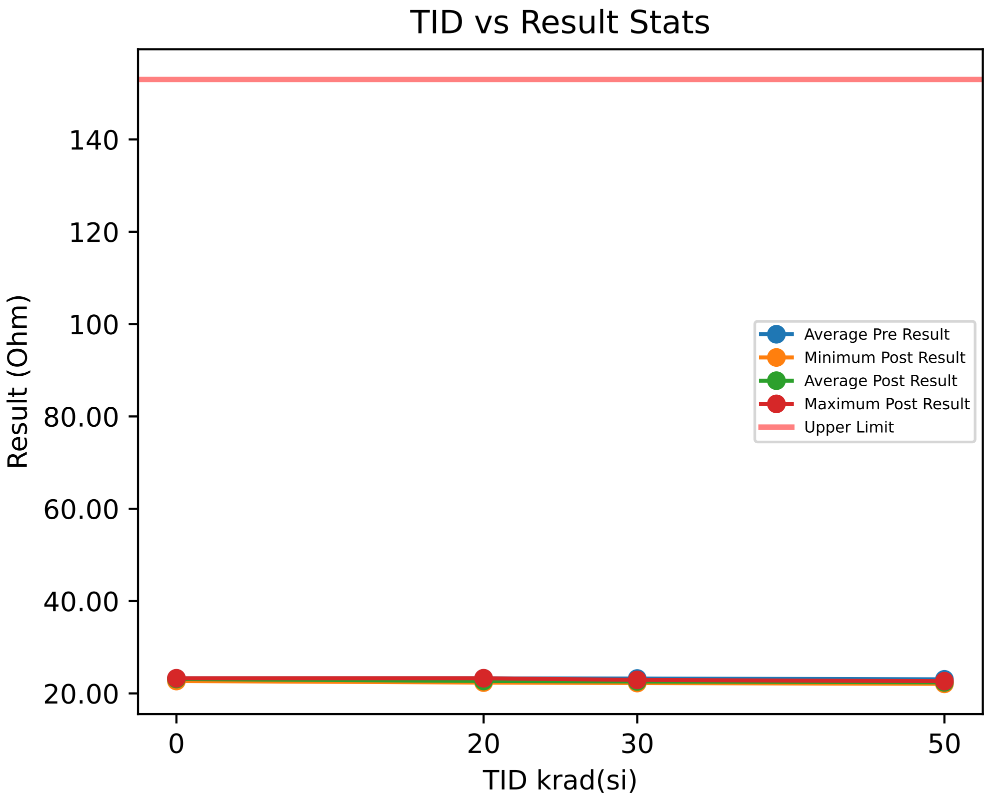
Test Results (Upper Limit = 153.0 (Ohm))

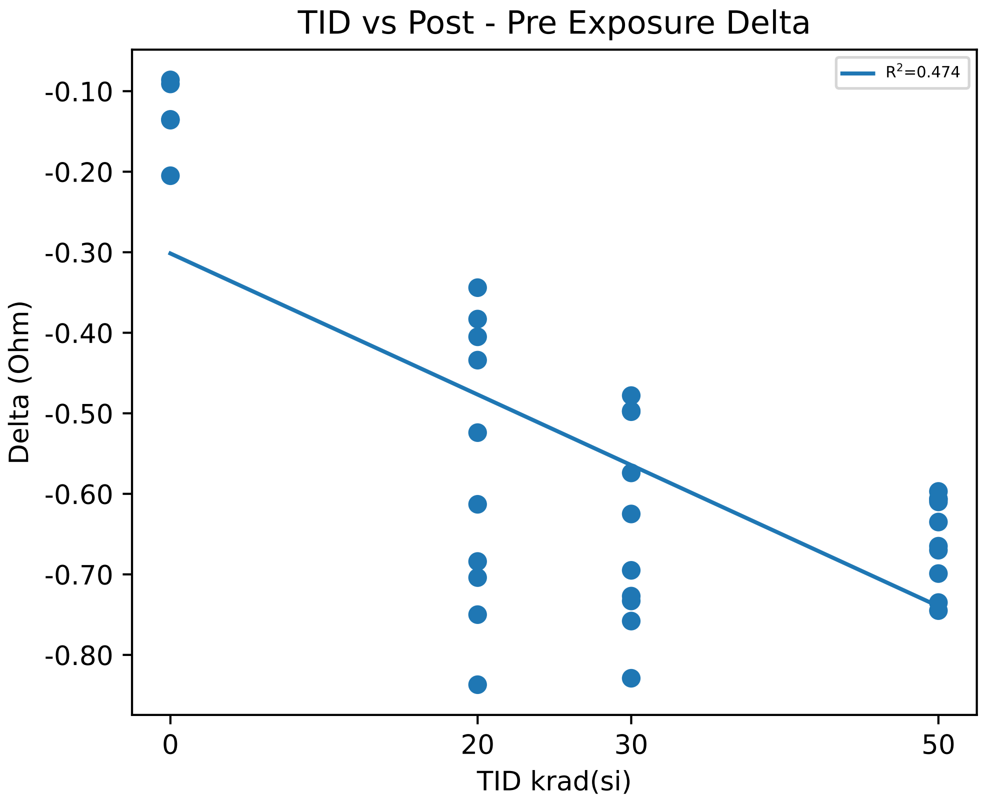
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	27.35	27.014	-0.336
2	20	Unbiased	27.326	26.902	-0.424
3	20	Unbiased	27.455	27.054	-0.401
4	20	Unbiased	27.195	26.816	-0.379
5	20	Unbiased	27.079	26.558	-0.521
6	20	7V Biased	27.515	25.105	-2.41
7	20	7V Biased	27.13	24.783	-2.347
8	20	7V Biased	27.654	25.102	-2.552
9	20	7V Biased	27.13	24.701	-2.429
10	20	7V Biased	28.312	25.759	-2.553
11	30	Unbiased	27.596	27.073	-0.523
12	30	Unbiased	26.719	26.13	-0.589
13	30	Unbiased	27.399	26.845	-0.554
14	30	Unbiased	27.156	26.639	-0.517
15	30	Unbiased	27.511	26.937	-0.574
16	30	7V Biased	27.252	24.271	-2.981
17	30	7V Biased	27.46	24.504	-2.956
18	30	7V Biased	27.368	24.392	-2.976
19	30	7V Biased	27.472	24.487	-2.985
20	30	7V Biased	27.618	24.544	-3.074
21	50	Unbiased	27.476	26.781	-0.695
22	50	Unbiased	26.931	26.264	-0.667
23	50	Unbiased	26.961	26.298	-0.663
24	50	Unbiased	27.183	26.451	-0.732
25	50	Unbiased	27.247	26.555	-0.692
26	50	7V Biased	26.887	23.58	-3.307
27	50	7V Biased	27.341	23.8	-3.541
28	50	7V Biased	27.169	23.66	-3.509
29	50	7V Biased	26.904	23.514	-3.39
30	50	7V Biased	27.55	24.043	-3.507
31	0	Correlation	27.646	27.485	-0.161
32	0	Correlation	27.532	27.272	-0.26
33	0	Correlation	27.424	27.273	-0.151
34	0	Correlation	26.927	26.809	-0.118
35	0	Correlation	27.615	27.44	-0.175

Test Statistics (Ohm)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	26.927	27.429	27.646	0.2934	26.809	27.256	27.485	0.2677	-0.26	-0.173	-0.118	0.052976
20	27.079	27.415	28.312	0.36655	24.701	25.979	27.054	0.98656	-2.553	-1.4352	-0.336	1.081
30	26.719	27.355	27.618	0.26523	24.271	25.582	27.073	1.2313	-3.074	-1.7729	-0.517	1.2881
50	26.887	27.165	27.55	0.24147	23.514	25.095	26.781	1.463	-3.541	-2.0703	-0.663	1.4568

Device Test: 35.6 ILTIMER_PDR(ILT_PDresistance_10mA_Vin5p0V)





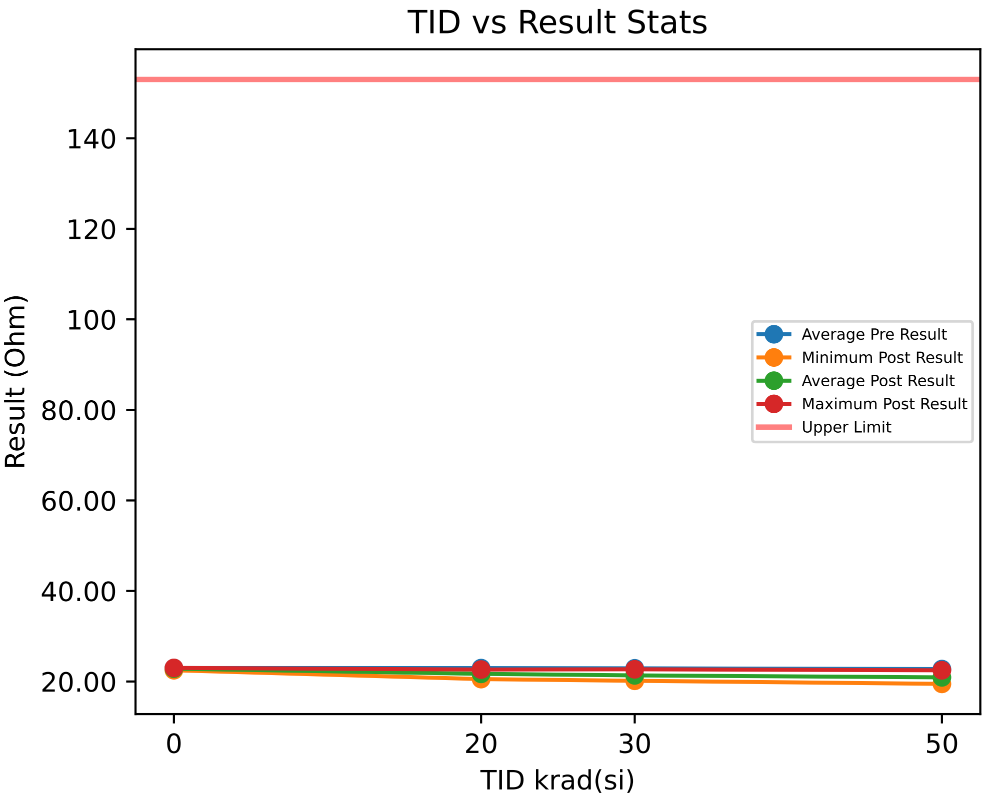
Test Results (Upper Limit = 153.0 (Ohm))

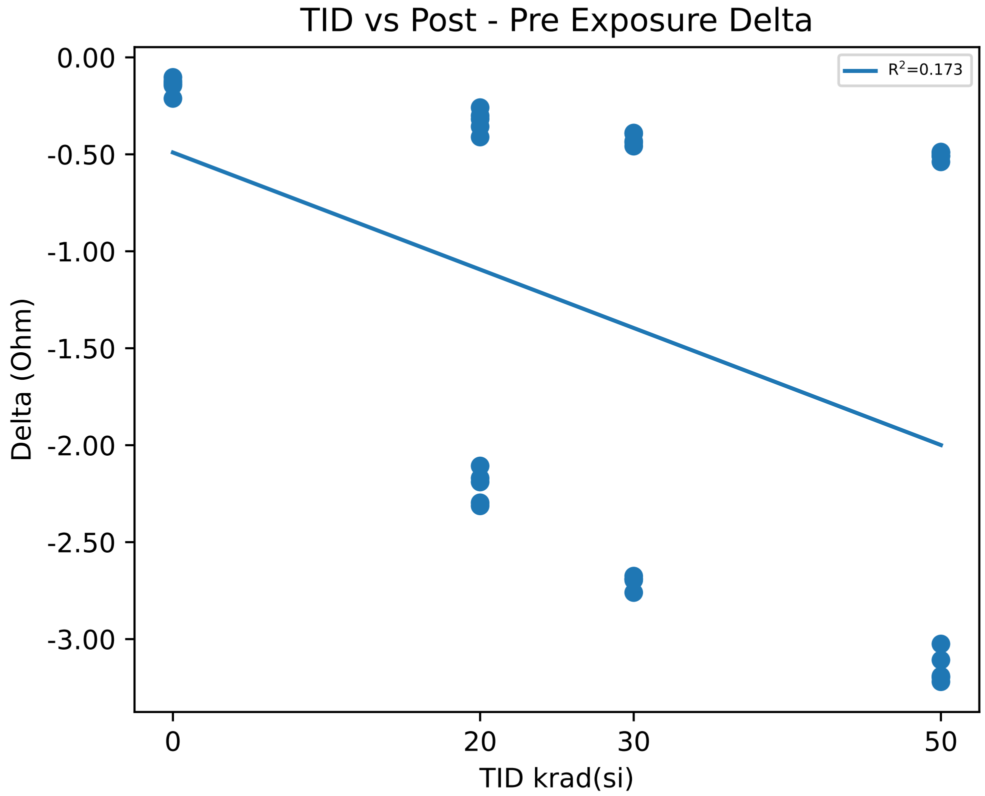
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	23.026	22.682	-0.344
2	20	Unbiased	23.153	22.719	-0.434
3	20	Unbiased	23.337	22.932	-0.405
4	20	Unbiased	23.064	22.681	-0.383
5	20	Unbiased	23.108	22.584	-0.524
6	20	7V Biased	23.232	22.482	-0.75
7	20	7V Biased	22.954	22.341	-0.613
8	20	7V Biased	23.429	22.745	-0.684
9	20	7V Biased	23.107	22.403	-0.704
10	20	7V Biased	24.121	23.284	-0.837
11	30	Unbiased	23.395	22.917	-0.478
12	30	Unbiased	22.737	22.24	-0.497
13	30	Unbiased	23.252	22.678	-0.574
14	30	Unbiased	23.297	22.672	-0.625
15	30	Unbiased	23.389	22.891	-0.498
16	30	7V Biased	23.211	22.484	-0.727
17	30	7V Biased	23.138	22.38	-0.758
18	30	7V Biased	23.198	22.369	-0.829
19	30	7V Biased	23.331	22.636	-0.695
20	30	7V Biased	23.312	22.579	-0.733
21	50	Unbiased	23.167	22.497	-0.67
22	50	Unbiased	22.809	22.064	-0.745
23	50	Unbiased	23.026	22.429	-0.597
24	50	Unbiased	23.076	22.441	-0.635
25	50	Unbiased	23.059	22.394	-0.665
26	50	7V Biased	22.819	22.12	-0.699
27	50	7V Biased	23.26	22.65	-0.61
28	50	7V Biased	22.9	22.294	-0.606
29	50	7V Biased	22.978	22.371	-0.607
30	50	7V Biased	23.371	22.636	-0.735
31	0	Correlation	23.309	23.218	-0.091
32	0	Correlation	23.414	23.279	-0.135
33	0	Correlation	23.323	23.187	-0.136
34	0	Correlation	22.883	22.678	-0.205
35	0	Correlation	23.301	23.215	-0.086

Test Statistics (Ohm)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.883	23.246	23.414	0.20792	22.678	23.115	23.279	0.24681	-0.205	-0.1306	-0.086	0.047805
20	22.954	23.253	24.121	0.3368	22.341	22.685	23.284	0.27363	-0.837	-0.5678	-0.344	0.17331
30	22.737	23.226	23.395	0.19065	22.24	22.585	22.917	0.22126	-0.829	-0.6414	-0.478	0.12486
50	22.809	23.047	23.371	0.18293	22.064	22.39	22.65	0.1922	-0.745	-0.6569	-0.597	0.054994

Device Test: 35.7 RTIMER_PDR(RT_PDresistance_10mA_Vin5p0V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

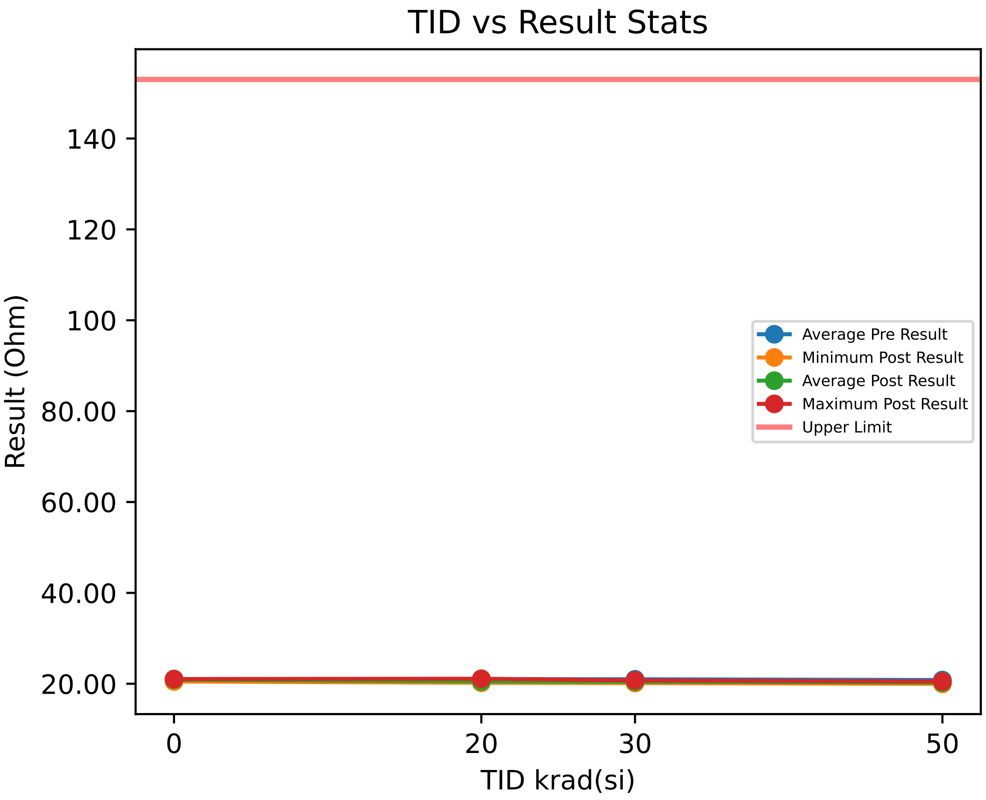
Test Results (Upper Limit = 153.0 (Ohm))

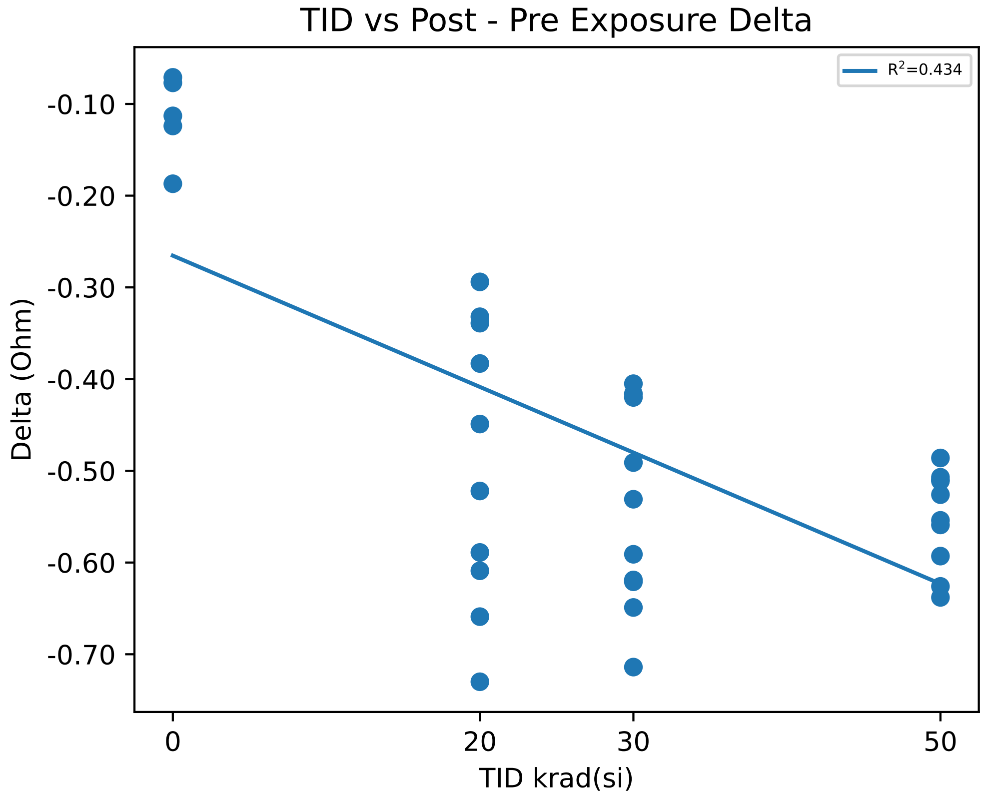
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	22.887	22.628	-0.259
2	20	Unbiased	22.918	22.561	-0.357
3	20	Unbiased	22.958	22.64	-0.318
4	20	Unbiased	22.756	22.455	-0.301
5	20	Unbiased	22.678	22.267	-0.411
6	20	7V Biased	23.058	20.888	-2.17
7	20	7V Biased	22.697	20.59	-2.107
8	20	7V Biased	23.162	20.865	-2.297
9	20	7V Biased	22.72	20.53	-2.19
10	20	7V Biased	23.767	21.454	-2.313
11	30	Unbiased	23.088	22.695	-0.393
12	30	Unbiased	22.44	21.982	-0.458
13	30	Unbiased	22.968	22.535	-0.433
14	30	Unbiased	22.822	22.432	-0.39
15	30	Unbiased	23.065	22.626	-0.439
16	30	7V Biased	22.845	20.155	-2.69
17	30	7V Biased	22.958	20.283	-2.675
18	30	7V Biased	22.904	20.215	-2.689
19	30	7V Biased	22.975	20.279	-2.696
20	30	7V Biased	23.057	20.297	-2.76
21	50	Unbiased	22.981	22.473	-0.508
22	50	Unbiased	22.555	22.063	-0.492
23	50	Unbiased	22.574	22.086	-0.488
24	50	Unbiased	22.729	22.19	-0.539
25	50	Unbiased	22.775	22.265	-0.51
26	50	7V Biased	22.522	19.497	-3.025
27	50	7V Biased	22.938	19.718	-3.22
28	50	7V Biased	22.707	19.516	-3.191
29	50	7V Biased	22.584	19.476	-3.108
30	50	7V Biased	23.065	19.867	-3.198
31	0	Correlation	23.133	22.999	-0.134
32	0	Correlation	23.058	22.846	-0.212
33	0	Correlation	23.006	22.884	-0.122
34	0	Correlation	22.584	22.481	-0.103
35	0	Correlation	23.085	22.94	-0.145

Test Statistics (Ohm)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.584	22.973	23.133	0.22236	22.481	22.83	22.999	0.20349	-0.212	-0.1432	-0.103	0.041493
20	22.678	22.96	23.767	0.32603	20.53	21.688	22.64	0.90641	-2.313	-1.2723	-0.259	0.99657
30	22.44	22.912	23.088	0.18858	20.155	21.35	22.695	1.1796	-2.76	-1.5623	-0.39	1.2017
50	22.522	22.743	23.065	0.19405	19.476	20.915	22.473	1.3798	-3.22	-1.8279	-0.488	1.393

Device Test: 35.8 ILTIMER_PDR(ILT_PDresistance_10mA_Vin7p0V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

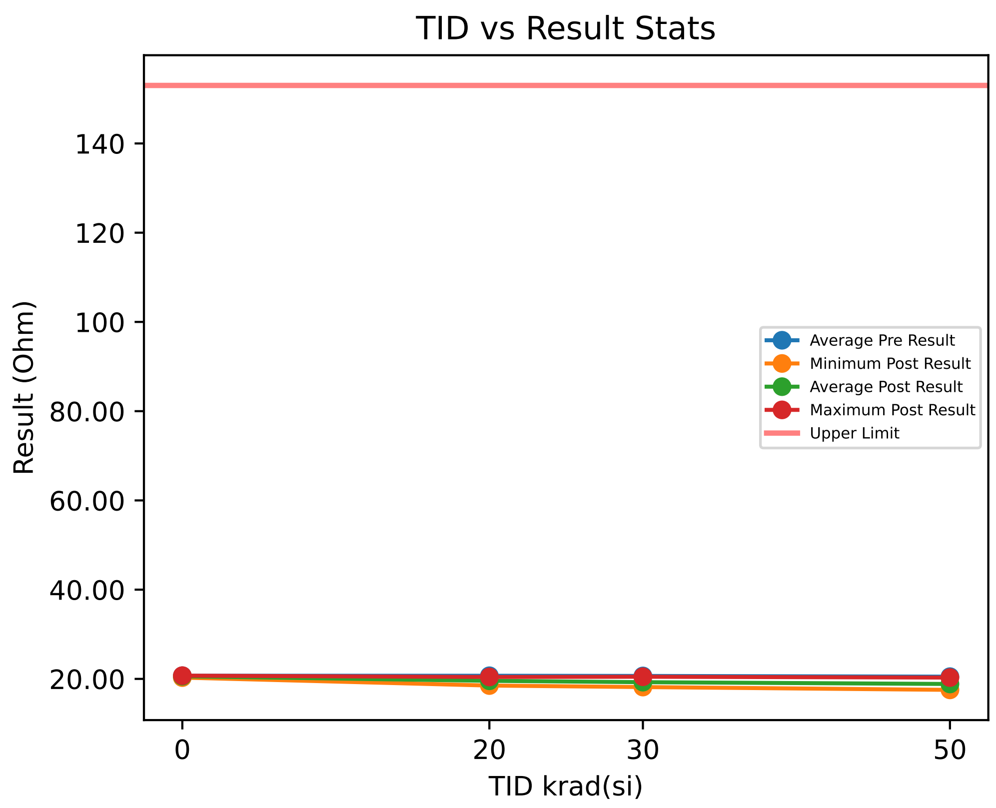
Test Results (Upper Limit = 153.0 (Ohm))

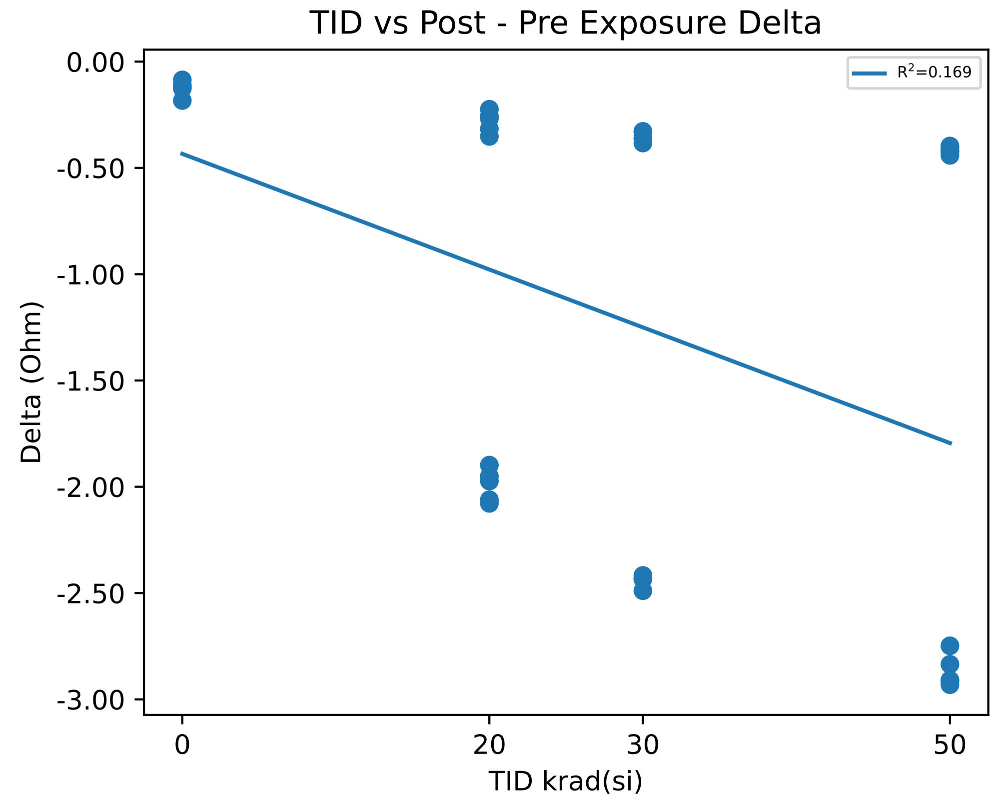
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	20.814	20.52	-0.294
2	20	Unbiased	20.948	20.565	-0.383
3	20	Unbiased	21.076	20.737	-0.339
4	20	Unbiased	20.861	20.529	-0.332
5	20	Unbiased	20.87	20.421	-0.449
6	20	7V Biased	20.998	20.339	-0.659
7	20	7V Biased	20.729	20.207	-0.522
8	20	7V Biased	21.161	20.572	-0.589
9	20	7V Biased	20.866	20.257	-0.609
10	20	7V Biased	21.831	21.101	-0.73
11	30	Unbiased	21.146	20.741	-0.405
12	30	Unbiased	20.567	20.151	-0.416
13	30	Unbiased	21.039	20.548	-0.491
14	30	Unbiased	21.081	20.55	-0.531
15	30	Unbiased	21.132	20.712	-0.42
16	30	7V Biased	20.976	20.357	-0.619
17	30	7V Biased	20.898	20.249	-0.649
18	30	7V Biased	20.957	20.243	-0.714
19	30	7V Biased	21.068	20.477	-0.591
20	30	7V Biased	21.05	20.429	-0.621
21	50	Unbiased	20.939	20.38	-0.559
22	50	Unbiased	20.612	19.974	-0.638
23	50	Unbiased	20.79	20.304	-0.486
24	50	Unbiased	20.831	20.305	-0.526
25	50	Unbiased	20.814	20.26	-0.554
26	50	7V Biased	20.617	20.024	-0.593
27	50	7V Biased	21.024	20.514	-0.51
28	50	7V Biased	20.672	20.165	-0.507
29	50	7V Biased	20.772	20.261	-0.511
30	50	7V Biased	21.116	20.49	-0.626
31	0	Correlation	21.07	20.999	-0.071
32	0	Correlation	21.149	21.036	-0.113
33	0	Correlation	21.081	20.957	-0.124
34	0	Correlation	20.685	20.498	-0.187
35	0	Correlation	21.052	20.975	-0.077

Test Statistics (Ohm)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.685	21.007	21.149	0.18393	20.498	20.893	21.036	0.22278	-0.187	-0.1144	-0.071	0.046495
20	20.729	21.015	21.831	0.31355	20.207	20.525	21.101	0.25797	-0.73	-0.4906	-0.294	0.15292
30	20.567	20.991	21.146	0.16784	20.151	20.446	20.741	0.19867	-0.714	-0.5457	-0.405	0.1094
50	20.612	20.819	21.116	0.1677	19.974	20.268	20.514	0.17692	-0.638	-0.551	-0.486	0.052808

Device Test: 35.9 RTIMER_PDR(RT_PDresistance_10mA_Vin7p0V)





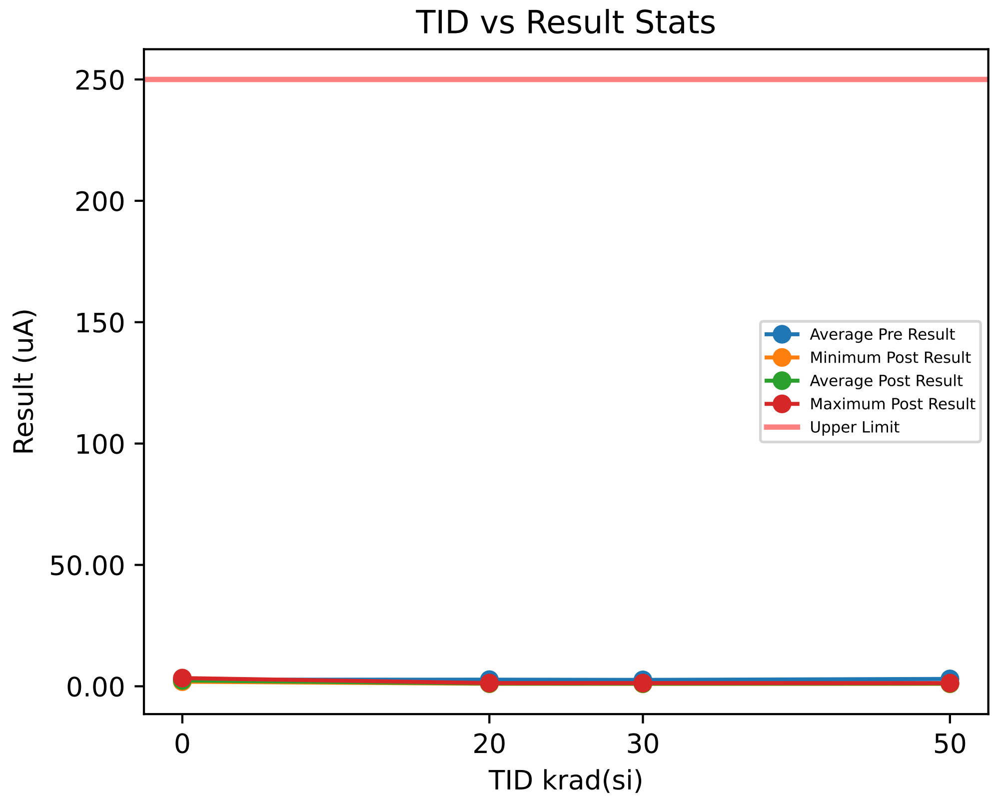
Test Results (Upper Limit = 153.0 (Ohm))

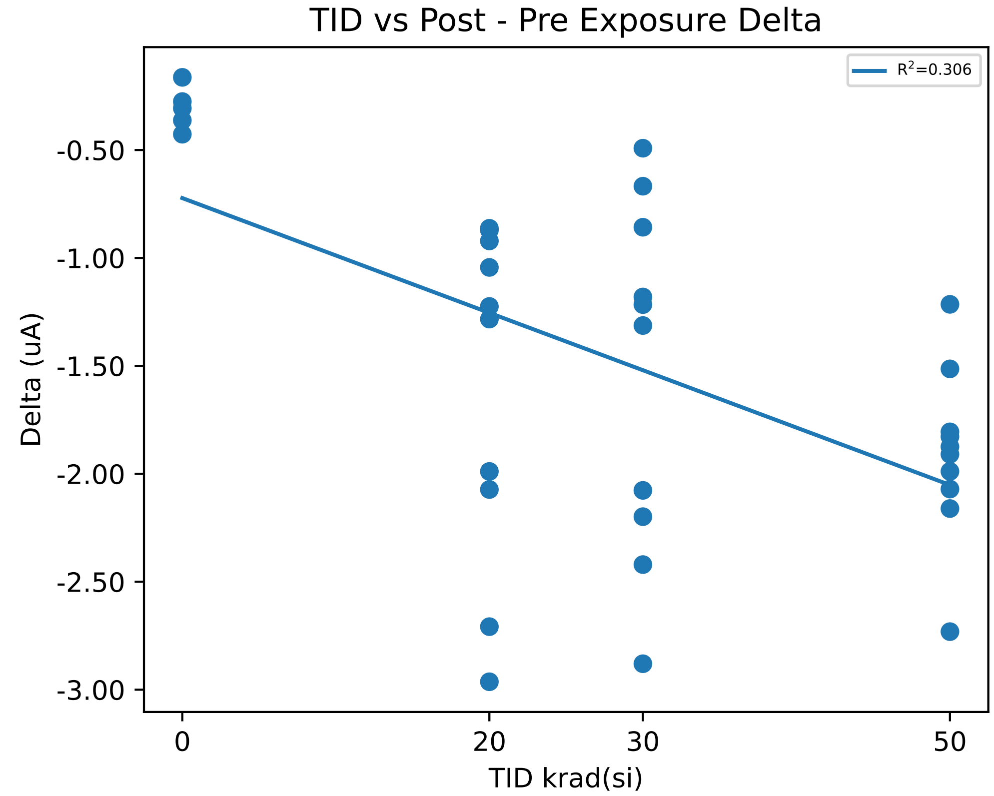
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	20.626	20.402	-0.224
2	20	Unbiased	20.686	20.37	-0.316
3	20	Unbiased	20.698	20.43	-0.268
4	20	Unbiased	20.517	20.261	-0.256
5	20	Unbiased	20.45	20.098	-0.352
6	20	7V Biased	20.789	18.839	-1.95
7	20	7V Biased	20.461	18.563	-1.898
8	20	7V Biased	20.871	18.81	-2.061
9	20	7V Biased	20.48	18.507	-1.973
10	20	7V Biased	21.454	19.376	-2.078
11	30	Unbiased	20.809	20.479	-0.33
12	30	Unbiased	20.26	19.877	-0.383
13	30	Unbiased	20.725	20.364	-0.361
14	30	Unbiased	20.614	20.286	-0.328
15	30	Unbiased	20.8	20.437	-0.363
16	30	7V Biased	20.602	18.168	-2.434
17	30	7V Biased	20.679	18.262	-2.417
18	30	7V Biased	20.639	18.211	-2.428
19	30	7V Biased	20.7	18.266	-2.434
20	30	7V Biased	20.761	18.272	-2.489
21	50	Unbiased	20.715	20.294	-0.421
22	50	Unbiased	20.345	19.938	-0.407
23	50	Unbiased	20.349	19.952	-0.397
24	50	Unbiased	20.473	20.032	-0.441
25	50	Unbiased	20.524	20.1	-0.424
26	50	7V Biased	20.299	17.551	-2.748
27	50	7V Biased	20.696	17.765	-2.931
28	50	7V Biased	20.452	17.539	-2.913
29	50	7V Biased	20.378	17.543	-2.835
30	50	7V Biased	20.786	17.877	-2.909
31	0	Correlation	20.847	20.726	-0.121
32	0	Correlation	20.783	20.6	-0.183
33	0	Correlation	20.753	20.643	-0.11
34	0	Correlation	20.373	20.287	-0.086
35	0	Correlation	20.796	20.67	-0.126

Test Statistics (Ohm)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	20.373	20.71	20.847	0.19164	20.287	20.585	20.726	0.17284	-0.183	-0.1252	-0.086	0.035801
20	20.45	20.703	21.454	0.30051	18.507	19.566	20.43	0.82472	-2.078	-1.1376	-0.224	0.90267
30	20.26	20.659	20.809	0.1578	18.168	19.262	20.479	1.0943	-2.489	-1.3967	-0.328	1.1004
50	20.299	20.502	20.786	0.17389	17.539	18.859	20.294	1.2772	-2.931	-1.6426	-0.397	1.2919

Device Test: 4.1 FORWARD_LEAKAGE(Forward_Leakage_1p5V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

Test Results (Upper Limit = 250.0 (uA))

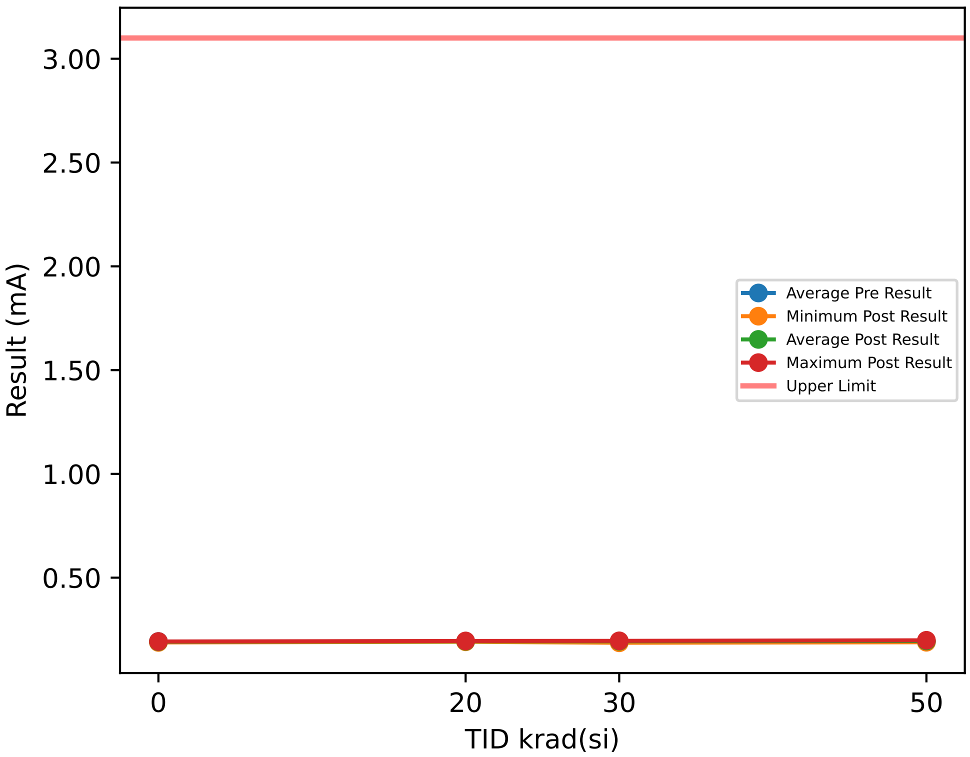
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	2.0676	1.0237	-1.0439
2	20	Unbiased	2.1722	1.3009	-0.8713
3	20	Unbiased	3.775	1.0669	-2.7081
4	20	Unbiased	2.3151	1.0903	-1.2248
5	20	Unbiased	4.0202	1.0568	-2.9634
6	20	7V Biased	2.1846	1.3219	-0.8627
7	20	7V Biased	2.3411	1.0578	-1.2833
8	20	7V Biased	3.0934	1.1043	-1.9891
9	20	7V Biased	3.1115	1.0387	-2.0728
10	20	7V Biased	2.2421	1.3209	-0.9212
11	30	Unbiased	1.5348	1.0431	-0.4917
12	30	Unbiased	4.0017	1.1218	-2.8799
13	30	Unbiased	1.8741	1.0163	-0.8578
14	30	Unbiased	2.5437	1.3275	-1.2162
15	30	Unbiased	2.218	1.0371	-1.1809
16	30	7V Biased	1.7492	1.0815	-0.6677
17	30	7V Biased	3.1905	0.9919	-2.1986
18	30	7V Biased	3.3606	1.2838	-2.0768
19	30	7V Biased	2.3148	1.0017	-1.3131
20	30	7V Biased	3.5047	1.0841	-2.4206
21	50	Unbiased	2.2296	1.0146	-1.215
22	50	Unbiased	4.0374	1.3062	-2.7312
23	50	Unbiased	3.0928	1.0221	-2.0707
24	50	Unbiased	2.9377	1.132	-1.8057
25	50	Unbiased	2.5612	1.0473	-1.5139
26	50	7V Biased	3.4505	1.2895	-2.161
27	50	7V Biased	3.0027	1.0139	-1.9888
28	50	7V Biased	2.9935	1.0841	-1.9094
29	50	7V Biased	2.8304	1.0028	-1.8276
30	50	7V Biased	3.1572	1.2827	-1.8745
31	0	Correlation	2.3086	1.8817	-0.4269
32	0	Correlation	2.538	2.1753	-0.3627
33	0	Correlation	3.6865	3.3799	-0.3066
34	0	Correlation	2.7863	2.6228	-0.1635
35	0	Correlation	2.1959	1.9202	-0.2757

Test Statistics (uA)

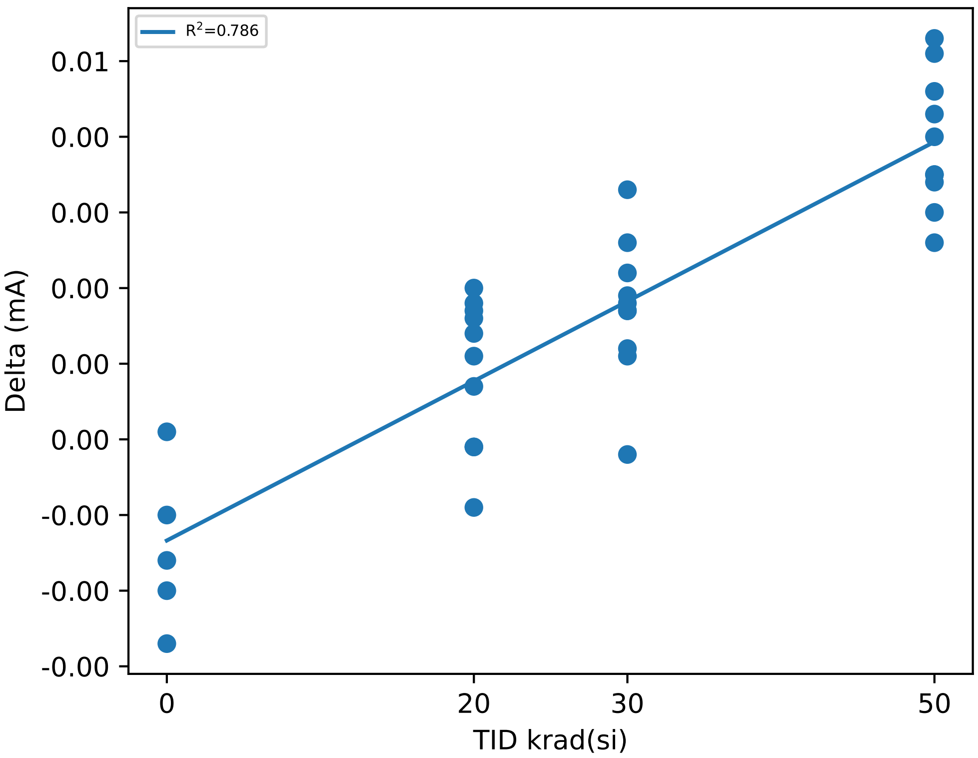
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.1959	2.7031	3.6865	0.59459	1.8817	2.396	3.3799	0.62432	-0.4269	-0.30708	-0.1635	0.098806
20	2.0676	2.7323	4.0202	0.71825	1.0237	1.1382	1.3219	0.12393	-2.9634	-1.5941	-0.8627	0.78507
30	1.5348	2.6292	4.0017	0.83784	0.9919	1.0989	1.3275	0.1165	-2.8799	-1.5303	-0.4917	0.80982
50	2.2296	3.0293	4.0374	0.48564	1.0028	1.1195	1.3062	0.12573	-2.7312	-1.9098	-1.215	0.39837

Device Test: 4.2 ISD_VIN_1p8V(ISD_Vin_1p8V)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



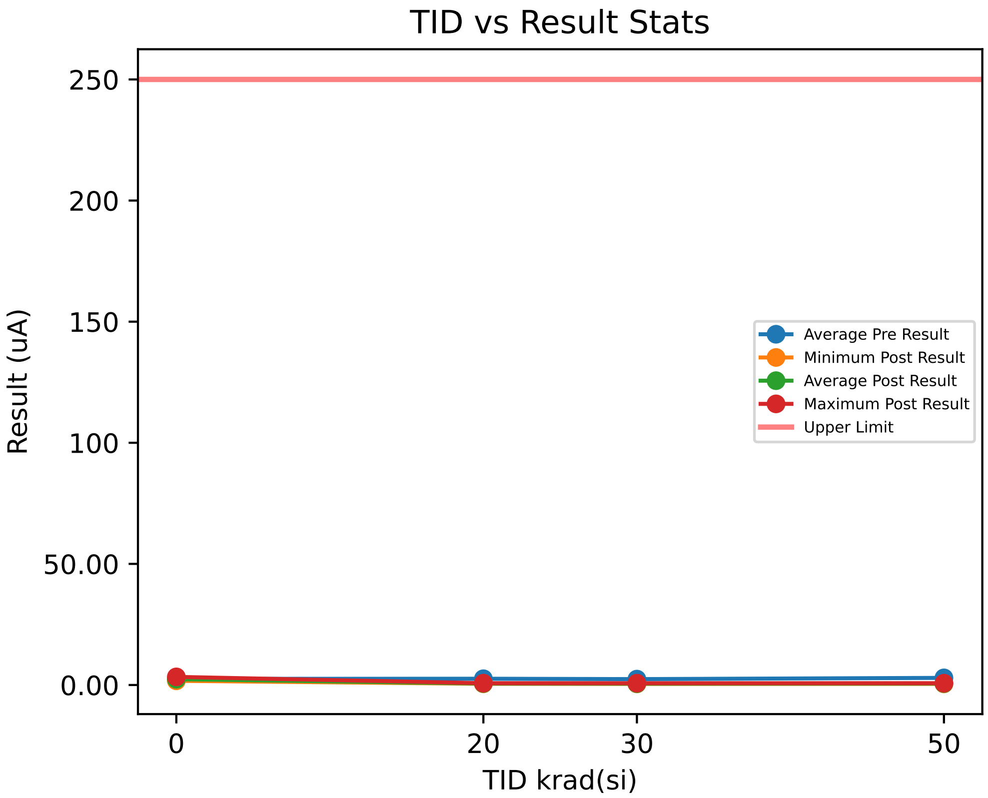
Test Results (Upper Limit = 3.1 (mA))

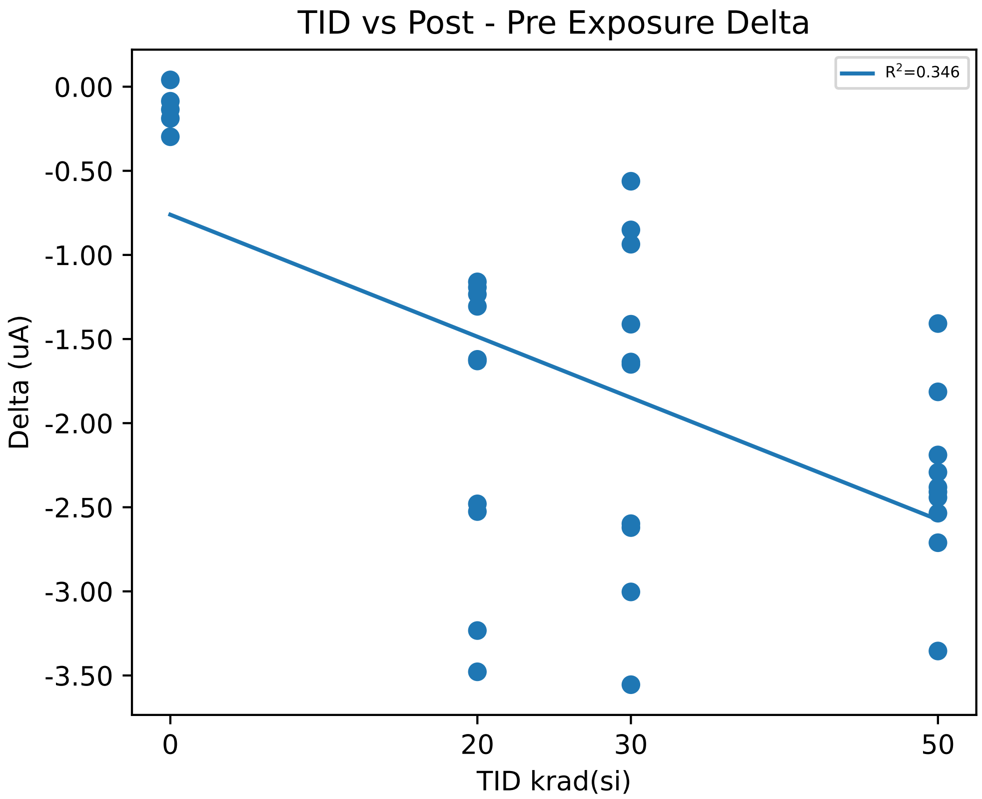
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.1931	0.1951	0.002
2	20	Unbiased	0.1926	0.1944	0.0018
3	20	Unbiased	0.1934	0.1948	0.0014
4	20	Unbiased	0.1935	0.1952	0.0017
5	20	Unbiased	0.1906	0.1917	0.0011
6	20	7V Biased	0.1941	0.194	-0.0001
7	20	7V Biased	0.192	0.1911	-0.0009
8	20	7V Biased	0.1937	0.1944	0.0007
9	20	7V Biased	0.1911	0.1927	0.0016
10	20	7V Biased	0.1935	0.1934	-0.0001
11	30	Unbiased	0.1919	0.1936	0.0017
12	30	Unbiased	0.1865	0.1863	-0.0002
13	30	Unbiased	0.1914	0.1947	0.0033
14	30	Unbiased	0.1935	0.1957	0.0022
15	30	Unbiased	0.1936	0.1955	0.0019
16	30	7V Biased	0.1939	0.1951	0.0012
17	30	7V Biased	0.1913	0.1939	0.0026
18	30	7V Biased	0.1916	0.1933	0.0017
19	30	7V Biased	0.1934	0.1945	0.0011
20	30	7V Biased	0.1935	0.1953	0.0018
21	50	Unbiased	0.1938	0.1984	0.0046
22	50	Unbiased	0.1854	0.1889	0.0035
23	50	Unbiased	0.1904	0.193	0.0026
24	50	Unbiased	0.1916	0.1959	0.0043
25	50	Unbiased	0.1916	0.1969	0.0053
26	50	7V Biased	0.1901	0.1936	0.0035
27	50	7V Biased	0.1925	0.1955	0.003
28	50	7V Biased	0.1913	0.1947	0.0034
29	50	7V Biased	0.1891	0.1942	0.0051
30	50	7V Biased	0.1944	0.1984	0.004
31	0	Correlation	0.1937	0.191	-0.0027
32	0	Correlation	0.1942	0.1926	-0.0016
33	0	Correlation	0.1929	0.1919	-0.001
34	0	Correlation	0.188	0.1881	0.0001
35	0	Correlation	0.1943	0.1923	-0.002

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.188	0.19262	0.1943	0.0026414	0.1881	0.19118	0.1926	0.001824	-0.0027	-0.00144	0.0001	0.0010597
20	0.1906	0.19276	0.1941	0.0011702	0.1911	0.19368	0.1952	0.0014274	-0.0009	0.00092	0.002	0.0009841
30	0.1865	0.19206	0.1939	0.0022077	0.1863	0.19379	0.1957	0.0027546	-0.0002	0.00173	0.0033	0.00093577
50	0.1854	0.19102	0.1944	0.0025516	0.1889	0.19495	0.1984	0.0028218	0.0026	0.00393	0.0053	0.00088951

Device Test: 4.3 FORWARD_LEAKAGE(Forward_Leakage_1p8V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

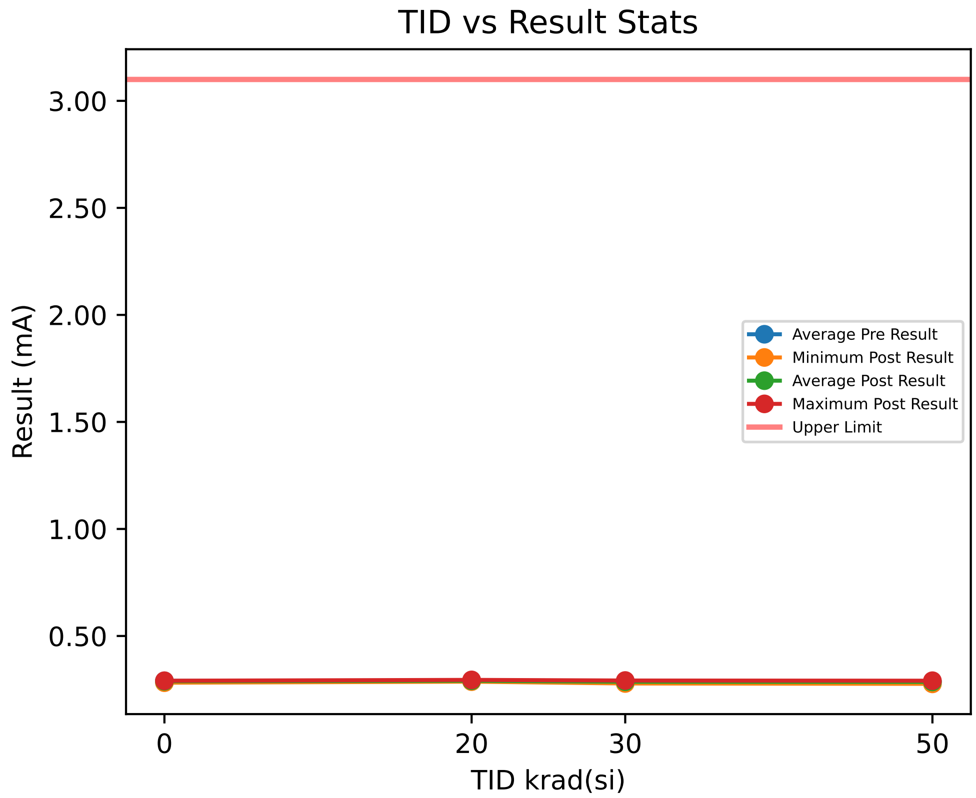
Test Results (Upper Limit = 250.0 (uA))

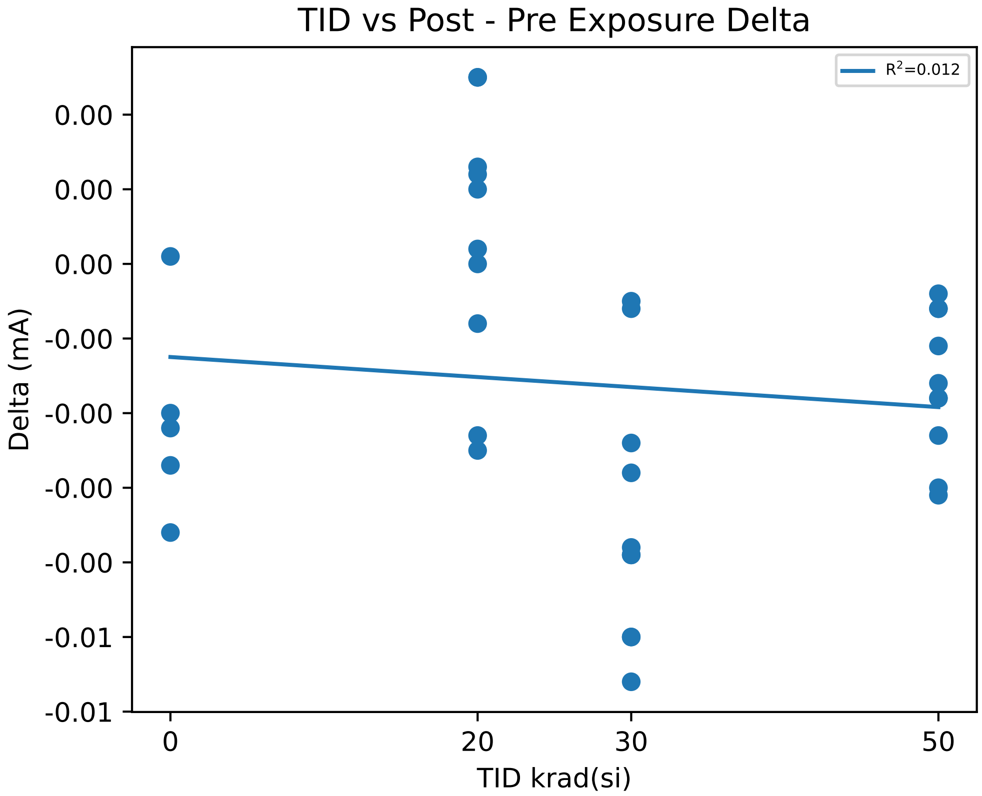
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	1.7626	0.5283	-1.2343
2	20	Unbiased	1.8688	0.7086	-1.1602
3	20	Unbiased	3.8017	0.5687	-3.233
4	20	Unbiased	2.1252	0.4948	-1.6304
5	20	Unbiased	4.0359	0.5577	-3.4782
6	20	7V Biased	1.9451	0.7521	-1.193
7	20	7V Biased	2.156	0.5353	-1.6207
8	20	7V Biased	2.9956	0.5157	-2.4799
9	20	7V Biased	3.086	0.5604	-2.5256
10	20	7V Biased	2.0395	0.7338	-1.3057
11	30	Unbiased	1.0585	0.4965	-0.562
12	30	Unbiased	4.0729	0.518	-3.5549
13	30	Unbiased	1.4593	0.523	-0.9363
14	30	Unbiased	2.3744	0.7378	-1.6366
15	30	Unbiased	1.9096	0.4977	-1.4119
16	30	7V Biased	1.3334	0.4822	-0.8512
17	30	7V Biased	3.1245	0.5036	-2.6209
18	30	7V Biased	3.2945	0.6968	-2.5977
19	30	7V Biased	2.1158	0.4652	-1.6506
20	30	7V Biased	3.5021	0.4988	-3.0033
21	50	Unbiased	1.9433	0.5354	-1.4079
22	50	Unbiased	4.1021	0.7475	-3.3546
23	50	Unbiased	3.0377	0.5025	-2.5352
24	50	Unbiased	2.83	0.538	-2.292
25	50	Unbiased	2.3819	0.5679	-1.814
26	50	7V Biased	3.4209	0.71	-2.7109
27	50	7V Biased	2.9125	0.4702	-2.4423
28	50	7V Biased	2.9257	0.5167	-2.409
29	50	7V Biased	2.7314	0.5423	-2.1891
30	50	7V Biased	3.1099	0.7286	-2.3813
31	0	Correlation	2.0327	1.897	-0.1357
32	0	Correlation	2.3109	2.2245	-0.0864
33	0	Correlation	3.6478	3.3503	-0.2975
34	0	Correlation	2.7225	2.763	0.0405
35	0	Correlation	1.9172	1.7288	-0.1884

Test Statistics (uA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9172	2.5262	3.6478	0.69952	1.7288	2.3927	3.3503	0.665	-0.2975	-0.1335	0.0405	0.12491
20	1.7626	2.5816	4.0359	0.83644	0.4948	0.59554	0.7521	0.096879	-3.4782	-1.9861	-1.1602	0.87657
30	1.0585	2.4245	4.0729	1.0261	0.4652	0.54196	0.7378	0.094331	-3.5549	-1.8825	-0.562	1.0082
50	1.9433	2.9395	4.1021	0.57558	0.4702	0.58591	0.7475	0.10224	-3.3546	-2.3536	-1.4079	0.5154

Device Test: 4.4 ISD_VIN_3p3V(ISD_Vin_3p3V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

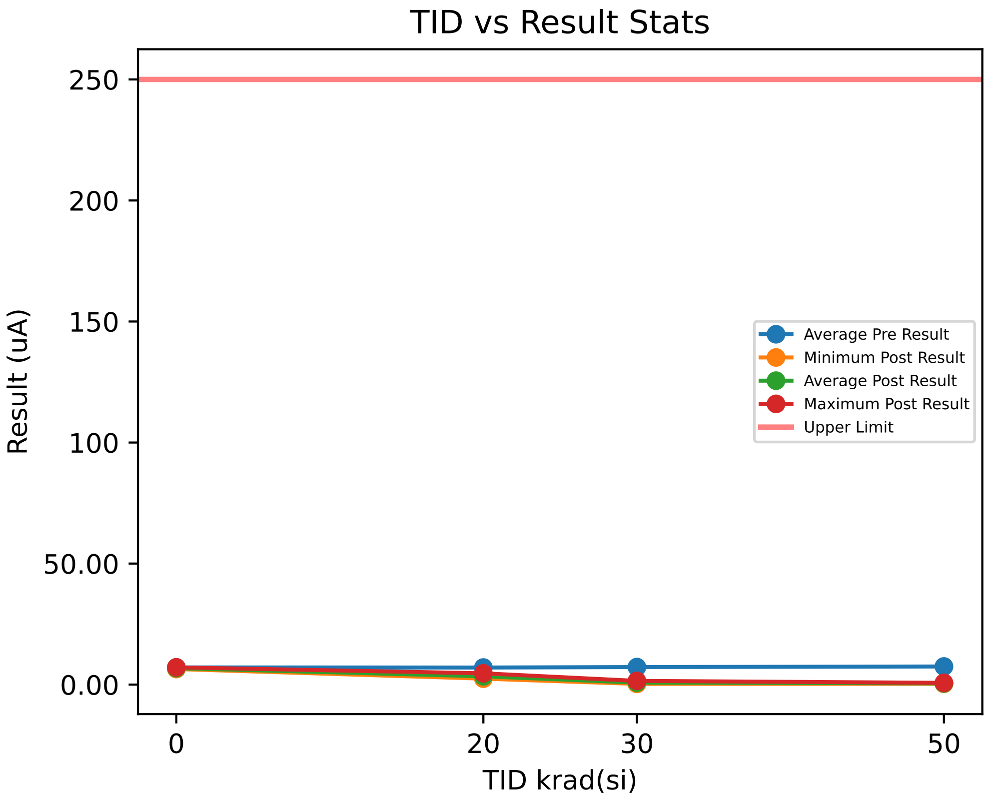
Test Results (Upper Limit = 3.1 (mA))

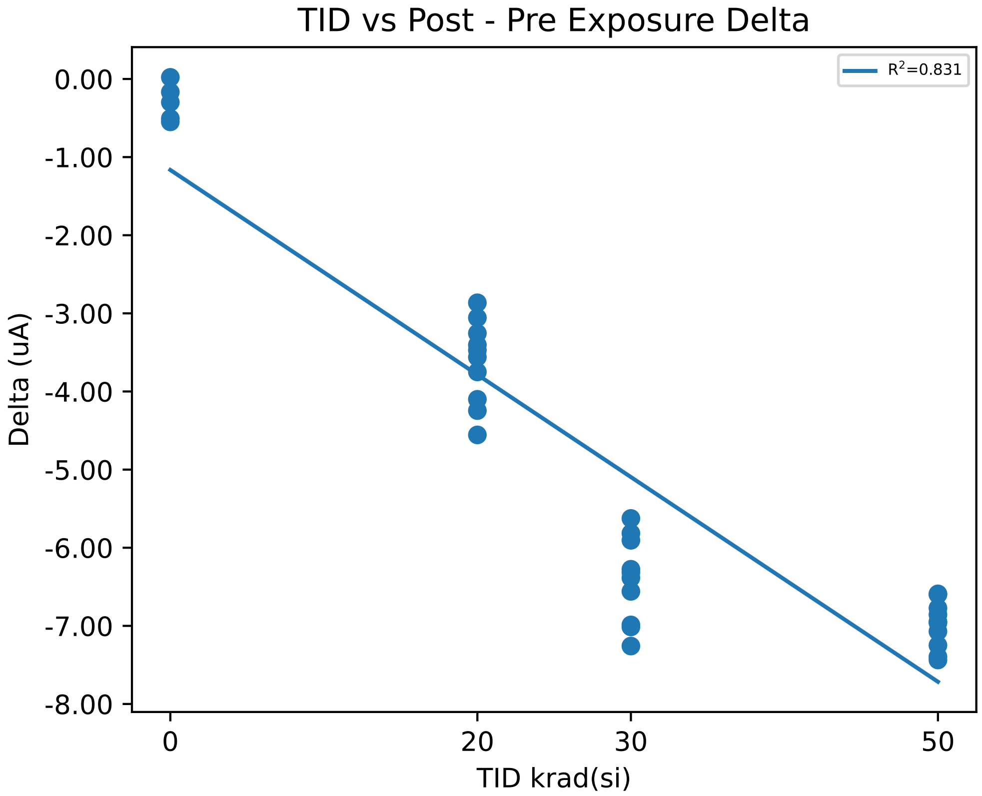
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.2913	0.2913	0
2	20	Unbiased	0.2901	0.2911	0.001
3	20	Unbiased	0.2904	0.2929	0.0025
4	20	Unbiased	0.2924	0.2949	0.0025
5	20	Unbiased	0.2867	0.288	0.0013
6	20	7V Biased	0.2921	0.2913	-0.0008
7	20	7V Biased	0.2891	0.2866	-0.0025
8	20	7V Biased	0.2911	0.2923	0.0012
9	20	7V Biased	0.2877	0.2879	0.0002
10	20	7V Biased	0.2927	0.2904	-0.0023
11	30	Unbiased	0.2898	0.2859	-0.0039
12	30	Unbiased	0.2787	0.2781	-0.0006
13	30	Unbiased	0.289	0.2862	-0.0028
14	30	Unbiased	0.292	0.2896	-0.0024
15	30	Unbiased	0.2925	0.292	-0.0005
16	30	7V Biased	0.2921	0.2883	-0.0038
17	30	7V Biased	0.2888	0.2849	-0.0039
18	30	7V Biased	0.2884	0.2834	-0.005
19	30	7V Biased	0.2917	0.2867	-0.005
20	30	7V Biased	0.2911	0.2855	-0.0056
21	50	Unbiased	0.29	0.2894	-0.0006
22	50	Unbiased	0.2781	0.2763	-0.0018
23	50	Unbiased	0.2851	0.2833	-0.0018
24	50	Unbiased	0.2878	0.2872	-0.0006
25	50	Unbiased	0.2889	0.2873	-0.0016
26	50	7V Biased	0.2865	0.2834	-0.0031
27	50	7V Biased	0.29	0.287	-0.003
28	50	7V Biased	0.2877	0.2854	-0.0023
29	50	7V Biased	0.2847	0.2836	-0.0011
30	50	7V Biased	0.2915	0.2911	-0.0004
31	0	Correlation	0.2927	0.29	-0.0027
32	0	Correlation	0.293	0.291	-0.002
33	0	Correlation	0.2893	0.2894	0.0001
34	0	Correlation	0.2839	0.2817	-0.0022
35	0	Correlation	0.2934	0.2898	-0.0036

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2839	0.29046	0.2934	0.0040153	0.2817	0.28838	0.291	0.0037805	-0.0036	-0.00208	0.0001	0.0013664
20	0.2867	0.29036	0.2927	0.0020062	0.2866	0.29067	0.2949	0.0025373	-0.0025	0.00031	0.0025	0.0017603
30	0.2787	0.28941	0.2925	0.0040553	0.2781	0.28606	0.292	0.0037325	-0.0056	-0.00335	-0.0005	0.0017703
50	0.2781	0.28703	0.2915	0.0038201	0.2763	0.2854	0.2911	0.0041145	-0.0031	-0.00163	-0.0004	0.00096959

Device Test: 4.5 FORWARD_LEAKAGE(Forward_Leakage_3p3V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

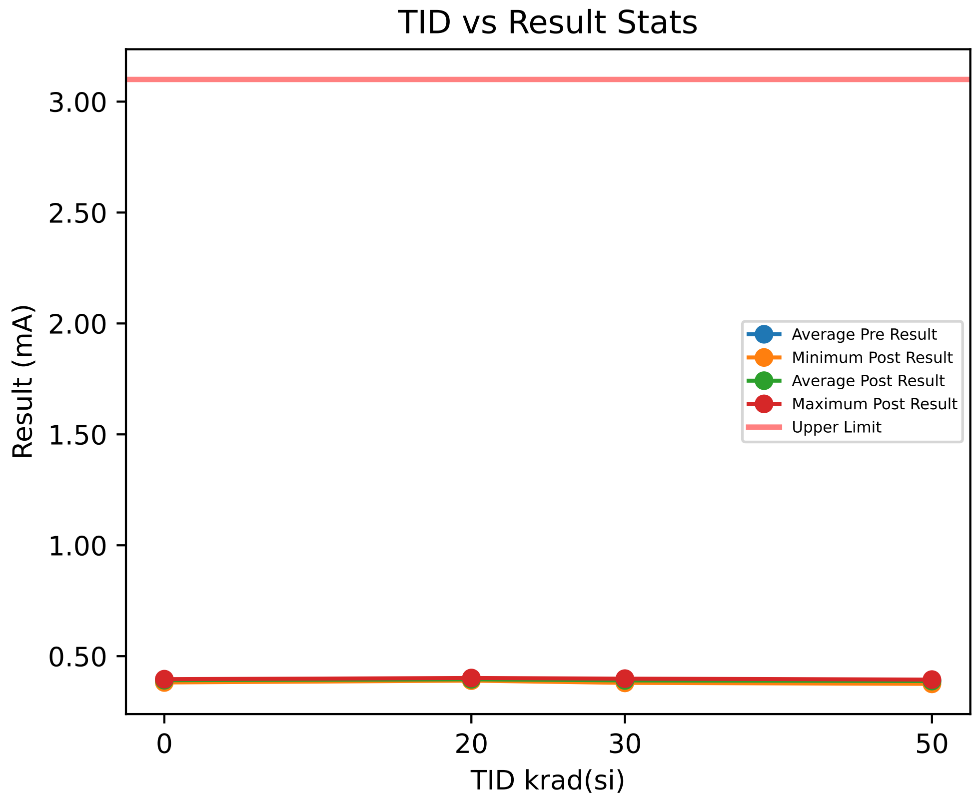
Test Results (Upper Limit = 250.0 (uA))

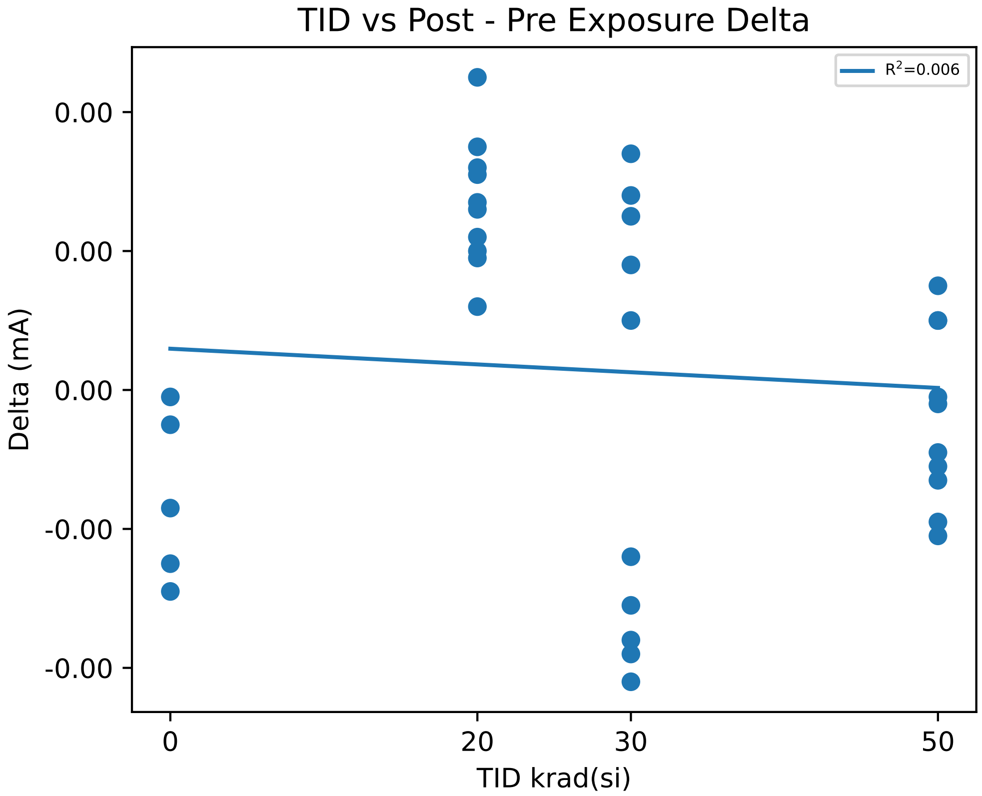
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	6.4577	3.2025	-3.2552
2	20	Unbiased	6.4764	3.0047	-3.4717
3	20	Unbiased	7.5199	4.6552	-2.8647
4	20	Unbiased	6.6728	3.1121	-3.5607
5	20	Unbiased	7.4564	4.4003	-3.0561
6	20	7V Biased	7.0821	3.3322	-3.7499
7	20	7V Biased	7.2114	2.9666	-4.2448
8	20	7V Biased	7.1683	3.7643	-3.404
9	20	7V Biased	7.4304	3.3303	-4.1001
10	20	7V Biased	7.0055	2.4496	-4.5559
11	30	Unbiased	6.8152	1.0004	-5.8148
12	30	Unbiased	7.7847	1.5093	-6.2754
13	30	Unbiased	7.1167	0.8019	-6.3148
14	30	Unbiased	7.4289	1.5237	-5.9052
15	30	Unbiased	7.1275	1.5025	-5.625
16	30	7V Biased	6.8791	0.3204	-6.5587
17	30	7V Biased	7.3784	0.3647	-7.0137
18	30	7V Biased	7.5128	0.5249	-6.9879
19	30	7V Biased	6.6829	0.2968	-6.3861
20	30	7V Biased	7.577	0.3185	-7.2585
21	50	Unbiased	7.0889	0.4982	-6.5907
22	50	Unbiased	7.4944	0.721	-6.7734
23	50	Unbiased	7.57	0.4989	-7.0711
24	50	Unbiased	7.5199	0.5725	-6.9474
25	50	Unbiased	7.3795	0.5232	-6.8563
26	50	7V Biased	7.9267	0.531	-7.3957
27	50	7V Biased	7.2825	0.3219	-6.9606
28	50	7V Biased	7.7895	0.3528	-7.4367
29	50	7V Biased	7.649	0.4004	-7.2486
30	50	7V Biased	7.1388	0.5401	-6.5987
31	0	Correlation	6.7061	6.7268	0.0207
32	0	Correlation	7.2689	6.7625	-0.5064
33	0	Correlation	7.0523	6.8844	-0.1679
34	0	Correlation	7.4276	7.1288	-0.2988
35	0	Correlation	6.9829	6.4336	-0.5493

Test Statistics (uA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.7061	7.0876	7.4276	0.27669	6.4336	6.7872	7.1288	0.2527	-0.5493	-0.30034	0.0207	0.2372
20	6.4577	7.0481	7.5199	0.39381	2.4496	3.4218	4.6552	0.67353	-4.5559	-3.6263	-2.8647	0.5382
30	6.6829	7.2303	7.7847	0.36324	0.2968	0.81631	1.5237	0.53105	-7.2585	-6.414	-5.625	0.54705
50	7.0889	7.4839	7.9267	0.26918	0.3219	0.496	0.721	0.11564	-7.4367	-6.9879	-6.5907	0.3014

Device Test: 4.6 ISD_VIN_5V(ISD_Vin_5p0V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

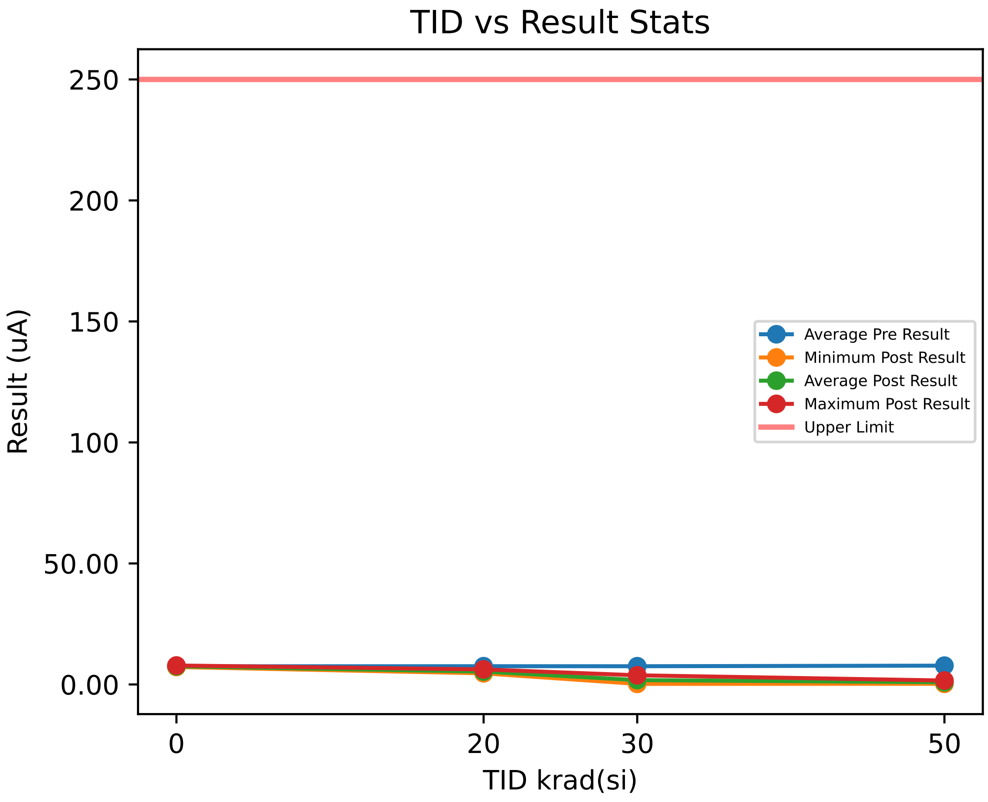
Test Results (Upper Limit = 3.1 (mA))

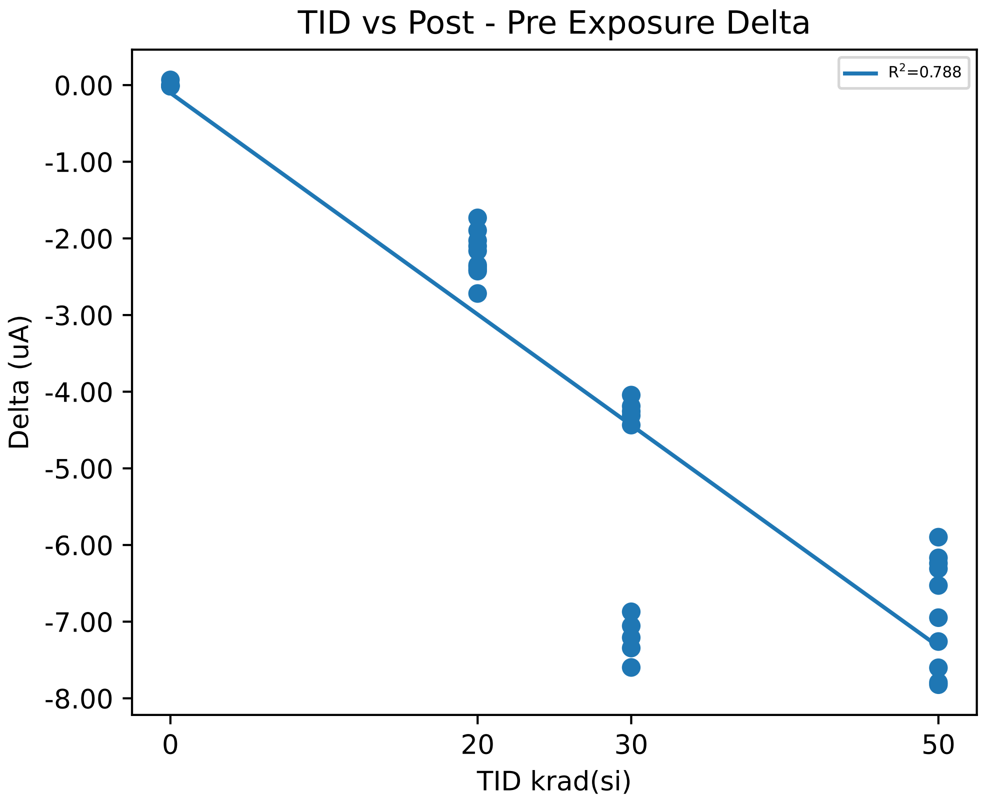
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.3943	0.3975	0.0032
2	20	Unbiased	0.3938	0.396	0.0022
3	20	Unbiased	0.3942	0.3977	0.0035
4	20	Unbiased	0.3971	0.4016	0.0045
5	20	Unbiased	0.387	0.3897	0.0027
6	20	7V Biased	0.3949	0.3969	0.002
7	20	7V Biased	0.3895	0.3907	0.0012
8	20	7V Biased	0.3952	0.3978	0.0026
9	20	7V Biased	0.3897	0.3916	0.0019
10	20	7V Biased	0.3951	0.3982	0.0031
11	30	Unbiased	0.3925	0.3935	0.001
12	30	Unbiased	0.3762	0.3796	0.0034
13	30	Unbiased	0.3901	0.3929	0.0028
14	30	Unbiased	0.3939	0.3964	0.0025
15	30	Unbiased	0.397	0.3988	0.0018
16	30	7V Biased	0.396	0.3929	-0.0031
17	30	7V Biased	0.3896	0.3872	-0.0024
18	30	7V Biased	0.39	0.3858	-0.0042
19	30	7V Biased	0.3947	0.3909	-0.0038
20	30	7V Biased	0.3941	0.3905	-0.0036
21	50	Unbiased	0.393	0.3945	0.0015
22	50	Unbiased	0.3754	0.3752	-0.0002
23	50	Unbiased	0.3863	0.385	-0.0013
24	50	Unbiased	0.3894	0.3904	0.001
25	50	Unbiased	0.39	0.391	0.001
26	50	7V Biased	0.3862	0.3841	-0.0021
27	50	7V Biased	0.3917	0.3908	-0.0009
28	50	7V Biased	0.3893	0.3882	-0.0011
29	50	7V Biased	0.3854	0.3835	-0.0019
30	50	7V Biased	0.3945	0.3944	-0.0001
31	0	Correlation	0.3967	0.3938	-0.0029
32	0	Correlation	0.3965	0.3964	-0.0001
33	0	Correlation	0.3924	0.3919	-0.0005
34	0	Correlation	0.3832	0.3815	-0.0017
35	0	Correlation	0.3971	0.3946	-0.0025

Test Statistics (mA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.3832	0.39318	0.3971	0.0058947	0.3815	0.39164	0.3964	0.0058943	-0.0029	-0.00154	-0.0001	0.0012198
20	0.387	0.39308	0.3971	0.0032062	0.3897	0.39577	0.4016	0.0038297	0.0012	0.00269	0.0045	0.00093862
30	0.3762	0.39141	0.397	0.0059263	0.3796	0.39085	0.3988	0.0055272	-0.0042	-0.00056	0.0034	0.0031121
50	0.3754	0.38812	0.3945	0.0053758	0.3752	0.38771	0.3945	0.0059002	-0.0021	-0.00041	0.0015	0.0012627

Device Test: 4.7 FORWARD_LEAKAGE(Forward_Leakage_5p0V)





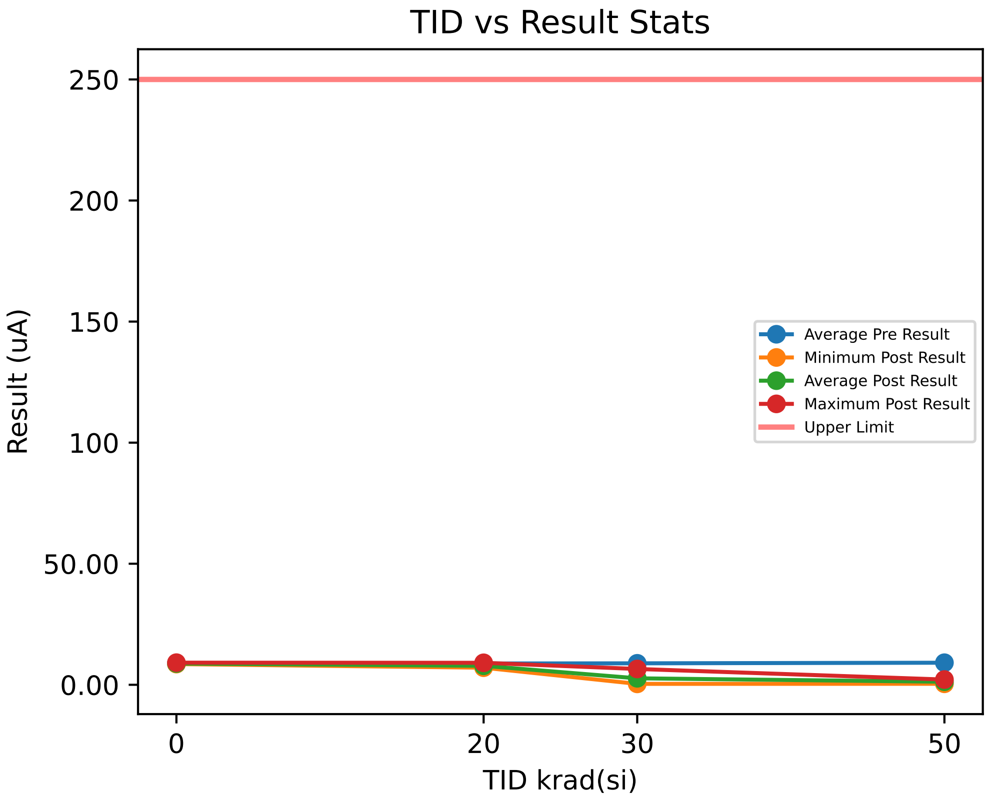
Test Results (Upper Limit = 250.0 (uA))

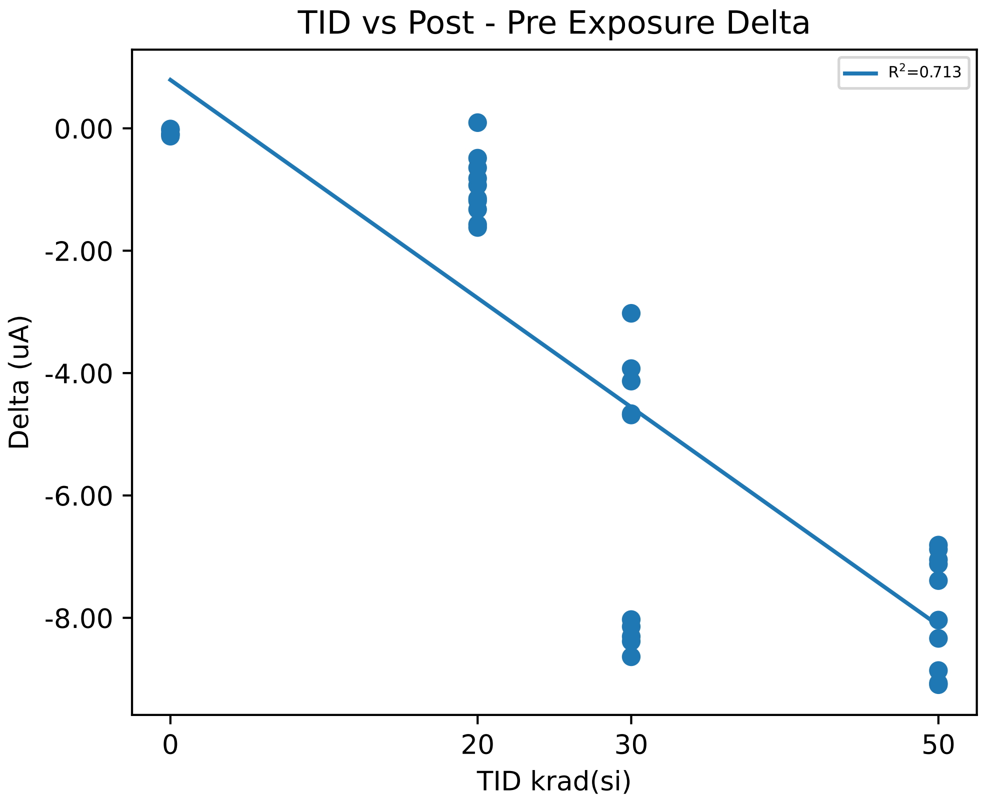
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	7.4036	5.303	-2.1006
2	20	Unbiased	7.2751	4.9277	-2.3474
3	20	Unbiased	8.1077	6.2118	-1.8959
4	20	Unbiased	7.5862	5.2141	-2.3721
5	20	Unbiased	7.7256	5.9933	-1.7323
6	20	7V Biased	7.3475	5.1847	-2.1628
7	20	7V Biased	7.4433	5.0165	-2.4268
8	20	7V Biased	7.4311	5.4026	-2.0285
9	20	7V Biased	7.7092	5.3062	-2.403
10	20	7V Biased	7.3057	4.587	-2.7187
11	30	Unbiased	7.0148	2.8261	-4.1887
12	30	Unbiased	8.0907	3.7792	-4.3115
13	30	Unbiased	7.3775	2.9418	-4.4357
14	30	Unbiased	7.679	3.4228	-4.2562
15	30	Unbiased	7.3694	3.3253	-4.0441
16	30	7V Biased	7.1058	0.2345	-6.8713
17	30	7V Biased	7.6654	0.4579	-7.2075
18	30	7V Biased	7.7878	0.444	-7.3438
19	30	7V Biased	7.298	0.2427	-7.0553
20	30	7V Biased	7.8522	0.2547	-7.5975
21	50	Unbiased	7.3485	1.4509	-5.8976
22	50	Unbiased	7.7916	1.6235	-6.1681
23	50	Unbiased	7.876	1.3479	-6.5281
24	50	Unbiased	7.7781	1.4689	-6.3092
25	50	Unbiased	7.6418	1.4032	-6.2386
26	50	7V Biased	8.2516	0.459	-7.7926
27	50	7V Biased	7.5156	0.2564	-7.2592
28	50	7V Biased	8.0915	0.2691	-7.8224
29	50	7V Biased	7.9386	0.3368	-7.6018
30	50	7V Biased	7.4108	0.4627	-6.9481
31	0	Correlation	7.4539	7.4385	-0.0154
32	0	Correlation	7.5304	7.5188	-0.0116
33	0	Correlation	7.5091	7.5146	0.0055
34	0	Correlation	7.7596	7.8274	0.0678
35	0	Correlation	7.2228	7.2086	-0.0142

Test Statistics (uA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.2228	7.4952	7.7596	0.19186	7.2086	7.5016	7.8274	0.22161	-0.0154	0.00642	0.0678	0.035335
20	7.2751	7.5335	8.1077	0.25582	4.587	5.3147	6.2118	0.47941	-2.7187	-2.2188	-1.7323	0.29086
30	7.0148	7.5241	8.0907	0.3453	0.2345	1.7929	3.7792	1.5683	-7.5975	-5.7312	-4.0441	1.578
50	7.3485	7.7644	8.2516	0.29117	0.2564	0.90784	1.6235	0.58869	-7.8224	-6.8566	-5.8976	0.72402

Device Test: 4.9 FORWARD_LEAKAGE(Forward_Leakage_7p0V)





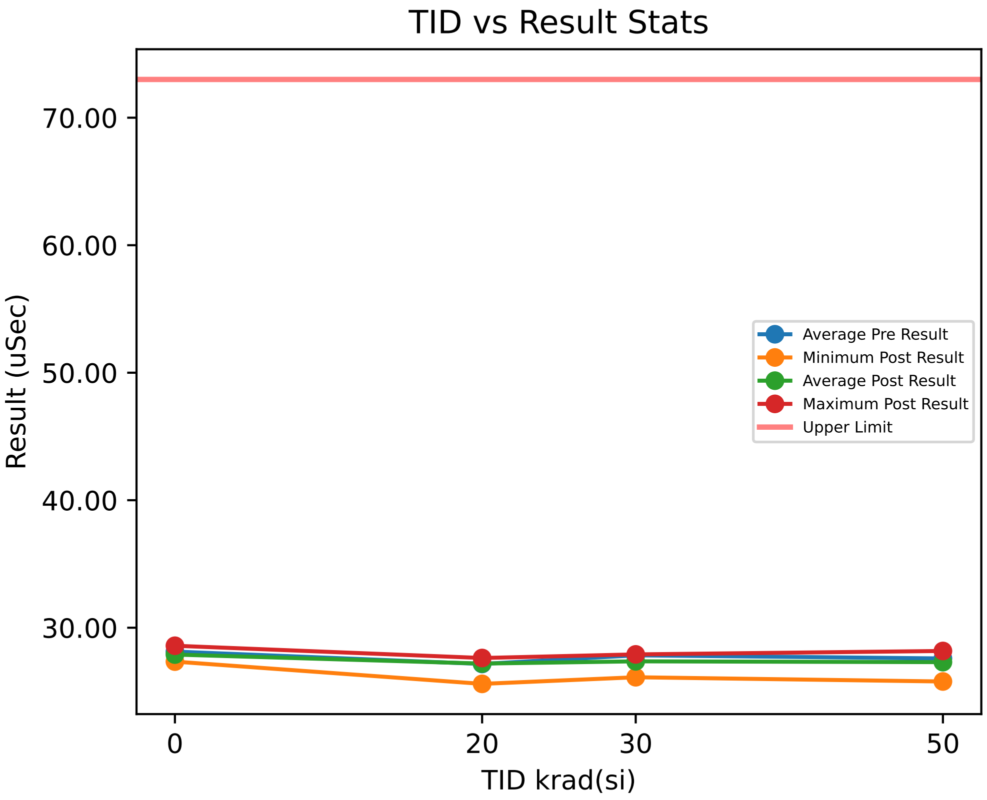
Test Results (Upper Limit = 250.0 (uA))

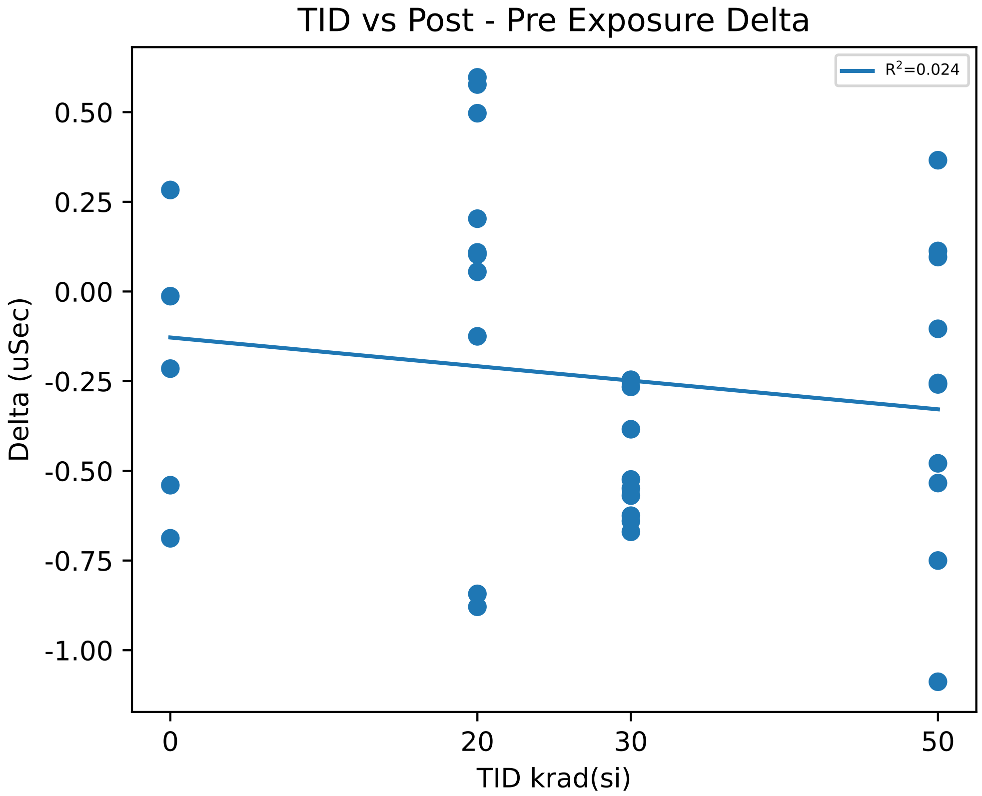
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	8.6879	7.7568	-0.9311
2	20	Unbiased	8.528	7.2028	-1.3252
3	20	Unbiased	9.1597	8.672	-0.4877
4	20	Unbiased	8.8634	7.7156	-1.1478
5	20	Unbiased	8.9886	9.0815	0.0929
6	20	7V Biased	8.5562	7.3731	-1.1831
7	20	7V Biased	8.6772	7.0567	-1.6205
8	20	7V Biased	8.637	7.9921	-0.6449
9	20	7V Biased	9.1043	8.286	-0.8183
10	20	7V Biased	8.7716	7.1997	-1.5719
11	30	Unbiased	8.4845	3.8211	-4.6634
12	30	Unbiased	9.5592	6.536	-3.0232
13	30	Unbiased	8.9522	4.2674	-4.6848
14	30	Unbiased	9.0777	4.9463	-4.1314
15	30	Unbiased	8.6448	4.7182	-3.9266
16	30	7V Biased	8.4073	0.379	-8.0283
17	30	7V Biased	9.0055	0.7007	-8.3048
18	30	7V Biased	8.9729	0.5881	-8.3848
19	30	7V Biased	8.5417	0.3978	-8.1439
20	30	7V Biased	9.0294	0.3931	-8.6363
21	50	Unbiased	8.8483	2.0374	-6.8109
22	50	Unbiased	9.0472	2.1654	-6.8818
23	50	Unbiased	9.2795	1.8881	-7.3914
24	50	Unbiased	9.1362	2.0142	-7.122
25	50	Unbiased	8.9766	1.9261	-7.0505
26	50	7V Biased	9.6543	0.5872	-9.0671
27	50	7V Biased	8.7442	0.4082	-8.336
28	50	7V Biased	9.5049	0.4122	-9.0927
29	50	7V Biased	9.3493	0.488	-8.8613
30	50	7V Biased	8.6282	0.5915	-8.0367
31	0	Correlation	8.8179	8.7178	-0.1001
32	0	Correlation	8.9046	8.8129	-0.0917
33	0	Correlation	8.7046	8.6936	-0.011
34	0	Correlation	9.1668	9.1371	-0.0297
35	0	Correlation	8.6835	8.555	-0.1285

Test Statistics (uA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.6835	8.8555	9.1668	0.19563	8.555	8.7833	9.1371	0.21824	-0.1285	-0.0722	-0.011	0.049699
20	8.528	8.7974	9.1597	0.22359	7.0567	7.8336	9.0815	0.67702	-1.6205	-0.96376	0.0929	0.52502
30	8.4073	8.8675	9.5592	0.34966	0.379	2.6748	6.536	2.4039	-8.6363	-6.1928	-3.0232	2.272
50	8.6282	9.1169	9.6543	0.33243	0.4082	1.2518	2.1654	0.80072	-9.0927	-7.865	-6.8109	0.92579

Device Test: 40.0 IOUT_CS_DELAY_FALLING(IOUT_CS_FallingDELAY_1p5V)





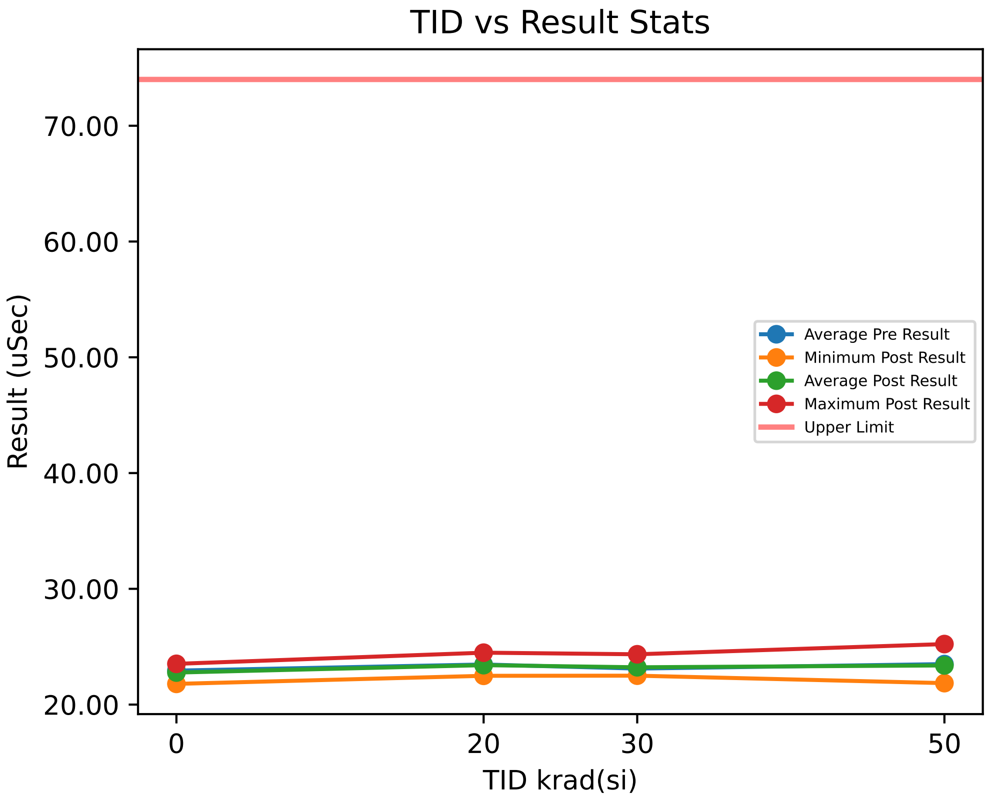
Test Results (Upper Limit = 73.0 (uSec))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	26.777	27.354	0.577
2	20	Unbiased	26.853	27.45	0.597
3	20	Unbiased	27.497	27.552	0.055
4	20	Unbiased	27.493	27.596	0.103
5	20	Unbiased	27.046	27.155	0.109
6	20	7V Biased	26.548	27.045	0.497
7	20	7V Biased	27.75	27.625	-0.125
8	20	7V Biased	26.475	25.596	-0.879
9	20	7V Biased	27.367	27.57	0.203
10	20	7V Biased	27.774	26.931	-0.843
11	30	Unbiased	28.358	27.688	-0.67
12	30	Unbiased	27.211	26.945	-0.266
13	30	Unbiased	28.306	27.782	-0.524
14	30	Unbiased	27.625	27	-0.625
15	30	Unbiased	28.477	27.908	-0.569
16	30	7V Biased	26.362	26.115	-0.247
17	30	7V Biased	28.089	27.705	-0.384
18	30	7V Biased	27.467	26.918	-0.549
19	30	7V Biased	28.136	27.89	-0.246
20	30	7V Biased	28.325	27.685	-0.64
21	50	Unbiased	28.063	28.176	0.113
22	50	Unbiased	27.461	26.927	-0.534
23	50	Unbiased	27.407	26.657	-0.75
24	50	Unbiased	28.358	27.27	-1.088
25	50	Unbiased	26.038	25.783	-0.255
26	50	7V Biased	27.221	27.317	0.096
27	50	7V Biased	27.603	27.969	0.366
28	50	7V Biased	27.682	27.578	-0.104
29	50	7V Biased	28.035	27.776	-0.259
30	50	7V Biased	28.026	27.547	-0.479
31	0	Correlation	28.128	27.44	-0.688
32	0	Correlation	28.469	27.929	-0.54
33	0	Correlation	27.059	27.342	0.283
34	0	Correlation	28.188	28.175	-0.013
35	0	Correlation	28.801	28.586	-0.215

Test Statistics (uSec)

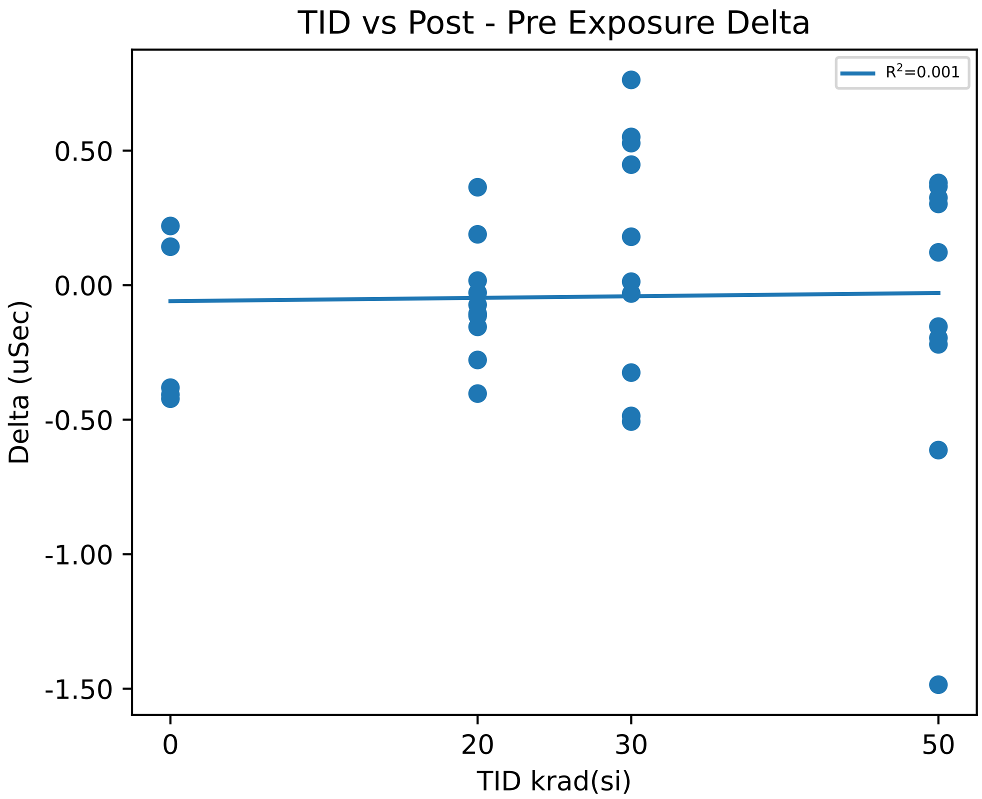
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	27.059	28.129	28.801	0.6549	27.342	27.894	28.586	0.51717	-0.688	-0.2346	0.283	0.39251
20	26.475	27.158	27.774	0.4819	25.596	27.187	27.625	0.61047	-0.879	0.0294	0.597	0.52634
30	26.362	27.836	28.477	0.67011	26.115	27.364	27.908	0.59054	-0.67	-0.472	-0.246	0.17022
50	26.038	27.589	28.358	0.65024	25.783	27.3	28.176	0.70197	-1.088	-0.2894	0.366	0.43744

Device Test: 40.1 IOUT_CS_DELAY_RISING(IOUT_CS_RisingDELAY_1p5V)



Test Results (Upper Limit = 74.0 (uSec))

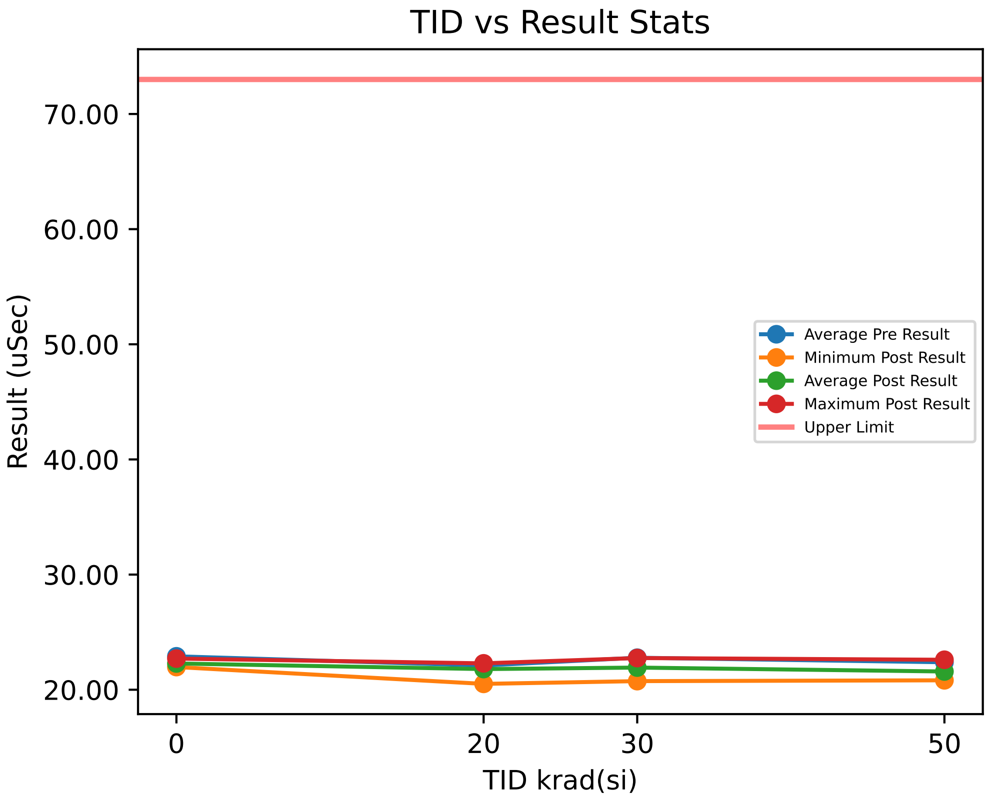
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	23.981	23.578	-0.403
2	20	Unbiased	23.249	23.266	0.017
3	20	Unbiased	22.773	22.7	-0.073
4	20	Unbiased	22.641	22.486	-0.155
5	20	Unbiased	24.146	24.118	-0.028
6	20	7V Biased	23.722	23.608	-0.114
7	20	7V Biased	22.808	22.53	-0.278
8	20	7V Biased	24.295	24.484	0.189
9	20	7V Biased	23.341	23.235	-0.106
10	20	7V Biased	23.689	24.053	0.364
11	30	Unbiased	22.98	22.949	-0.031
12	30	Unbiased	23.923	23.437	-0.486
13	30	Unbiased	22.551	23.314	0.763
14	30	Unbiased	23.198	23.646	0.448
15	30	Unbiased	22.185	22.736	0.551
16	30	7V Biased	24.166	24.346	0.18
17	30	7V Biased	22.944	23.472	0.528
18	30	7V Biased	23.35	23.025	-0.325
19	30	7V Biased	22.485	22.498	0.013
20	30	7V Biased	23.315	22.808	-0.507
21	50	Unbiased	23.382	23.162	-0.22
22	50	Unbiased	23.645	23.97	0.325
23	50	Unbiased	23.741	24.121	0.38
24	50	Unbiased	22.341	22.708	0.367
25	50	Unbiased	24.926	25.228	0.302
26	50	7V Biased	24.021	23.867	-0.154
27	50	7V Biased	23.339	21.854	-1.485
28	50	7V Biased	23.592	22.979	-0.613
29	50	7V Biased	23.294	23.416	0.122
30	50	7V Biased	22.707	22.511	-0.196
31	0	Correlation	22.934	23.077	0.143
32	0	Correlation	22.906	22.499	-0.407
33	0	Correlation	23.3	23.52	0.22
34	0	Correlation	23.368	22.946	-0.422
35	0	Correlation	22.171	21.79	-0.381

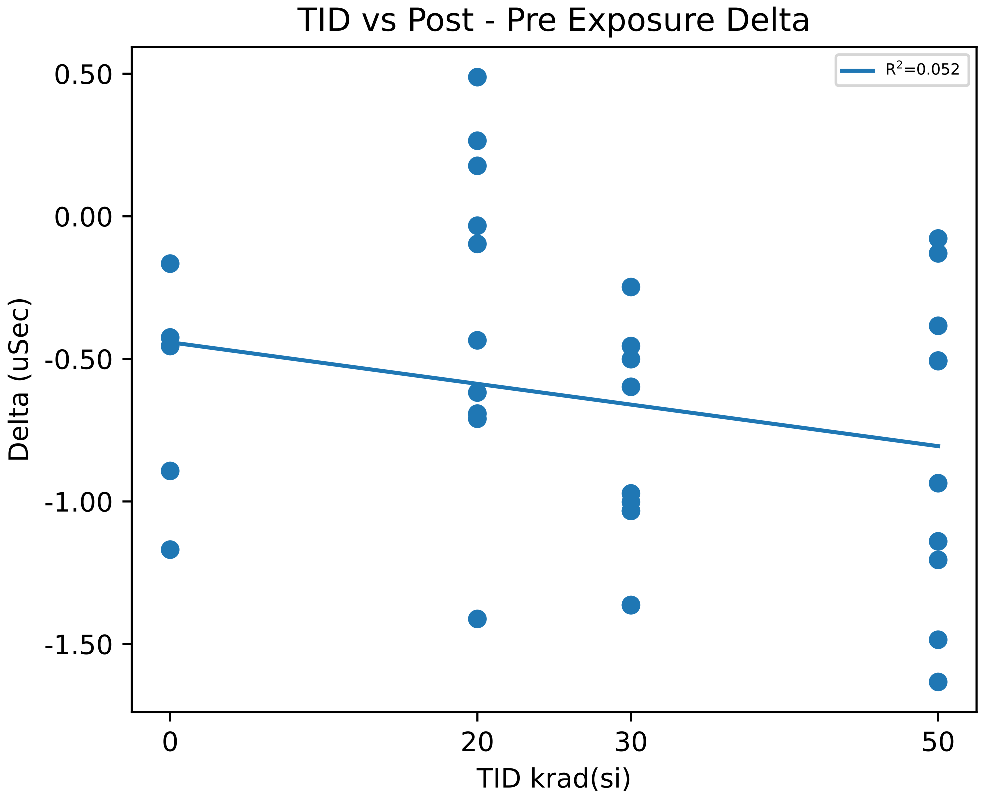


Test Statistics (uSec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.171	22.936	23.368	0.47572	21.79	22.766	23.52	0.65603	-0.422	-0.1694	0.22	0.32182
20	22.641	23.465	24.295	0.59504	22.486	23.406	24.484	0.69275	-0.403	-0.0587	0.364	0.2181
30	22.185	23.11	24.166	0.62242	22.498	23.223	24.346	0.53805	-0.507	0.1134	0.763	0.45571
50	22.341	23.499	24.926	0.70292	21.854	23.382	25.228	0.96	-1.485	-0.1172	0.38	0.58166

Device Test: 40.2 IOUT_CS_DELAY_FALLING(IOUT_CS_FallingDELAY_1p8V)





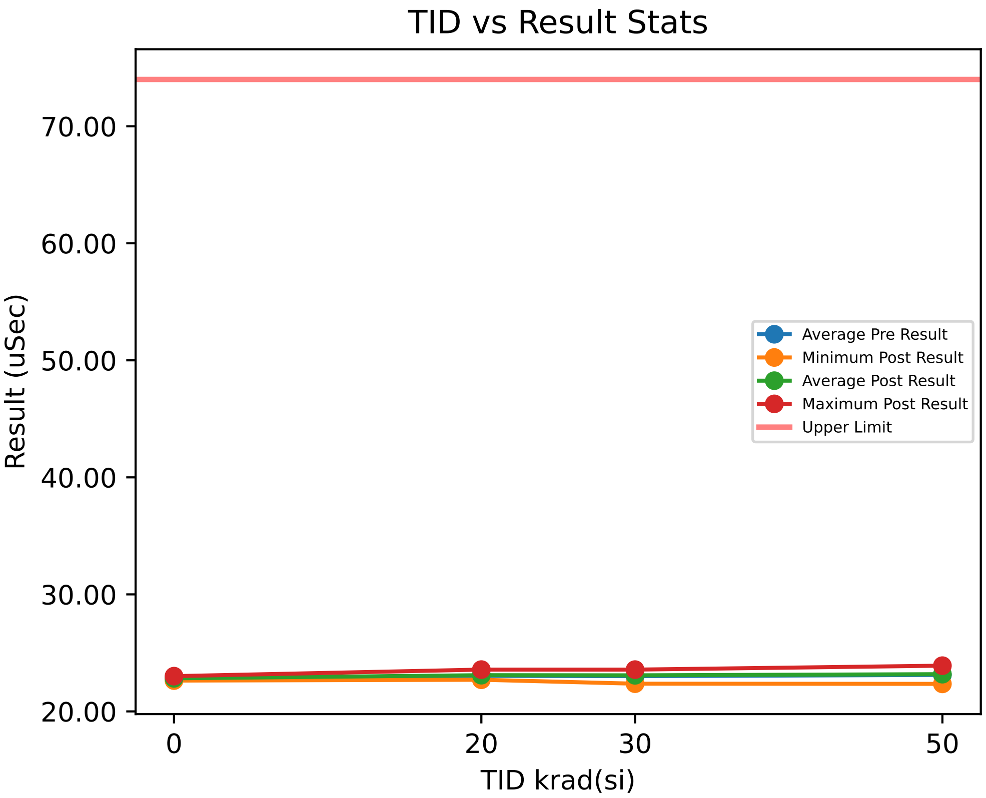
Test Results (Upper Limit = 73.0 (uSec))

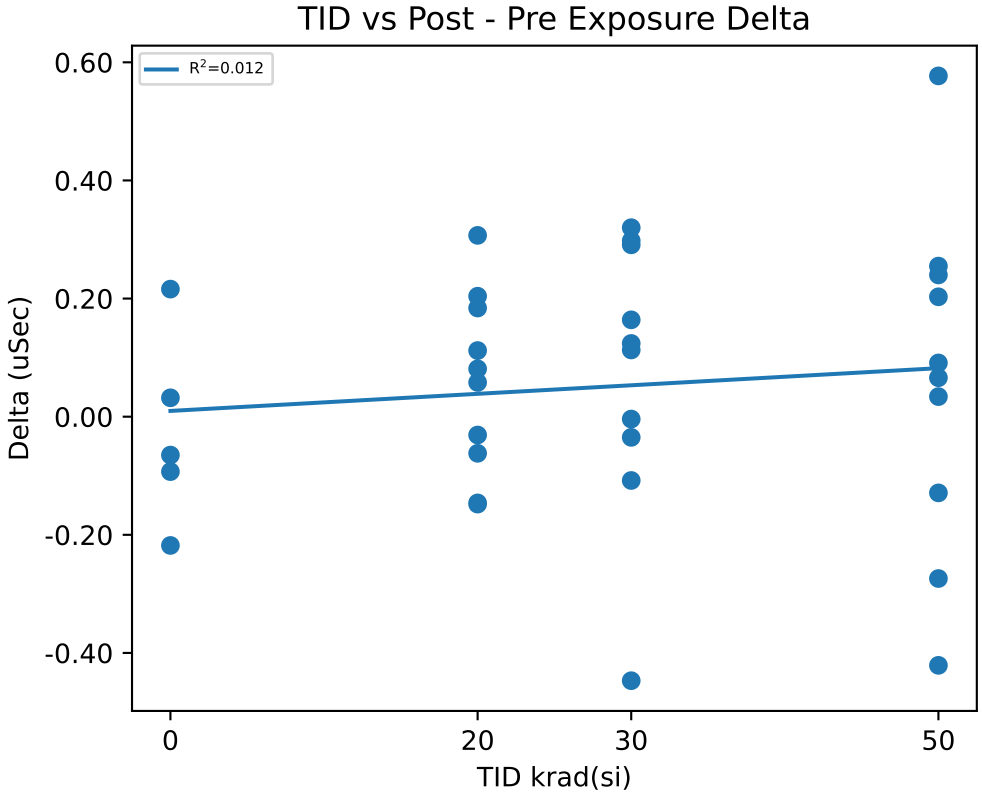
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	22.182	22.085	-0.097
2	20	Unbiased	21.592	22.08	0.488
3	20	Unbiased	22.486	22.051	-0.435
4	20	Unbiased	21.412	21.677	0.265
5	20	Unbiased	22.324	22.291	-0.033
6	20	7V Biased	22.345	21.653	-0.692
7	20	7V Biased	22.401	21.783	-0.618
8	20	7V Biased	21.921	20.509	-1.412
9	20	7V Biased	21.945	22.122	0.177
10	20	7V Biased	22.395	21.685	-0.71
11	30	Unbiased	22.782	22.281	-0.501
12	30	Unbiased	22.622	21.589	-1.033
13	30	Unbiased	23.01	22.555	-0.455
14	30	Unbiased	22.514	21.481	-1.033
15	30	Unbiased	23.152	22.554	-0.598
16	30	7V Biased	22.111	20.747	-1.364
17	30	7V Biased	22.999	22.751	-0.248
18	30	7V Biased	22.506	21.534	-0.972
19	30	7V Biased	23.215	22.213	-1.002
20	30	7V Biased	22.893	21.53	-1.363
21	50	Unbiased	22.681	22.603	-0.078
22	50	Unbiased	22.023	20.818	-1.205
23	50	Unbiased	22.362	21.426	-0.936
24	50	Unbiased	22.908	21.423	-1.485
25	50	Unbiased	21.383	20.875	-0.508
26	50	7V Biased	21.765	21.259	-0.506
27	50	7V Biased	22.575	22.191	-0.384
28	50	7V Biased	22.527	20.894	-1.633
29	50	7V Biased	22.628	22.498	-0.13
30	50	7V Biased	23.004	21.864	-1.14
31	0	Correlation	22.886	22.431	-0.455
32	0	Correlation	23.139	21.97	-1.169
33	0	Correlation	22.305	22.139	-0.166
34	0	Correlation	23.051	22.158	-0.893
35	0	Correlation	23.129	22.704	-0.425

Test Statistics (uSec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.305	22.902	23.139	0.34877	21.97	22.28	22.704	0.28872	-1.169	-0.6216	-0.166	0.40227
20	21.412	22.1	22.486	0.36984	20.509	21.794	22.291	0.50375	-1.412	-0.3067	0.488	0.57324
30	22.111	22.78	23.215	0.34312	20.747	21.924	22.751	0.64041	-1.364	-0.8569	-0.248	0.38523
50	21.383	22.386	23.004	0.5142	20.818	21.585	22.603	0.67021	-1.633	-0.8005	-0.078	0.5554

Device Test: 40.3 IOUT_CS_DELAY_RISING(IOUT_CS_RisingDELAY_1p8V)





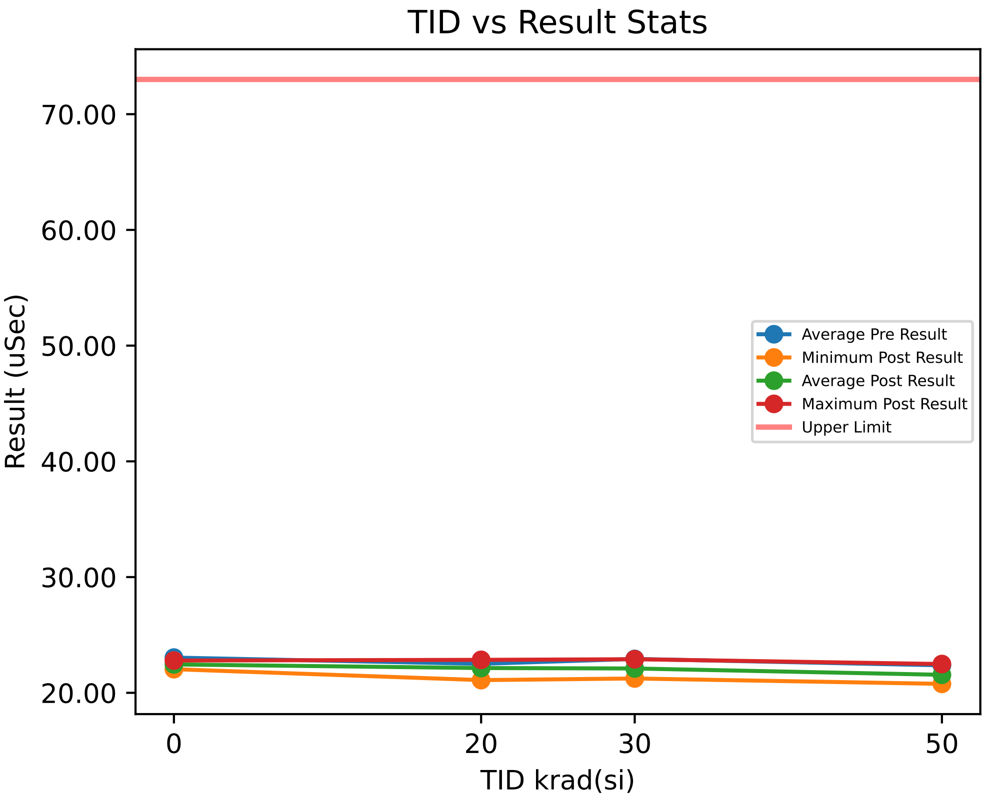
Test Results (Upper Limit = 74.0 (uSec))

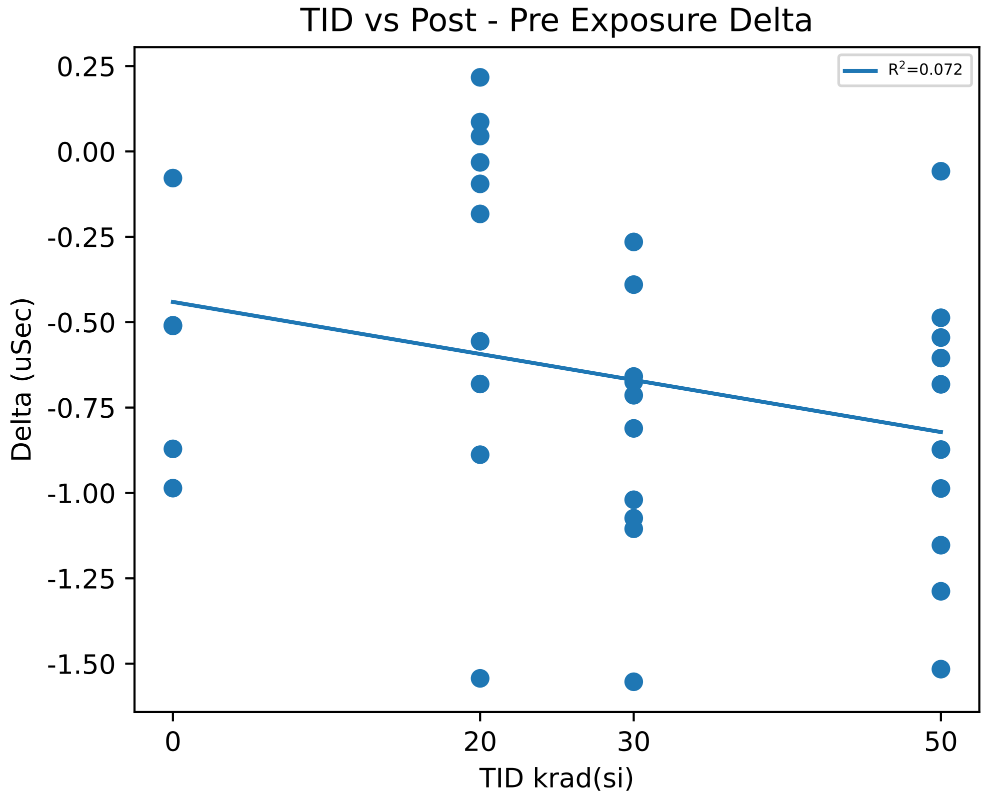
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	23.1	23.181	0.081
2	20	Unbiased	23.029	22.883	-0.146
3	20	Unbiased	22.851	22.703	-0.148
4	20	Unbiased	22.705	22.817	0.112
5	20	Unbiased	23.415	23.384	-0.031
6	20	7V Biased	23.316	23.254	-0.062
7	20	7V Biased	22.661	22.719	0.058
8	20	7V Biased	23.24	23.424	0.184
9	20	7V Biased	22.7	23.007	0.307
10	20	7V Biased	23.367	23.571	0.204
11	30	Unbiased	22.924	23.037	0.113
12	30	Unbiased	23.406	23.57	0.164
13	30	Unbiased	23.049	23.173	0.124
14	30	Unbiased	23.069	23.367	0.298
15	30	Unbiased	22.504	22.5	-0.004
16	30	7V Biased	23.203	23.523	0.32
17	30	7V Biased	23.088	22.98	-0.108
18	30	7V Biased	23.014	22.979	-0.035
19	30	7V Biased	22.815	22.368	-0.447
20	30	7V Biased	23.039	23.33	0.291
21	50	Unbiased	23.142	23.208	0.066
22	50	Unbiased	23.26	23.515	0.255
23	50	Unbiased	23.416	23.507	0.091
24	50	Unbiased	22.413	22.99	0.577
25	50	Unbiased	23.667	23.907	0.24
26	50	7V Biased	23.488	23.522	0.034
27	50	7V Biased	22.773	22.352	-0.421
28	50	7V Biased	23.316	23.042	-0.274
29	50	7V Biased	23.232	23.103	-0.129
30	50	7V Biased	22.46	22.663	0.203
31	0	Correlation	23.065	22.847	-0.218
32	0	Correlation	22.651	22.683	0.032
33	0	Correlation	23.017	22.952	-0.065
34	0	Correlation	23.104	23.011	-0.093
35	0	Correlation	22.417	22.633	0.216

Test Statistics (uSec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.417	22.851	23.104	0.30237	22.633	22.825	23.011	0.1645	-0.218	-0.0256	0.216	0.16187
20	22.661	23.038	23.415	0.29337	22.703	23.094	23.571	0.31199	-0.148	0.0559	0.307	0.15238
30	22.504	23.011	23.406	0.23745	22.368	23.083	23.57	0.4021	-0.447	0.0716	0.32	0.2339
50	22.413	23.117	23.667	0.42805	22.352	23.181	23.907	0.45697	-0.421	0.0642	0.577	0.28641

Device Test: 40.4 IOUT_CS_DELAY_FALLING(IOUT_CS_FallingDELAY_3p3V)





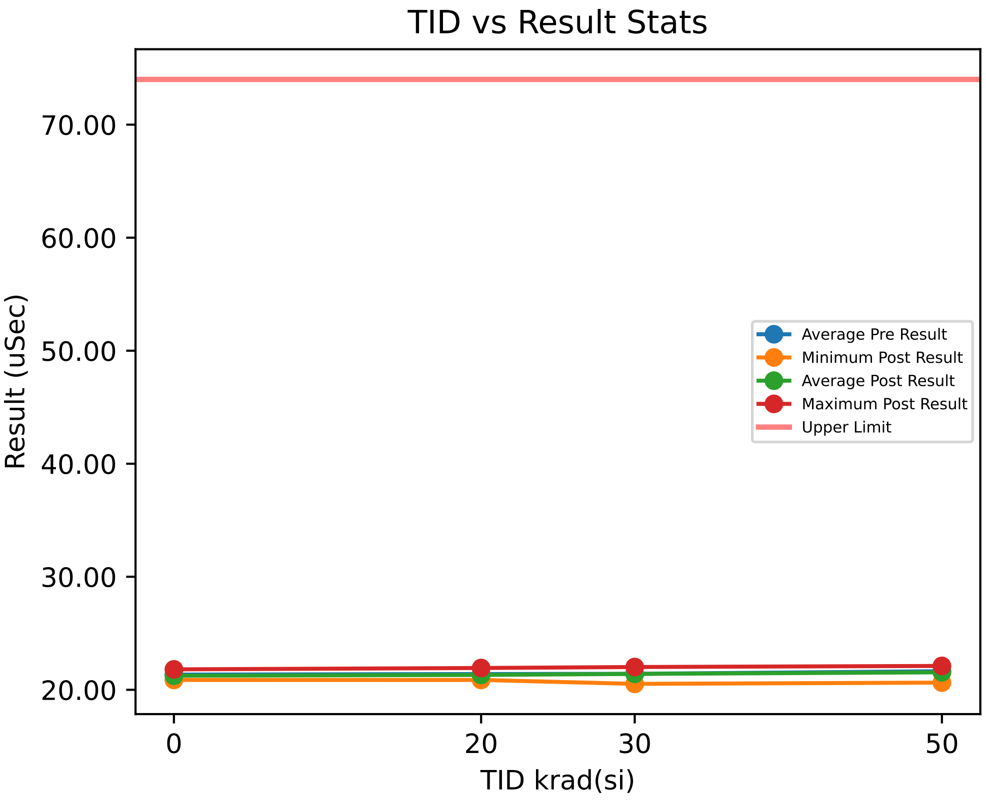
Test Results (Upper Limit = 73.0 (uSec))

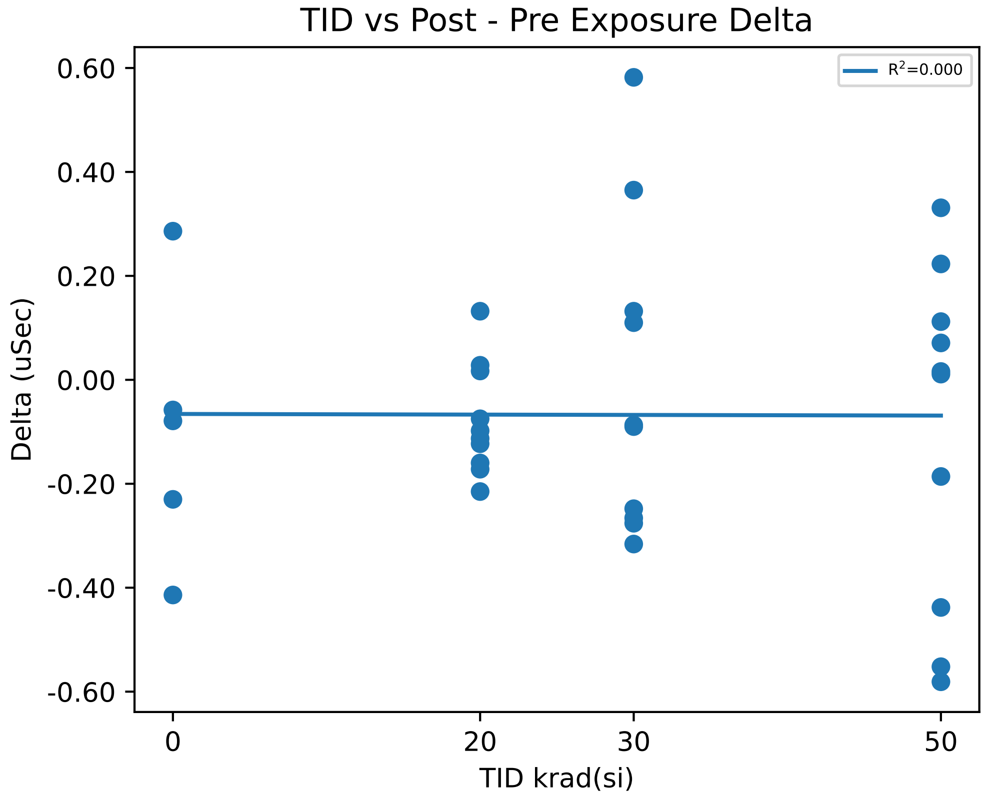
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	22.299	22.385	0.086
2	20	Unbiased	22.632	22.849	0.217
3	20	Unbiased	22.996	22.813	-0.183
4	20	Unbiased	21.644	21.612	-0.032
5	20	Unbiased	22.519	22.564	0.045
6	20	7V Biased	23.077	22.521	-0.556
7	20	7V Biased	22.577	21.896	-0.681
8	20	7V Biased	22.641	21.098	-1.543
9	20	7V Biased	22.433	22.338	-0.095
10	20	7V Biased	22.224	21.336	-0.888
11	30	Unbiased	22.878	22.067	-0.811
12	30	Unbiased	22.799	21.779	-1.02
13	30	Unbiased	22.778	22.513	-0.265
14	30	Unbiased	22.311	21.597	-0.714
15	30	Unbiased	23.541	22.866	-0.675
16	30	7V Biased	22.312	21.238	-1.074
17	30	7V Biased	22.9	22.51	-0.39
18	30	7V Biased	23.092	21.987	-1.105
19	30	7V Biased	23.562	22.903	-0.659
20	30	7V Biased	23.115	21.562	-1.553
21	50	Unbiased	22.282	22.224	-0.058
22	50	Unbiased	21.926	20.773	-1.153
23	50	Unbiased	22.438	21.565	-0.873
24	50	Unbiased	22.903	21.387	-1.516
25	50	Unbiased	21.432	20.887	-0.545
26	50	7V Biased	21.485	20.803	-0.682
27	50	7V Biased	22.688	22.083	-0.605
28	50	7V Biased	22.034	21.047	-0.987
29	50	7V Biased	22.797	22.31	-0.487
30	50	7V Biased	23.776	22.488	-1.288
31	0	Correlation	23.3	22.789	-0.511
32	0	Correlation	23.364	22.378	-0.986
33	0	Correlation	22.555	22.477	-0.078
34	0	Correlation	22.913	22.042	-0.871
35	0	Correlation	23.088	22.579	-0.509

Test Statistics (uSec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	22.555	23.044	23.364	0.3264	22.042	22.453	22.789	0.27563	-0.986	-0.591	-0.078	0.35732
20	21.644	22.504	23.077	0.40499	21.098	22.141	22.849	0.61916	-1.543	-0.363	0.217	0.55022
30	22.311	22.929	23.562	0.42716	21.238	22.102	22.903	0.57471	-1.553	-0.8266	-0.265	0.37621
50	21.432	22.376	23.776	0.70942	20.773	21.557	22.488	0.67301	-1.516	-0.8194	-0.058	0.43172

Device Test: 40.5 IOUT_CS_DELAY_RISING(IOUT_CS_RisingDELAY_3p3V)





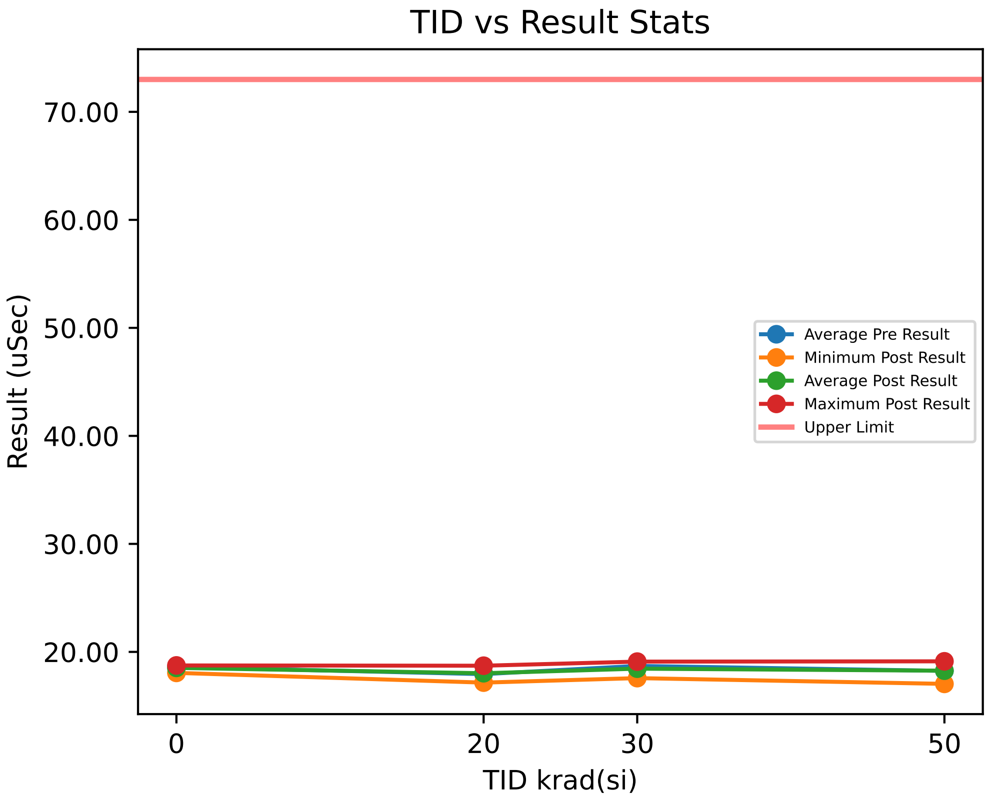
Test Results (Upper Limit = 74.0 (uSec))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	21.353	21.24	-0.113
2	20	Unbiased	20.867	20.884	0.017
3	20	Unbiased	21.085	20.87	-0.215
4	20	Unbiased	20.914	21.046	0.132
5	20	Unbiased	22.003	21.928	-0.075
6	20	7V Biased	21.45	21.352	-0.098
7	20	7V Biased	21.371	21.211	-0.16
8	20	7V Biased	21.616	21.644	0.028
9	20	7V Biased	21.199	21.076	-0.123
10	20	7V Biased	22.082	21.91	-0.172
11	30	Unbiased	21.421	21.786	0.365
12	30	Unbiased	22.055	21.779	-0.276
13	30	Unbiased	21.433	22.015	0.582
14	30	Unbiased	21.74	21.85	0.11
15	30	Unbiased	20.947	20.86	-0.087
16	30	7V Biased	21.726	21.858	0.132
17	30	7V Biased	21.318	21.228	-0.09
18	30	7V Biased	21.185	20.937	-0.248
19	30	7V Biased	20.79	20.524	-0.266
20	30	7V Biased	21.526	21.21	-0.316
21	50	Unbiased	22.144	21.958	-0.186
22	50	Unbiased	21.912	21.983	0.071
23	50	Unbiased	22.052	22.063	0.011
24	50	Unbiased	20.807	21.138	0.331
25	50	Unbiased	21.888	22.111	0.223
26	50	7V Biased	21.844	21.956	0.112
27	50	7V Biased	21.217	20.636	-0.581
28	50	7V Biased	22.075	21.523	-0.552
29	50	7V Biased	21.893	21.455	-0.438
30	50	7V Biased	20.627	20.643	0.016
31	0	Correlation	21.347	21.289	-0.058
32	0	Correlation	21.285	20.871	-0.414
33	0	Correlation	21.55	21.32	-0.23
34	0	Correlation	21.522	21.808	0.286
35	0	Correlation	21.016	20.937	-0.079

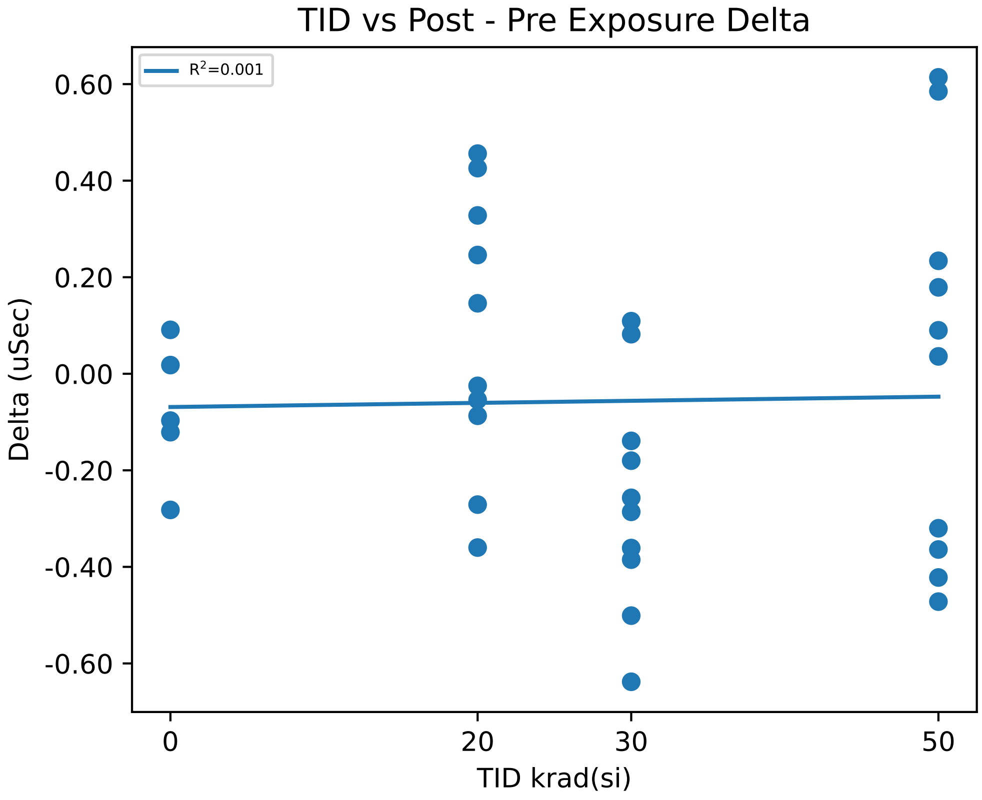
Test Statistics (uSec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.016	21.344	21.55	0.21517	20.871	21.245	21.808	0.37392	-0.414	-0.099	0.286	0.25821
20	20.867	21.394	22.082	0.41372	20.87	21.316	21.928	0.39003	-0.215	-0.0779	0.132	0.10664
30	20.79	21.414	22.055	0.37956	20.524	21.405	22.015	0.51875	-0.316	-0.0094	0.582	0.30268
50	20.627	21.646	22.144	0.55305	20.636	21.547	22.111	0.57097	-0.581	-0.0993	0.331	0.32444

Device Test: 40.6 IOUT_CS_DELAY_FALLING(IOUT_CS_FallingDELAY_5V)



TID vs Result Stats



TID vs Post - Pre Exposure Delta

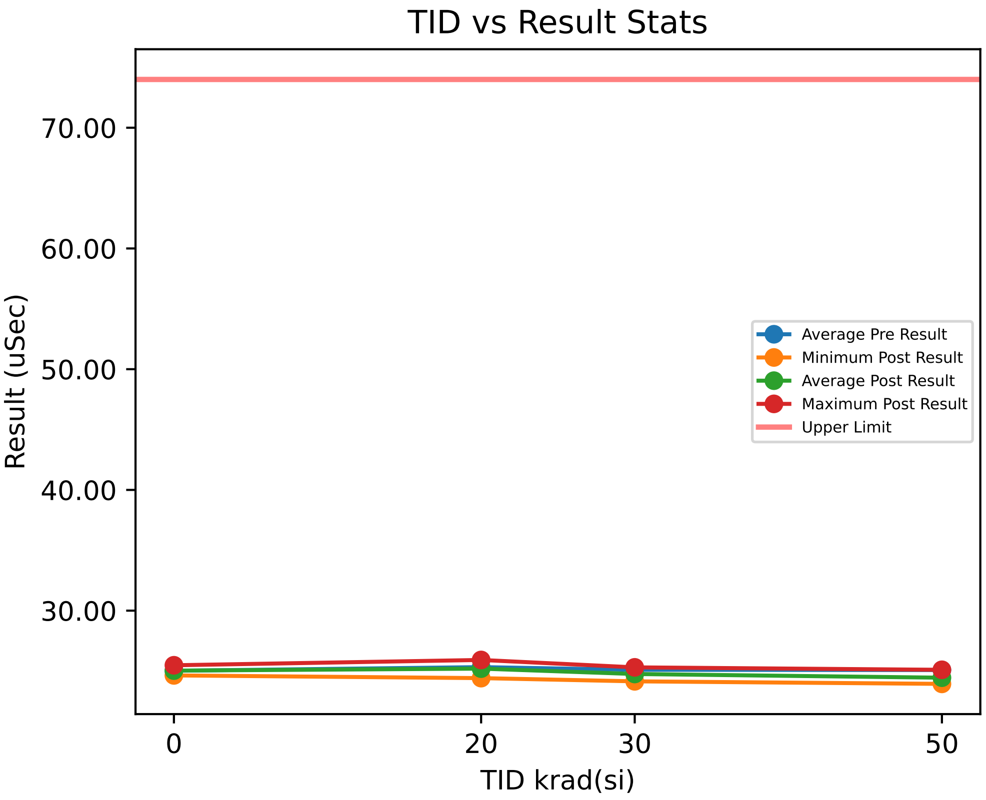
Test Results (Upper Limit = 73.0 (uSec))

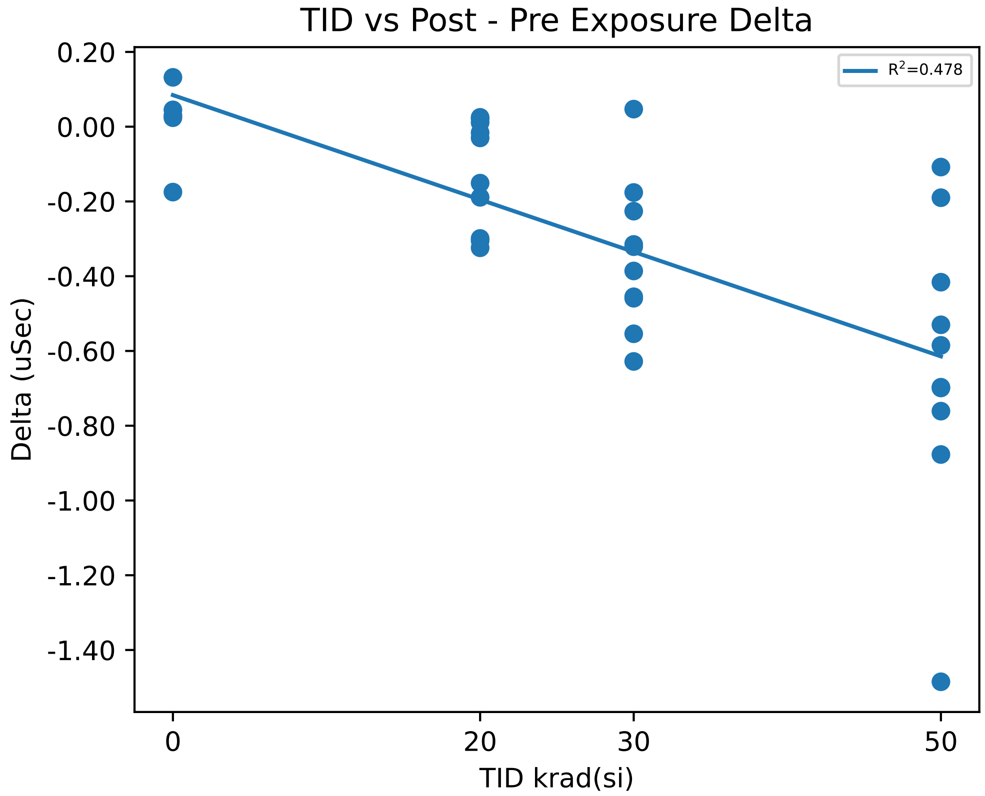
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	17.587	17.833	0.246
2	20	Unbiased	18.295	18.721	0.426
3	20	Unbiased	17.754	17.9	0.146
4	20	Unbiased	18.248	18.576	0.328
5	20	Unbiased	17.489	17.945	0.456
6	20	7V Biased	18.219	18.165	-0.054
7	20	7V Biased	18.748	18.477	-0.271
8	20	7V Biased	17.516	17.156	-0.36
9	20	7V Biased	17.473	17.386	-0.087
10	20	7V Biased	18.1	18.075	-0.025
11	30	Unbiased	18.82	18.459	-0.361
12	30	Unbiased	18.834	18.654	-0.18
13	30	Unbiased	18.872	18.615	-0.257
14	30	Unbiased	17.958	17.573	-0.385
15	30	Unbiased	19.279	18.641	-0.638
16	30	7V Biased	17.914	17.775	-0.139
17	30	7V Biased	18.991	19.1	0.109
18	30	7V Biased	19.076	18.79	-0.286
19	30	7V Biased	18.718	18.217	-0.501
20	30	7V Biased	18.564	18.646	0.082
21	50	Unbiased	18.514	19.128	0.614
22	50	Unbiased	17.512	17.04	-0.472
23	50	Unbiased	18.476	18.054	-0.422
24	50	Unbiased	18.793	18.429	-0.364
25	50	Unbiased	17.357	17.536	0.179
26	50	7V Biased	18.117	18.207	0.09
27	50	7V Biased	18.036	18.27	0.234
28	50	7V Biased	18.151	18.736	0.585
29	50	7V Biased	18.649	18.685	0.036
30	50	7V Biased	18.83	18.51	-0.32
31	0	Correlation	18.844	18.747	-0.097
32	0	Correlation	18.392	18.483	0.091
33	0	Correlation	18.04	18.058	0.018
34	0	Correlation	18.843	18.722	-0.121
35	0	Correlation	18.874	18.592	-0.282

Test Statistics (uSec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	18.04	18.599	18.874	0.37098	18.058	18.52	18.747	0.27943	-0.282	-0.0782	0.091	0.14283
20	17.473	17.943	18.748	0.43939	17.156	18.023	18.721	0.49853	-0.36	0.0805	0.456	0.28444
30	17.914	18.703	19.279	0.4485	17.573	18.447	19.1	0.46677	-0.638	-0.2556	0.109	0.23604
50	17.357	18.244	18.83	0.50839	17.04	18.259	19.128	0.60641	-0.472	0.016	0.614	0.4012

Device Test: 40.7 IOUT_CS_DELAY_RISING(IOUT_CS_RisingDELAY_5V)





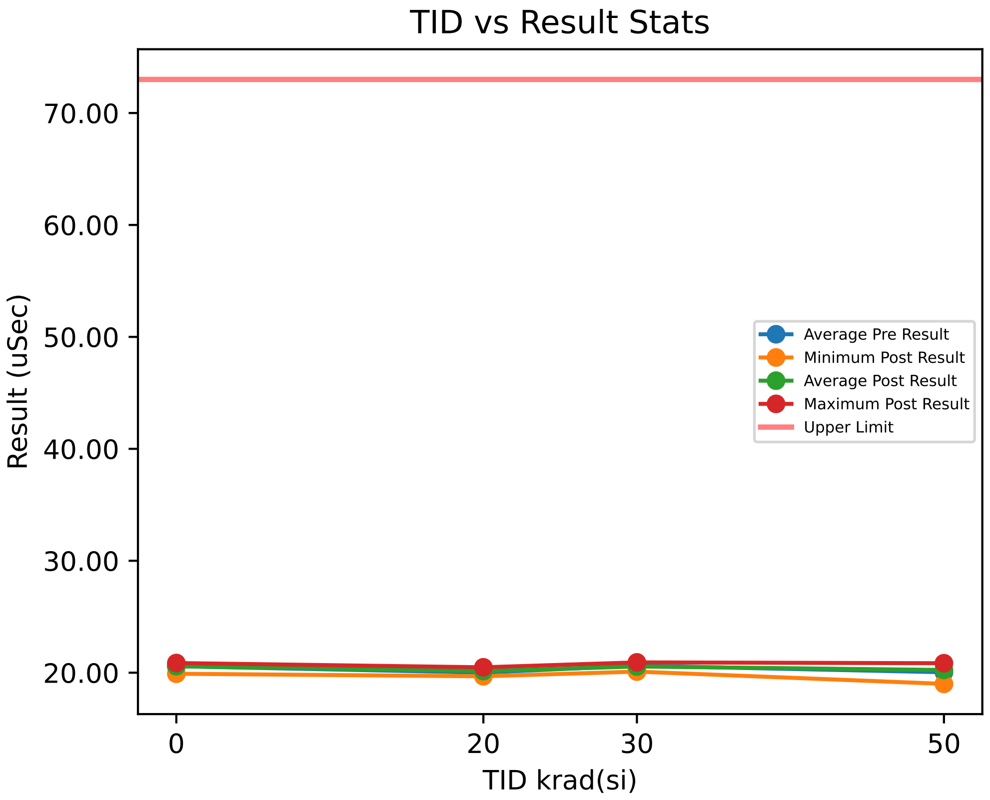
Test Results (Upper Limit = 74.0 (uSec))

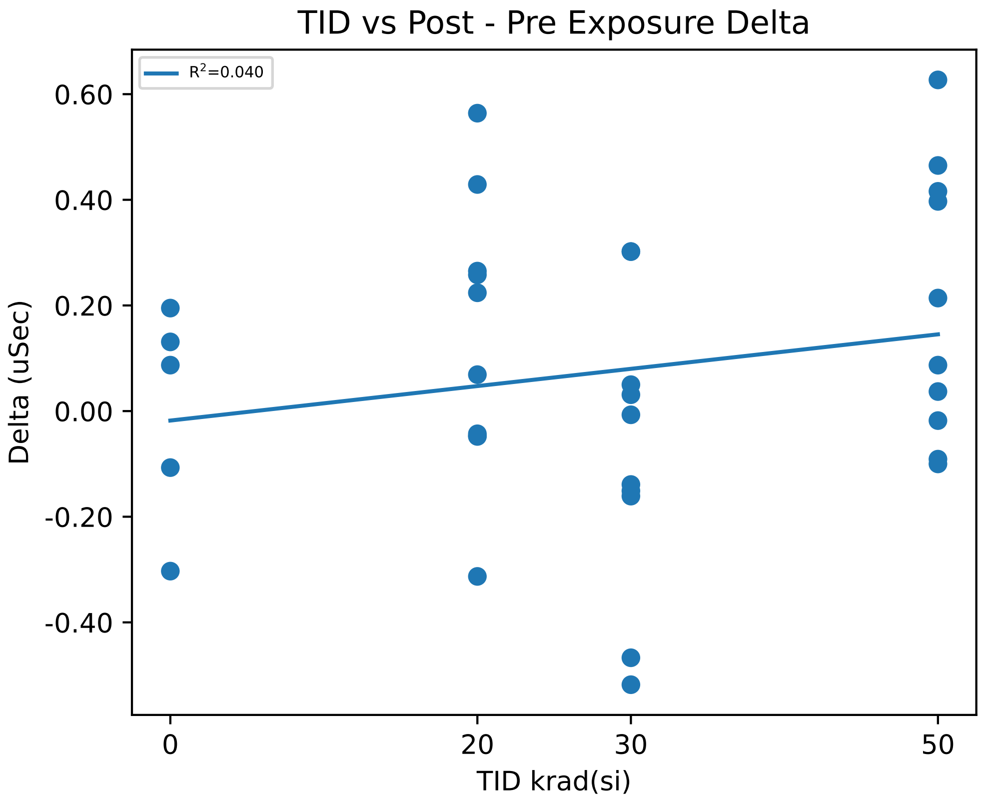
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	25.543	25.554	0.011
2	20	Unbiased	25.17	25.195	0.025
3	20	Unbiased	25.302	25.323	0.021
4	20	Unbiased	24.792	24.776	-0.016
5	20	Unbiased	26.104	25.915	-0.189
6	20	7V Biased	25.233	25.203	-0.03
7	20	7V Biased	24.561	24.41	-0.151
8	20	7V Biased	25.795	25.496	-0.299
9	20	7V Biased	25.456	25.132	-0.324
10	20	7V Biased	25.266	24.961	-0.305
11	30	Unbiased	25.183	24.862	-0.321
12	30	Unbiased	25.403	24.849	-0.554
13	30	Unbiased	24.804	24.851	0.047
14	30	Unbiased	25.688	25.302	-0.386
15	30	Unbiased	24.735	24.509	-0.226
16	30	7V Biased	25.489	25.03	-0.459
17	30	7V Biased	24.891	24.576	-0.315
18	30	7V Biased	24.32	24.144	-0.176
19	30	7V Biased	25.303	24.848	-0.455
20	30	7V Biased	25.174	24.546	-0.628
21	50	Unbiased	25	24.303	-0.697
22	50	Unbiased	25.289	25.099	-0.19
23	50	Unbiased	25.413	24.828	-0.585
24	50	Unbiased	24.529	23.999	-0.53
25	50	Unbiased	25.16	25.052	-0.108
26	50	7V Biased	24.962	24.263	-0.699
27	50	7V Biased	24.915	24.038	-0.877
28	50	7V Biased	25.419	23.934	-1.485
29	50	7V Biased	25.144	24.383	-0.761
30	50	7V Biased	24.97	24.554	-0.416
31	0	Correlation	24.998	25.043	0.045
32	0	Correlation	25.192	25.017	-0.175
33	0	Correlation	25.343	25.475	0.132
34	0	Correlation	24.963	24.987	0.024
35	0	Correlation	24.605	24.635	0.03

Test Statistics (uSec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.605	25.02	25.343	0.27833	24.635	25.031	25.475	0.29842	-0.175	0.0112	0.132	0.11283
20	24.561	25.322	26.104	0.44679	24.41	25.197	25.915	0.42227	-0.324	-0.1257	0.025	0.1454
30	24.32	25.099	25.688	0.41033	24.144	24.752	25.302	0.32014	-0.628	-0.3473	0.047	0.19674
50	24.529	25.08	25.419	0.26734	23.934	24.445	25.099	0.42656	-1.485	-0.6348	-0.108	0.38617

Device Test: 40.8 IOUT_CS_DELAY_FALLING(IOUT_CS_FallingDELAY_7V)





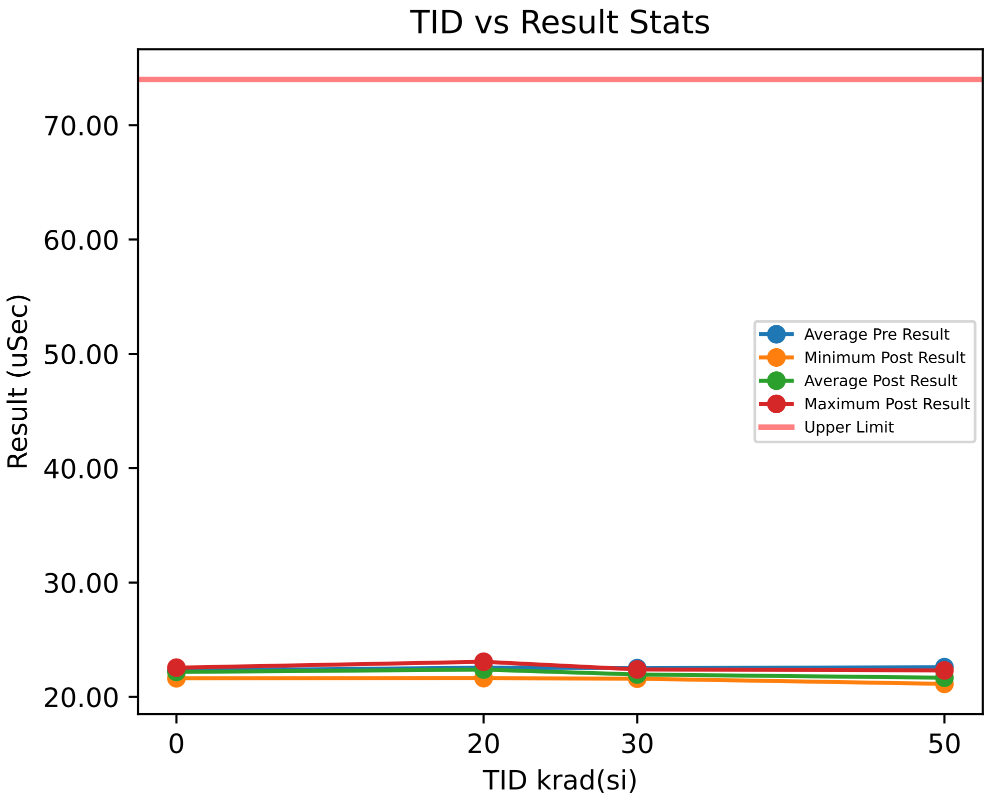
Test Results (Upper Limit = 73.0 (uSec))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	19.695	19.96	0.265
2	20	Unbiased	19.984	20.413	0.429
3	20	Unbiased	20.384	20.337	-0.047
4	20	Unbiased	20.524	20.481	-0.043
5	20	Unbiased	19.592	20.156	0.564
6	20	7V Biased	19.964	20.033	0.069
7	20	7V Biased	20.422	20.374	-0.048
8	20	7V Biased	19.421	19.679	0.258
9	20	7V Biased	19.555	19.779	0.224
10	20	7V Biased	20.567	20.254	-0.313
11	30	Unbiased	20.848	20.898	0.05
12	30	Unbiased	20.802	20.663	-0.139
13	30	Unbiased	20.74	20.733	-0.007
14	30	Unbiased	20.068	20.099	0.031
15	30	Unbiased	21.072	20.921	-0.151
16	30	7V Biased	19.875	20.177	0.302
17	30	7V Biased	20.897	20.43	-0.467
18	30	7V Biased	20.625	20.464	-0.161
19	30	7V Biased	20.873	20.355	-0.518
20	30	7V Biased	20.488	20.79	0.302
21	50	Unbiased	20.364	20.829	0.465
22	50	Unbiased	19.368	19.405	0.037
23	50	Unbiased	19.822	20.036	0.214
24	50	Unbiased	20.581	20.563	-0.018
25	50	Unbiased	19.102	19.002	-0.1
26	50	7V Biased	19.569	19.966	0.397
27	50	7V Biased	20.366	20.453	0.087
28	50	7V Biased	20.198	20.614	0.416
29	50	7V Biased	20.219	20.846	0.627
30	50	7V Biased	20.812	20.721	-0.091
31	0	Correlation	20.969	20.666	-0.303
32	0	Correlation	20.579	20.774	0.195
33	0	Correlation	19.819	19.906	0.087
34	0	Correlation	20.788	20.681	-0.107
35	0	Correlation	20.732	20.863	0.131

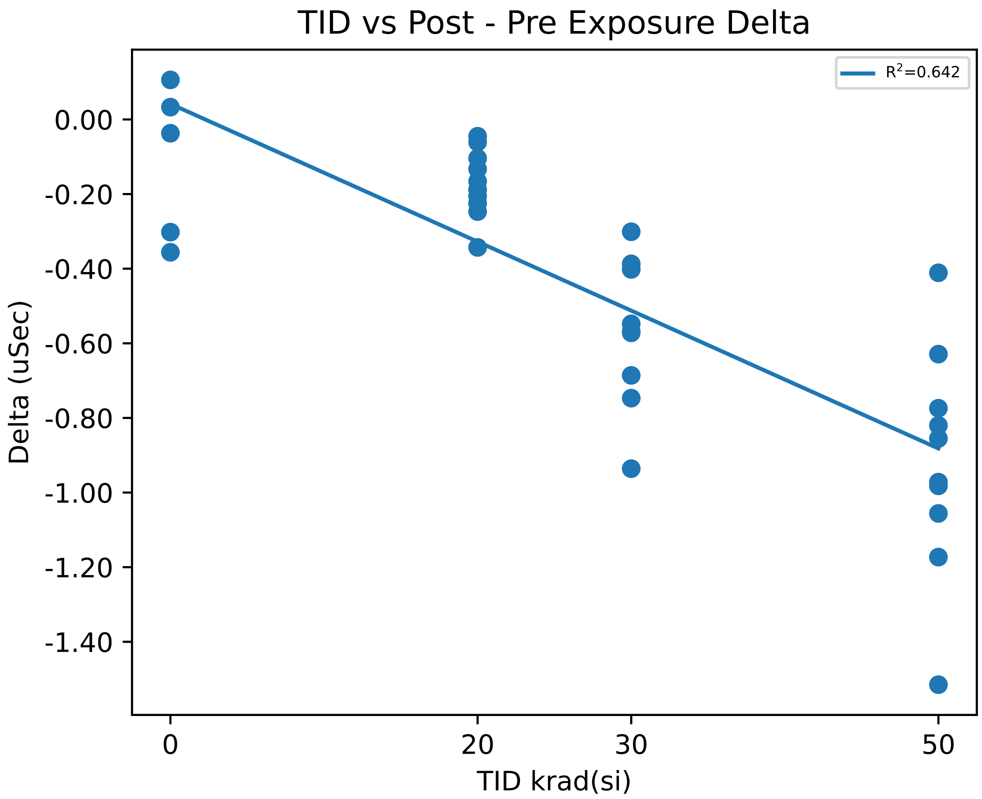
Test Statistics (uSec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.819	20.577	20.969	0.44631	19.906	20.578	20.863	0.38392	-0.303	0.0006	0.195	0.20372
20	19.421	20.011	20.567	0.43649	19.679	20.147	20.481	0.27566	-0.313	0.1358	0.564	0.26115
30	19.875	20.629	21.072	0.38311	20.099	20.553	20.921	0.29152	-0.518	-0.0758	0.302	0.27546
50	19.102	20.04	20.812	0.55355	19.002	20.244	20.846	0.63083	-0.1	0.2034	0.627	0.25812

Device Test: 40.9 IOUT_CS_DELAY_RISING(IOUT_CS_RisingDELAY_7V)



TID vs Result Stats



TID vs Post - Pre Exposure Delta

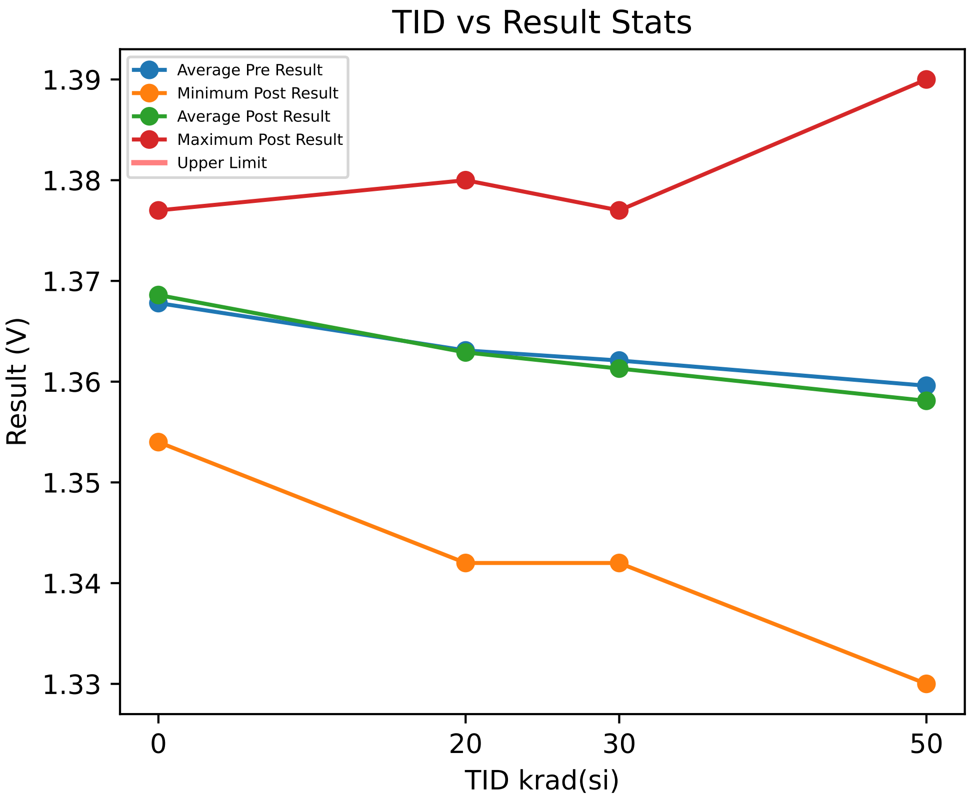
Test Results (Upper Limit = 74.0 (uSec))

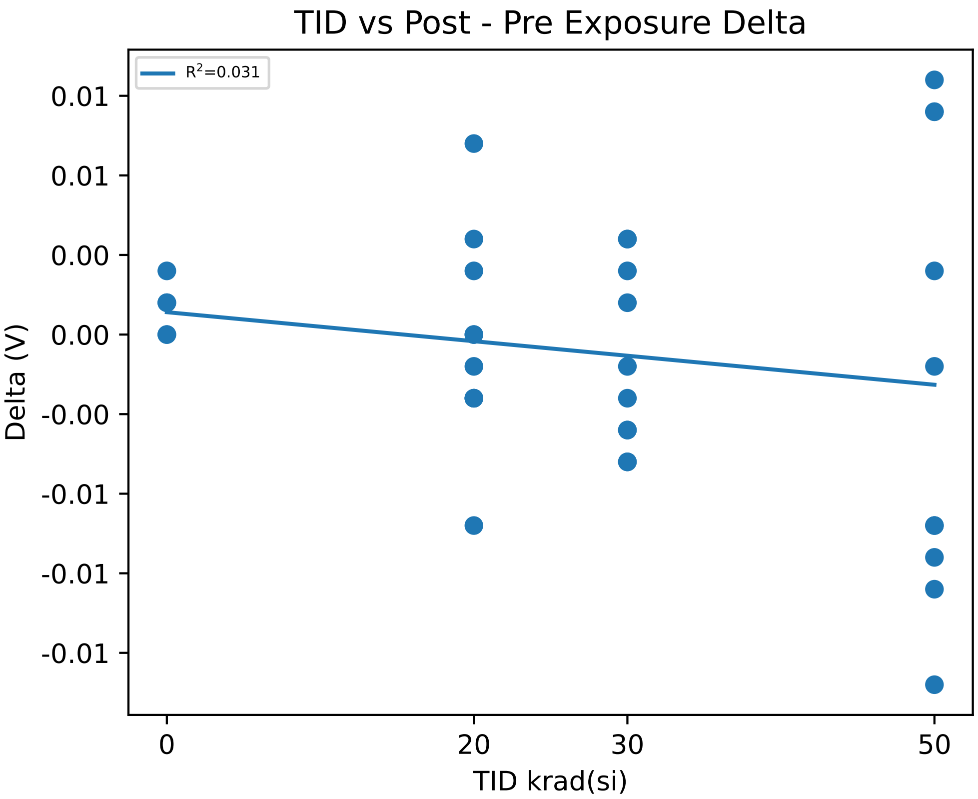
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	22.604	22.559	-0.045
2	20	Unbiased	22.857	22.796	-0.061
3	20	Unbiased	22.505	22.317	-0.188
4	20	Unbiased	21.984	21.641	-0.343
5	20	Unbiased	23.177	23.073	-0.104
6	20	7V Biased	22.909	22.776	-0.133
7	20	7V Biased	22.012	21.806	-0.206
8	20	7V Biased	22.862	22.637	-0.225
9	20	7V Biased	22.155	21.989	-0.166
10	20	7V Biased	22.529	22.282	-0.247
11	30	Unbiased	22.359	21.972	-0.387
12	30	Unbiased	22.948	22.4	-0.548
13	30	Unbiased	22.161	21.86	-0.301
14	30	Unbiased	22.724	22.156	-0.568
15	30	Unbiased	21.993	21.592	-0.401
16	30	7V Biased	22.882	22.31	-0.572
17	30	7V Biased	22.758	22.072	-0.686
18	30	7V Biased	22.155	21.753	-0.402
19	30	7V Biased	22.653	21.717	-0.936
20	30	7V Biased	22.496	21.749	-0.747
21	50	Unbiased	22.338	21.165	-1.173
22	50	Unbiased	22.883	22.063	-0.82
23	50	Unbiased	22.945	22.316	-0.629
24	50	Unbiased	22.194	21.138	-1.056
25	50	Unbiased	22.723	22.312	-0.411
26	50	7V Biased	22.821	21.966	-0.855
27	50	7V Biased	22.35	21.378	-0.972
28	50	7V Biased	22.721	21.206	-1.515
29	50	7V Biased	22.637	21.655	-0.982
30	50	7V Biased	22.36	21.586	-0.774
31	0	Correlation	22.27	22.376	0.106
32	0	Correlation	22.196	21.84	-0.356
33	0	Correlation	22.856	22.554	-0.302
34	0	Correlation	22.547	22.51	-0.037
35	0	Correlation	21.597	21.63	0.033

Test Statistics (uSec)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.597	22.293	22.856	0.46793	21.63	22.182	22.554	0.4199	-0.356	-0.1112	0.106	0.20604
20	21.984	22.559	23.177	0.40606	21.641	22.388	23.073	0.46544	-0.343	-0.1718	-0.045	0.090503
30	21.993	22.513	22.948	0.33267	21.592	21.958	22.4	0.2706	-0.936	-0.5548	-0.301	0.19424
50	22.194	22.597	22.945	0.26512	21.138	21.678	22.316	0.46148	-1.515	-0.9187	-0.411	0.30228

Device Test: 5.0 VIN_UVLO_Rising(VIN_UVLO_RISING)





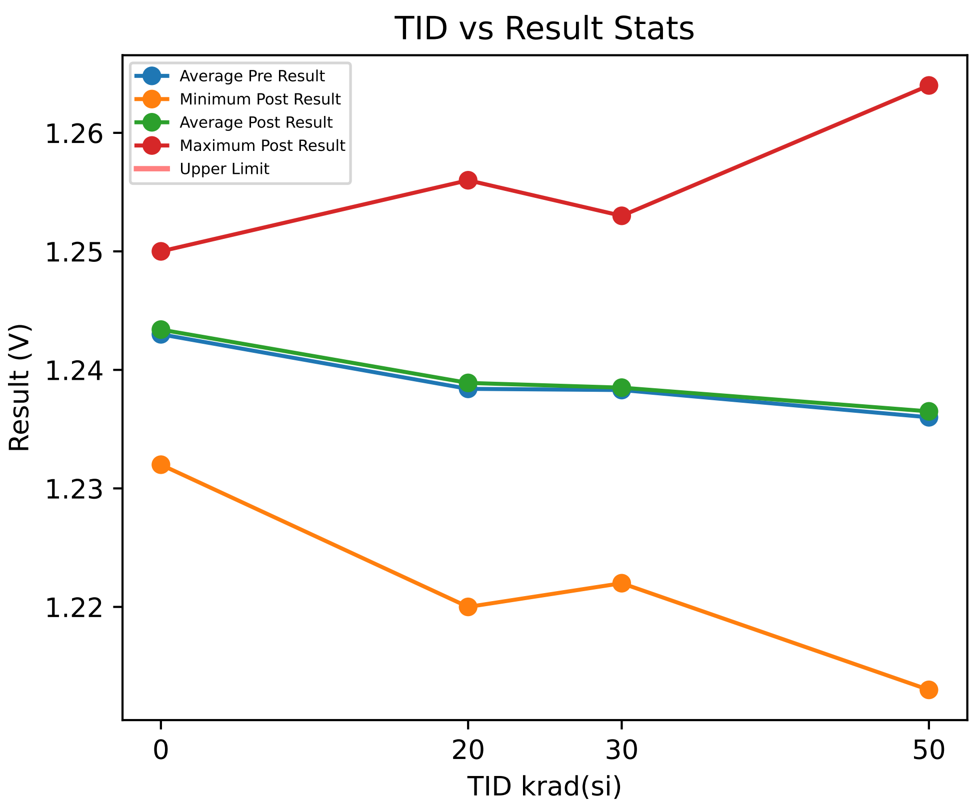
Test Results (No Limits Specified (V))

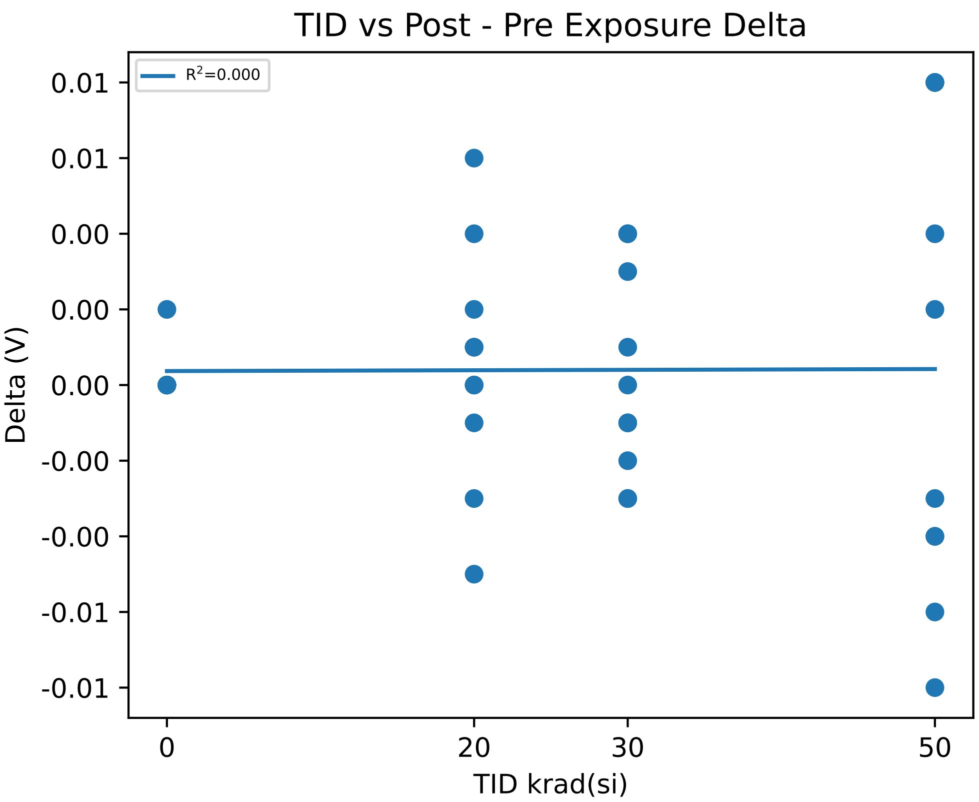
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	1.342	1.342	0
2	20	Unbiased	1.364	1.367	0.003
3	20	Unbiased	1.368	1.37	0.002
4	20	Unbiased	1.357	1.355	-0.002
5	20	Unbiased	1.358	1.364	0.006
6	20	7V Biased	1.374	1.374	0
7	20	7V Biased	1.371	1.369	-0.002
8	20	7V Biased	1.366	1.365	-0.001
9	20	7V Biased	1.382	1.38	-0.002
10	20	7V Biased	1.349	1.343	-0.006
11	30	Unbiased	1.38	1.377	-0.003
12	30	Unbiased	1.361	1.364	0.003
13	30	Unbiased	1.367	1.369	0.002
14	30	Unbiased	1.369	1.372	0.003
15	30	Unbiased	1.349	1.348	-0.001
16	30	7V Biased	1.346	1.342	-0.004
17	30	7V Biased	1.359	1.357	-0.002
18	30	7V Biased	1.355	1.352	-0.003
19	30	7V Biased	1.366	1.362	-0.004
20	30	7V Biased	1.369	1.37	0.001
21	50	Unbiased	1.382	1.39	0.008
22	50	Unbiased	1.359	1.366	0.007
23	50	Unbiased	1.365	1.364	-0.001
24	50	Unbiased	1.358	1.365	0.007
25	50	Unbiased	1.347	1.349	0.002
26	50	7V Biased	1.353	1.342	-0.011
27	50	7V Biased	1.363	1.355	-0.008
28	50	7V Biased	1.352	1.346	-0.006
29	50	7V Biased	1.337	1.33	-0.007
30	50	7V Biased	1.38	1.374	-0.006
31	0	Correlation	1.376	1.377	0.001
32	0	Correlation	1.372	1.374	0.002
33	0	Correlation	1.354	1.354	0
34	0	Correlation	1.366	1.366	0
35	0	Correlation	1.371	1.372	0.001

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.354	1.3678	1.376	0.0084971	1.354	1.3686	1.377	0.0090995	0	0.0008	0.002	0.00083666
20	1.342	1.3631	1.382	0.011921	1.342	1.3629	1.38	0.012565	-0.006	-0.0002	0.006	0.0032931
30	1.346	1.3621	1.38	0.010257	1.342	1.3613	1.377	0.011344	-0.004	-0.0008	0.003	0.0028206
50	1.337	1.3596	1.382	0.013874	1.33	1.3581	1.39	0.01733	-0.011	-0.0015	0.008	0.007075

Device Test: 5.1 VIN_UVLO_Falling(VIN_UVLO_FALLING)





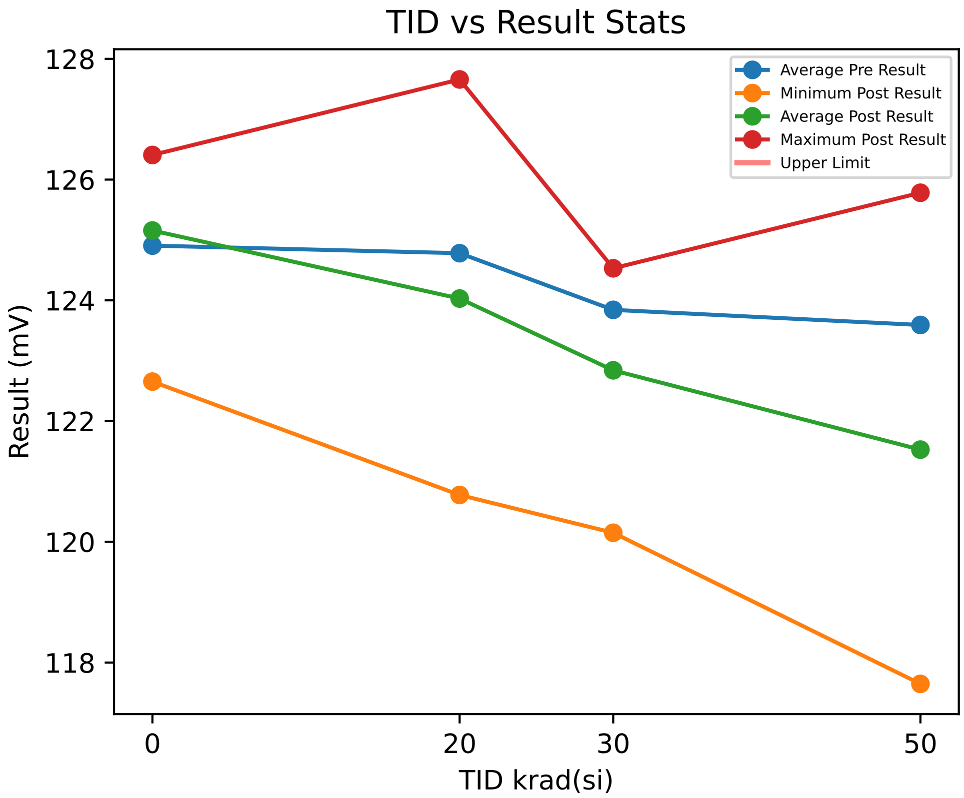
Test Results (No Limits Specified (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	1.219	1.22	0.001
2	20	Unbiased	1.238	1.242	0.004
3	20	Unbiased	1.24	1.242	0.002
4	20	Unbiased	1.232	1.231	-0.001
5	20	Unbiased	1.235	1.241	0.006
6	20	7V Biased	1.249	1.25	0.001
7	20	7V Biased	1.246	1.243	-0.003
8	20	7V Biased	1.242	1.242	0
9	20	7V Biased	1.256	1.256	0
10	20	7V Biased	1.227	1.222	-0.005
11	30	Unbiased	1.254	1.253	-0.001
12	30	Unbiased	1.237	1.24	0.003
13	30	Unbiased	1.243	1.247	0.004
14	30	Unbiased	1.244	1.248	0.004
15	30	Unbiased	1.227	1.227	0
16	30	7V Biased	1.225	1.222	-0.003
17	30	7V Biased	1.235	1.234	-0.001
18	30	7V Biased	1.232	1.23	-0.002
19	30	7V Biased	1.242	1.239	-0.003
20	30	7V Biased	1.244	1.245	0.001
21	50	Unbiased	1.256	1.264	0.008
22	50	Unbiased	1.235	1.243	0.008
23	50	Unbiased	1.24	1.242	0.002
24	50	Unbiased	1.235	1.243	0.008
25	50	Unbiased	1.226	1.23	0.004
26	50	7V Biased	1.23	1.222	-0.008
27	50	7V Biased	1.239	1.233	-0.006
28	50	7V Biased	1.23	1.226	-0.004
29	50	7V Biased	1.216	1.213	-0.003
30	50	7V Biased	1.253	1.249	-0.004
31	0	Correlation	1.25	1.25	0
32	0	Correlation	1.247	1.247	0
33	0	Correlation	1.23	1.232	0.002
34	0	Correlation	1.241	1.241	0
35	0	Correlation	1.247	1.247	0

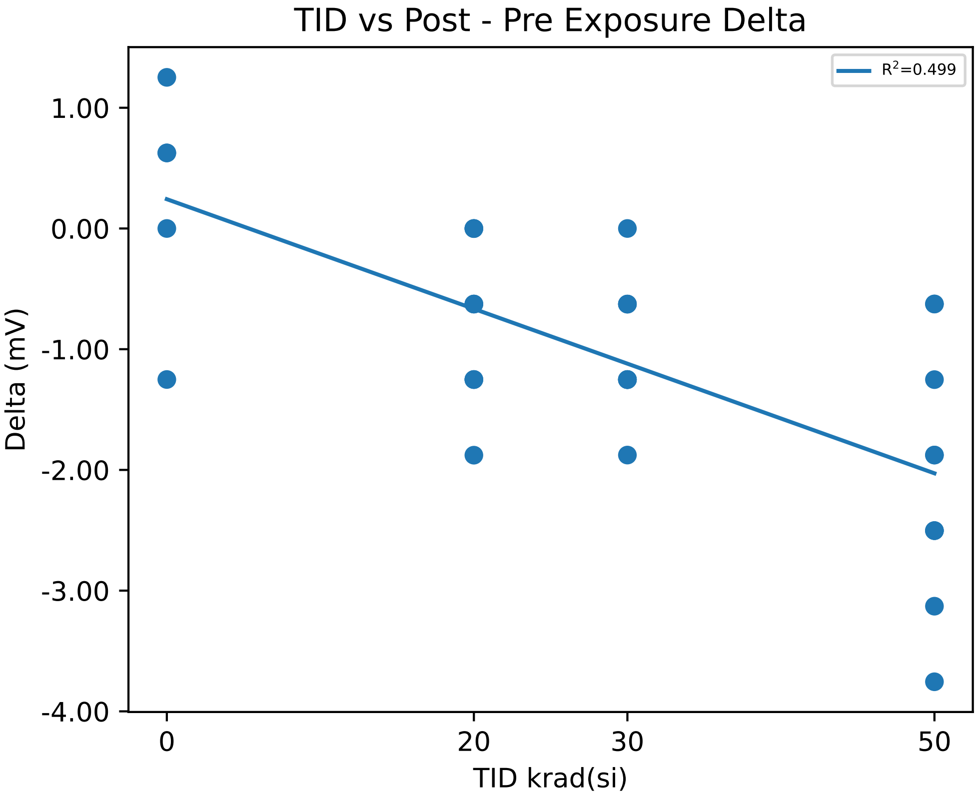
Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.23	1.243	1.25	0.0079687	1.232	1.2434	1.25	0.0071624	0	0.0004	0.002	0.00089443
20	1.219	1.2384	1.256	0.010824	1.22	1.2389	1.256	0.011406	-0.005	0.0005	0.006	0.003171
30	1.225	1.2383	1.254	0.008845	1.222	1.2385	1.253	0.01008	-0.003	0.0002	0.004	0.0026998
50	1.216	1.236	1.256	0.011963	1.213	1.2365	1.264	0.014737	-0.008	0.0005	0.008	0.0062405

Device Test: 5.2 VIN_Hysteresis(VIN_UVLO_HYSTERESIS)



TID vs Result Stats



TID vs Post - Pre Exposure Delta

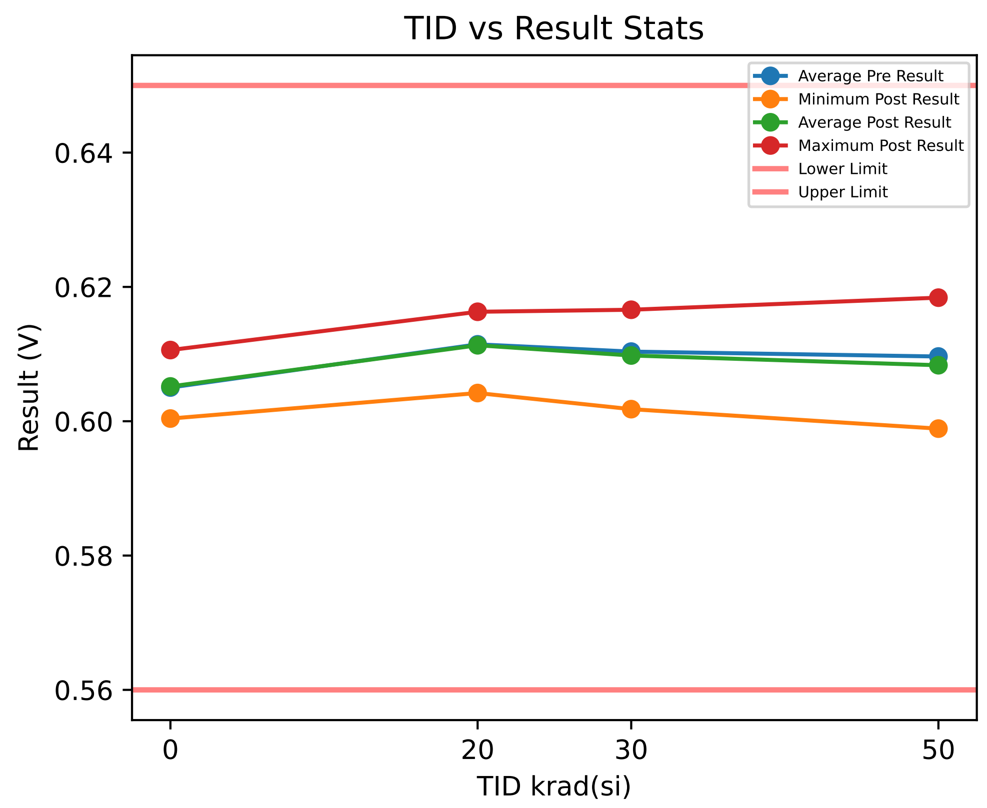
Test Results (No Limits Specified (mV))

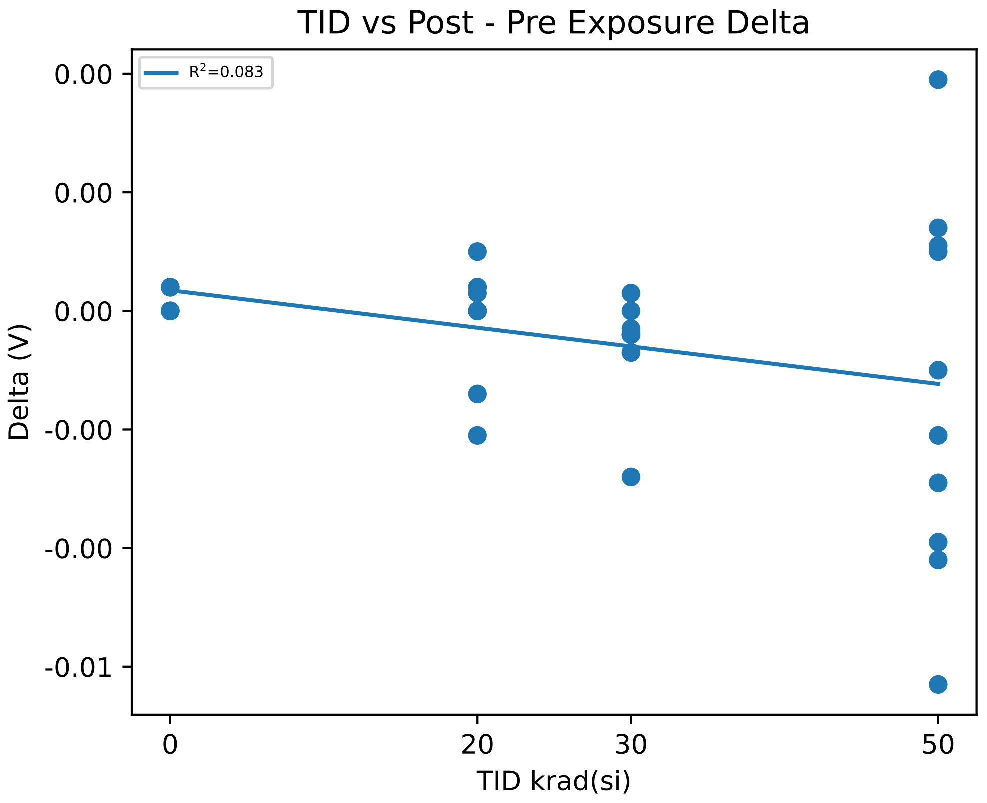
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	123.28	122.03	-1.252
2	20	Unbiased	125.78	125.78	0
3	20	Unbiased	127.66	127.66	-0.001
4	20	Unbiased	125.78	123.91	-1.878
5	20	Unbiased	123.28	122.65	-0.626
6	20	7V Biased	125.16	124.53	-0.626
7	20	7V Biased	125.16	125.16	0
8	20	7V Biased	123.91	123.28	-0.626
9	20	7V Biased	125.78	124.53	-1.251
10	20	7V Biased	122.03	120.78	-1.251
11	30	Unbiased	125.78	124.53	-1.251
12	30	Unbiased	124.53	124.53	0
13	30	Unbiased	123.91	122.03	-1.877
14	30	Unbiased	124.53	123.91	-0.626
15	30	Unbiased	122.03	120.78	-1.252
16	30	7V Biased	121.4	120.15	-1.252
17	30	7V Biased	123.91	122.65	-1.252
18	30	7V Biased	123.28	122.03	-1.251
19	30	7V Biased	123.91	123.28	-0.626
20	30	7V Biased	125.16	124.53	-0.627
21	50	Unbiased	126.41	125.78	-0.626
22	50	Unbiased	123.28	122.65	-0.625
23	50	Unbiased	125.78	122.03	-3.755
24	50	Unbiased	123.28	122.03	-1.252
25	50	Unbiased	121.4	118.9	-2.503
26	50	7V Biased	122.65	120.15	-2.503
27	50	7V Biased	123.91	121.4	-2.503
28	50	7V Biased	122.03	120.15	-1.877
29	50	7V Biased	120.78	117.65	-3.129
30	50	7V Biased	126.41	124.53	-1.877
31	0	Correlation	125.78	126.41	0.626
32	0	Correlation	125.16	126.41	1.252
33	0	Correlation	123.91	122.65	-1.251
34	0	Correlation	125.16	125.16	0
35	0	Correlation	124.53	125.16	0.626

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	123.91	124.91	125.78	0.71336	122.65	125.16	126.41	1.5326	-1.251	0.2506	1.252	0.94898
20	122.03	124.78	127.66	1.648	120.78	124.03	127.66	1.9745	-1.878	-0.7511	0	0.64623
30	121.4	123.84	125.78	1.3339	120.15	122.84	124.53	1.5898	-1.877	-1.0014	0	0.52752
50	120.78	123.59	126.41	2.0277	117.65	121.53	125.78	2.4645	-3.755	-2.065	-0.625	1.0241

Device Test: 6.0 EN_VTH_RISING(EN_UVLO_RISING_1p5V)





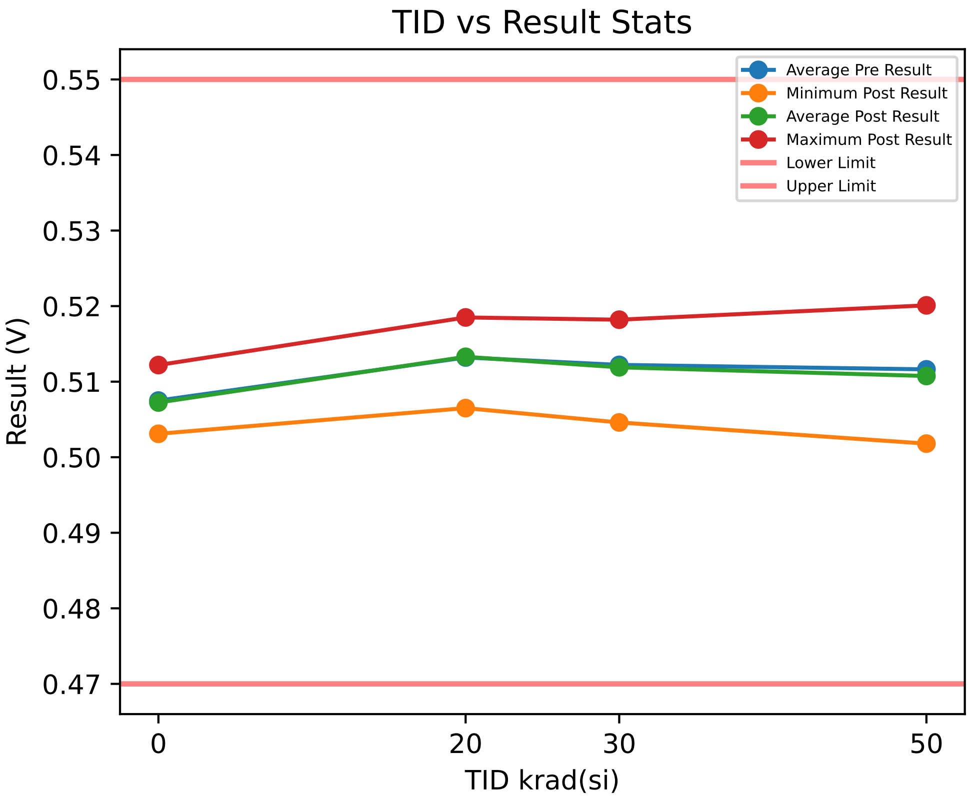
Test Results (Lower Limit = 0.56, Upper Limit = 0.65 (V))

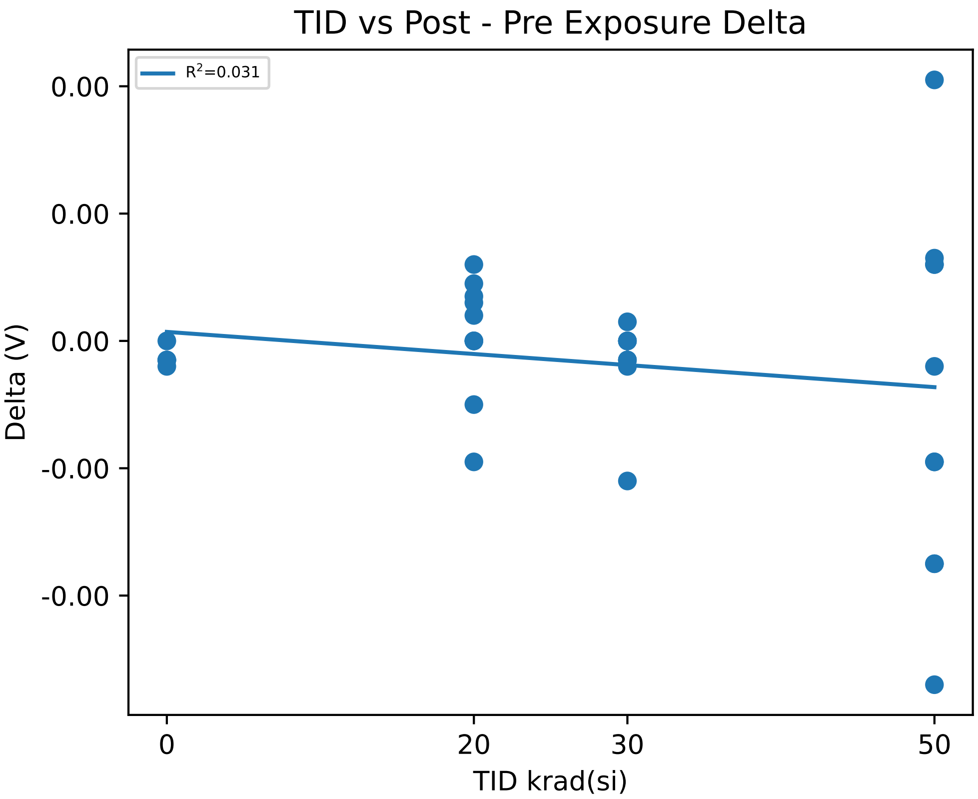
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.6145	0.6145	0
2	20	Unbiased	0.6117	0.6127	0.001
3	20	Unbiased	0.6152	0.6155	0.0003
4	20	Unbiased	0.6159	0.6163	0.0004
5	20	Unbiased	0.6064	0.6064	0
6	20	7V Biased	0.6134	0.612	-0.0014
7	20	7V Biased	0.6127	0.6127	0
8	20	7V Biased	0.6113	0.6117	0.0004
9	20	7V Biased	0.6042	0.6042	0
10	20	7V Biased	0.6092	0.6071	-0.0021
11	30	Unbiased	0.6067	0.6039	-0.0028
12	30	Unbiased	0.6085	0.6088	0.0003
13	30	Unbiased	0.617	0.6166	-0.0004
14	30	Unbiased	0.6163	0.6159	-0.0004
15	30	Unbiased	0.6138	0.6134	-0.0004
16	30	7V Biased	0.6124	0.6117	-0.0007
17	30	7V Biased	0.6049	0.6046	-0.0003
18	30	7V Biased	0.6064	0.606	-0.0004
19	30	7V Biased	0.6025	0.6018	-0.0007
20	30	7V Biased	0.6152	0.6152	0
21	50	Unbiased	0.617	0.6184	0.0014
22	50	Unbiased	0.6074	0.6113	0.0039
23	50	Unbiased	0.6092	0.6102	0.001
24	50	Unbiased	0.6102	0.6113	0.0011
25	50	Unbiased	0.6088	0.6078	-0.001
26	50	7V Biased	0.6134	0.6071	-0.0063
27	50	7V Biased	0.6053	0.6032	-0.0021
28	50	7V Biased	0.6053	0.6011	-0.0042
29	50	7V Biased	0.6028	0.5989	-0.0039
30	50	7V Biased	0.617	0.6141	-0.0029
31	0	Correlation	0.6	0.6004	0.0004
32	0	Correlation	0.6102	0.6106	0.0004
33	0	Correlation	0.6071	0.6071	0
34	0	Correlation	0.6011	0.6011	0
35	0	Correlation	0.6067	0.6067	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6	0.60502	0.6102	0.0043171	0.6004	0.60518	0.6106	0.0043263	0	0.00016	0.0004	0.00021909
20	0.6042	0.61145	0.6159	0.003826	0.6042	0.61131	0.6163	0.0040758	-0.0021	-0.00014	0.001	0.00091797
30	0.6025	0.61037	0.617	0.0051953	0.6018	0.60979	0.6166	0.005482	-0.0028	-0.00058	0.0003	0.00083506
50	0.6028	0.60964	0.617	0.0048667	0.5989	0.60834	0.6184	0.0060106	-0.0063	-0.0013	0.0039	0.0031418

Device Test: 6.1 EN_VTH_FALLING(EN_UVLO_FALLING_1p5V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

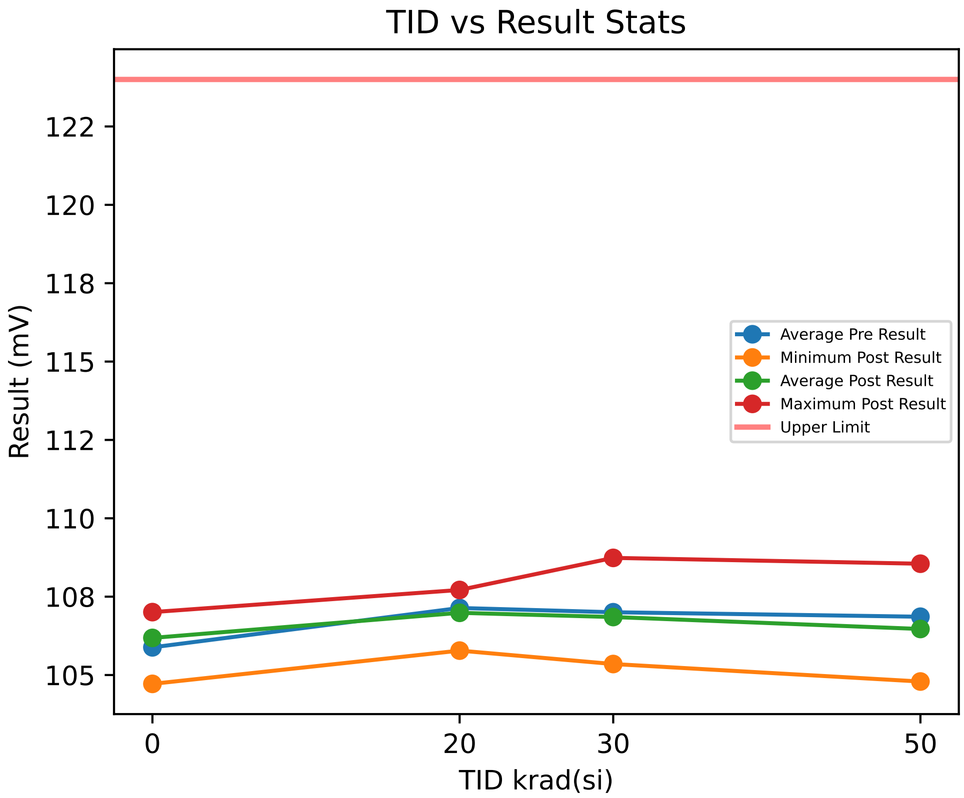
Test Results (Lower Limit = 0.47, Upper Limit = 0.55 (V))

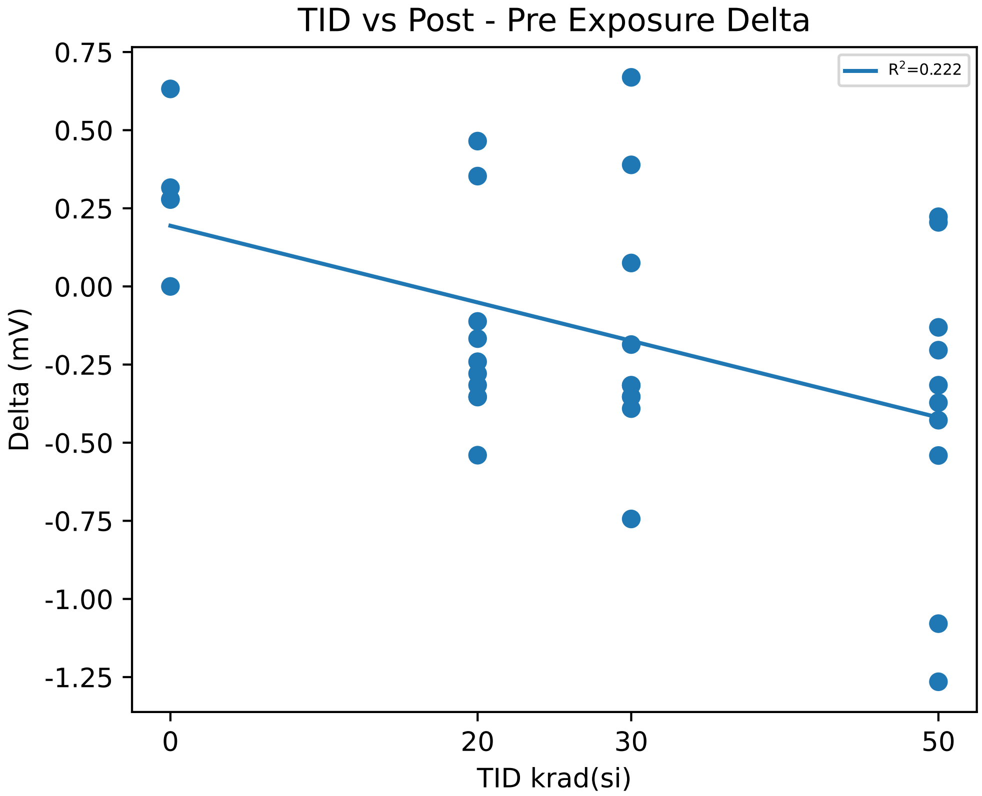
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.516	0.516	0
2	20	Unbiased	0.5132	0.5141	0.0009
3	20	Unbiased	0.5166	0.5173	0.0007
4	20	Unbiased	0.5179	0.5185	0.0006
5	20	Unbiased	0.5084	0.5084	0
6	20	7V Biased	0.5151	0.5141	-0.001
7	20	7V Biased	0.5144	0.5148	0.0004
8	20	7V Biased	0.5129	0.5141	0.0012
9	20	7V Biased	0.5065	0.5065	0
10	20	7V Biased	0.511	0.5091	-0.0019
11	30	Unbiased	0.5087	0.5065	-0.0022
12	30	Unbiased	0.5097	0.51	0.0003
13	30	Unbiased	0.5182	0.5182	0
14	30	Unbiased	0.5176	0.5173	-0.0003
15	30	Unbiased	0.516	0.5157	-0.0003
16	30	7V Biased	0.5138	0.5138	0
17	30	7V Biased	0.5075	0.5075	0
18	30	7V Biased	0.5084	0.5084	0
19	30	7V Biased	0.505	0.5046	-0.0004
20	30	7V Biased	0.5173	0.517	-0.0003
21	50	Unbiased	0.5189	0.5201	0.0012
22	50	Unbiased	0.5084	0.5125	0.0041
23	50	Unbiased	0.511	0.5122	0.0012
24	50	Unbiased	0.5122	0.5135	0.0013
25	50	Unbiased	0.511	0.5106	-0.0004
26	50	7V Biased	0.5148	0.5094	-0.0054
27	50	7V Biased	0.5084	0.5065	-0.0019
28	50	7V Biased	0.5078	0.5043	-0.0035
29	50	7V Biased	0.5053	0.5018	-0.0035
30	50	7V Biased	0.5185	0.5166	-0.0019
31	0	Correlation	0.5034	0.5031	-0.0003
32	0	Correlation	0.5125	0.5122	-0.0003
33	0	Correlation	0.5091	0.5087	-0.0004
34	0	Correlation	0.5034	0.5031	-0.0003
35	0	Correlation	0.5091	0.5091	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5034	0.5075	0.5125	0.0039919	0.5031	0.50724	0.5122	0.0040147	-0.0004	-0.00026	0	0.00015166
20	0.5065	0.5132	0.5179	0.0036423	0.5065	0.51329	0.5185	0.0039776	-0.0019	9e-05	0.0012	0.00093029
30	0.505	0.51222	0.5182	0.004888	0.5046	0.5119	0.5182	0.0050616	-0.0022	-0.00032	0.0003	0.0006941
50	0.5053	0.51163	0.5189	0.0045561	0.5018	0.51075	0.5201	0.0055376	-0.0054	-0.00088	0.0041	0.0028805

Device Test: 6.10 EN_HYST(EN_UVLO_HYSTERESIS_3p3V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

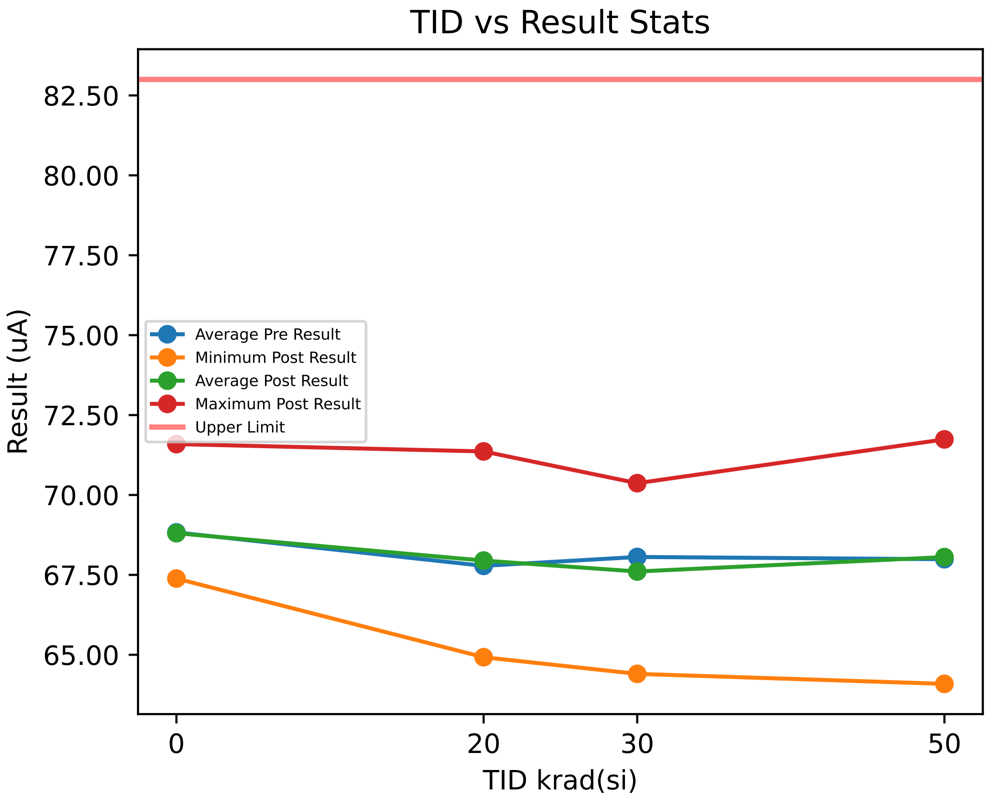
Test Results (Upper Limit = 124.0 (mV))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	107.81	107.49	-0.316
2	20	Unbiased	107.01	107.47	0.465
3	20	Unbiased	107.99	107.71	-0.279
4	20	Unbiased	107.88	107.64	-0.241
5	20	Unbiased	105.43	105.78	0.353
6	20	7V Biased	107.38	107.27	-0.112
7	20	7V Biased	107.66	107.31	-0.353
8	20	7V Biased	107.16	106.99	-0.167
9	20	7V Biased	106.19	105.83	-0.354
10	20	7V Biased	106.89	106.36	-0.54
11	30	Unbiased	105.54	105.35	-0.186
12	30	Unbiased	106.63	106.28	-0.353
13	30	Unbiased	108.42	108.03	-0.391
14	30	Unbiased	108.66	108.74	0.075
15	30	Unbiased	107.96	107.21	-0.744
16	30	7V Biased	107.47	107.16	-0.316
17	30	7V Biased	105.85	105.54	-0.317
18	30	7V Biased	105.85	106.24	0.389
19	30	7V Biased	105.02	105.69	0.669
20	30	7V Biased	108.62	108.27	-0.353
21	50	Unbiased	108.33	108.55	0.223
22	50	Unbiased	107.12	107.32	0.205
23	50	Unbiased	106.97	106.77	-0.204
24	50	Unbiased	107.21	107.08	-0.131
25	50	Unbiased	106.47	106.15	-0.316
26	50	7V Biased	108.12	106.86	-1.265
27	50	7V Biased	105.43	104.89	-0.541
28	50	7V Biased	105.24	104.87	-0.372
29	50	7V Biased	105.87	104.79	-1.079
30	50	7V Biased	107.84	107.42	-0.428
31	0	Correlation	104.09	104.72	0.632
32	0	Correlation	106.69	107.01	0.316
33	0	Correlation	106.75	106.75	0
34	0	Correlation	105.54	105.81	0.278
35	0	Correlation	106.36	106.63	0.279

Test Statistics (mV)

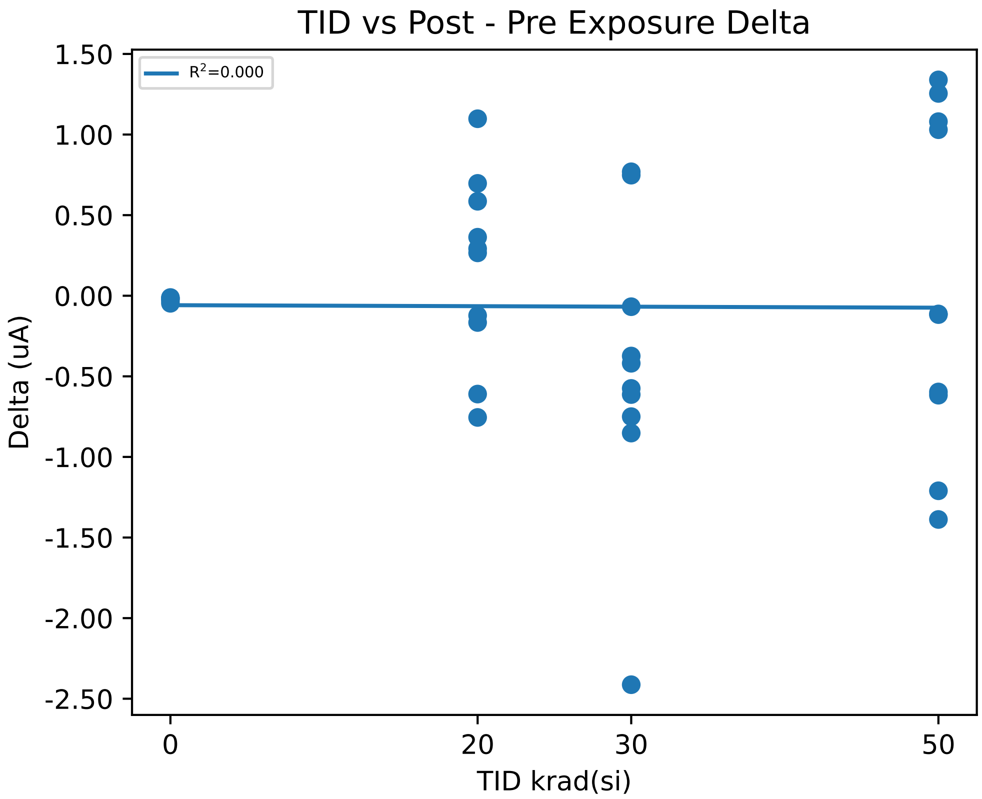
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	104.09	105.88	106.75	1.1146	104.72	106.18	107.01	0.93287	0	0.301	0.632	0.22439
20	105.43	107.14	107.99	0.81439	105.78	106.98	107.71	0.73119	-0.54	-0.1544	0.465	0.31975
30	105.02	107	108.66	1.3903	105.35	106.85	108.74	1.212	-0.744	-0.1527	0.669	0.41659
50	105.24	106.86	108.33	1.0922	104.79	106.47	108.55	1.272	-1.265	-0.3908	0.223	0.48326

Device Test: 6.11 SS_I_Charge(SS_Icharge_3p3V)



Test Results (Upper Limit = 83.0 (uA))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	64.822	65.92	1.098
2	20	Unbiased	70.999	71.362	0.363
3	20	Unbiased	69.788	70.054	0.266
4	20	Unbiased	67.266	67.143	-0.123
5	20	Unbiased	68.772	68.606	-0.166
6	20	7V Biased	68.177	68.763	0.586
7	20	7V Biased	66.759	67.456	0.697
8	20	7V Biased	65.679	64.924	-0.755
9	20	7V Biased	66.941	67.233	0.292
10	20	7V Biased	68.622	68.012	-0.61
11	30	Unbiased	69.6	70.369	0.769
12	30	Unbiased	68.132	67.382	-0.75
13	30	Unbiased	66.289	67.037	0.748
14	30	Unbiased	67.329	66.91	-0.419
15	30	Unbiased	69.886	69.273	-0.613
16	30	7V Biased	64.471	64.403	-0.068
17	30	7V Biased	69.729	67.316	-2.413
18	30	7V Biased	68.66	68.286	-0.374
19	30	7V Biased	68.773	67.921	-0.852
20	30	7V Biased	67.732	67.157	-0.575
21	50	Unbiased	68.048	67.931	-0.117
22	50	Unbiased	65.478	64.09	-1.388
23	50	Unbiased	70.709	71.739	1.03
24	50	Unbiased	68.616	69.955	1.339
25	50	Unbiased	64.735	65.99	1.255
26	50	7V Biased	65.82	66.9	1.08
27	50	7V Biased	67.178	67.065	-0.113
28	50	7V Biased	69.724	69.107	-0.617
29	50	7V Biased	69.569	68.972	-0.597
30	50	7V Biased	70.027	68.817	-1.21
31	0	Correlation	71.609	71.592	-0.017
32	0	Correlation	67.433	67.386	-0.047
33	0	Correlation	68.392	68.381	-0.011
34	0	Correlation	68.318	68.288	-0.03
35	0	Correlation	68.391	68.373	-0.018

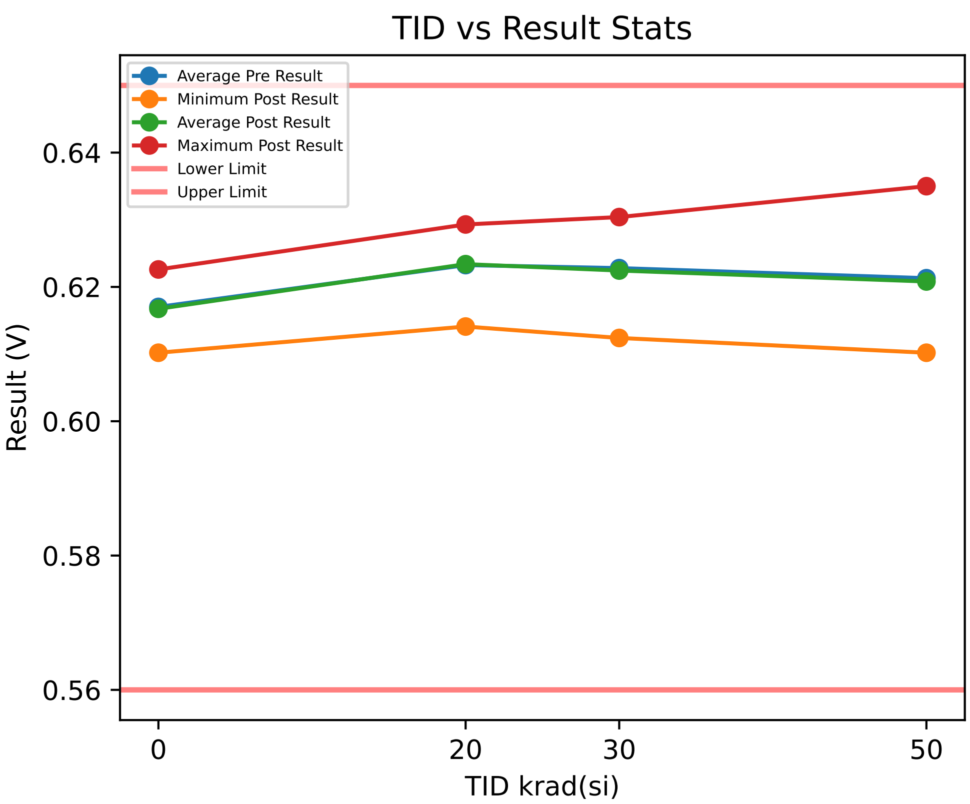


Test Statistics (uA)

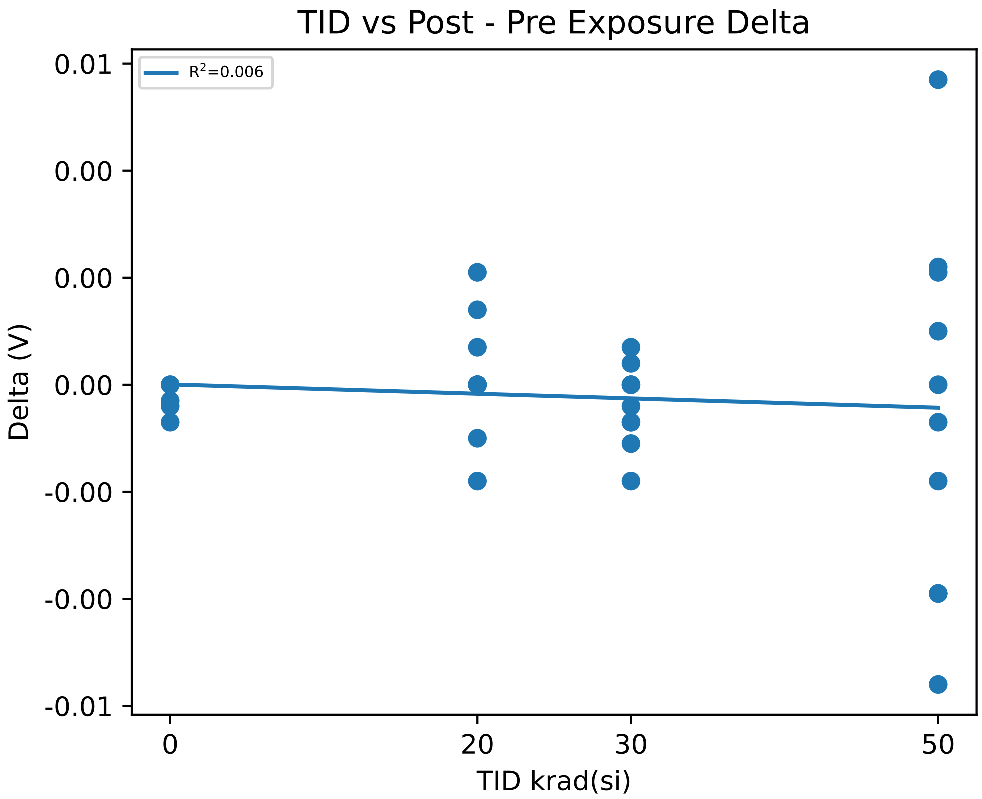
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	67.433	68.829	71.609	1.6063	67.386	68.804	71.592	1.6136	-0.047	-0.0246	-0.011	0.014293
20	64.822	67.782	70.999	1.8684	64.924	67.947	71.362	1.8812	-0.755	0.1648	1.098	0.58079
30	64.471	68.06	69.886	1.7005	64.403	67.605	70.369	1.5768	-2.413	-0.4547	0.769	0.89572
50	64.735	67.99	70.709	2.1006	64.09	68.057	71.739	2.1609	-1.388	0.0662	1.339	1.0385

Device Test: 6.12 EN_VTH_RISING(EN_UVLO_RISING_5V)

TID vs Result Stats



TID vs Post - Pre Exposure Delta



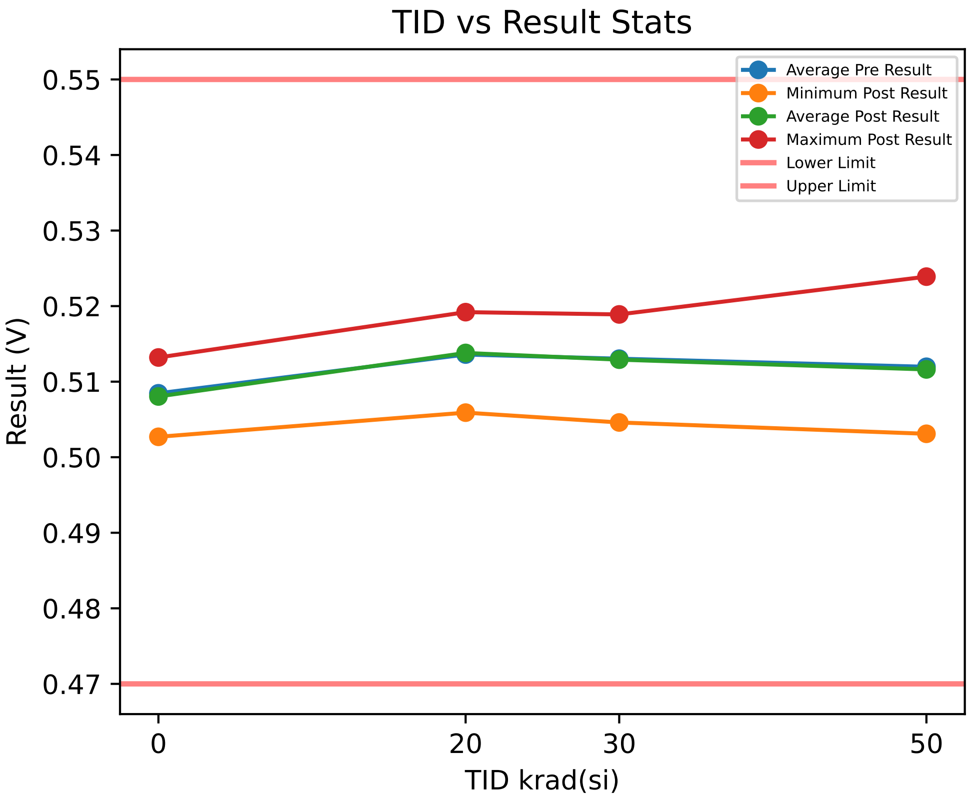
Test Results (Lower Limit = 0.56, Upper Limit = 0.65 (V))

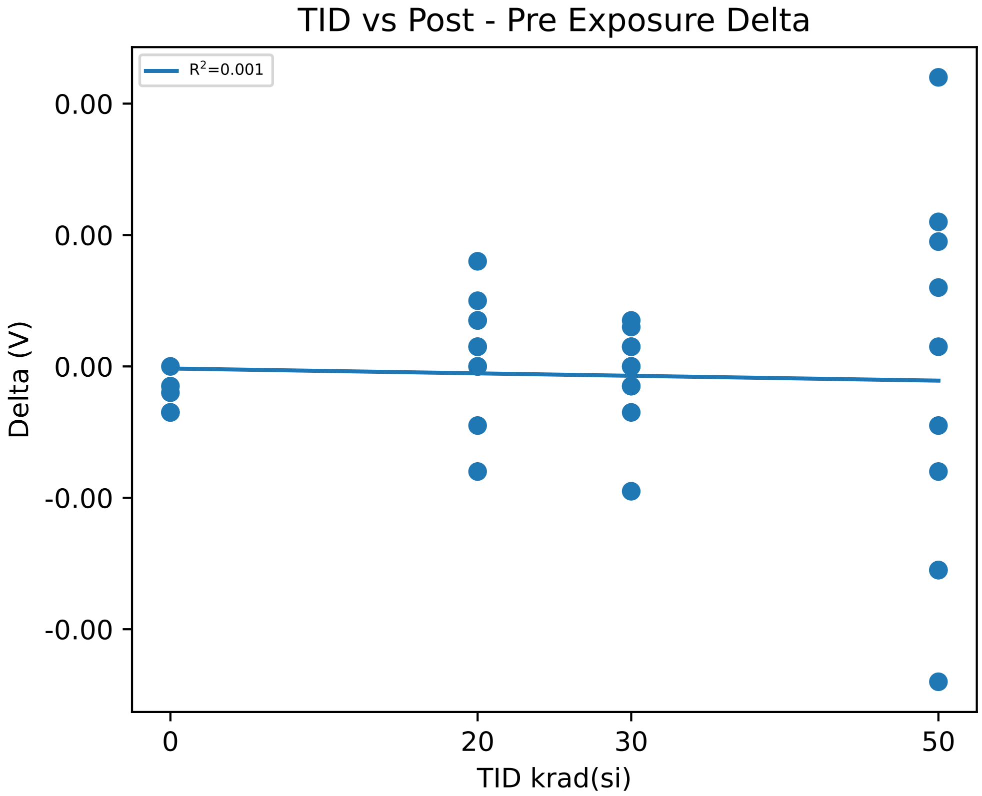
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.6265	0.6265	0
2	20	Unbiased	0.6216	0.623	0.0014
3	20	Unbiased	0.6293	0.6293	0
4	20	Unbiased	0.6269	0.6276	0.0007
5	20	Unbiased	0.6166	0.6166	0
6	20	7V Biased	0.6261	0.6251	-0.001
7	20	7V Biased	0.6258	0.6258	0
8	20	7V Biased	0.624	0.6261	0.0021
9	20	7V Biased	0.6141	0.6141	0
10	20	7V Biased	0.6216	0.6198	-0.0018
11	30	Unbiased	0.6184	0.6166	-0.0018
12	30	Unbiased	0.6187	0.6187	0
13	30	Unbiased	0.6304	0.6293	-0.0011
14	30	Unbiased	0.6297	0.6304	0.0007
15	30	Unbiased	0.629	0.6283	-0.0007
16	30	7V Biased	0.6233	0.6237	0.0004
17	30	7V Biased	0.6184	0.6184	0
18	30	7V Biased	0.6184	0.618	-0.0004
19	30	7V Biased	0.6131	0.6124	-0.0007
20	30	7V Biased	0.6286	0.6286	0
21	50	Unbiased	0.6329	0.635	0.0021
22	50	Unbiased	0.6166	0.6223	0.0057
23	50	Unbiased	0.6223	0.6233	0.001
24	50	Unbiased	0.6208	0.623	0.0022
25	50	Unbiased	0.6208	0.6208	0
26	50	7V Biased	0.6279	0.6223	-0.0056
27	50	7V Biased	0.6163	0.6145	-0.0018
28	50	7V Biased	0.6141	0.6102	-0.0039
29	50	7V Biased	0.6152	0.6113	-0.0039
30	50	7V Biased	0.6261	0.6254	-0.0007
31	0	Correlation	0.6102	0.6102	0
32	0	Correlation	0.623	0.6226	-0.0004
33	0	Correlation	0.6205	0.6205	0
34	0	Correlation	0.6113	0.611	-0.0003
35	0	Correlation	0.6201	0.6194	-0.0007

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6102	0.61702	0.623	0.0058435	0.6102	0.61674	0.6226	0.0057287	-0.0007	-0.00028	0	0.00029496
20	0.6141	0.62325	0.6293	0.0048197	0.6141	0.62339	0.6293	0.0049872	-0.0018	0.00014	0.0021	0.0011007
30	0.6131	0.6228	0.6304	0.0062064	0.6124	0.62244	0.6304	0.0064051	-0.0018	-0.00036	0.0007	0.00074117
50	0.6141	0.6213	0.6329	0.0061355	0.6102	0.62081	0.635	0.0073082	-0.0056	-0.00049	0.0057	0.0034294

Device Test: 6.13 EN_VTH_FALLING(EN_UVLO_FALLING_5V)





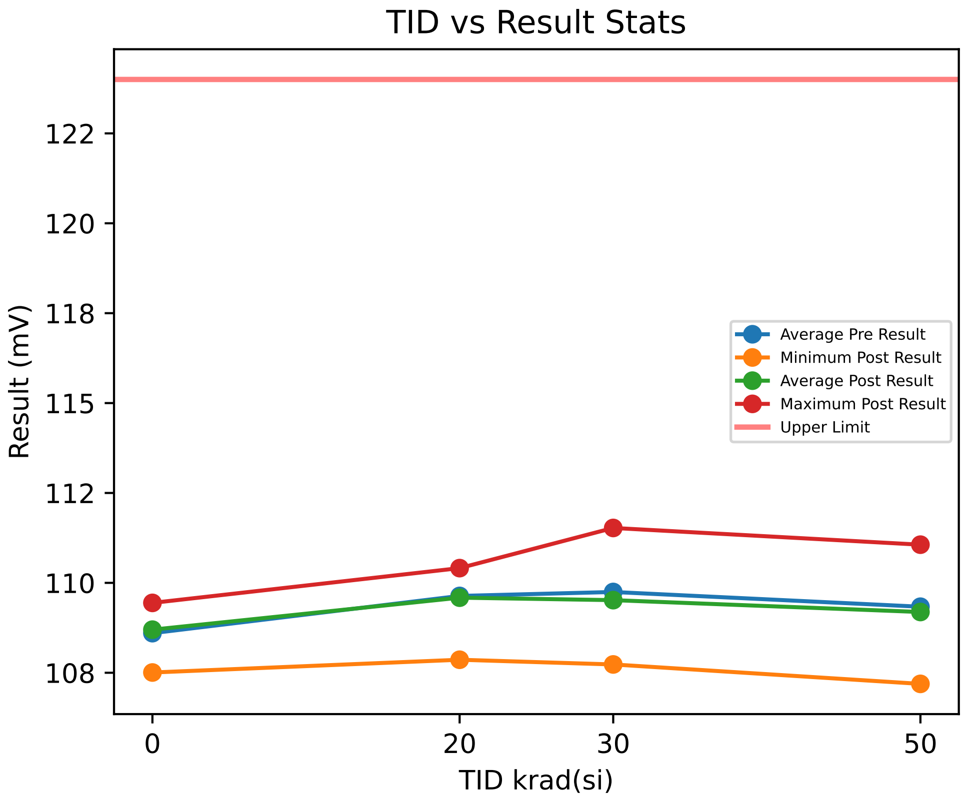
Test Results (Lower Limit = 0.47, Upper Limit = 0.55 (V))

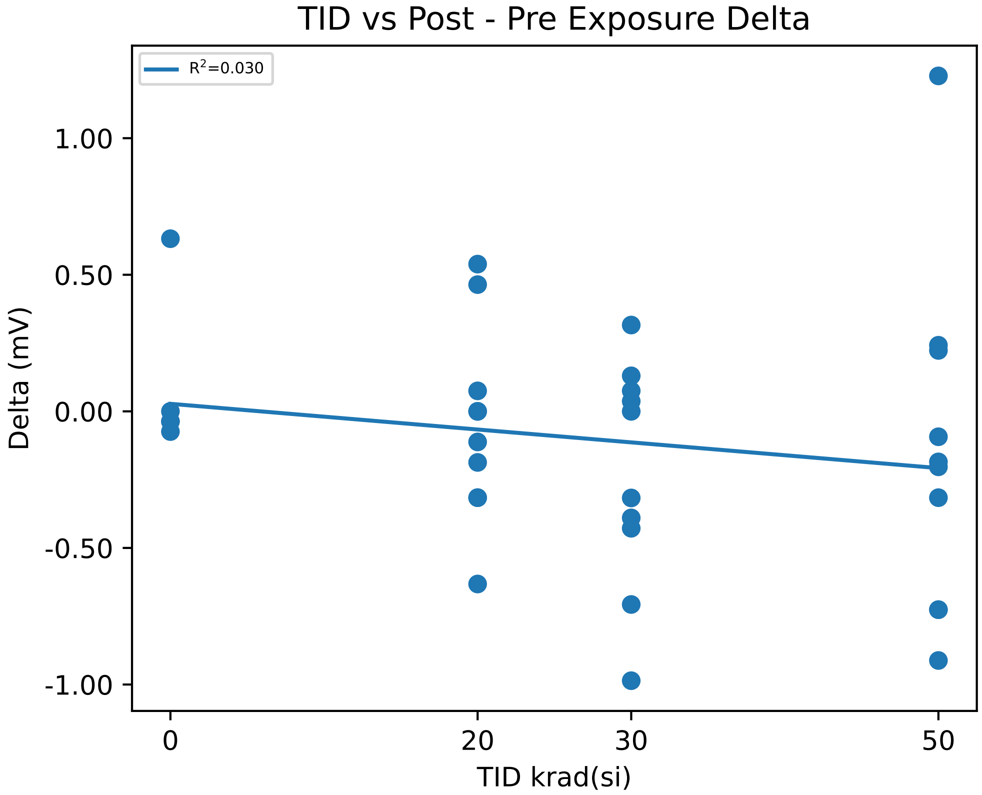
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.5163	0.5166	0.0003
2	20	Unbiased	0.5122	0.5132	0.001
3	20	Unbiased	0.5185	0.5192	0.0007
4	20	Unbiased	0.5166	0.5173	0.0007
5	20	Unbiased	0.5084	0.5087	0.0003
6	20	7V Biased	0.5163	0.5154	-0.0009
7	20	7V Biased	0.5154	0.5154	0
8	20	7V Biased	0.5144	0.516	0.0016
9	20	7V Biased	0.5059	0.5059	0
10	20	7V Biased	0.5119	0.5103	-0.0016
11	30	Unbiased	0.51	0.5081	-0.0019
12	30	Unbiased	0.5097	0.5097	0
13	30	Unbiased	0.5192	0.5185	-0.0007
14	30	Unbiased	0.5182	0.5189	0.0007
15	30	Unbiased	0.5185	0.5182	-0.0003
16	30	7V Biased	0.5138	0.5141	0.0003
17	30	7V Biased	0.5097	0.51	0.0003
18	30	7V Biased	0.5091	0.5097	0.0006
19	30	7V Biased	0.5046	0.5046	0
20	30	7V Biased	0.5176	0.5173	-0.0003
21	50	Unbiased	0.5217	0.5239	0.0022
22	50	Unbiased	0.5078	0.5122	0.0044
23	50	Unbiased	0.5129	0.5141	0.0012
24	50	Unbiased	0.5113	0.5132	0.0019
25	50	Unbiased	0.5116	0.5119	0.0003
26	50	7V Biased	0.517	0.5122	-0.0048
27	50	7V Biased	0.5084	0.5068	-0.0016
28	50	7V Biased	0.5062	0.5031	-0.0031
29	50	7V Biased	0.5065	0.5034	-0.0031
30	50	7V Biased	0.5163	0.5154	-0.0009
31	0	Correlation	0.5034	0.5027	-0.0007
32	0	Correlation	0.5135	0.5132	-0.0003
33	0	Correlation	0.5113	0.5113	0
34	0	Correlation	0.5031	0.5027	-0.0004
35	0	Correlation	0.511	0.5103	-0.0007

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5031	0.50846	0.5135	0.0048542	0.5027	0.50804	0.5132	0.0049848	-0.0007	-0.00042	0	0.00029496
20	0.5059	0.51359	0.5185	0.0039812	0.5059	0.5138	0.5192	0.0042195	-0.0016	0.00021	0.0016	0.00092189
30	0.5046	0.51304	0.5192	0.0050997	0.5046	0.51291	0.5189	0.0051323	-0.0019	-0.00013	0.0007	0.00075579
50	0.5062	0.51197	0.5217	0.0050938	0.5031	0.51162	0.5239	0.0061271	-0.0048	-0.00035	0.0044	0.0028625

Device Test: 6.14 EN_HYST(EN_UVLO_HYSTERESIS_5V)





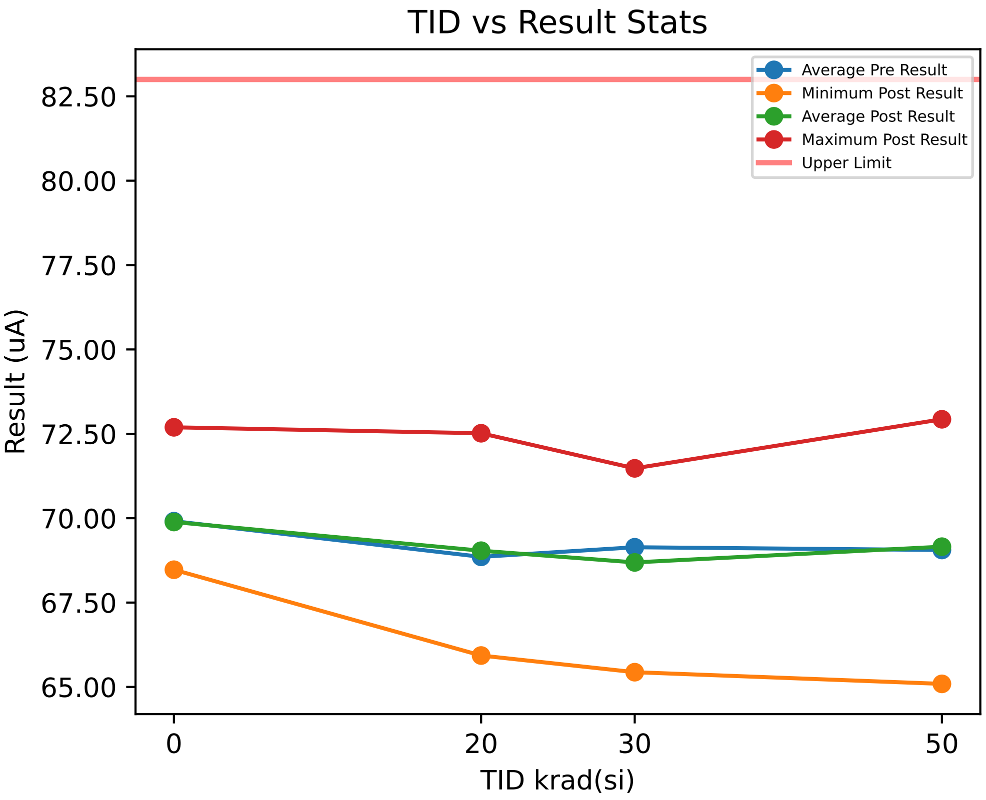
Test Results (Upper Limit = 124.0 (mV))

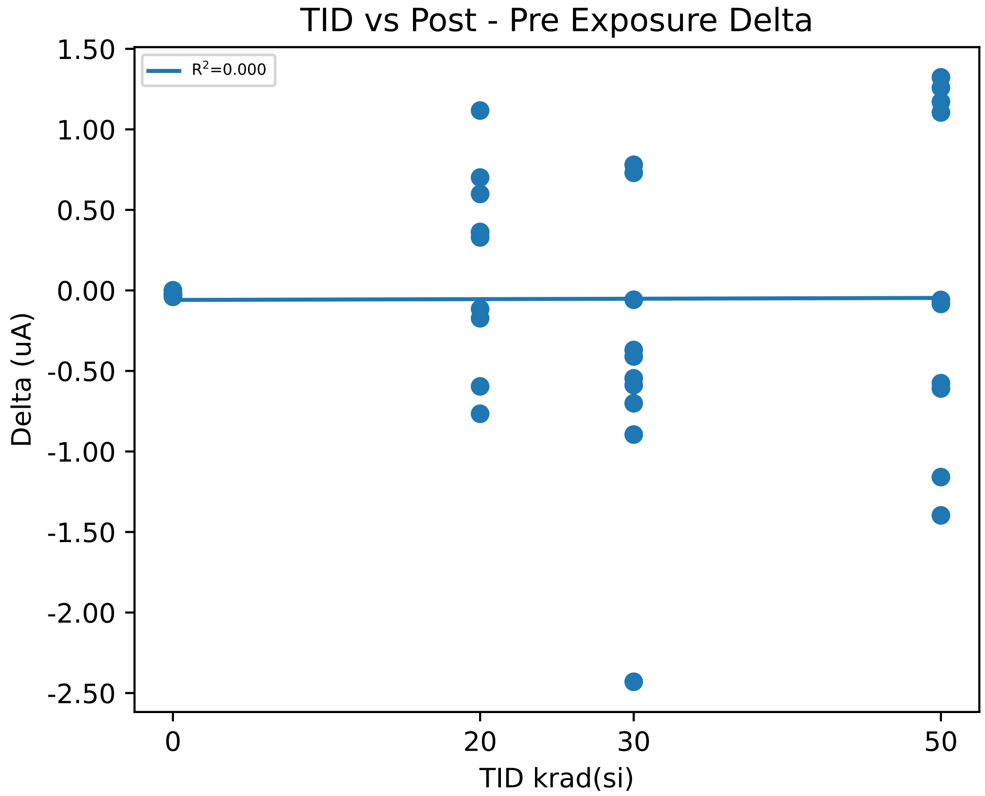
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	110.17	109.85	-0.316
2	20	Unbiased	109.33	109.8	0.464
3	20	Unbiased	110.78	110.15	-0.632
4	20	Unbiased	110.21	110.28	0.075
5	20	Unbiased	108.18	107.86	-0.316
6	20	7V Biased	109.81	109.7	-0.112
7	20	7V Biased	110.41	110.41	0
8	20	7V Biased	109.59	110.13	0.539
9	20	7V Biased	108.23	108.23	0
10	20	7V Biased	109.65	109.46	-0.187
11	30	Unbiased	108.36	108.49	0.13
12	30	Unbiased	109.03	109.03	0
13	30	Unbiased	111.21	110.78	-0.428
14	30	Unbiased	111.45	111.53	0.075
15	30	Unbiased	110.43	110.04	-0.39
16	30	7V Biased	109.52	109.56	0.037
17	30	7V Biased	108.68	108.36	-0.317
18	30	7V Biased	109.31	108.33	-0.986
19	30	7V Biased	108.44	107.73	-0.707
20	30	7V Biased	111.03	111.34	0.316
21	50	Unbiased	111.16	111.06	-0.093
22	50	Unbiased	108.81	110.04	1.228
23	50	Unbiased	109.41	109.2	-0.203
24	50	Unbiased	109.57	109.8	0.223
25	50	Unbiased	109.26	108.94	-0.316
26	50	7V Biased	110.95	110.04	-0.912
27	50	7V Biased	107.82	107.64	-0.185
28	50	7V Biased	107.92	107.19	-0.726
29	50	7V Biased	108.66	107.94	-0.726
30	50	7V Biased	109.81	110.06	0.242
31	0	Correlation	106.88	107.51	0.632
32	0	Correlation	109.48	109.44	-0.037
33	0	Correlation	109.22	109.22	0
34	0	Correlation	108.25	108.21	-0.037
35	0	Correlation	109.18	109.11	-0.074

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	106.88	108.6	109.48	1.0718	107.51	108.7	109.44	0.81369	-0.074	0.0968	0.632	0.30033
20	108.18	109.64	110.78	0.86566	107.86	109.59	110.41	0.86446	-0.632	-0.0485	0.539	0.35505
30	108.36	109.75	111.45	1.186	107.73	109.52	111.53	1.3523	-0.986	-0.227	0.316	0.41046
50	107.82	109.34	111.16	1.1177	107.19	109.19	111.06	1.2517	-0.912	-0.1468	1.228	0.62099

Device Test: 6.15 SS_I_Charge(SS_Icharge_5V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

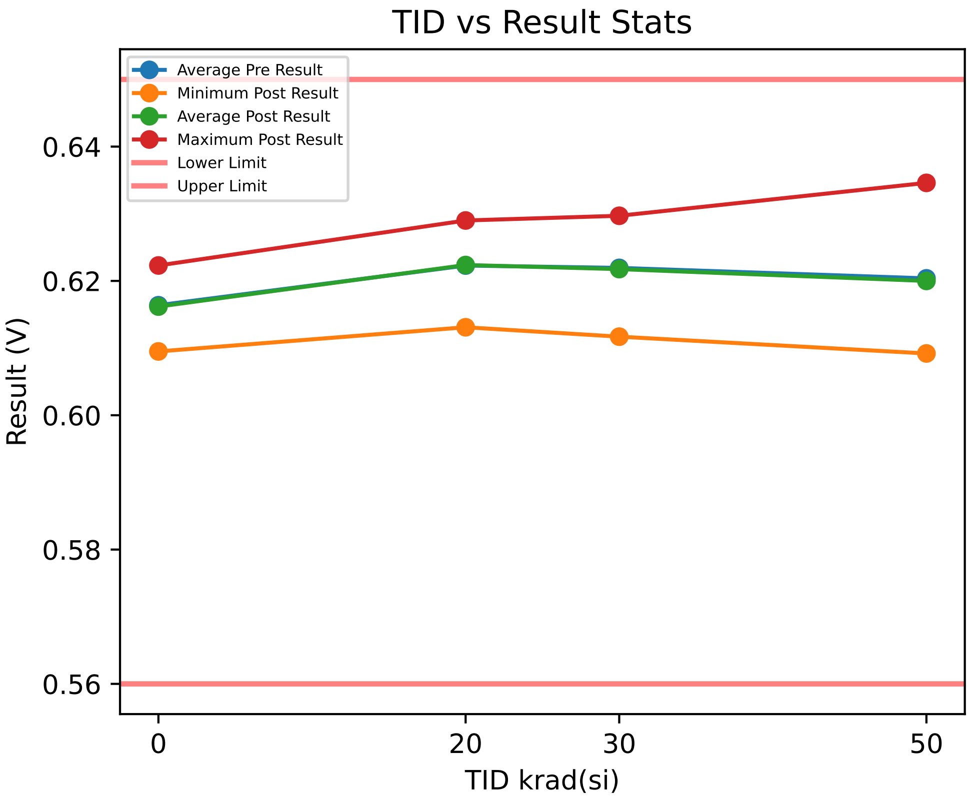
Test Results (Upper Limit = 83.0 (uA))

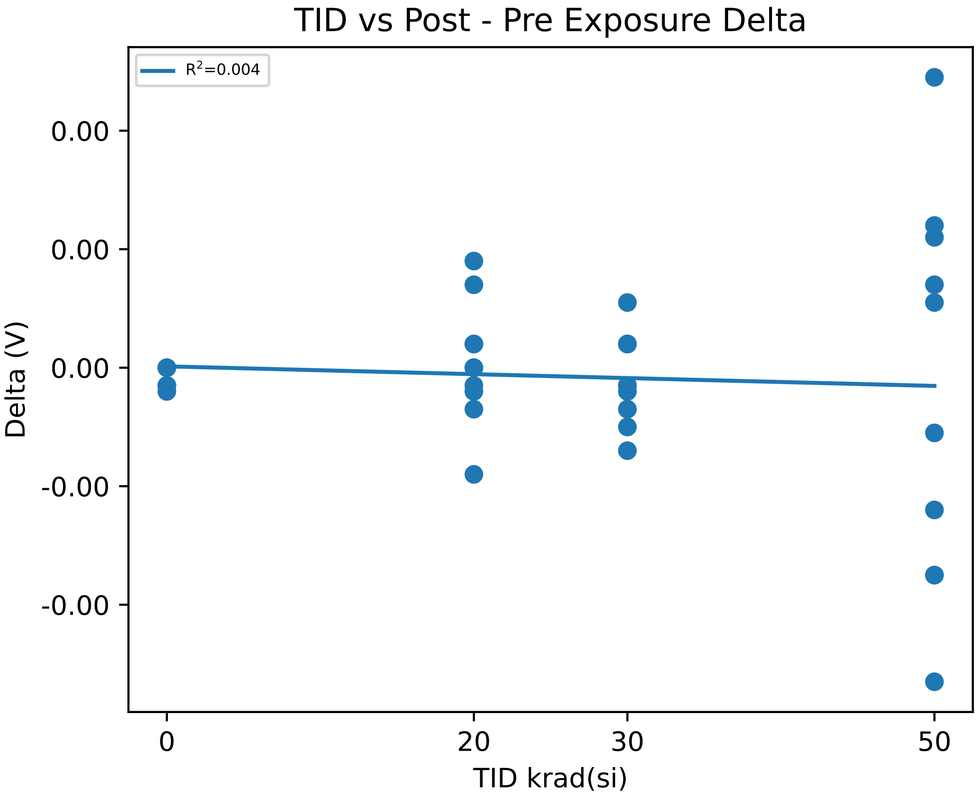
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	65.852	66.969	1.117
2	20	Unbiased	72.157	72.517	0.36
3	20	Unbiased	70.883	71.246	0.363
4	20	Unbiased	68.342	68.227	-0.115
5	20	Unbiased	69.858	69.685	-0.173
6	20	7V Biased	69.238	69.837	0.599
7	20	7V Biased	67.837	68.538	0.701
8	20	7V Biased	66.697	65.931	-0.766
9	20	7V Biased	67.991	68.32	0.329
10	20	7V Biased	69.691	69.095	-0.596
11	30	Unbiased	70.697	71.477	0.78
12	30	Unbiased	69.216	68.515	-0.701
13	30	Unbiased	67.323	68.053	0.73
14	30	Unbiased	68.391	67.981	-0.41
15	30	Unbiased	70.97	70.424	-0.546
16	30	7V Biased	65.495	65.437	-0.058
17	30	7V Biased	70.838	68.408	-2.43
18	30	7V Biased	69.75	69.38	-0.37
19	30	7V Biased	69.865	68.97	-0.895
20	30	7V Biased	68.842	68.254	-0.588
21	50	Unbiased	69.103	69.019	-0.084
22	50	Unbiased	66.488	65.091	-1.397
23	50	Unbiased	71.826	72.931	1.105
24	50	Unbiased	69.711	71.034	1.323
25	50	Unbiased	65.754	67.012	1.258
26	50	7V Biased	66.84	68.011	1.171
27	50	7V Biased	68.248	68.189	-0.059
28	50	7V Biased	70.847	70.271	-0.576
29	50	7V Biased	70.668	70.059	-0.609
30	50	7V Biased	71.098	69.939	-1.159
31	0	Correlation	72.733	72.693	-0.04
32	0	Correlation	68.497	68.473	-0.024
33	0	Correlation	69.462	69.463	0.001
34	0	Correlation	69.402	69.366	-0.036
35	0	Correlation	69.465	69.441	-0.024

Test Statistics (uA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	68.497	69.912	72.733	1.6296	68.473	69.887	72.693	1.622	-0.04	-0.0246	0.001	0.015994
20	65.852	68.855	72.157	1.9029	65.931	69.037	72.517	1.9263	-0.766	0.1819	1.117	0.58895
30	65.495	69.139	70.97	1.7255	65.437	68.69	71.477	1.6028	-2.43	-0.4488	0.78	0.89917
50	65.754	69.058	71.826	2.1381	65.091	69.156	72.931	2.2069	-1.397	0.0973	1.323	1.0455

Device Test: 6.16 EN_VTH_RISING(EN_UVLO_RISING_7V)





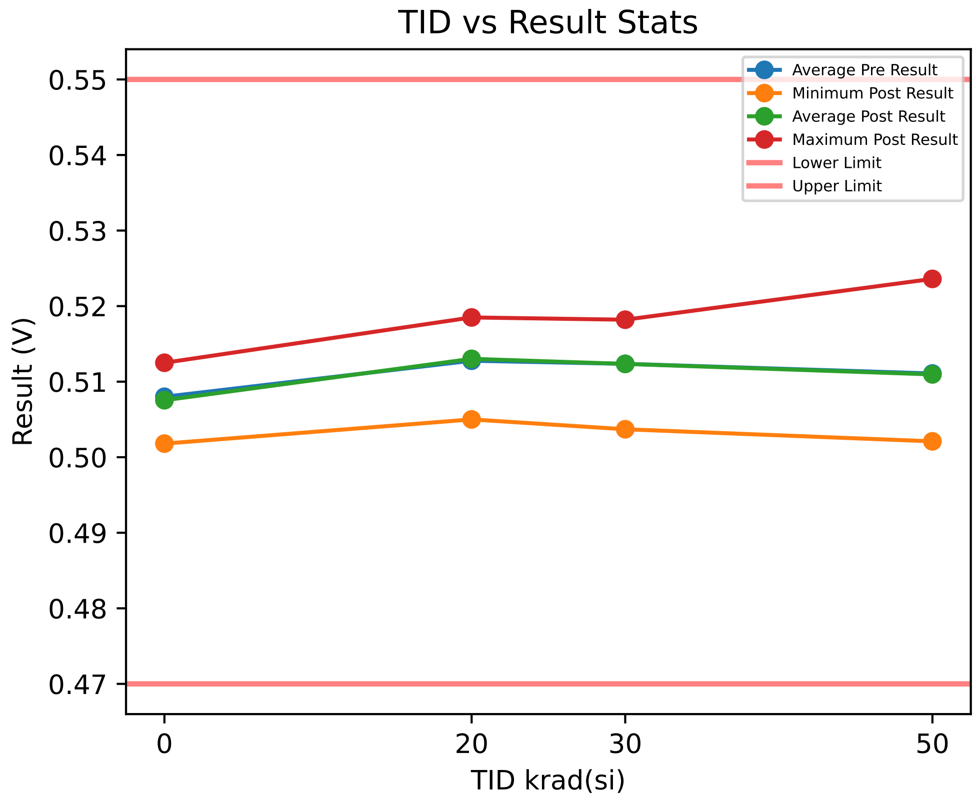
Test Results (Lower Limit = 0.56, Upper Limit = 0.65 (V))

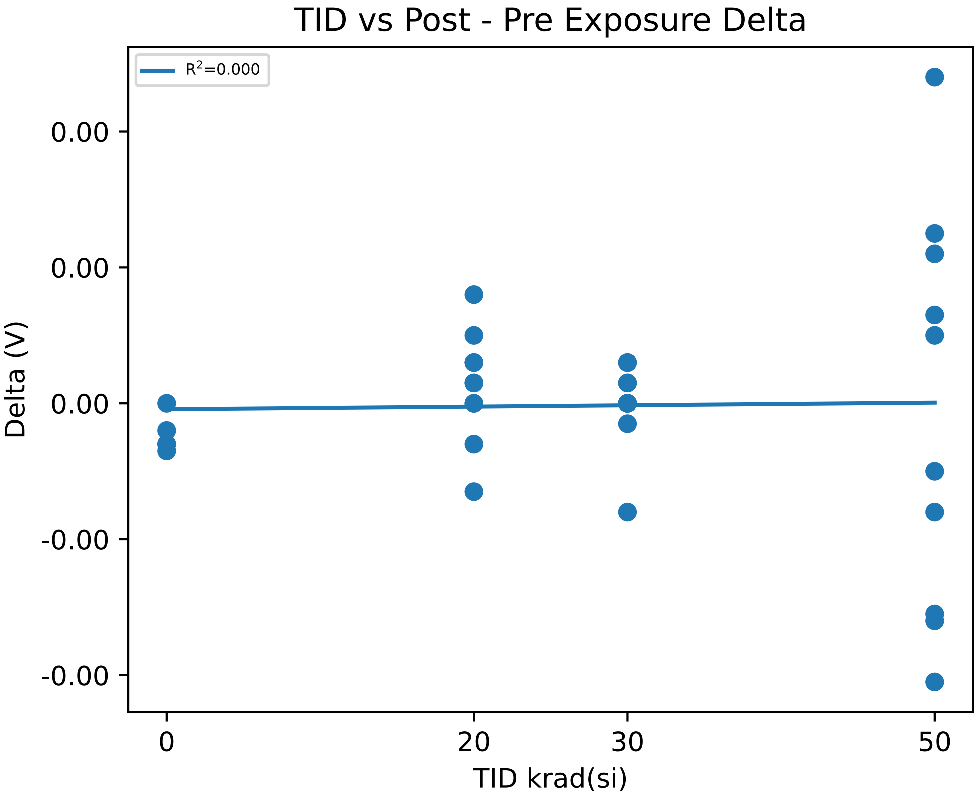
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.6254	0.6254	0
2	20	Unbiased	0.6194	0.6212	0.0018
3	20	Unbiased	0.6286	0.629	0.0004
4	20	Unbiased	0.6254	0.6258	0.0004
5	20	Unbiased	0.6163	0.6163	0
6	20	7V Biased	0.6251	0.6244	-0.0007
7	20	7V Biased	0.6251	0.6247	-0.0004
8	20	7V Biased	0.6237	0.6251	0.0014
9	20	7V Biased	0.6134	0.6131	-0.0003
10	20	7V Biased	0.6205	0.6187	-0.0018
11	30	Unbiased	0.6177	0.6163	-0.0014
12	30	Unbiased	0.618	0.6177	-0.0003
13	30	Unbiased	0.6293	0.6283	-0.001
14	30	Unbiased	0.6286	0.6297	0.0011
15	30	Unbiased	0.6283	0.6279	-0.0004
16	30	7V Biased	0.6226	0.623	0.0004
17	30	7V Biased	0.618	0.6184	0.0004
18	30	7V Biased	0.6177	0.617	-0.0007
19	30	7V Biased	0.6113	0.6117	0.0004
20	30	7V Biased	0.6279	0.6276	-0.0003
21	50	Unbiased	0.6322	0.6346	0.0024
22	50	Unbiased	0.6159	0.6208	0.0049
23	50	Unbiased	0.6212	0.6226	0.0014
24	50	Unbiased	0.6201	0.6223	0.0022
25	50	Unbiased	0.6194	0.6205	0.0011
26	50	7V Biased	0.6272	0.6219	-0.0053
27	50	7V Biased	0.6155	0.6131	-0.0024
28	50	7V Biased	0.6127	0.6092	-0.0035
29	50	7V Biased	0.6145	0.611	-0.0035
30	50	7V Biased	0.6251	0.624	-0.0011
31	0	Correlation	0.6099	0.6095	-0.0004
32	0	Correlation	0.6223	0.6223	0
33	0	Correlation	0.6201	0.6201	0
34	0	Correlation	0.6102	0.6099	-0.0003
35	0	Correlation	0.6194	0.6191	-0.0003

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6099	0.61638	0.6223	0.0058777	0.6095	0.61618	0.6223	0.0060293	-0.0004	-0.0002	0	0.00018708
20	0.6134	0.62229	0.6286	0.0047541	0.6131	0.62237	0.629	0.0049387	-0.0018	8e-05	0.0018	0.0010239
30	0.6113	0.62194	0.6293	0.0062818	0.6117	0.62176	0.6297	0.0063299	-0.0014	-0.00018	0.0011	0.00075689
50	0.6127	0.62038	0.6322	0.0062152	0.6092	0.62	0.6346	0.0073859	-0.0053	-0.00038	0.0049	0.0032642

Device Test: 6.17 EN_VTH_FALLING(EN_UVLO_FALLING_7V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

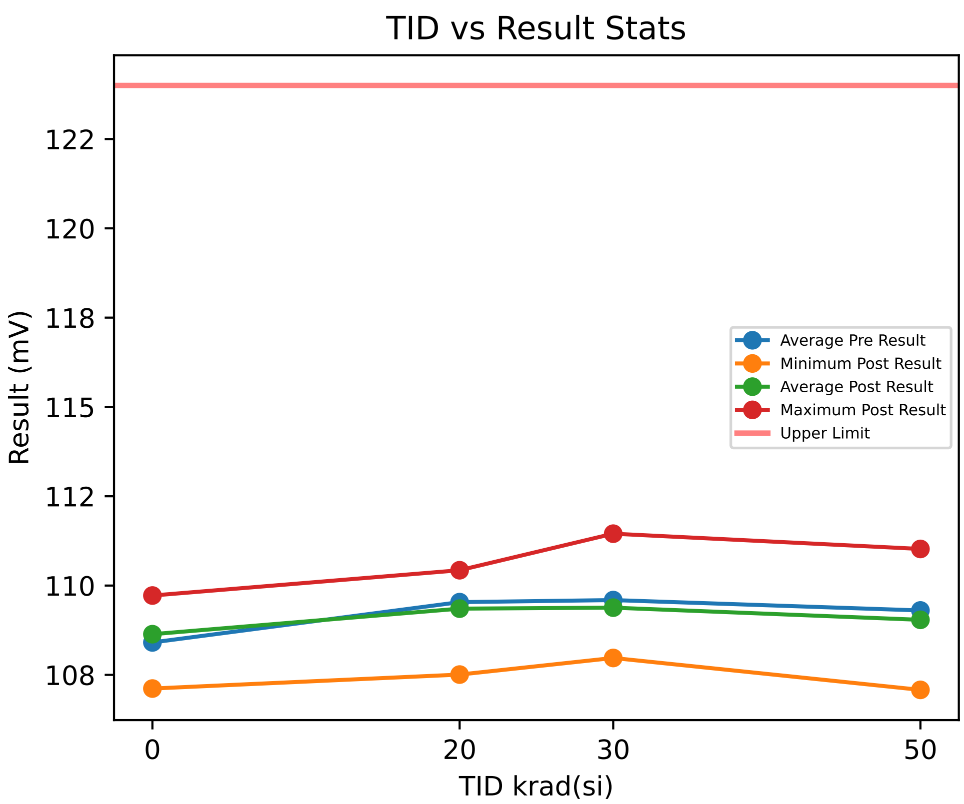
Test Results (Lower Limit = 0.47, Upper Limit = 0.55 (V))

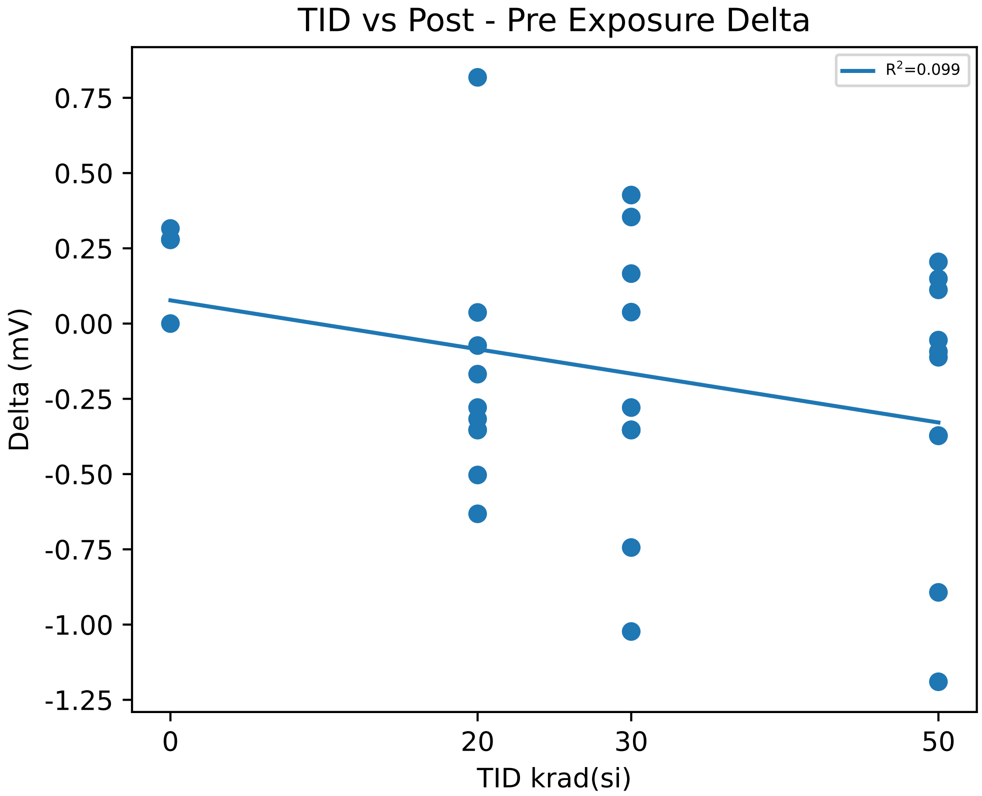
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.5151	0.5154	0.0003
2	20	Unbiased	0.5106	0.5116	0.001
3	20	Unbiased	0.5182	0.5185	0.0003
4	20	Unbiased	0.5154	0.516	0.0006
5	20	Unbiased	0.5081	0.5087	0.0006
6	20	7V Biased	0.5154	0.5148	-0.0006
7	20	7V Biased	0.5148	0.5148	0
8	20	7V Biased	0.5138	0.5154	0.0016
9	20	7V Biased	0.505	0.505	0
10	20	7V Biased	0.5113	0.51	-0.0013
11	30	Unbiased	0.5094	0.5078	-0.0016
12	30	Unbiased	0.5091	0.5091	0
13	30	Unbiased	0.5182	0.5179	-0.0003
14	30	Unbiased	0.5176	0.5182	0.0006
15	30	Unbiased	0.5179	0.5179	0
16	30	7V Biased	0.5129	0.5135	0.0006
17	30	7V Biased	0.5094	0.5097	0.0003
18	30	7V Biased	0.5084	0.5087	0.0003
19	30	7V Biased	0.5037	0.5037	0
20	30	7V Biased	0.517	0.517	0
21	50	Unbiased	0.5211	0.5236	0.0025
22	50	Unbiased	0.5065	0.5113	0.0048
23	50	Unbiased	0.5119	0.5132	0.0013
24	50	Unbiased	0.5103	0.5125	0.0022
25	50	Unbiased	0.5106	0.5116	0.001
26	50	7V Biased	0.5163	0.5122	-0.0041
27	50	7V Biased	0.5075	0.5059	-0.0016
28	50	7V Biased	0.5053	0.5021	-0.0032
29	50	7V Biased	0.5062	0.5031	-0.0031
30	50	7V Biased	0.5151	0.5141	-0.001
31	0	Correlation	0.5031	0.5024	-0.0007
32	0	Correlation	0.5129	0.5125	-0.0004
33	0	Correlation	0.511	0.511	0
34	0	Correlation	0.5024	0.5018	-0.0006
35	0	Correlation	0.5106	0.51	-0.0006

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5024	0.508	0.5129	0.004877	0.5018	0.50754	0.5125	0.0050496	-0.0007	-0.00046	0	0.00027928
20	0.505	0.51277	0.5182	0.0039858	0.505	0.51302	0.5185	0.0040919	-0.0013	0.00025	0.0016	0.00080863
30	0.5037	0.51236	0.5182	0.0050871	0.5037	0.51235	0.5182	0.0052197	-0.0016	-1e-05	0.0006	0.00062796
50	0.5053	0.51108	0.5211	0.0051244	0.5021	0.51096	0.5236	0.0061911	-0.0041	-0.00012	0.0048	0.002923

Device Test: 6.18 EN_HYST(EN_UVLO_HYSTERESIS_7V)





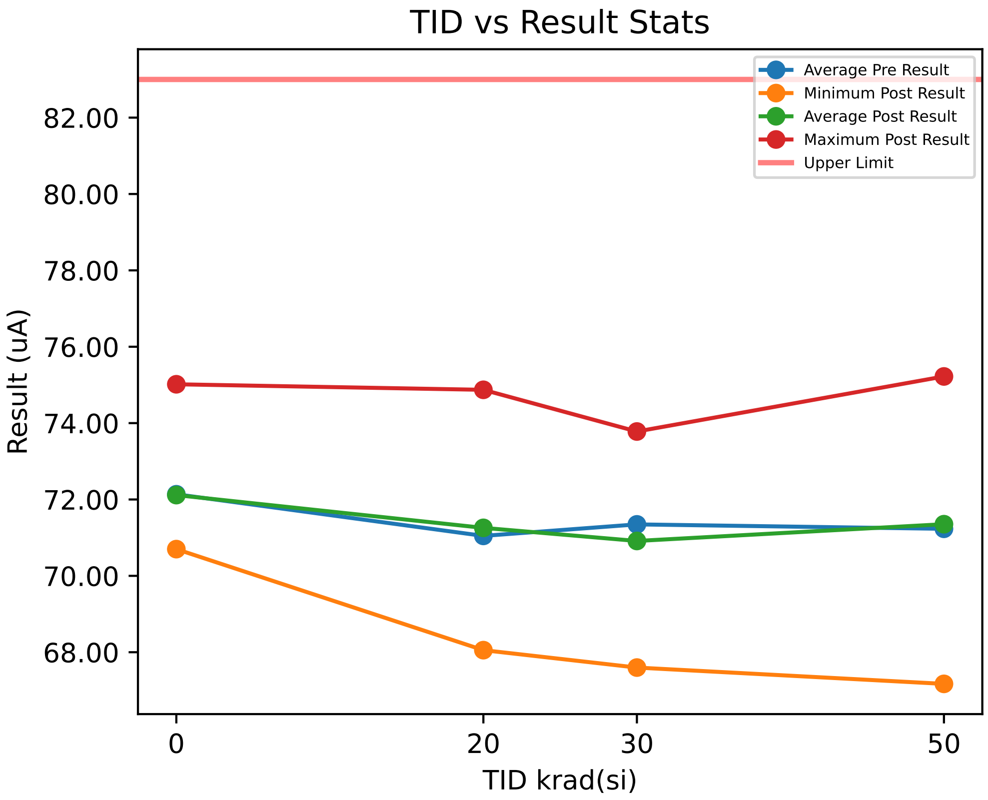
Test Results (Upper Limit = 124.0 (mV))

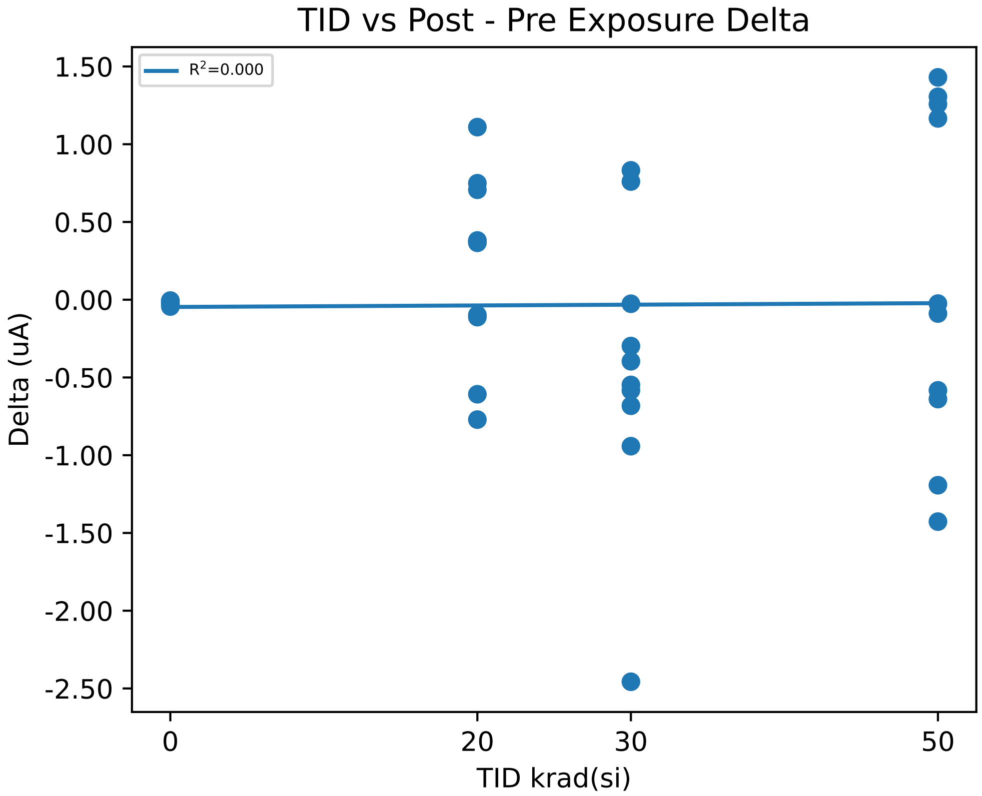
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	110.37	110.06	-0.317
2	20	Unbiased	108.79	109.61	0.818
3	20	Unbiased	110.39	110.43	0.037
4	20	Unbiased	110.06	109.78	-0.279
5	20	Unbiased	108.14	107.51	-0.632
6	20	7V Biased	109.7	109.63	-0.073
7	20	7V Biased	110.34	109.98	-0.353
8	20	7V Biased	109.87	109.7	-0.168
9	20	7V Biased	108.47	108.12	-0.354
10	20	7V Biased	109.22	108.72	-0.503
11	30	Unbiased	108.29	108.46	0.166
12	30	Unbiased	108.96	108.61	-0.353
13	30	Unbiased	111.1	110.36	-0.744
14	30	Unbiased	111.03	111.45	0.427
15	30	Unbiased	110.36	110	-0.354
16	30	7V Biased	109.76	109.48	-0.279
17	30	7V Biased	108.64	108.68	0.038
18	30	7V Biased	109.24	108.22	-1.023
19	30	7V Biased	107.62	107.97	0.354
20	30	7V Biased	110.95	110.6	-0.353
21	50	Unbiased	111.08	111.03	-0.055
22	50	Unbiased	109.37	109.57	0.205
23	50	Unbiased	109.29	109.44	0.149
24	50	Unbiased	109.81	109.72	-0.093
25	50	Unbiased	108.79	108.9	0.112
26	50	7V Biased	110.88	109.69	-1.19
27	50	7V Biased	108.07	107.17	-0.893
28	50	7V Biased	107.45	107.08	-0.372
29	50	7V Biased	108.27	107.9	-0.373
30	50	7V Biased	110.02	109.91	-0.112
31	0	Correlation	106.84	107.12	0.279
32	0	Correlation	109.41	109.72	0.316
33	0	Correlation	109.18	109.18	0
34	0	Correlation	107.82	108.1	0.28
35	0	Correlation	108.79	109.07	0.278

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	106.84	108.41	109.41	1.0663	107.12	108.64	109.72	1.0314	0	0.2306	0.316	0.1299
20	108.14	109.54	110.39	0.83096	107.51	109.35	110.43	0.93229	-0.632	-0.1824	0.818	0.40167
30	107.62	109.59	111.1	1.238	107.97	109.38	111.45	1.1737	-1.023	-0.2121	0.427	0.46419
50	107.45	109.3	111.08	1.1875	107.08	109.04	111.03	1.2767	-1.19	-0.2622	0.205	0.46002

Device Test: 6.19 SS_I_Charge(SS_Icharge_7V)





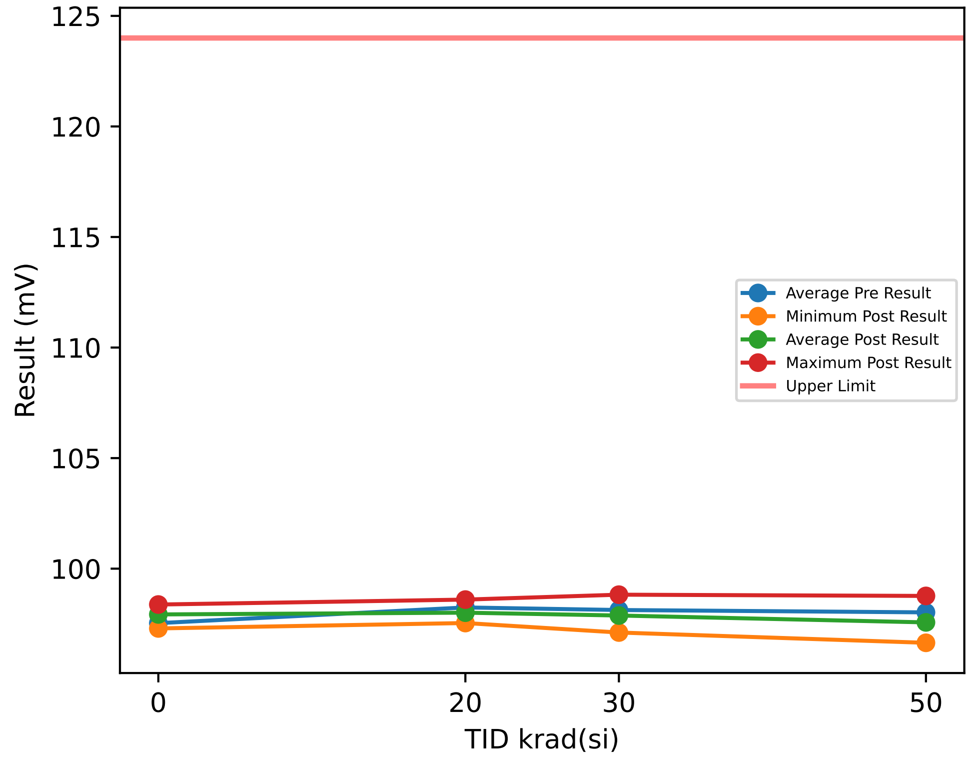
Test Results (Upper Limit = 83.0 (uA))

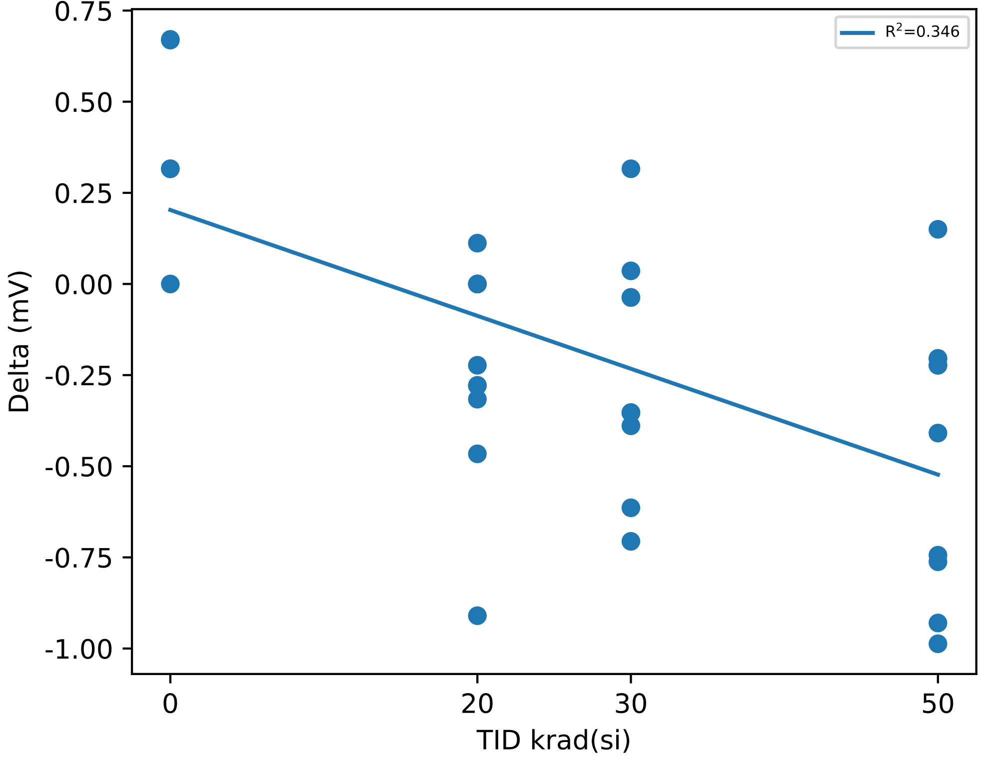
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	68.005	69.115	1.11
2	20	Unbiased	74.491	74.872	0.381
3	20	Unbiased	73.113	73.489	0.376
4	20	Unbiased	70.517	70.419	-0.098
5	20	Unbiased	72.027	71.915	-0.112
6	20	7V Biased	71.406	72.113	0.707
7	20	7V Biased	69.977	70.726	0.749
8	20	7V Biased	68.825	68.054	-0.771
9	20	7V Biased	70.127	70.493	0.366
10	20	7V Biased	71.978	71.37	-0.608
11	30	Unbiased	72.948	73.78	0.832
12	30	Unbiased	71.423	70.741	-0.682
13	30	Unbiased	69.543	70.303	0.76
14	30	Unbiased	70.619	70.223	-0.396
15	30	Unbiased	73.211	72.628	-0.583
16	30	7V Biased	67.624	67.598	-0.026
17	30	7V Biased	73.051	70.594	-2.457
18	30	7V Biased	71.904	71.606	-0.298
19	30	7V Biased	72.106	71.164	-0.942
20	30	7V Biased	71.047	70.499	-0.548
21	50	Unbiased	71.341	71.252	-0.089
22	50	Unbiased	68.598	67.171	-1.427
23	50	Unbiased	74.056	75.222	1.166
24	50	Unbiased	71.906	73.336	1.43
25	50	Unbiased	67.85	69.155	1.305
26	50	7V Biased	68.933	70.191	1.258
27	50	7V Biased	70.396	70.371	-0.025
28	50	7V Biased	73.056	72.417	-0.639
29	50	7V Biased	72.874	72.291	-0.583
30	50	7V Biased	73.313	72.12	-1.193
31	0	Correlation	75.023	75.017	-0.006
32	0	Correlation	70.744	70.7	-0.044
33	0	Correlation	71.643	71.637	-0.006
34	0	Correlation	71.585	71.56	-0.025
35	0	Correlation	71.687	71.661	-0.026

Test Statistics (uA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	70.744	72.136	75.023	1.6599	70.7	72.115	75.017	1.6708	-0.044	-0.0214	-0.006	0.015962
20	68.005	71.047	74.491	1.9593	68.054	71.257	74.872	1.9901	-0.771	0.21	1.11	0.60173
30	67.624	71.348	73.211	1.7502	67.598	70.914	73.78	1.6277	-2.457	-0.434	0.832	0.92268
50	67.85	71.232	74.056	2.1897	67.171	71.353	75.222	2.2644	-1.427	0.1203	1.43	1.0935

Device Test: 6.2 EN_HYST(EN_UVLO_HYSTERESIS_1p5V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

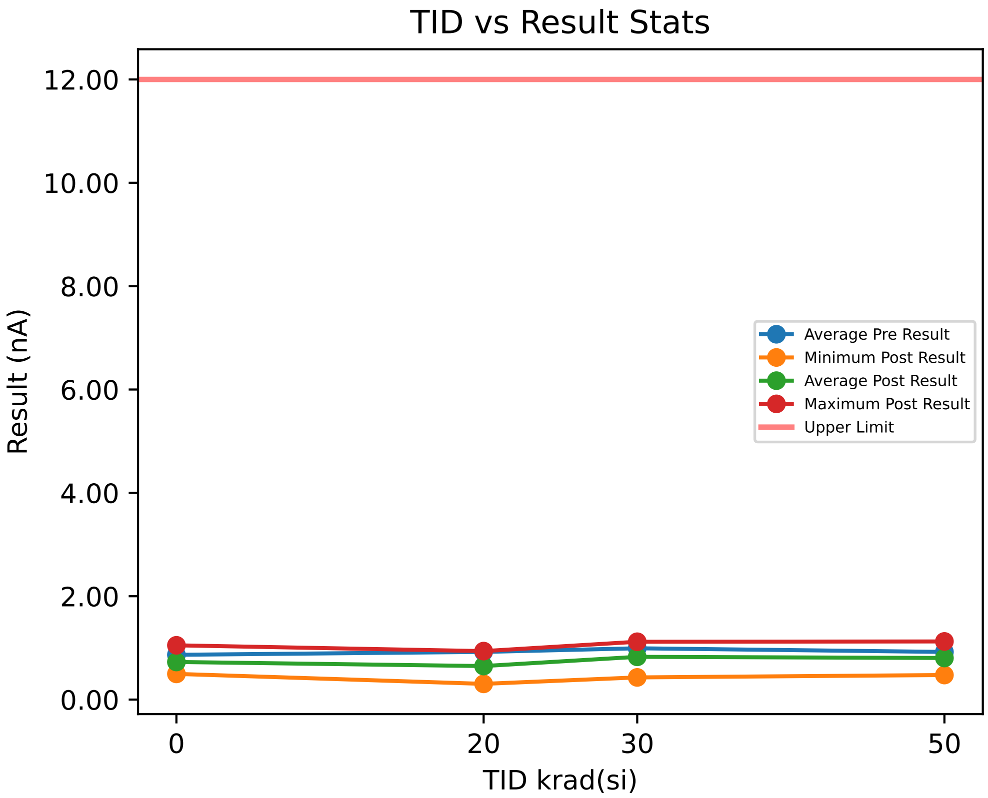
Test Results (Upper Limit = 124.0 (mV))

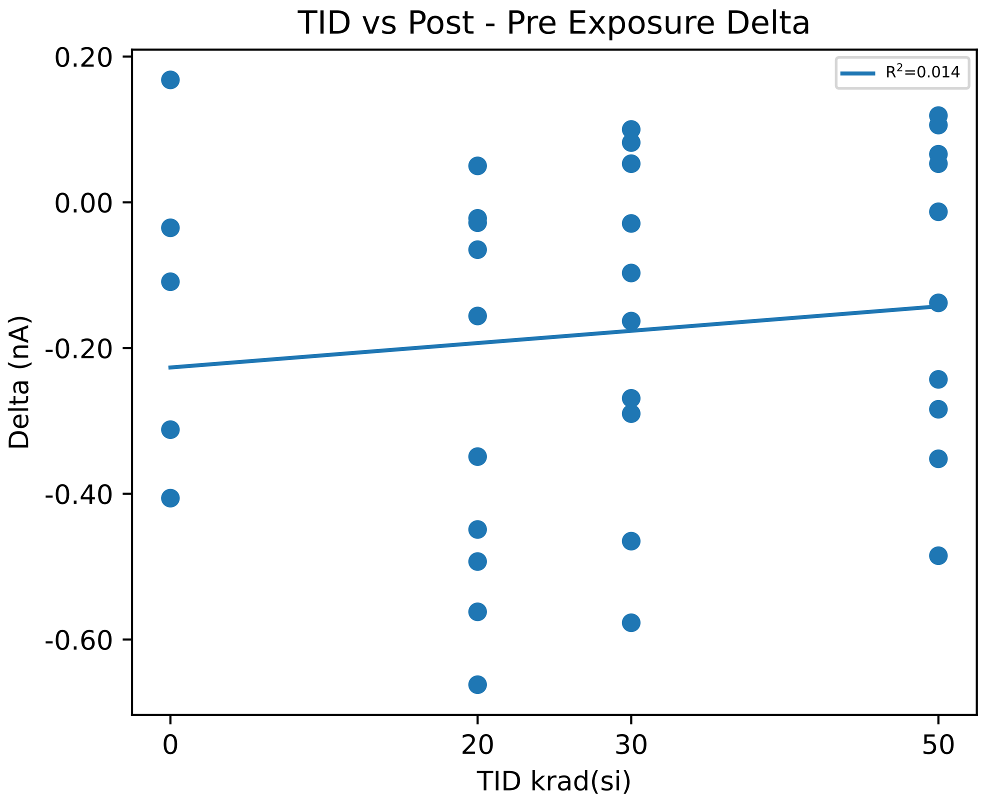
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	98.471	98.471	0
2	20	Unbiased	98.489	98.601	0.112
3	20	Unbiased	98.545	98.267	-0.278
4	20	Unbiased	97.987	97.708	-0.279
5	20	Unbiased	97.93	97.93	0
6	20	7V Biased	98.36	97.894	-0.466
7	20	7V Biased	98.285	97.969	-0.316
8	20	7V Biased	98.451	97.541	-0.91
9	20	7V Biased	97.707	97.707	0
10	20	7V Biased	98.228	98.005	-0.223
11	30	Unbiased	97.968	97.354	-0.614
12	30	Unbiased	98.787	98.823	0.036
13	30	Unbiased	98.731	98.378	-0.353
14	30	Unbiased	98.657	98.62	-0.037
15	30	Unbiased	97.764	97.727	-0.037
16	30	7V Biased	98.563	97.857	-0.706
17	30	7V Biased	97.465	97.112	-0.353
18	30	7V Biased	97.93	97.577	-0.353
19	30	7V Biased	97.52	97.131	-0.389
20	30	7V Biased	97.913	98.229	0.316
21	50	Unbiased	98.099	98.249	0.15
22	50	Unbiased	98.99	98.767	-0.223
23	50	Unbiased	98.228	98.024	-0.204
24	50	Unbiased	98.024	97.819	-0.205
25	50	Unbiased	97.875	97.131	-0.744
26	50	7V Biased	98.676	97.689	-0.987
27	50	7V Biased	96.87	96.647	-0.223
28	50	7V Biased	97.502	96.74	-0.762
29	50	7V Biased	97.558	97.149	-0.409
30	50	7V Biased	98.415	97.485	-0.93
31	0	Correlation	96.628	97.297	0.669
32	0	Correlation	97.707	98.378	0.671
33	0	Correlation	98.005	98.321	0.316
34	0	Correlation	97.688	98.004	0.316
35	0	Correlation	97.652	97.652	0

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	96.628	97.536	98.005	0.52684	97.297	97.93	98.378	0.45745	0	0.3944	0.671	0.28274
20	97.707	98.245	98.545	0.28154	97.541	98.009	98.601	0.34195	-0.91	-0.236	0.112	0.29917
30	97.465	98.13	98.787	0.50768	97.112	97.881	98.823	0.61009	-0.706	-0.249	0.316	0.31349
50	96.87	98.024	98.99	0.61481	96.647	97.57	98.767	0.67447	-0.987	-0.4537	0.15	0.37826

Device Test: 6.20 IEN_VIN_5V(EN_I_5V)





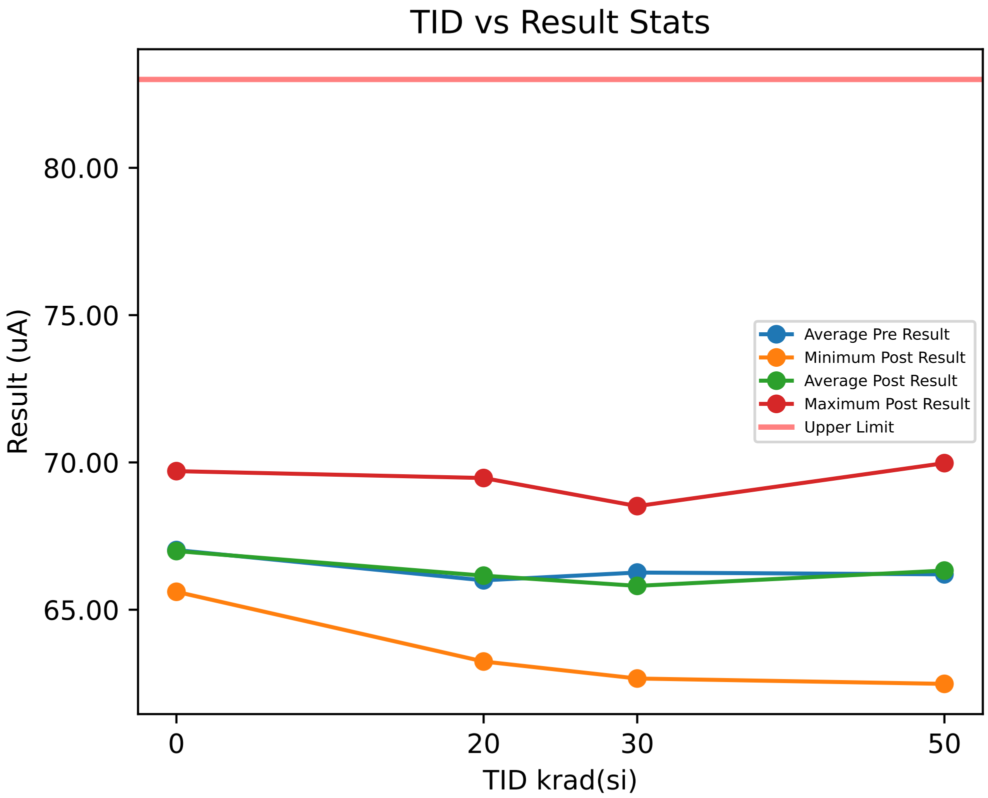
Test Results (Upper Limit = 12.0 (nA))

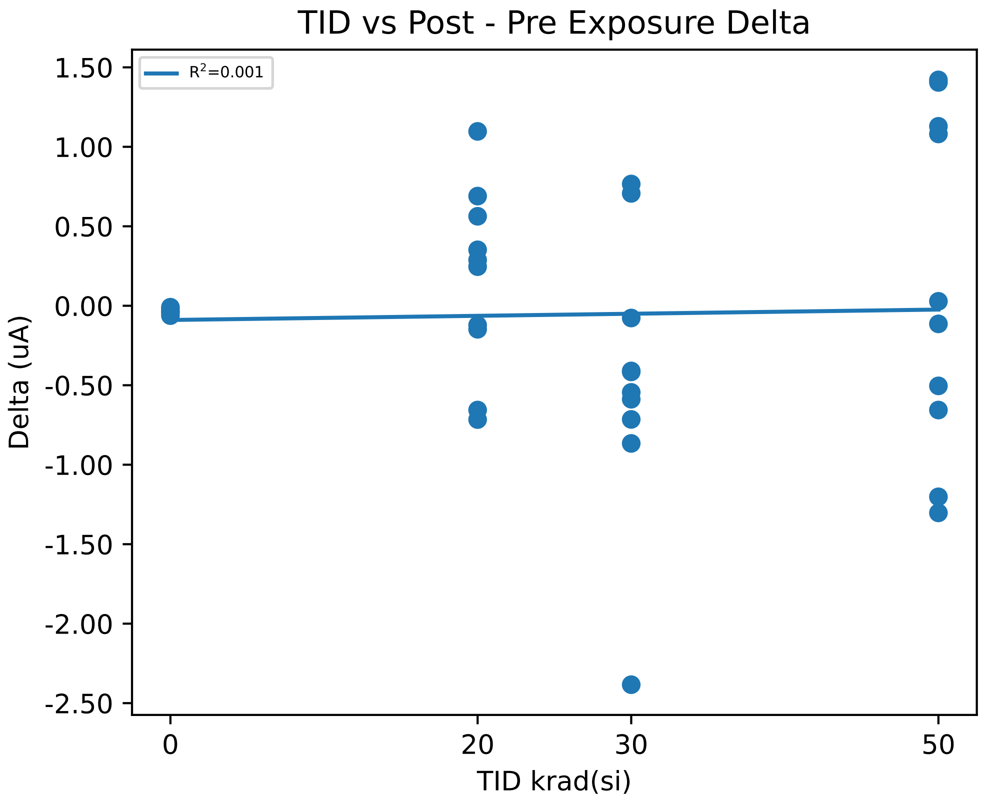
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.885	0.935	0.05
2	20	Unbiased	0.91	0.417	-0.493
3	20	Unbiased	0.653	0.304	-0.349
4	20	Unbiased	0.937	0.872	-0.065
5	20	Unbiased	0.96	0.938	-0.022
6	20	7V Biased	1.003	0.441	-0.562
7	20	7V Biased	1.019	0.357	-0.662
8	20	7V Biased	0.928	0.772	-0.156
9	20	7V Biased	0.956	0.928	-0.028
10	20	7V Biased	0.972	0.523	-0.449
11	30	Unbiased	1.006	0.429	-0.577
12	30	Unbiased	0.991	0.828	-0.163
13	30	Unbiased	0.922	1.022	0.1
14	30	Unbiased	1.003	0.713	-0.29
15	30	Unbiased	1.006	0.541	-0.465
16	30	7V Biased	0.975	0.878	-0.097
17	30	7V Biased	1.066	1.119	0.053
18	30	7V Biased	0.95	1.032	0.082
19	30	7V Biased	1.038	0.769	-0.269
20	30	7V Biased	0.969	0.94	-0.029
21	50	Unbiased	1.019	1.125	0.106
22	50	Unbiased	0.925	0.641	-0.284
23	50	Unbiased	0.96	0.475	-0.485
24	50	Unbiased	0.903	0.765	-0.138
25	50	Unbiased	0.922	0.975	0.053
26	50	7V Biased	0.91	1.029	0.119
27	50	7V Biased	0.931	0.688	-0.243
28	50	7V Biased	0.878	0.865	-0.013
29	50	7V Biased	0.925	0.991	0.066
30	50	7V Biased	0.847	0.495	-0.352
31	0	Correlation	0.903	0.497	-0.406
32	0	Correlation	0.85	0.815	-0.035
33	0	Correlation	0.882	1.05	0.168
34	0	Correlation	0.847	0.738	-0.109
35	0	Correlation	0.85	0.538	-0.312

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.847	0.8664	0.903	0.024986	0.497	0.7276	1.05	0.22406	-0.406	-0.1388	0.168	0.22759
20	0.653	0.9223	1.019	0.10285	0.304	0.6487	0.938	0.26358	-0.662	-0.2736	0.05	0.25912
30	0.922	0.9926	1.066	0.041612	0.429	0.8271	1.119	0.22041	-0.577	-0.1655	0.1	0.23287
50	0.847	0.922	1.019	0.045969	0.475	0.8049	1.125	0.22776	-0.485	-0.1171	0.119	0.21434

Device Test: 6.3 SS_I_Charge(SS_Icharge_1p5V)





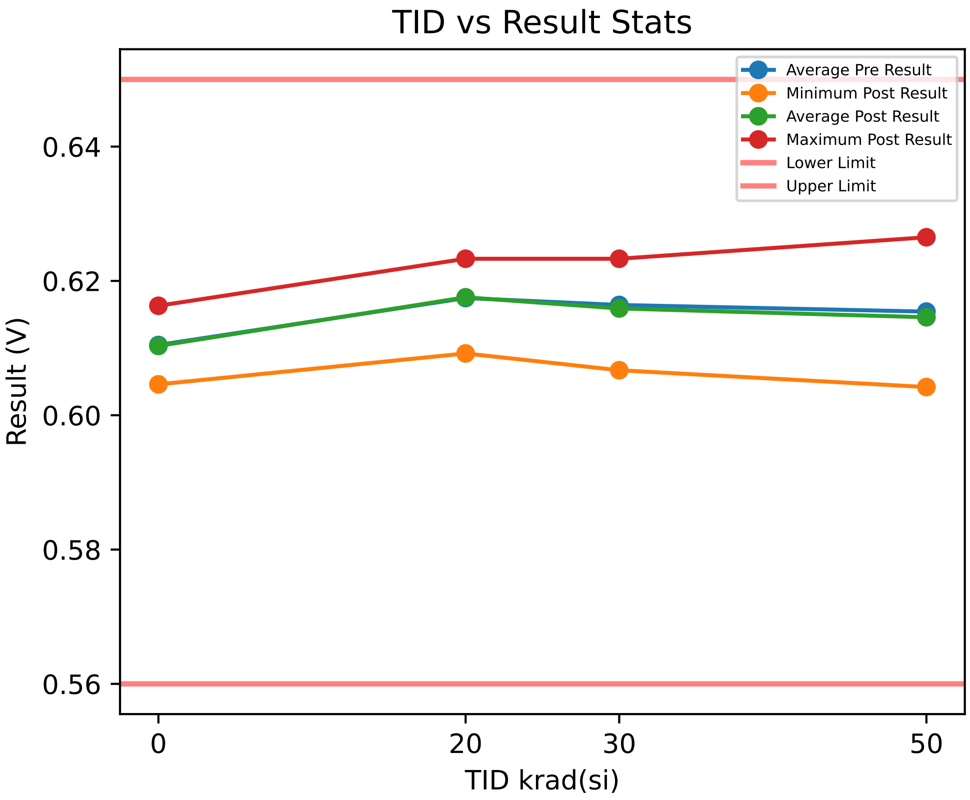
Test Results (Upper Limit = 83.0 (uA))

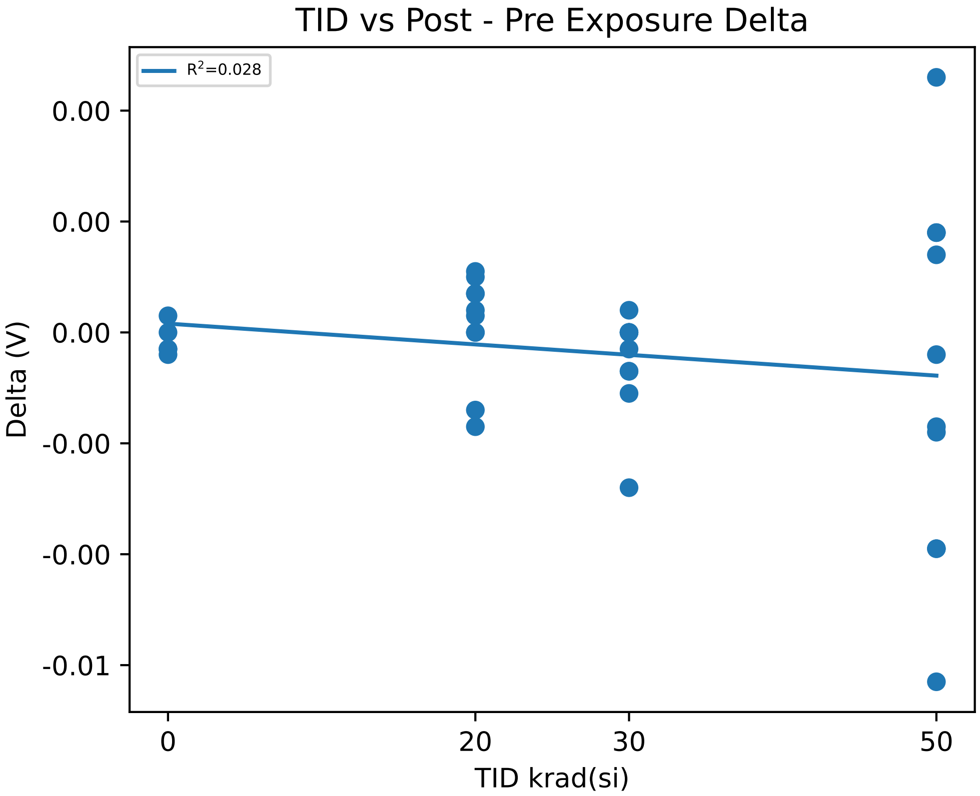
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	63.077	64.174	1.097
2	20	Unbiased	69.119	69.471	0.352
3	20	Unbiased	67.936	68.224	0.288
4	20	Unbiased	65.503	65.381	-0.122
5	20	Unbiased	66.961	66.813	-0.148
6	20	7V Biased	66.42	66.983	0.563
7	20	7V Biased	64.997	65.687	0.69
8	20	7V Biased	63.958	63.242	-0.716
9	20	7V Biased	65.193	65.439	0.246
10	20	7V Biased	66.813	66.157	-0.656
11	30	Unbiased	67.751	68.517	0.766
12	30	Unbiased	66.306	65.591	-0.715
13	30	Unbiased	64.553	65.26	0.707
14	30	Unbiased	65.565	65.149	-0.416
15	30	Unbiased	68.048	67.503	-0.545
16	30	7V Biased	62.742	62.665	-0.077
17	30	7V Biased	67.911	65.527	-2.384
18	30	7V Biased	66.862	66.452	-0.41
19	30	7V Biased	66.992	66.126	-0.866
20	30	7V Biased	65.891	65.303	-0.588
21	50	Unbiased	66.23	66.258	0.028
22	50	Unbiased	63.786	62.483	-1.303
23	50	Unbiased	68.847	69.976	1.129
24	50	Unbiased	66.8	68.205	1.405
25	50	Unbiased	63.043	64.464	1.421
26	50	7V Biased	64.065	65.146	1.081
27	50	7V Biased	65.407	65.293	-0.114
28	50	7V Biased	67.888	67.232	-0.656
29	50	7V Biased	67.739	67.235	-0.504
30	50	7V Biased	68.205	67.003	-1.202
31	0	Correlation	69.766	69.704	-0.062
32	0	Correlation	65.649	65.609	-0.04
33	0	Correlation	66.6	66.591	-0.009
34	0	Correlation	66.52	66.48	-0.04
35	0	Correlation	66.593	66.571	-0.022

Test Statistics (uA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	65.649	67.026	69.766	1.5834	65.609	66.991	69.704	1.5707	-0.062	-0.0346	-0.009	0.020144
20	63.077	65.998	69.119	1.8213	63.242	66.157	69.471	1.8299	-0.716	0.1594	1.097	0.57634
30	62.742	66.262	68.048	1.6652	62.665	65.809	68.517	1.5535	-2.384	-0.4528	0.766	0.88008
50	63.043	66.201	68.847	2.0436	62.483	66.329	69.976	2.0992	-1.303	0.1285	1.421	1.06

Device Test: 6.4 EN_VTH_RISING(EN_UVLO_RISING_1p8V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

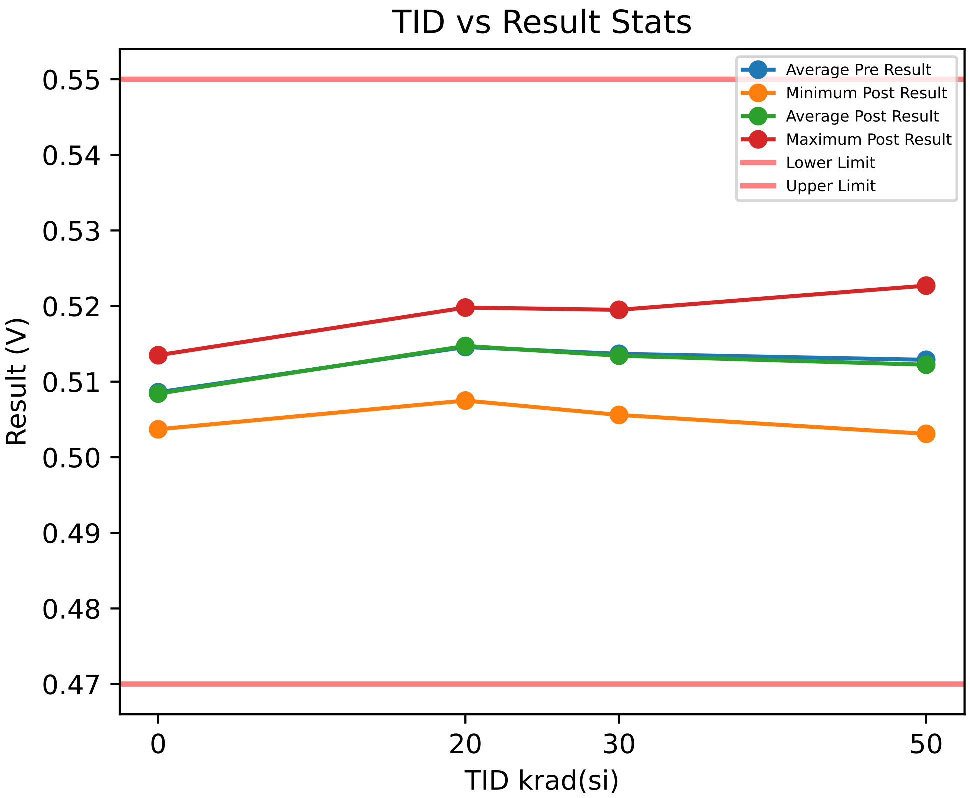
Test Results (Lower Limit = 0.56, Upper Limit = 0.65 (V))

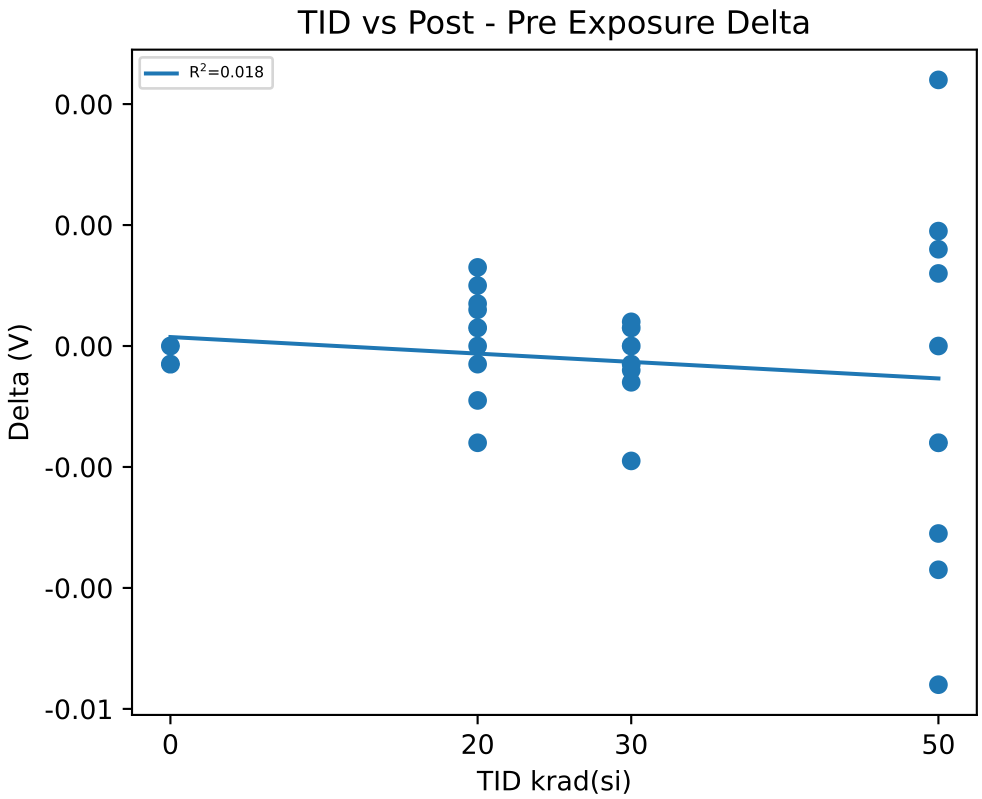
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.6208	0.6212	0.0004
2	20	Unbiased	0.6177	0.6187	0.001
3	20	Unbiased	0.6219	0.6226	0.0007
4	20	Unbiased	0.6226	0.6233	0.0007
5	20	Unbiased	0.611	0.6113	0.0003
6	20	7V Biased	0.6198	0.6184	-0.0014
7	20	7V Biased	0.6194	0.6194	0
8	20	7V Biased	0.6173	0.6184	0.0011
9	20	7V Biased	0.6092	0.6092	0
10	20	7V Biased	0.6148	0.6131	-0.0017
11	30	Unbiased	0.612	0.6092	-0.0028
12	30	Unbiased	0.6134	0.6138	0.0004
13	30	Unbiased	0.624	0.6233	-0.0007
14	30	Unbiased	0.6233	0.6233	0
15	30	Unbiased	0.6212	0.6201	-0.0011
16	30	7V Biased	0.6184	0.6184	0
17	30	7V Biased	0.6102	0.6102	0
18	30	7V Biased	0.612	0.6117	-0.0003
19	30	7V Biased	0.6074	0.6067	-0.0007
20	30	7V Biased	0.6223	0.6223	0
21	50	Unbiased	0.6247	0.6265	0.0018
22	50	Unbiased	0.6124	0.617	0.0046
23	50	Unbiased	0.6148	0.6166	0.0018
24	50	Unbiased	0.6166	0.618	0.0014
25	50	Unbiased	0.6145	0.6141	-0.0004
26	50	7V Biased	0.6201	0.6138	-0.0063
27	50	7V Biased	0.6102	0.6085	-0.0017
28	50	7V Biased	0.6099	0.606	-0.0039
29	50	7V Biased	0.6081	0.6042	-0.0039
30	50	7V Biased	0.623	0.6212	-0.0018
31	0	Correlation	0.6049	0.6046	-0.0003
32	0	Correlation	0.6166	0.6163	-0.0003
33	0	Correlation	0.6127	0.6127	0
34	0	Correlation	0.6057	0.606	0.0003
35	0	Correlation	0.6124	0.612	-0.0004

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6049	0.61046	0.6166	0.0050013	0.6046	0.61032	0.6163	0.0048895	-0.0004	-0.00014	0.0003	0.0002881
20	0.6092	0.61745	0.6226	0.0045172	0.6092	0.61756	0.6233	0.0047919	-0.0017	0.00011	0.0011	0.00095272
30	0.6074	0.61642	0.624	0.0060953	0.6067	0.6159	0.6233	0.0063108	-0.0028	-0.00052	0.0004	0.00091748
50	0.6081	0.61543	0.6247	0.005662	0.6042	0.61459	0.6265	0.0068856	-0.0063	-0.00084	0.0046	0.0033157

Device Test: 6.5 EN_VTH_FALLING(EN_UVLO_FALLING_1p8V)





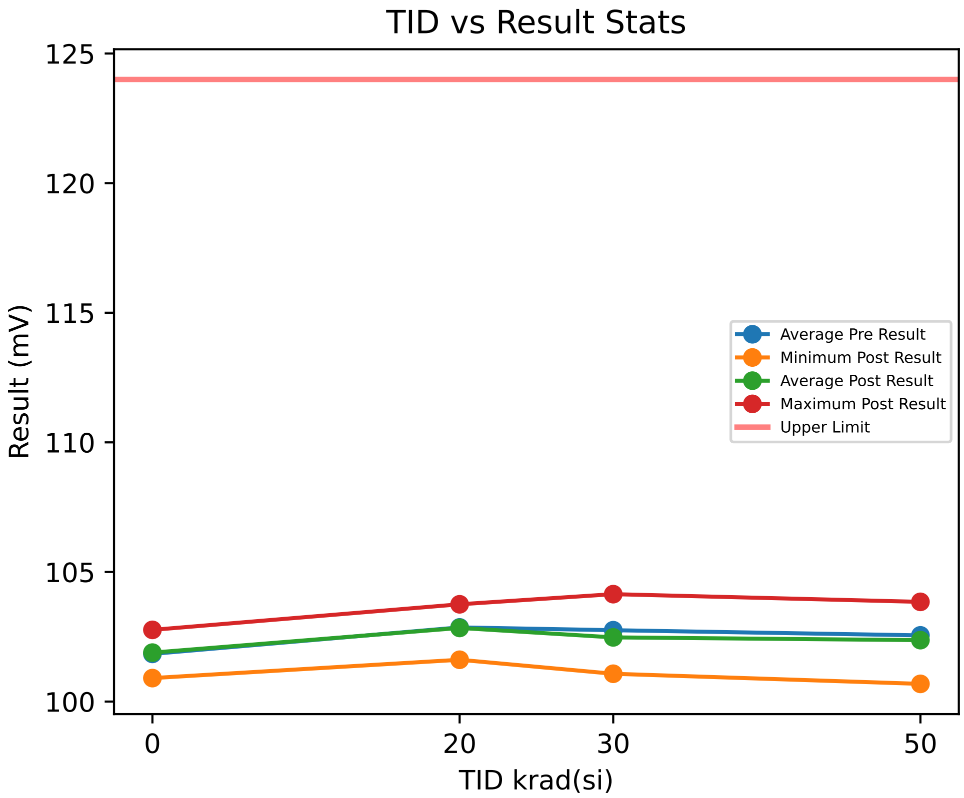
Test Results (Lower Limit = 0.47,
Upper Limit = 0.55 (V))

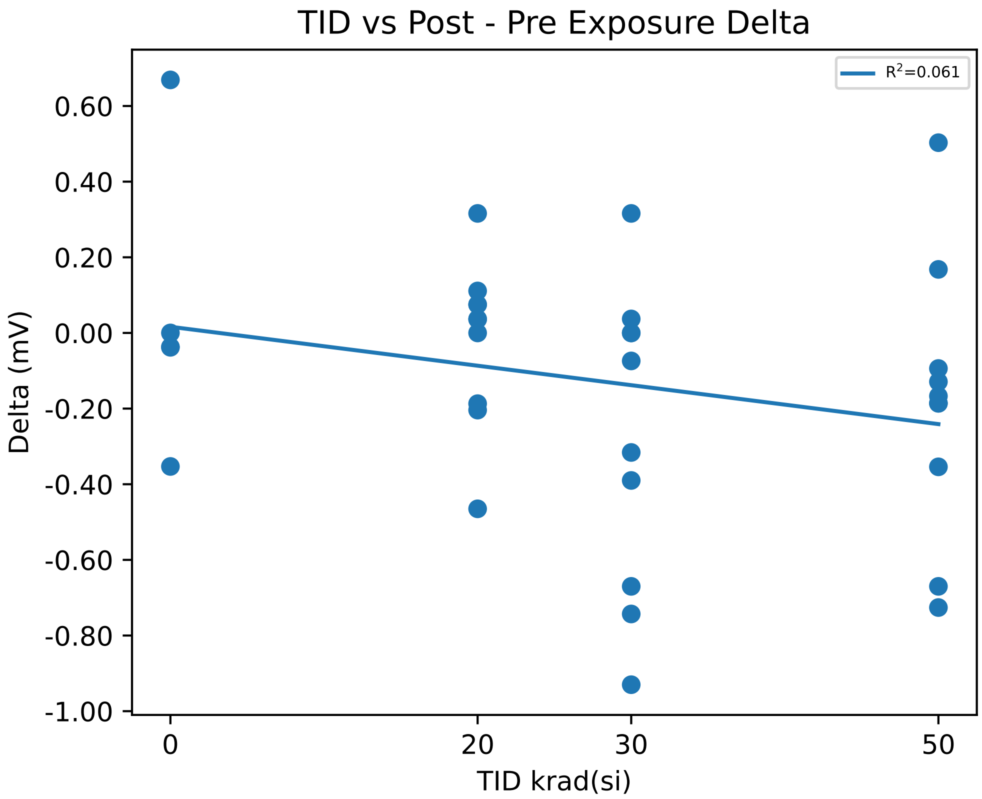
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.5176	0.5179	0.0003
2	20	Unbiased	0.5144	0.5154	0.001
3	20	Unbiased	0.5182	0.5189	0.0007
4	20	Unbiased	0.5192	0.5198	0.0006
5	20	Unbiased	0.5094	0.5097	0.0003
6	20	7V Biased	0.5166	0.5157	-0.0009
7	20	7V Biased	0.5163	0.516	-0.0003
8	20	7V Biased	0.5144	0.5157	0.0013
9	20	7V Biased	0.5075	0.5075	0
10	20	7V Biased	0.5122	0.5106	-0.0016
11	30	Unbiased	0.51	0.5081	-0.0019
12	30	Unbiased	0.511	0.5113	0.0003
13	30	Unbiased	0.5198	0.5195	-0.0003
14	30	Unbiased	0.5192	0.5192	0
15	30	Unbiased	0.5179	0.5176	-0.0003
16	30	7V Biased	0.5154	0.5154	0
17	30	7V Biased	0.5087	0.5091	0.0004
18	30	7V Biased	0.5097	0.51	0.0003
19	30	7V Biased	0.5062	0.5056	-0.0006
20	30	7V Biased	0.5189	0.5185	-0.0004
21	50	Unbiased	0.5208	0.5227	0.0019
22	50	Unbiased	0.5094	0.5138	0.0044
23	50	Unbiased	0.5129	0.5141	0.0012
24	50	Unbiased	0.5132	0.5148	0.0016
25	50	Unbiased	0.5122	0.5122	0
26	50	7V Biased	0.5166	0.511	-0.0056
27	50	7V Biased	0.5094	0.5078	-0.0016
28	50	7V Biased	0.5084	0.5053	-0.0031
29	50	7V Biased	0.5068	0.5031	-0.0037
30	50	7V Biased	0.5192	0.5176	-0.0016
31	0	Correlation	0.504	0.5037	-0.0003
32	0	Correlation	0.5138	0.5135	-0.0003
33	0	Correlation	0.5106	0.5106	0
34	0	Correlation	0.5043	0.504	-0.0003
35	0	Correlation	0.5103	0.5103	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.504	0.5086	0.5138	0.0042889	0.5037	0.50842	0.5135	0.0043563	-0.0003	-0.00018	0	0.00016432
20	0.5075	0.51458	0.5192	0.0038485	0.5075	0.51472	0.5198	0.0041058	-0.0016	0.00014	0.0013	0.00088091
30	0.5062	0.51368	0.5198	0.0050909	0.5056	0.51343	0.5195	0.0051842	-0.0019	-0.00025	0.0004	0.00066875
50	0.5068	0.51289	0.5208	0.0046943	0.5031	0.51224	0.5227	0.0058075	-0.0056	-0.00065	0.0044	0.0030281

Device Test: 6.6 EN_HYST(EN_UVLO_HYSTERESIS_1p8V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

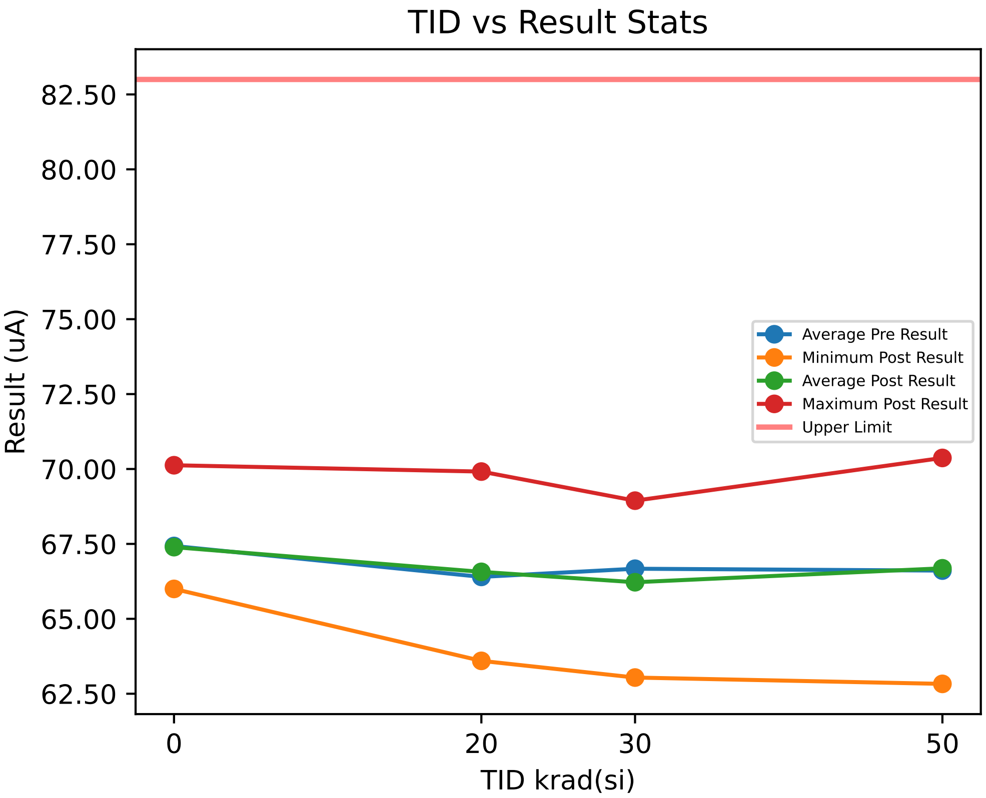
Test Results (Upper Limit = 124.0 (mV))

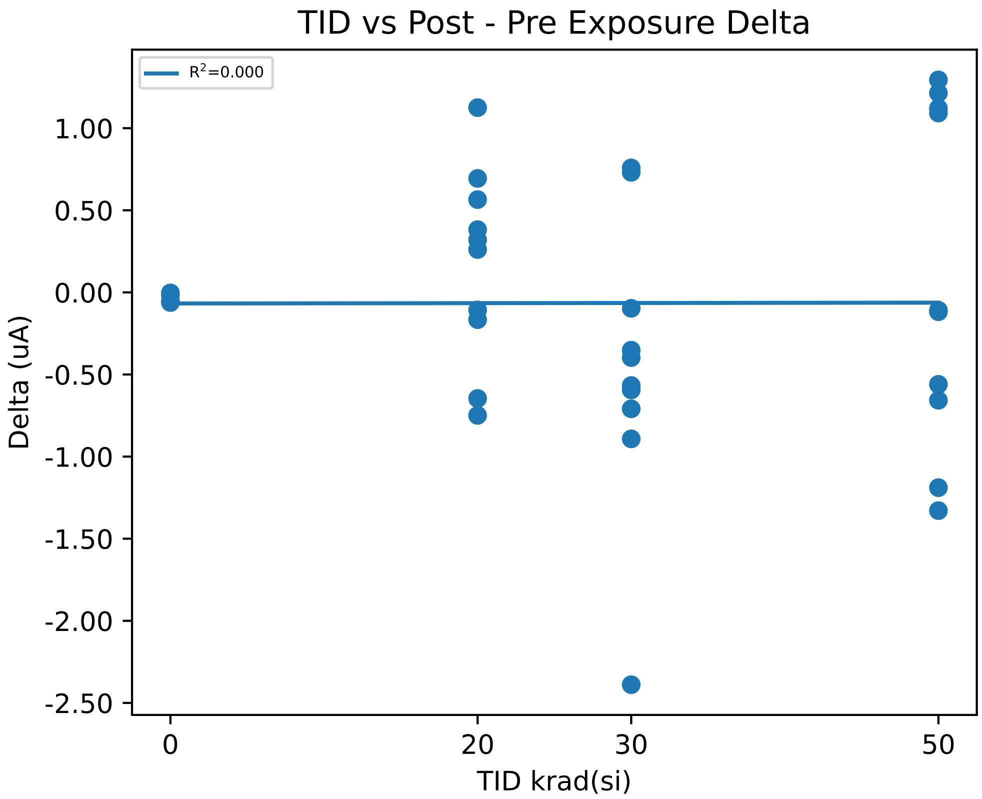
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	103.25	103.29	0.036
2	20	Unbiased	103.23	103.34	0.111
3	20	Unbiased	103.68	103.75	0.075
4	20	Unbiased	103.44	103.51	0.075
5	20	Unbiased	101.58	101.61	0.037
6	20	7V Biased	103.14	102.67	-0.465
7	20	7V Biased	103.1	103.42	0.316
8	20	7V Biased	102.88	102.67	-0.204
9	20	7V Biased	101.7	101.7	0
10	20	7V Biased	102.62	102.43	-0.187
11	30	Unbiased	102	101.07	-0.93
12	30	Unbiased	102.47	102.51	0.037
13	30	Unbiased	104.22	103.83	-0.39
14	30	Unbiased	104.14	104.14	0
15	30	Unbiased	103.29	102.54	-0.743
16	30	7V Biased	102.99	102.99	0
17	30	7V Biased	101.5	101.19	-0.316
18	30	7V Biased	102.32	101.65	-0.67
19	30	7V Biased	101.2	101.13	-0.074
20	30	7V Biased	103.4	103.72	0.316
21	50	Unbiased	103.98	103.85	-0.129
22	50	Unbiased	102.99	103.16	0.168
23	50	Unbiased	101.98	102.49	0.503
24	50	Unbiased	103.44	103.27	-0.167
25	50	Unbiased	102.27	101.91	-0.354
26	50	7V Biased	103.49	102.82	-0.67
27	50	7V Biased	100.87	100.68	-0.186
28	50	7V Biased	101.46	100.74	-0.726
29	50	7V Biased	101.28	101.18	-0.094
30	50	7V Biased	103.79	103.6	-0.186
31	0	Correlation	100.94	100.91	-0.037
32	0	Correlation	102.8	102.77	-0.038
33	0	Correlation	102.08	102.08	0
34	0	Correlation	101.33	102	0.669
35	0	Correlation	102.04	101.69	-0.353

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	100.94	101.84	102.8	0.72225	100.91	101.89	102.77	0.67545	-0.353	0.0482	0.669	0.37529
20	101.58	102.86	103.68	0.70485	101.61	102.84	103.75	0.7519	-0.465	-0.0206	0.316	0.21465
30	101.2	102.75	104.22	1.035	101.07	102.48	104.14	1.1807	-0.93	-0.277	0.316	0.40238
50	100.87	102.55	103.98	1.1284	100.68	102.37	103.85	1.1774	-0.726	-0.1841	0.503	0.35996

Device Test: 6.7 SS_I_Charge(SS_Icharge_1p8V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

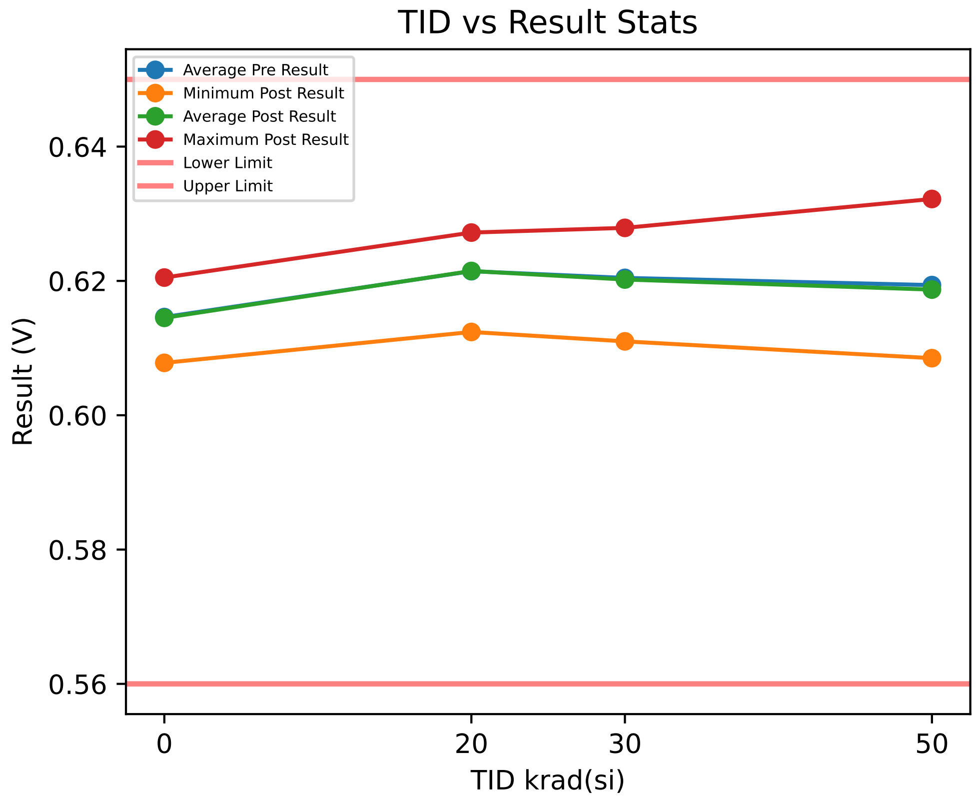
Test Results (Upper Limit = 83.0 (uA))

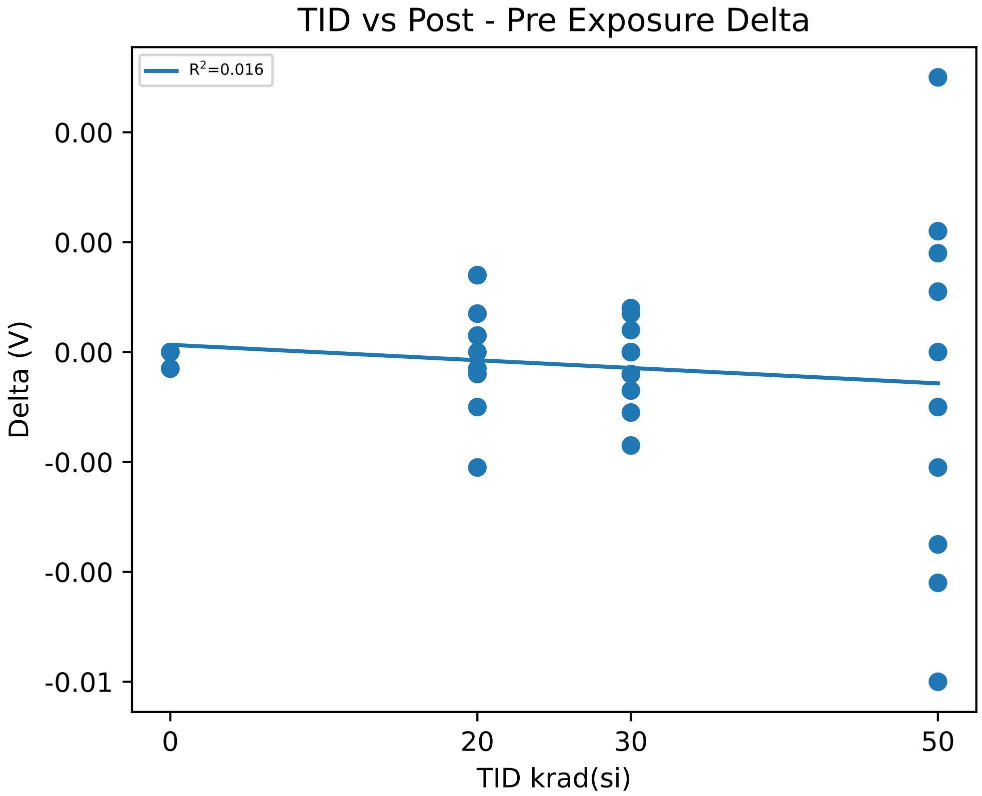
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	63.488	64.613	1.125
2	20	Unbiased	69.532	69.914	0.382
3	20	Unbiased	68.344	68.664	0.32
4	20	Unbiased	65.906	65.799	-0.107
5	20	Unbiased	67.37	67.204	-0.166
6	20	7V Biased	66.805	67.37	0.565
7	20	7V Biased	65.4	66.094	0.694
8	20	7V Biased	64.346	63.597	-0.749
9	20	7V Biased	65.575	65.836	0.261
10	20	7V Biased	67.226	66.58	-0.646
11	30	Unbiased	68.185	68.943	0.758
12	30	Unbiased	66.712	66.003	-0.709
13	30	Unbiased	64.928	65.659	0.731
14	30	Unbiased	65.961	65.564	-0.397
15	30	Unbiased	68.479	67.912	-0.567
16	30	7V Biased	63.137	63.04	-0.097
17	30	7V Biased	68.337	65.948	-2.389
18	30	7V Biased	67.271	66.919	-0.352
19	30	7V Biased	67.393	66.501	-0.892
20	30	7V Biased	66.312	65.718	-0.594
21	50	Unbiased	66.655	66.546	-0.109
22	50	Unbiased	64.158	62.829	-1.329
23	50	Unbiased	69.277	70.369	1.092
24	50	Unbiased	67.222	68.516	1.294
25	50	Unbiased	63.426	64.64	1.214
26	50	7V Biased	64.46	65.581	1.121
27	50	7V Biased	65.811	65.693	-0.118
28	50	7V Biased	68.313	67.656	-0.657
29	50	7V Biased	68.161	67.601	-0.56
30	50	7V Biased	68.615	67.426	-1.189
31	0	Correlation	70.177	70.125	-0.052
32	0	Correlation	66.06	65.998	-0.062
33	0	Correlation	66.999	66.996	-0.003
34	0	Correlation	66.938	66.88	-0.058
35	0	Correlation	66.981	66.963	-0.018

Test Statistics (uA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	66.06	67.431	70.177	1.5853	65.998	67.392	70.125	1.5824	-0.062	-0.0386	-0.003	0.026435
20	63.488	66.399	69.532	1.8257	63.597	66.567	69.914	1.845	-0.749	0.1679	1.125	0.58863
30	63.137	66.672	68.479	1.6793	63.04	66.221	68.943	1.5662	-2.389	-0.4508	0.758	0.88491
50	63.426	66.61	69.277	2.0609	62.829	66.686	70.369	2.1221	-1.329	0.0759	1.294	1.0269

Device Test: 6.8 EN_VTH_RISING(EN_UVLO_RISING_3p3V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

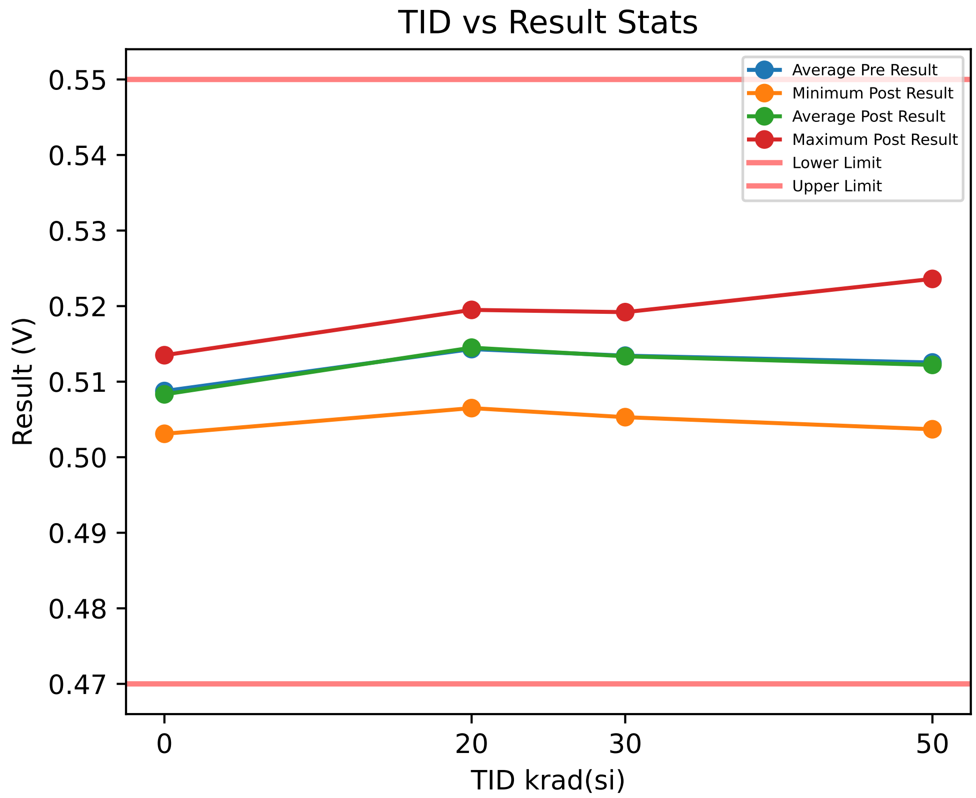
Test Results (Lower Limit = 0.56, Upper Limit = 0.65 (V))

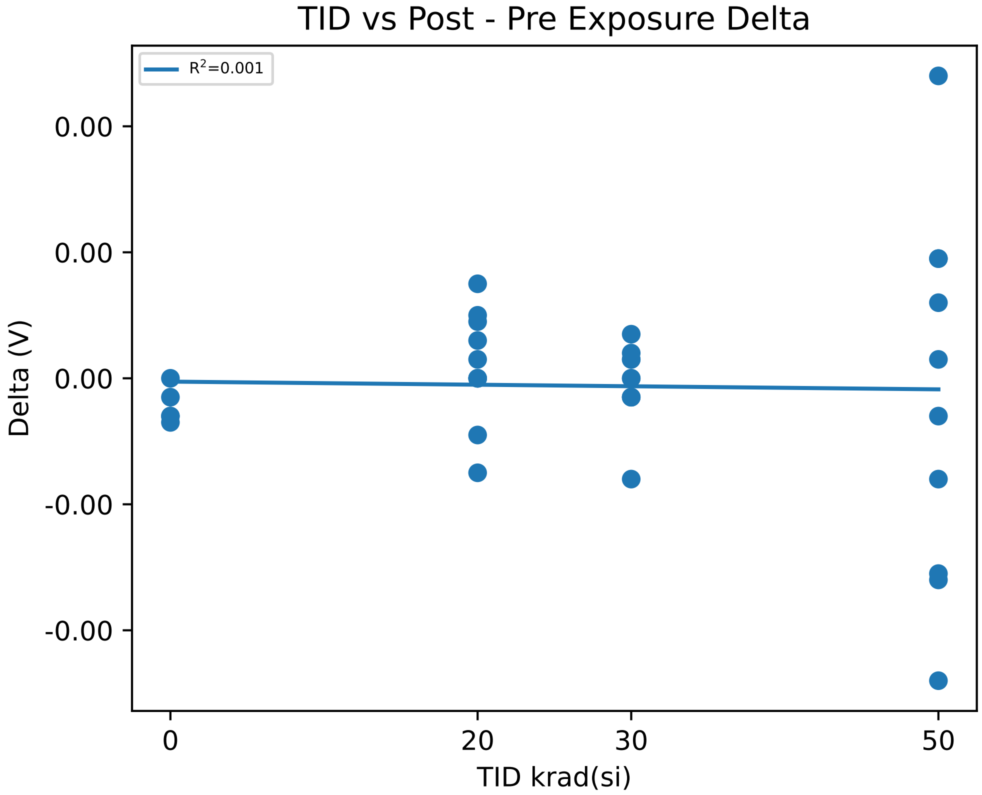
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.6251	0.6251	0
2	20	Unbiased	0.6205	0.6219	0.0014
3	20	Unbiased	0.6269	0.6272	0.0003
4	20	Unbiased	0.6258	0.6265	0.0007
5	20	Unbiased	0.6145	0.6148	0.0003
6	20	7V Biased	0.624	0.623	-0.001
7	20	7V Biased	0.6237	0.6233	-0.0004
8	20	7V Biased	0.6219	0.6233	0.0014
9	20	7V Biased	0.6127	0.6124	-0.0003
10	20	7V Biased	0.6194	0.6173	-0.0021
11	30	Unbiased	0.6155	0.6138	-0.0017
12	30	Unbiased	0.617	0.6166	-0.0004
13	30	Unbiased	0.6279	0.6272	-0.0007
14	30	Unbiased	0.6272	0.6279	0.0007
15	30	Unbiased	0.6265	0.6254	-0.0011
16	30	7V Biased	0.6219	0.6219	0
17	30	7V Biased	0.6155	0.6155	0
18	30	7V Biased	0.6155	0.6163	0.0008
19	30	7V Biased	0.6106	0.611	0.0004
20	30	7V Biased	0.6269	0.6265	-0.0004
21	50	Unbiased	0.63	0.6322	0.0022
22	50	Unbiased	0.6155	0.6205	0.005
23	50	Unbiased	0.6201	0.6212	0.0011
24	50	Unbiased	0.6194	0.6212	0.0018
25	50	Unbiased	0.6184	0.6184	0
26	50	7V Biased	0.6251	0.6191	-0.006
27	50	7V Biased	0.6145	0.6124	-0.0021
28	50	7V Biased	0.6127	0.6092	-0.0035
29	50	7V Biased	0.6127	0.6085	-0.0042
30	50	7V Biased	0.6254	0.6244	-0.001
31	0	Correlation	0.6078	0.6078	0
32	0	Correlation	0.6205	0.6205	0
33	0	Correlation	0.618	0.618	0
34	0	Correlation	0.6095	0.6092	-0.0003
35	0	Correlation	0.6173	0.617	-0.0003

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6078	0.61462	0.6205	0.0056104	0.6078	0.6145	0.6205	0.0056454	-0.0003	-0.00012	0	0.00016432
20	0.6127	0.62145	0.6269	0.0047573	0.6124	0.62148	0.6272	0.0049964	-0.0021	3e-05	0.0014	0.0010667
30	0.6106	0.62045	0.6279	0.0063579	0.611	0.62021	0.6279	0.0062696	-0.0017	-0.00024	0.0008	0.0007905
50	0.6127	0.61938	0.63	0.0058816	0.6085	0.61871	0.6322	0.0071857	-0.006	-0.00067	0.005	0.0033516

Device Test: 6.9 EN_VTH_FALLING(EN_UVLO_FALLING_3p3V)





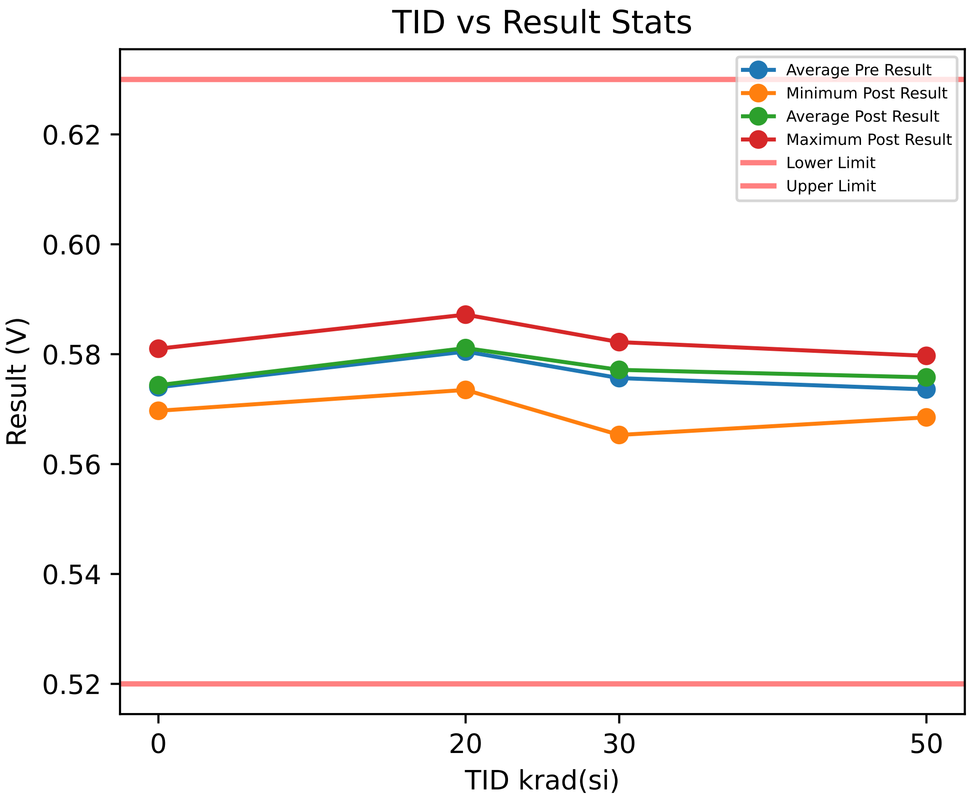
Test Results (Lower Limit = 0.47, Upper Limit = 0.55 (V))

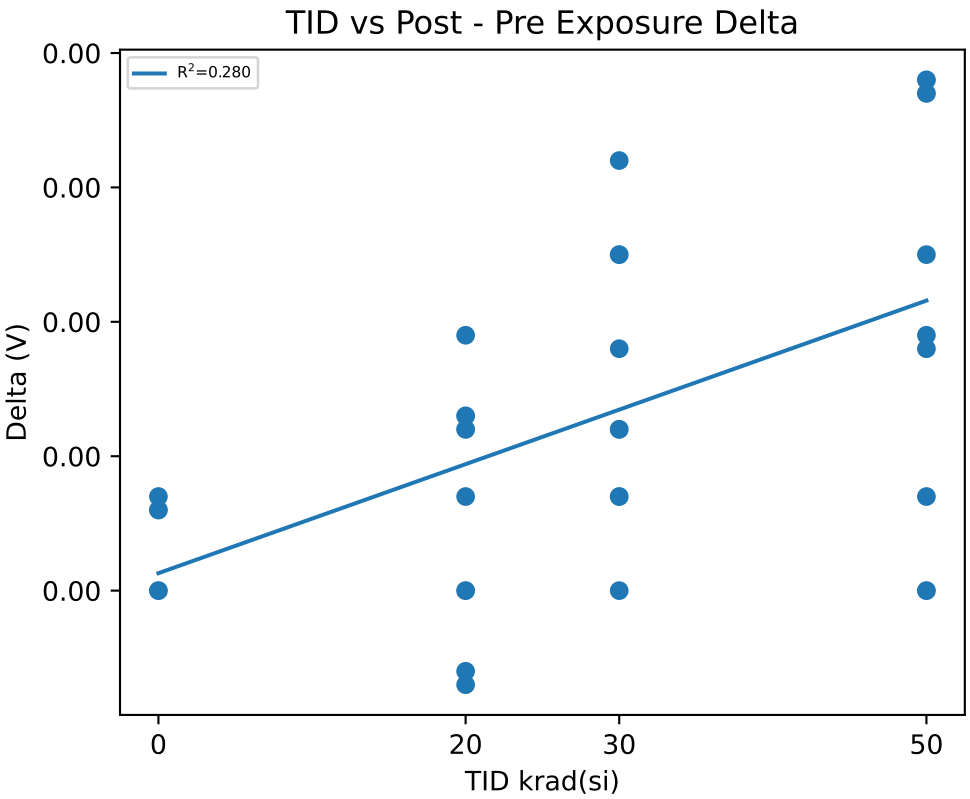
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.5173	0.5176	0.0003
2	20	Unbiased	0.5135	0.5144	0.0009
3	20	Unbiased	0.5189	0.5195	0.0006
4	20	Unbiased	0.5179	0.5189	0.001
5	20	Unbiased	0.5091	0.5091	0
6	20	7V Biased	0.5166	0.5157	-0.0009
7	20	7V Biased	0.516	0.516	0
8	20	7V Biased	0.5148	0.5163	0.0015
9	20	7V Biased	0.5065	0.5065	0
10	20	7V Biased	0.5125	0.511	-0.0015
11	30	Unbiased	0.51	0.5084	-0.0016
12	30	Unbiased	0.5103	0.5103	0
13	30	Unbiased	0.5195	0.5192	-0.0003
14	30	Unbiased	0.5185	0.5192	0.0007
15	30	Unbiased	0.5185	0.5182	-0.0003
16	30	7V Biased	0.5144	0.5148	0.0004
17	30	7V Biased	0.5097	0.51	0.0003
18	30	7V Biased	0.5097	0.51	0.0003
19	30	7V Biased	0.5056	0.5053	-0.0003
20	30	7V Biased	0.5182	0.5182	0
21	50	Unbiased	0.5217	0.5236	0.0019
22	50	Unbiased	0.5084	0.5132	0.0048
23	50	Unbiased	0.5132	0.5144	0.0012
24	50	Unbiased	0.5122	0.5141	0.0019
25	50	Unbiased	0.5119	0.5122	0.0003
26	50	7V Biased	0.517	0.5122	-0.0048
27	50	7V Biased	0.5091	0.5075	-0.0016
28	50	7V Biased	0.5075	0.5043	-0.0032
29	50	7V Biased	0.5068	0.5037	-0.0031
30	50	7V Biased	0.5176	0.517	-0.0006
31	0	Correlation	0.5037	0.5031	-0.0006
32	0	Correlation	0.5138	0.5135	-0.0003
33	0	Correlation	0.5113	0.5113	0
34	0	Correlation	0.504	0.5034	-0.0006
35	0	Correlation	0.511	0.5103	-0.0007

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5037	0.50876	0.5138	0.0046134	0.5031	0.50832	0.5135	0.004772	-0.0007	-0.00044	0	0.0002881
20	0.5065	0.51431	0.5189	0.0039904	0.5065	0.5145	0.5195	0.0042988	-0.0015	0.00019	0.0015	0.00089499
30	0.5056	0.51344	0.5195	0.0049738	0.5053	0.51336	0.5192	0.0051494	-0.0016	-8e-05	0.0007	0.0006321
50	0.5068	0.51254	0.5217	0.004918	0.5037	0.51222	0.5236	0.0059554	-0.0048	-0.00032	0.0048	0.0029169

Device Test: 7.0 OVP_VTH_Rising(OVP_UVLO_RISING_1p5V)





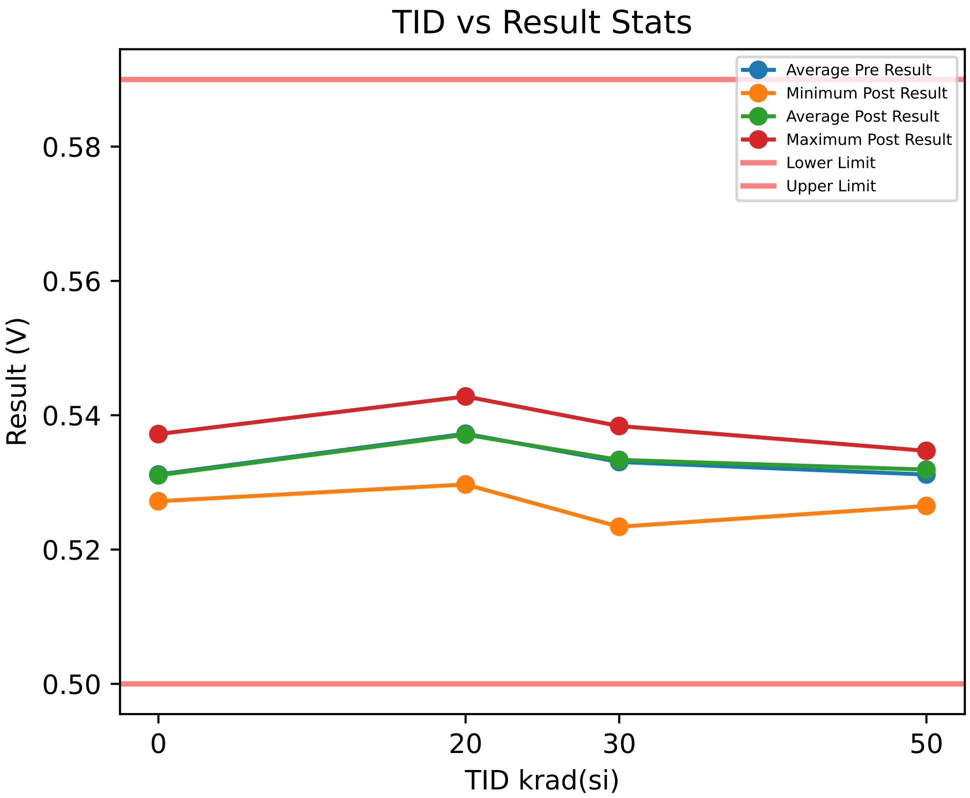
Test Results (Lower Limit = 0.52, Upper Limit = 0.63 (V))

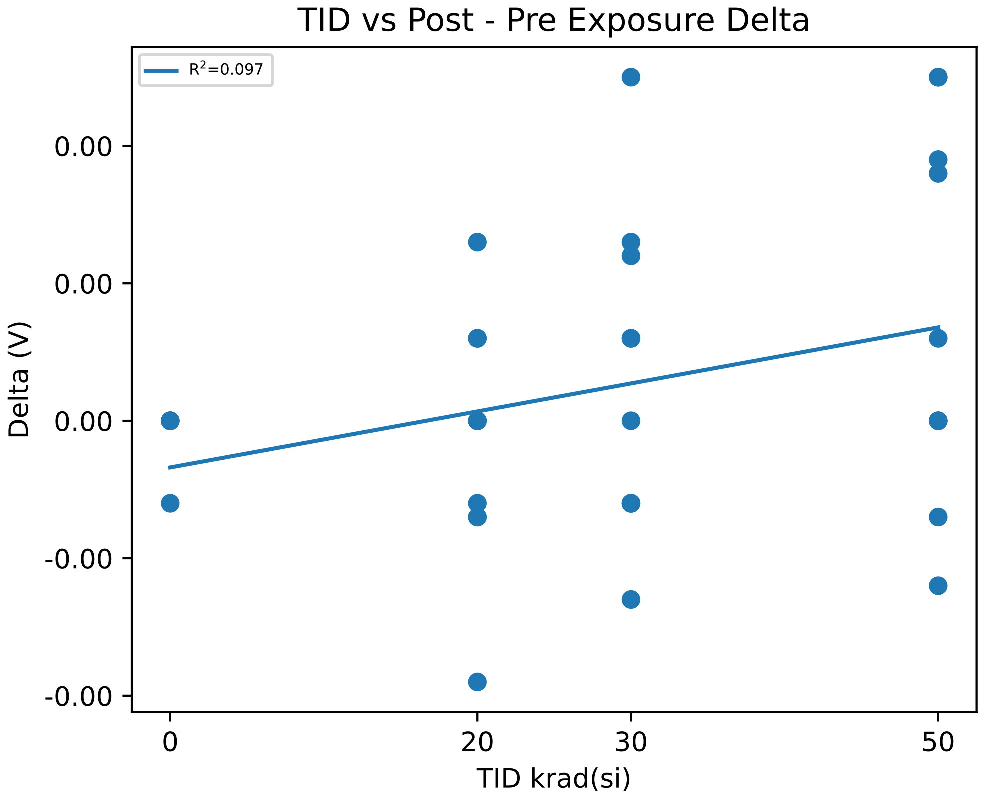
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.5753	0.5766	0.0013
2	20	Unbiased	0.5797	0.581	0.0013
3	20	Unbiased	0.5854	0.5854	0
4	20	Unbiased	0.5785	0.5785	0
5	20	Unbiased	0.5797	0.5791	-0.0006
6	20	7V Biased	0.5772	0.5791	0.0019
7	20	7V Biased	0.5879	0.5872	-0.0007
8	20	7V Biased	0.5854	0.5866	0.0012
9	20	7V Biased	0.5829	0.5841	0.0012
10	20	7V Biased	0.5728	0.5735	0.0007
11	30	Unbiased	0.5753	0.576	0.0007
12	30	Unbiased	0.5804	0.5816	0.0012
13	30	Unbiased	0.581	0.5822	0.0012
14	30	Unbiased	0.581	0.581	0
15	30	Unbiased	0.5778	0.5785	0.0007
16	30	7V Biased	0.5628	0.5653	0.0025
17	30	7V Biased	0.5716	0.5728	0.0012
18	30	7V Biased	0.576	0.5778	0.0018
19	30	7V Biased	0.5728	0.5753	0.0025
20	30	7V Biased	0.5778	0.581	0.0032
21	50	Unbiased	0.5728	0.5735	0.0007
22	50	Unbiased	0.5666	0.5685	0.0019
23	50	Unbiased	0.571	0.571	0
24	50	Unbiased	0.576	0.5778	0.0018
25	50	Unbiased	0.5772	0.5772	0
26	50	7V Biased	0.5772	0.5797	0.0025
27	50	7V Biased	0.5735	0.5772	0.0037
28	50	7V Biased	0.5747	0.5785	0.0038
29	50	7V Biased	0.5716	0.5753	0.0037
30	50	7V Biased	0.5753	0.5791	0.0038
31	0	Correlation	0.5735	0.5741	0.0006
32	0	Correlation	0.5804	0.581	0.0006
33	0	Correlation	0.571	0.571	0
34	0	Correlation	0.5697	0.5697	0
35	0	Correlation	0.5753	0.576	0.0007

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5697	0.57398	0.5804	0.0041949	0.5697	0.57436	0.581	0.004468	0	0.00038	0.0007	0.00034928
20	0.5728	0.58048	0.5879	0.0048424	0.5735	0.58111	0.5872	0.0045671	-0.0007	0.00063	0.0019	0.00089697
30	0.5628	0.57565	0.581	0.0055672	0.5653	0.57715	0.5822	0.0051778	0	0.0015	0.0032	0.0009877
50	0.5666	0.57359	0.5772	0.0032692	0.5685	0.57578	0.5797	0.0036995	0	0.00219	0.0038	0.0015595

Device Test: 7.1 OVP_VTH_Falling(OVP_UVLO_FALLING_1p5V)





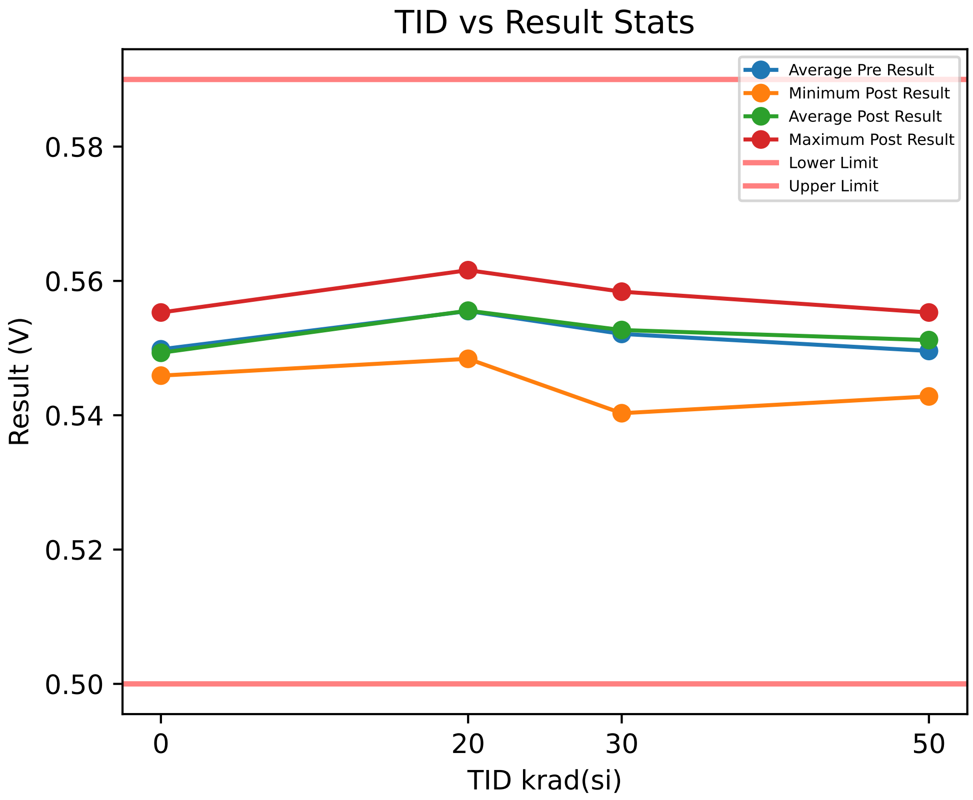
Test Results (Lower Limit = 0.5, Upper Limit = 0.59 (V))

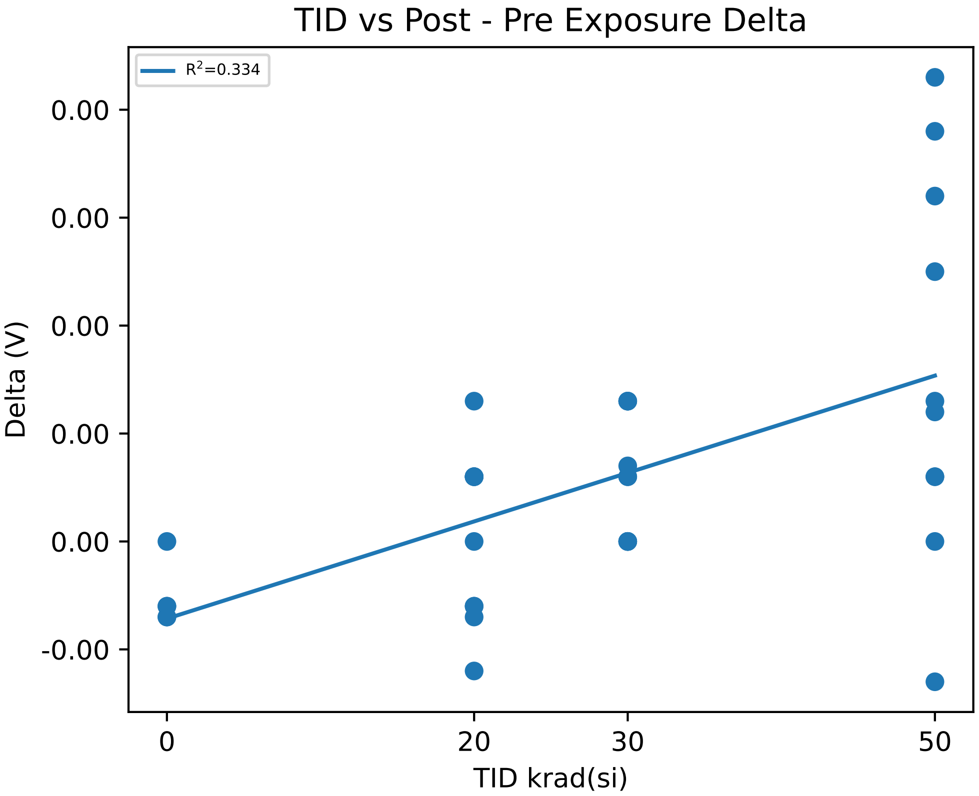
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.5328	0.5334	0.0006
2	20	Unbiased	0.5359	0.5372	0.0013
3	20	Unbiased	0.5416	0.5409	-0.0007
4	20	Unbiased	0.534	0.534	0
5	20	Unbiased	0.5372	0.5365	-0.0007
6	20	7V Biased	0.5347	0.5347	0
7	20	7V Biased	0.5447	0.5428	-0.0019
8	20	7V Biased	0.5416	0.5416	0
9	20	7V Biased	0.5397	0.5403	0.0006
10	20	7V Biased	0.5303	0.5297	-0.0006
11	30	Unbiased	0.5328	0.5315	-0.0013
12	30	Unbiased	0.5378	0.5372	-0.0006
13	30	Unbiased	0.5378	0.5384	0.0006
14	30	Unbiased	0.5378	0.5372	-0.0006
15	30	Unbiased	0.5353	0.5347	-0.0006
16	30	7V Biased	0.5209	0.5234	0.0025
17	30	7V Biased	0.529	0.5303	0.0013
18	30	7V Biased	0.5334	0.5334	0
19	30	7V Biased	0.5309	0.5315	0.0006
20	30	7V Biased	0.5347	0.5359	0.0012
21	50	Unbiased	0.5303	0.5303	0
22	50	Unbiased	0.5259	0.5265	0.0006
23	50	Unbiased	0.529	0.5278	-0.0012
24	50	Unbiased	0.5328	0.5328	0
25	50	Unbiased	0.5347	0.534	-0.0007
26	50	7V Biased	0.5347	0.5347	0
27	50	7V Biased	0.5303	0.5328	0.0025
28	50	7V Biased	0.5322	0.534	0.0018
29	50	7V Biased	0.529	0.5315	0.0025
30	50	7V Biased	0.5328	0.5347	0.0019
31	0	Correlation	0.5309	0.5309	0
32	0	Correlation	0.5372	0.5372	0
33	0	Correlation	0.5278	0.5278	0
34	0	Correlation	0.5272	0.5272	0
35	0	Correlation	0.5328	0.5322	-0.0006

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5272	0.53118	0.5372	0.0040684	0.5272	0.53106	0.5372	0.0040172	-0.0006	-0.00012	0	0.00026833
20	0.5303	0.53725	0.5447	0.0045503	0.5297	0.53711	0.5428	0.0042375	-0.0019	-0.00014	0.0013	0.00089219
30	0.5209	0.53304	0.5378	0.0052101	0.5234	0.53335	0.5384	0.004455	-0.0013	0.00031	0.0025	0.0011503
50	0.5259	0.53117	0.5347	0.0027889	0.5265	0.53191	0.5347	0.0028831	-0.0012	0.00074	0.0025	0.0013401

Device Test: 7.10 OVP_VTH_Falling(OVP_UVLO_FALLING_5V)





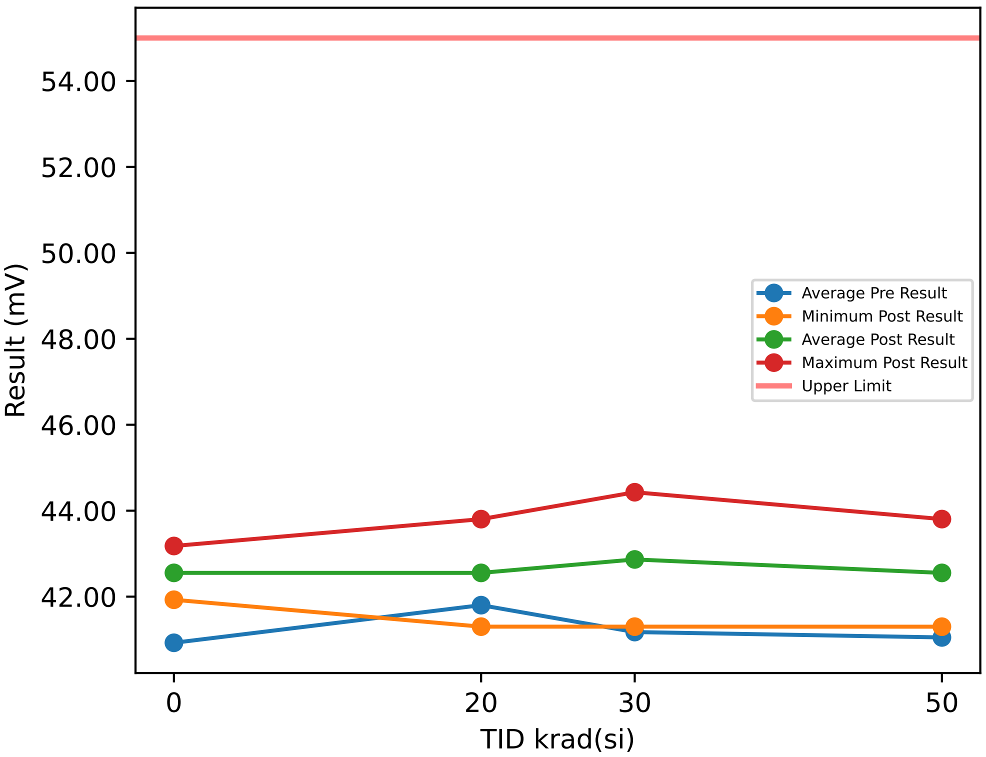
Test Results (Lower Limit = 0.5, Upper Limit = 0.59 (V))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.5497	0.5503	0.0006
2	20	Unbiased	0.5534	0.5547	0.0013
3	20	Unbiased	0.5616	0.561	-0.0006
4	20	Unbiased	0.5541	0.5541	0
5	20	Unbiased	0.5553	0.5547	-0.0006
6	20	7V Biased	0.5522	0.5528	0.0006
7	20	7V Biased	0.5628	0.5616	-0.0012
8	20	7V Biased	0.5591	0.5597	0.0006
9	20	7V Biased	0.5578	0.5584	0.0006
10	20	7V Biased	0.5491	0.5484	-0.0007
11	30	Unbiased	0.5516	0.5516	0
12	30	Unbiased	0.5553	0.5559	0.0006
13	30	Unbiased	0.5578	0.5584	0.0006
14	30	Unbiased	0.5578	0.5578	0
15	30	Unbiased	0.5566	0.5566	0
16	30	7V Biased	0.539	0.5403	0.0013
17	30	7V Biased	0.5459	0.5472	0.0013
18	30	7V Biased	0.5553	0.5553	0
19	30	7V Biased	0.5484	0.5497	0.0013
20	30	7V Biased	0.5534	0.5541	0.0007
21	50	Unbiased	0.5509	0.5522	0.0013
22	50	Unbiased	0.5416	0.5428	0.0012
23	50	Unbiased	0.5491	0.5478	-0.0013
24	50	Unbiased	0.5522	0.5528	0.0006
25	50	Unbiased	0.5522	0.5522	0
26	50	7V Biased	0.5547	0.5553	0.0006
27	50	7V Biased	0.5484	0.5516	0.0032
28	50	7V Biased	0.5497	0.5522	0.0025
29	50	7V Biased	0.5466	0.5509	0.0043
30	50	7V Biased	0.5503	0.5541	0.0038
31	0	Correlation	0.5497	0.5491	-0.0006
32	0	Correlation	0.5559	0.5553	-0.0006
33	0	Correlation	0.5466	0.5459	-0.0007
34	0	Correlation	0.5466	0.5459	-0.0007
35	0	Correlation	0.5503	0.5503	0

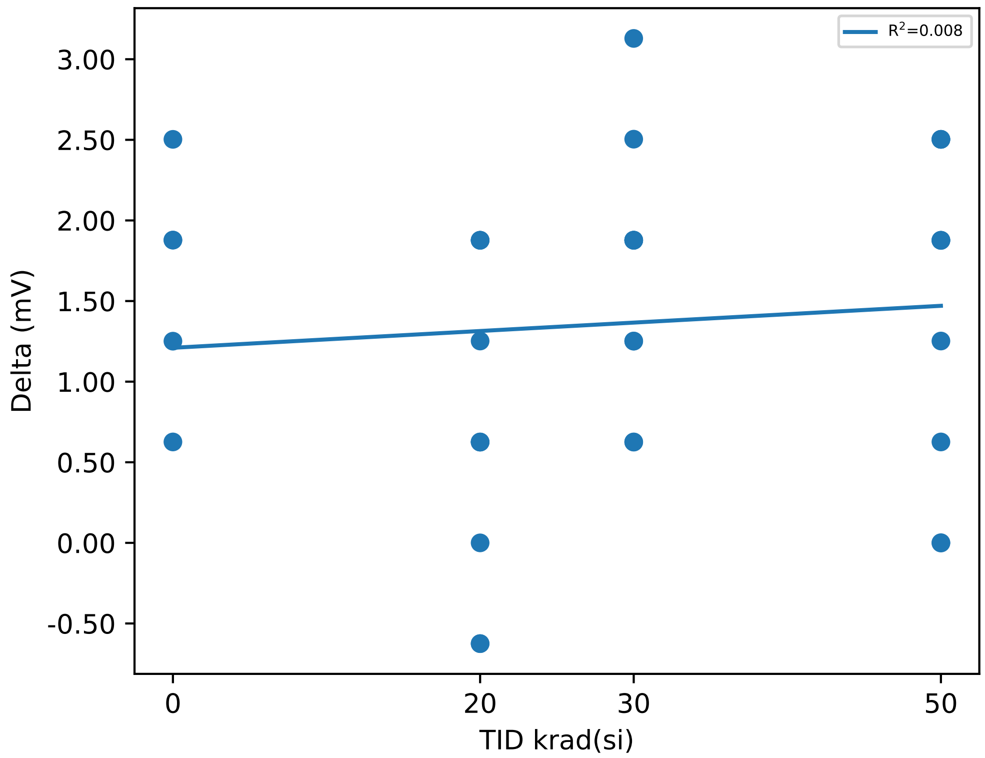
Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5466	0.54982	0.5559	0.0038062	0.5459	0.5493	0.5553	0.0038781	-0.0007	-0.00052	0	0.00029496
20	0.5491	0.55551	0.5628	0.0047217	0.5484	0.55557	0.5616	0.00449	-0.0012	6e-05	0.0013	0.00079889
30	0.539	0.55211	0.5578	0.006068	0.5403	0.55269	0.5584	0.0056459	0	0.00058	0.0013	0.00056921
50	0.5416	0.54957	0.5547	0.0035963	0.5428	0.55119	0.5553	0.0035457	-0.0013	0.00162	0.0043	0.0017862

Device Test: 7.11 OVP_HYST(OVP_UVLO_HYSTERESIS_5V)



TID vs Result Stats



TID vs Post - Pre Exposure Delta

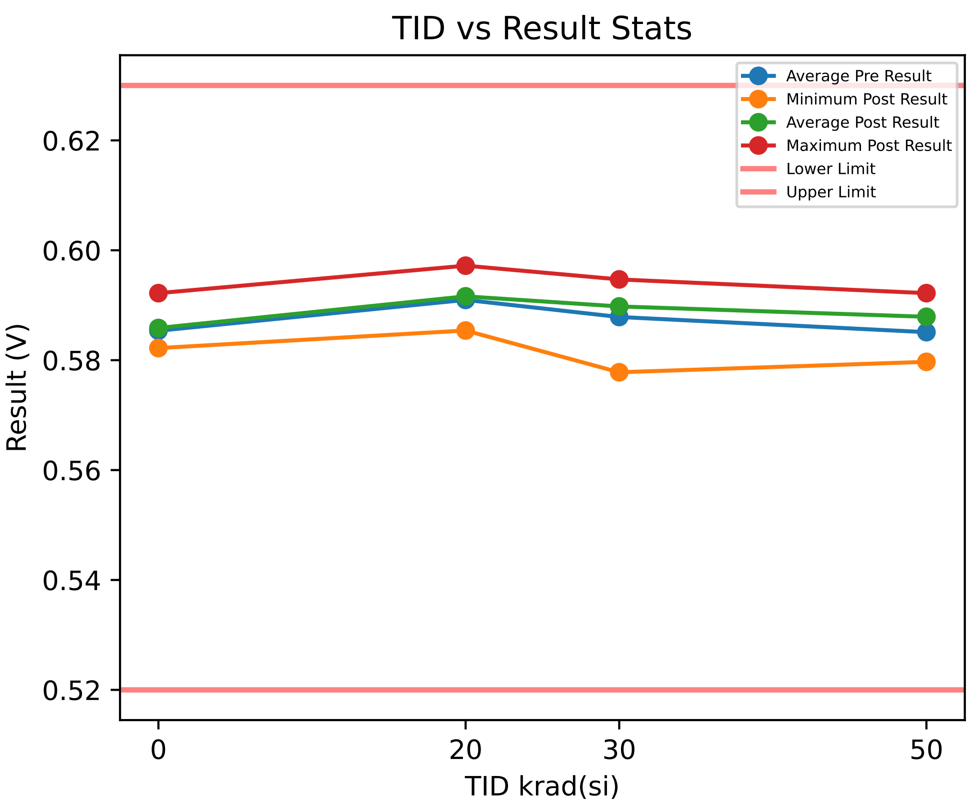
Test Results (Upper Limit = 55.0 (mV))

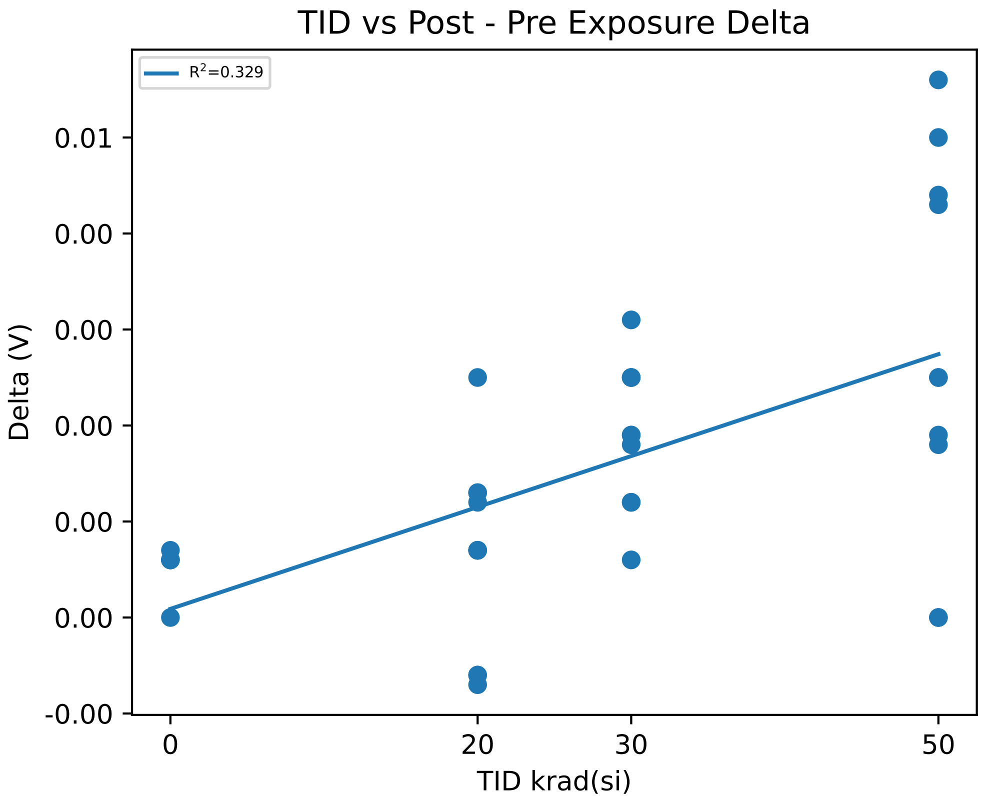
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	41.302	41.927	0.625
2	20	Unbiased	43.179	42.554	-0.625
3	20	Unbiased	42.553	41.928	-0.625
4	20	Unbiased	43.179	43.179	0
5	20	Unbiased	40.676	41.302	0.626
6	20	7V Biased	41.302	43.179	1.877
7	20	7V Biased	41.301	42.553	1.252
8	20	7V Biased	41.927	43.804	1.877
9	20	7V Biased	41.302	41.927	0.625
10	20	7V Biased	41.302	43.179	1.877
11	30	Unbiased	41.302	43.179	1.877
12	30	Unbiased	41.302	43.179	1.877
13	30	Unbiased	41.302	41.927	0.625
14	30	Unbiased	41.302	42.553	1.251
15	30	Unbiased	41.301	42.553	1.252
16	30	7V Biased	41.301	43.179	1.878
17	30	7V Biased	40.676	41.302	0.626
18	30	7V Biased	41.302	43.179	1.877
19	30	7V Biased	40.675	43.179	2.504
20	30	7V Biased	41.301	44.43	3.129
21	50	Unbiased	41.301	41.302	0.001
22	50	Unbiased	41.302	43.178	1.876
23	50	Unbiased	40.05	41.927	1.877
24	50	Unbiased	41.302	43.805	2.503
25	50	Unbiased	40.676	41.302	0.626
26	50	7V Biased	40.676	42.553	1.877
27	50	7V Biased	41.927	43.179	1.252
28	50	7V Biased	41.302	43.805	2.503
29	50	7V Biased	41.302	41.301	-0.001
30	50	7V Biased	40.676	43.179	2.503
31	0	Correlation	40.676	42.554	1.878
32	0	Correlation	40.676	43.179	2.503
33	0	Correlation	41.302	41.928	0.626
34	0	Correlation	40.676	42.554	1.878
35	0	Correlation	41.302	42.553	1.251

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	40.676	40.926	41.302	0.34287	41.928	42.554	43.179	0.4423	0.626	1.6272	2.503	0.71357
20	40.676	41.802	43.179	0.87501	41.302	42.553	43.804	0.78031	-0.625	0.7509	1.877	0.96912
30	40.675	41.176	41.302	0.264	41.302	42.866	44.43	0.8472	0.625	1.6896	3.129	0.78347
50	40.05	41.051	41.927	0.52765	41.301	42.553	43.805	1.0219	-0.001	1.5017	2.503	0.98708

Device Test: 7.12 OVP_VTH_Rising(OVP_UVLO_RISING_7V)





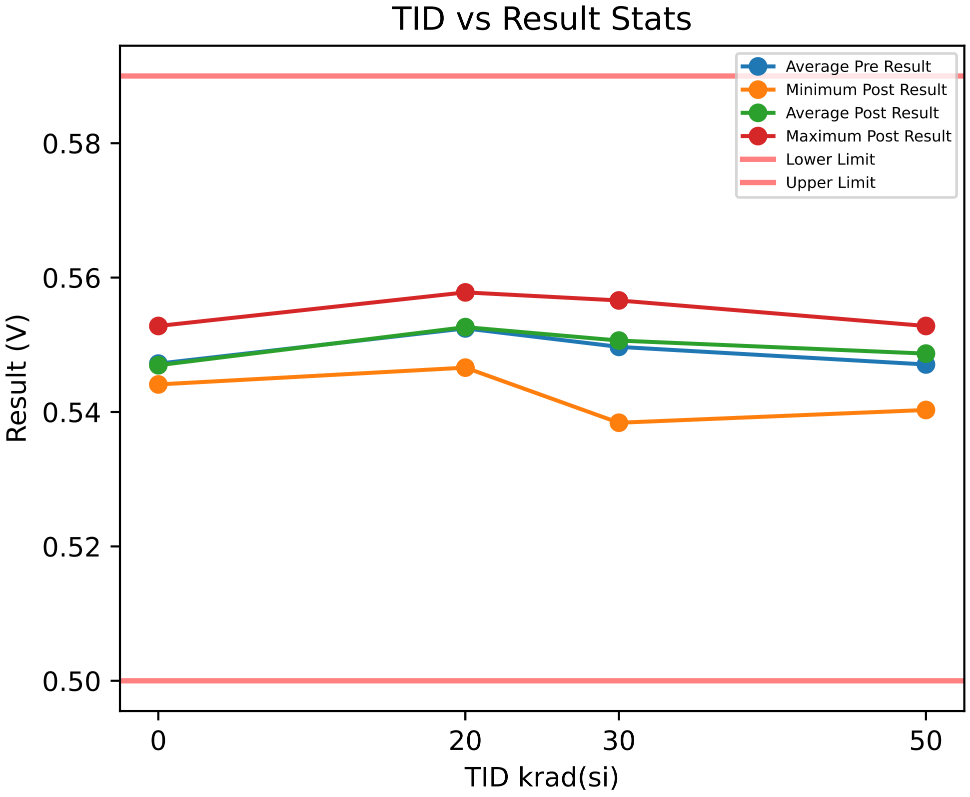
Test Results (Lower Limit = 0.52, Upper Limit = 0.63 (V))

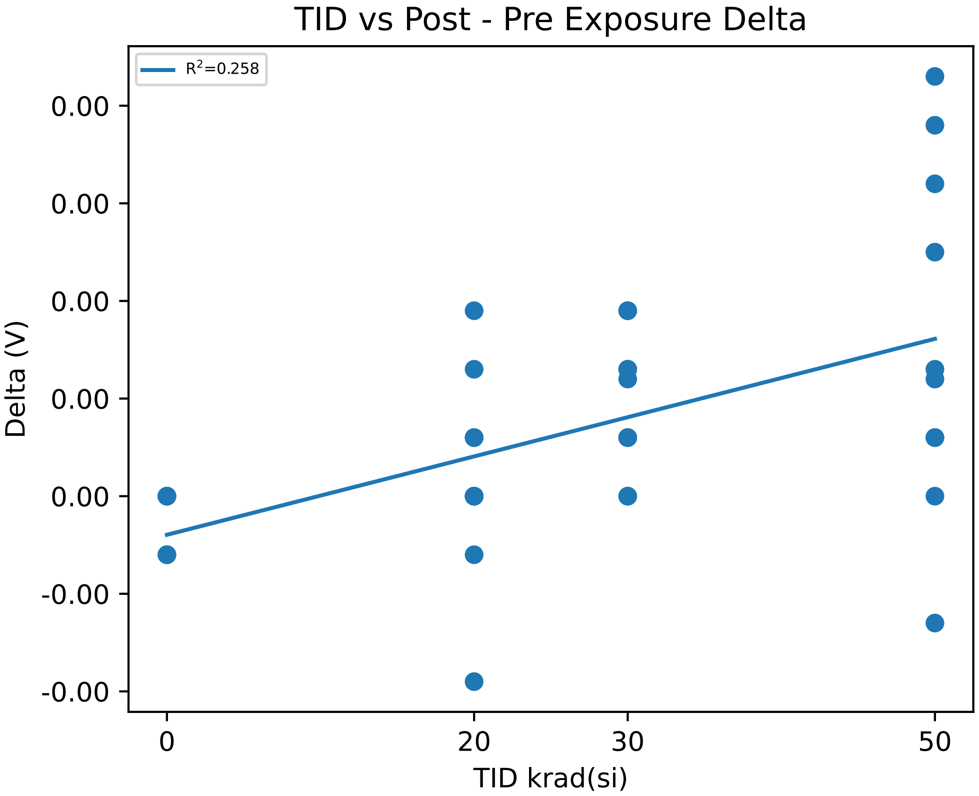
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.5847	0.5854	0.0007
2	20	Unbiased	0.5891	0.5904	0.0013
3	20	Unbiased	0.5972	0.5966	-0.0006
4	20	Unbiased	0.591	0.5904	-0.0006
5	20	Unbiased	0.5897	0.5904	0.0007
6	20	7V Biased	0.5872	0.5897	0.0025
7	20	7V Biased	0.5979	0.5972	-0.0007
8	20	7V Biased	0.5947	0.596	0.0013
9	20	7V Biased	0.5935	0.5947	0.0012
10	20	7V Biased	0.5847	0.5854	0.0007
11	30	Unbiased	0.5872	0.5891	0.0019
12	30	Unbiased	0.5904	0.5922	0.0018
13	30	Unbiased	0.5935	0.5947	0.0012
14	30	Unbiased	0.5941	0.5947	0.0006
15	30	Unbiased	0.5929	0.5941	0.0012
16	30	7V Biased	0.5753	0.5778	0.0025
17	30	7V Biased	0.5804	0.5829	0.0025
18	30	7V Biased	0.5916	0.5935	0.0019
19	30	7V Biased	0.5841	0.5866	0.0025
20	30	7V Biased	0.5891	0.5922	0.0031
21	50	Unbiased	0.5872	0.5891	0.0019
22	50	Unbiased	0.5772	0.5797	0.0025
23	50	Unbiased	0.5841	0.5841	0
24	50	Unbiased	0.5879	0.5897	0.0018
25	50	Unbiased	0.5872	0.5872	0
26	50	7V Biased	0.5897	0.5922	0.0025
27	50	7V Biased	0.5847	0.5891	0.0044
28	50	7V Biased	0.5854	0.5897	0.0043
29	50	7V Biased	0.5822	0.5872	0.005
30	50	7V Biased	0.5854	0.591	0.0056
31	0	Correlation	0.5854	0.586	0.0006
32	0	Correlation	0.5916	0.5922	0.0006
33	0	Correlation	0.5822	0.5822	0
34	0	Correlation	0.5822	0.5829	0.0007
35	0	Correlation	0.5854	0.586	0.0006

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5822	0.58536	0.5916	0.0038377	0.5822	0.58586	0.5922	0.0039494	0	0.0005	0.0007	0.00028284
20	0.5847	0.59097	0.5979	0.0047738	0.5854	0.59162	0.5972	0.0043479	-0.0007	0.00065	0.0025	0.0010288
30	0.5753	0.58786	0.5941	0.0062013	0.5778	0.58978	0.5947	0.005716	0.0006	0.00192	0.0031	0.00075982
50	0.5772	0.5851	0.5897	0.0034957	0.5797	0.5879	0.5922	0.0036533	0	0.0028	0.0056	0.0019765

Device Test: 7.13 OVP_VTH_Falling(OVP_UVLO_FALLING_7V)





Test Results (Lower Limit = 0.5, Upper Limit = 0.59 (V))

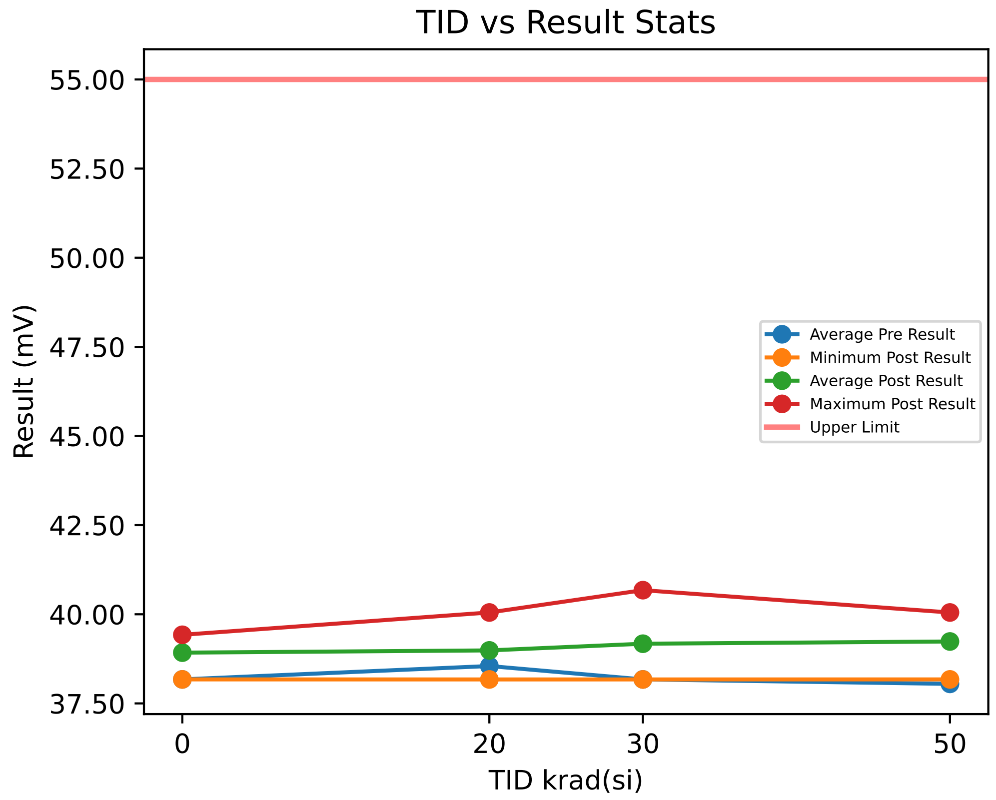
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.5466	0.5472	0.0006
2	20	Unbiased	0.5497	0.5516	0.0019
3	20	Unbiased	0.5578	0.5578	0
4	20	Unbiased	0.5509	0.5509	0
5	20	Unbiased	0.5528	0.5522	-0.0006
6	20	7V Biased	0.5491	0.5497	0.0006
7	20	7V Biased	0.5597	0.5578	-0.0019
8	20	7V Biased	0.5559	0.5559	0
9	20	7V Biased	0.5553	0.5566	0.0013
10	20	7V Biased	0.5466	0.5466	0
11	30	Unbiased	0.5491	0.5491	0
12	30	Unbiased	0.5522	0.5528	0.0006
13	30	Unbiased	0.5553	0.5566	0.0013
14	30	Unbiased	0.5553	0.5559	0.0006
15	30	Unbiased	0.5547	0.5553	0.0006
16	30	7V Biased	0.5372	0.5384	0.0012
17	30	7V Biased	0.5428	0.5447	0.0019
18	30	7V Biased	0.5541	0.5541	0
19	30	7V Biased	0.5459	0.5478	0.0019
20	30	7V Biased	0.5503	0.5516	0.0013
21	50	Unbiased	0.5491	0.5503	0.0012
22	50	Unbiased	0.539	0.5403	0.0013
23	50	Unbiased	0.5466	0.5453	-0.0013
24	50	Unbiased	0.5497	0.5503	0.0006
25	50	Unbiased	0.5491	0.5491	0
26	50	7V Biased	0.5522	0.5528	0.0006
27	50	7V Biased	0.5459	0.5491	0.0032
28	50	7V Biased	0.5472	0.5497	0.0025
29	50	7V Biased	0.5441	0.5484	0.0043
30	50	7V Biased	0.5478	0.5516	0.0038
31	0	Correlation	0.5472	0.5466	-0.0006
32	0	Correlation	0.5528	0.5528	0
33	0	Correlation	0.5441	0.5441	0
34	0	Correlation	0.5441	0.5441	0
35	0	Correlation	0.5478	0.5472	-0.0006

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5441	0.5472	0.5528	0.0035686	0.5441	0.54696	0.5528	0.0035585	-0.0006	-0.00024	0	0.00032863
20	0.5466	0.55244	0.5597	0.0046063	0.5466	0.55263	0.5578	0.0041976	-0.0019	0.00019	0.0019	0.0010344
30	0.5372	0.54969	0.5553	0.0060768	0.5384	0.55063	0.5566	0.0057542	0	0.00094	0.0019	0.00068993
50	0.539	0.54707	0.5522	0.0036142	0.5403	0.54869	0.5528	0.003557	-0.0013	0.00162	0.0043	0.0017862

Device Test: 7.14 OVP_HYST(OVP_UVLO_HYSTERESIS_7V)

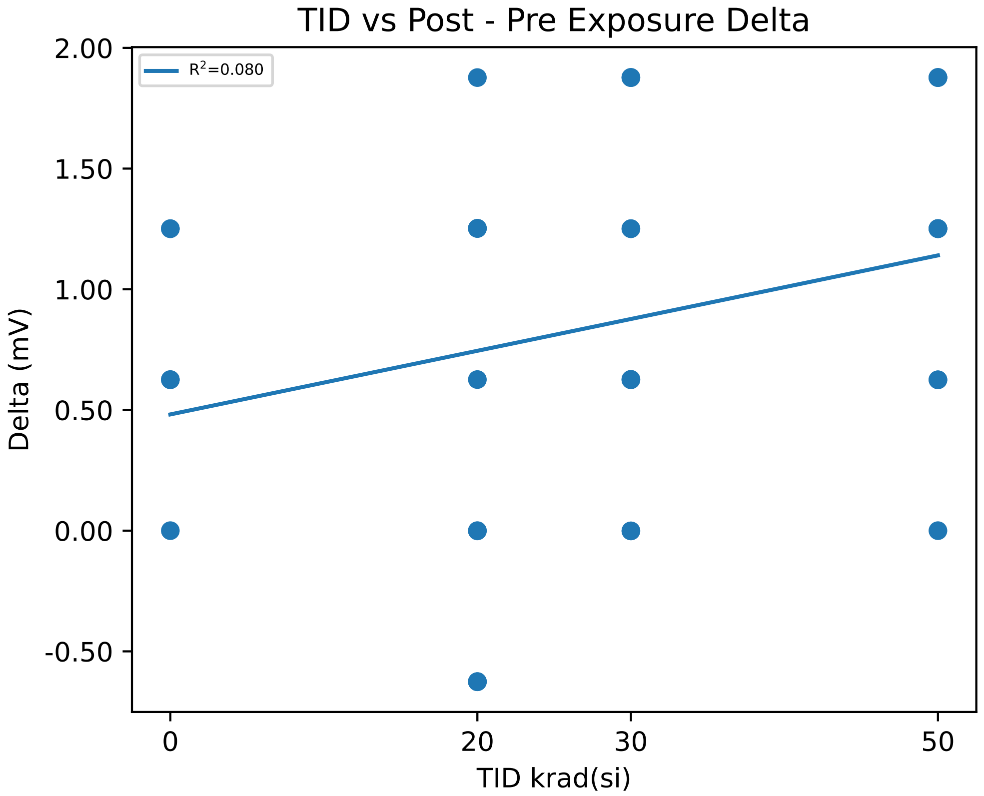
TID vs Result Stats



Test Results (Upper Limit = 55.0 (mV))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	38.173	38.173	0
2	20	Unbiased	39.424	38.799	-0.625
3	20	Unbiased	39.425	38.799	-0.626
4	20	Unbiased	40.05	39.424	-0.626
5	20	Unbiased	36.921	38.173	1.252
6	20	7V Biased	38.173	40.05	1.877
7	20	7V Biased	38.172	39.425	1.253
8	20	7V Biased	38.798	40.05	1.252
9	20	7V Biased	38.173	38.172	-0.001
10	20	7V Biased	38.173	38.799	0.626
11	30	Unbiased	38.173	40.05	1.877
12	30	Unbiased	38.173	39.424	1.251
13	30	Unbiased	38.173	38.172	-0.001
14	30	Unbiased	38.799	38.798	-0.001
15	30	Unbiased	38.173	38.799	0.626
16	30	7V Biased	38.173	39.424	1.251
17	30	7V Biased	37.546	38.173	0.627
18	30	7V Biased	37.547	39.424	1.877
19	30	7V Biased	38.173	38.798	0.625
20	30	7V Biased	38.798	40.676	1.878
21	50	Unbiased	38.173	38.798	0.625
22	50	Unbiased	38.173	39.425	1.252
23	50	Unbiased	37.547	38.798	1.251
24	50	Unbiased	38.173	39.424	1.251
25	50	Unbiased	38.173	38.173	0
26	50	7V Biased	37.547	39.424	1.877
27	50	7V Biased	38.799	40.05	1.251
28	50	7V Biased	38.173	40.05	1.877
29	50	7V Biased	38.173	38.798	0.625
30	50	7V Biased	37.547	39.425	1.878
31	0	Correlation	38.173	39.424	1.251
32	0	Correlation	38.799	39.424	0.625
33	0	Correlation	38.173	38.173	0
34	0	Correlation	38.173	38.799	0.626
35	0	Correlation	37.547	38.798	1.251

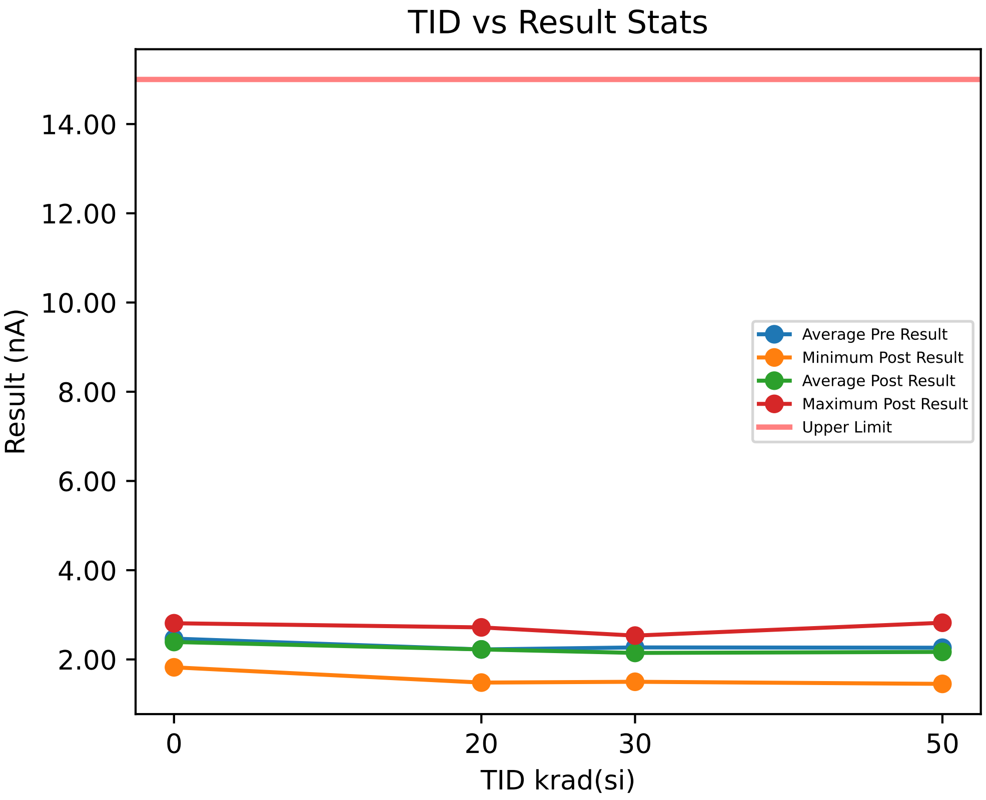
TID vs Post - Pre Exposure Delta

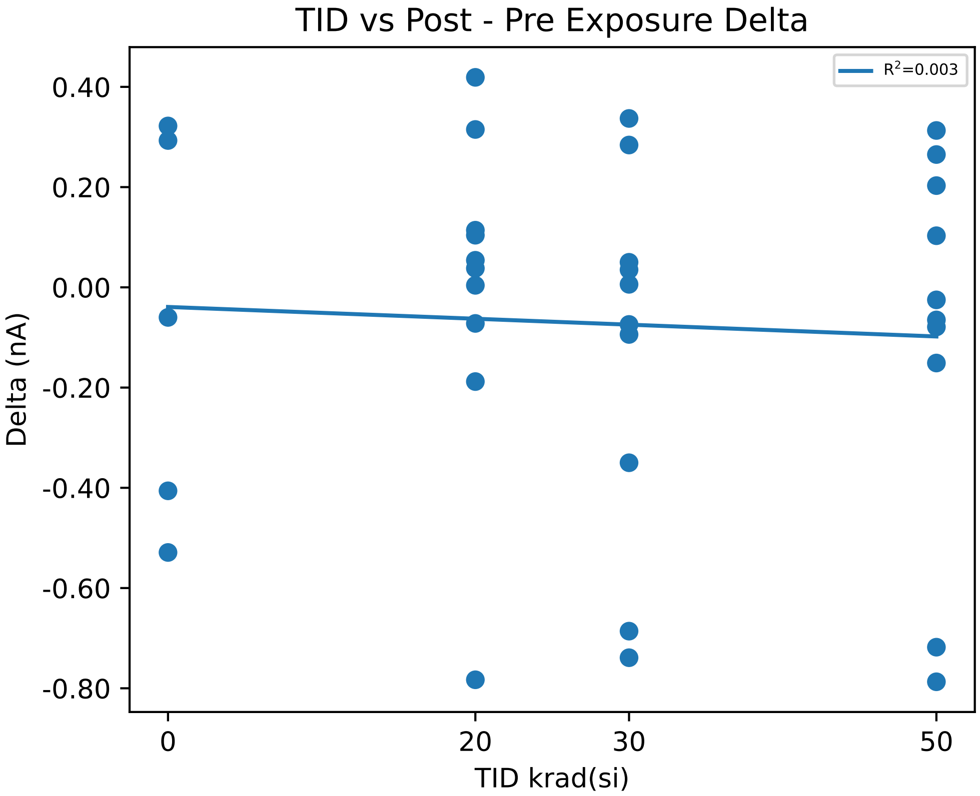


Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	37.547	38.173	38.799	0.44265	38.173	38.924	39.424	0.52333	0	0.7506	1.251	0.52333
20	36.921	38.548	40.05	0.8948	38.172	38.986	40.05	0.72558	-0.626	0.4382	1.877	0.93537
30	37.546	38.173	38.799	0.41733	38.172	39.174	40.676	0.79164	-0.001	1.001	1.878	0.73475
50	37.547	38.048	38.799	0.39592	38.173	39.236	40.05	0.59375	0	1.1887	1.878	0.62243

Device Test: 7.15 OVP_ILEAK(OVP_I_7V)





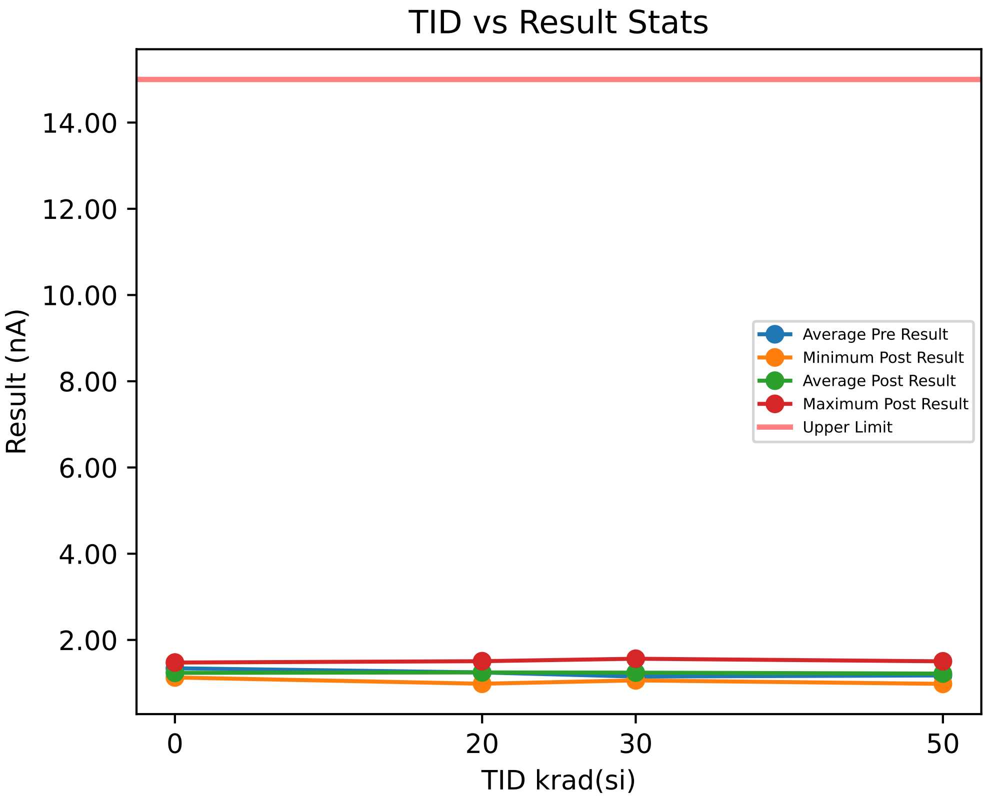
Test Results (Upper Limit = 15.0 (nA))

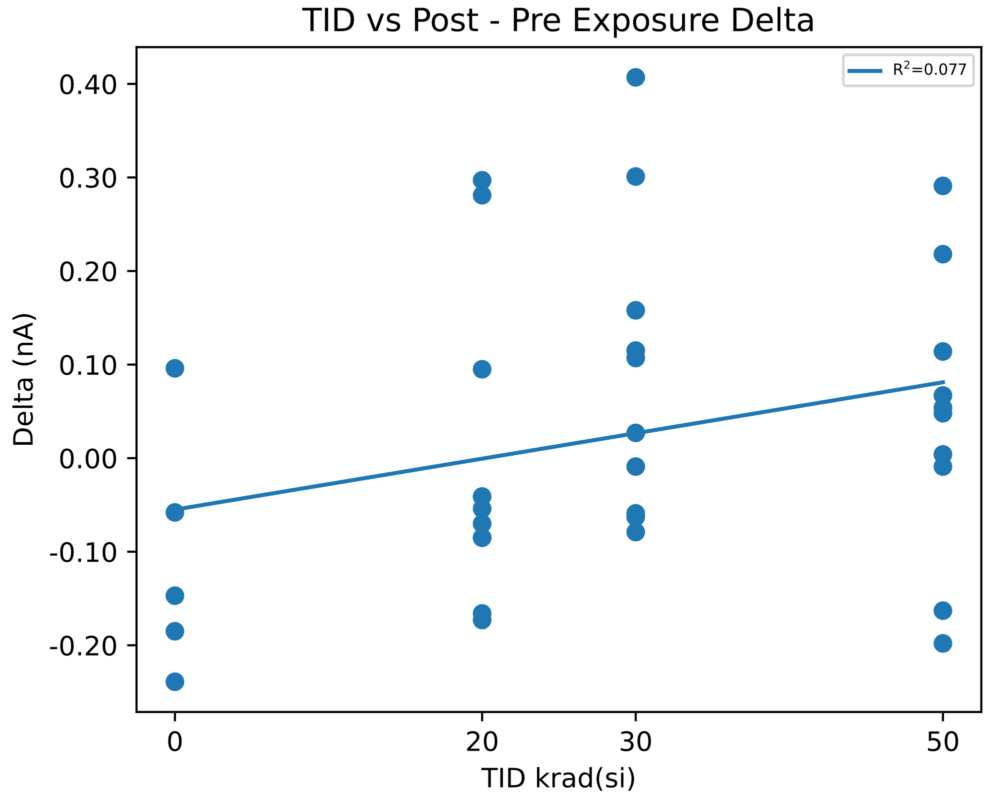
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	2.157	2.261	0.104
2	20	Unbiased	2.406	2.52	0.114
3	20	Unbiased	1.427	1.481	0.054
4	20	Unbiased	2.906	2.718	-0.188
5	20	Unbiased	2.182	2.22	0.038
6	20	7V Biased	2.214	2.633	0.419
7	20	7V Biased	2.264	1.481	-0.783
8	20	7V Biased	2.264	2.268	0.004
9	20	7V Biased	2.185	2.113	-0.072
10	20	7V Biased	2.233	2.548	0.315
11	30	Unbiased	2.308	1.569	-0.739
12	30	Unbiased	2.575	2.501	-0.074
13	30	Unbiased	2.528	2.534	0.006
14	30	Unbiased	2.148	2.432	0.284
15	30	Unbiased	2.123	1.773	-0.35
16	30	7V Biased	2.123	2.158	0.035
17	30	7V Biased	2.154	2.204	0.05
18	30	7V Biased	2.195	2.532	0.337
19	30	7V Biased	2.185	1.499	-0.686
20	30	7V Biased	2.349	2.255	-0.094
21	50	Unbiased	2.173	2.148	-0.025
22	50	Unbiased	2.299	2.564	0.265
23	50	Unbiased	2.17	1.452	-0.718
24	50	Unbiased	2.135	2.07	-0.065
25	50	Unbiased	2.123	2.226	0.103
26	50	7V Biased	2.509	2.822	0.313
27	50	7V Biased	2.255	1.468	-0.787
28	50	7V Biased	2.34	2.189	-0.151
29	50	7V Biased	2.264	2.185	-0.079
30	50	7V Biased	2.358	2.561	0.203
31	0	Correlation	2.374	1.968	-0.406
32	0	Correlation	2.299	2.592	0.293
33	0	Correlation	2.871	2.811	-0.06
34	0	Correlation	2.437	2.759	0.322
35	0	Correlation	2.352	1.823	-0.529

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.299	2.4666	2.871	0.23142	1.823	2.3906	2.811	0.462	-0.529	-0.076	0.322	0.39017
20	1.427	2.2238	2.906	0.35662	1.481	2.2243	2.718	0.43763	-0.783	0.0005	0.419	0.32602
30	2.123	2.2688	2.575	0.16722	1.499	2.1457	2.534	0.39629	-0.739	-0.1231	0.337	0.36515
50	2.123	2.2626	2.509	0.11998	1.452	2.1685	2.822	0.44168	-0.787	-0.0941	0.313	0.38009

Device Test: 7.16 OVP_ILEAK(OVP_I_5V)





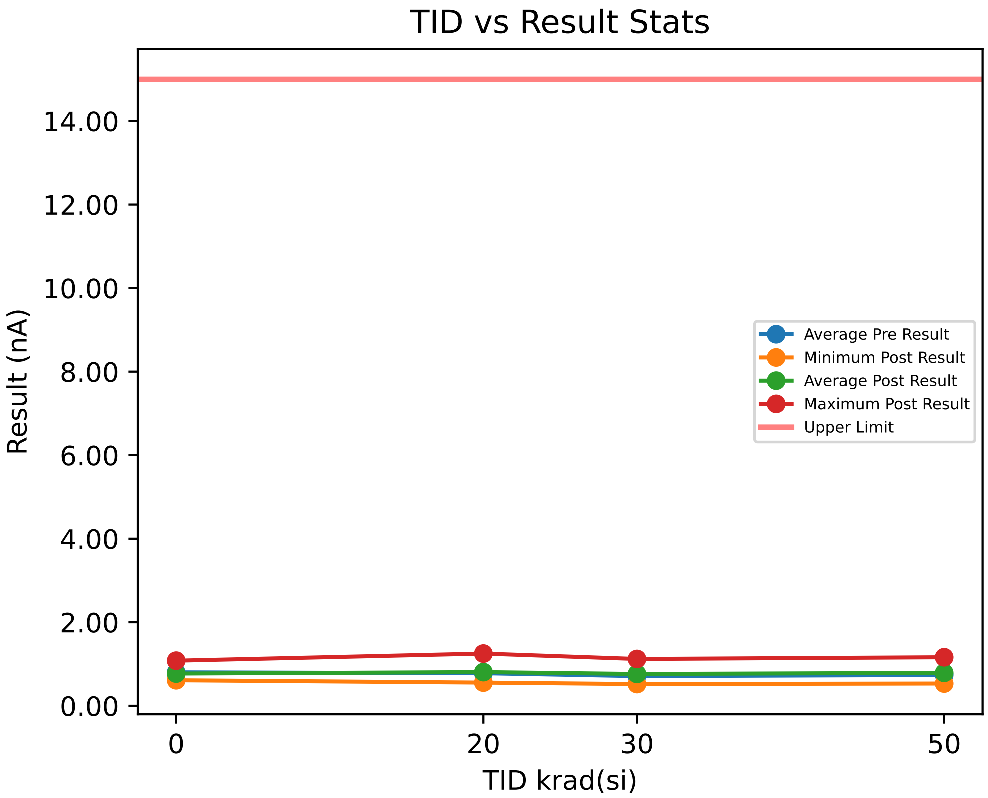
Test Results (Upper Limit = 15.0 (nA))

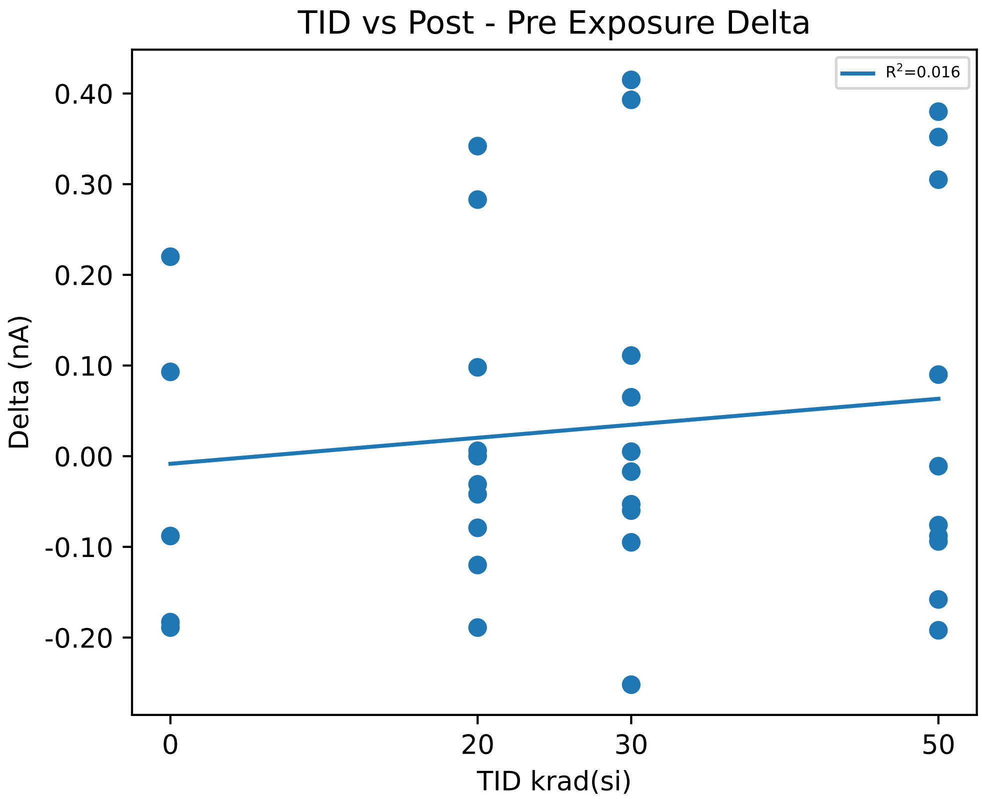
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	1.113	1.028	-0.085
2	20	Unbiased	1.485	1.4	-0.085
3	20	Unbiased	1.139	1.069	-0.07
4	20	Unbiased	1.548	1.494	-0.054
5	20	Unbiased	1.157	0.984	-0.173
6	20	7V Biased	1.207	1.504	0.297
7	20	7V Biased	1.301	1.135	-0.166
8	20	7V Biased	1.201	1.296	0.095
9	20	7V Biased	1.088	1.047	-0.041
10	20	7V Biased	1.226	1.507	0.281
11	30	Unbiased	1.116	1.107	-0.009
12	30	Unbiased	1.279	1.394	0.115
13	30	Unbiased	1.201	1.122	-0.079
14	30	Unbiased	1.157	1.564	0.407
15	30	Unbiased	1.044	1.151	0.107
16	30	7V Biased	1.056	1.214	0.158
17	30	7V Biased	1.125	1.062	-0.063
18	30	7V Biased	1.15	1.451	0.301
19	30	7V Biased	1.144	1.085	-0.059
20	30	7V Biased	1.235	1.262	0.027
21	50	Unbiased	1.144	0.981	-0.163
22	50	Unbiased	1.245	1.463	0.218
23	50	Unbiased	1.081	1.129	0.048
24	50	Unbiased	1.144	1.148	0.004
25	50	Unbiased	1.084	1.075	-0.009
26	50	7V Biased	1.213	1.504	0.291
27	50	7V Biased	1.163	1.217	0.054
28	50	7V Biased	1.201	1.268	0.067
29	50	7V Biased	1.21	1.012	-0.198
30	50	7V Biased	1.286	1.4	0.114
31	0	Correlation	1.276	1.129	-0.147
32	0	Correlation	1.257	1.199	-0.058
33	0	Correlation	1.443	1.204	-0.239
34	0	Correlation	1.38	1.476	0.096
35	0	Correlation	1.358	1.173	-0.185

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.257	1.3428	1.443	0.076614	1.129	1.2362	1.476	0.13731	-0.239	-0.1066	0.096	0.13107
20	1.088	1.2465	1.548	0.15539	0.984	1.2464	1.507	0.21649	-0.173	-0.0001	0.297	0.16919
30	1.044	1.1507	1.279	0.073333	1.062	1.2412	1.564	0.17308	-0.079	0.0905	0.407	0.16278
50	1.081	1.1771	1.286	0.06642	0.981	1.2197	1.504	0.18538	-0.198	0.0426	0.291	0.15005

Device Test: 7.17 OVP_ILEAK(OVP_I_3p3V)





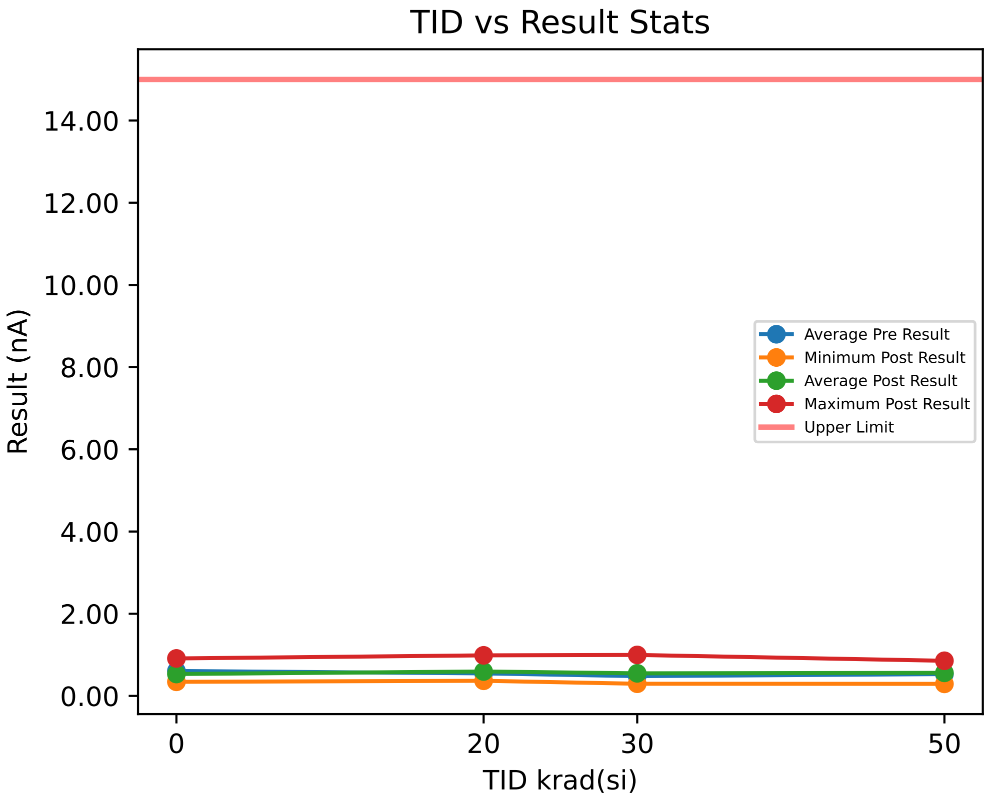
Test Results (Upper Limit = 15.0 (nA))

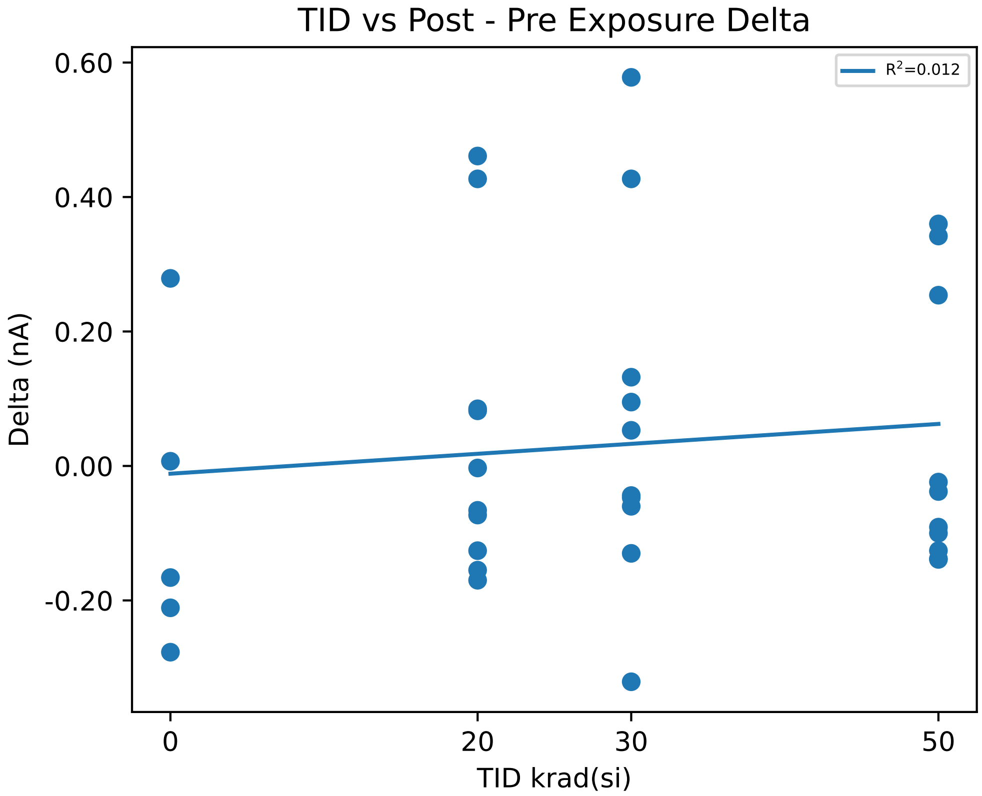
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.653	0.659	0.006
2	20	Unbiased	1.152	1.25	0.098
3	20	Unbiased	0.586	0.586	0
4	20	Unbiased	0.919	0.799	-0.12
5	20	Unbiased	0.7	0.621	-0.079
6	20	7V Biased	0.81	1.152	0.342
7	20	7V Biased	0.744	0.555	-0.189
8	20	7V Biased	0.728	0.686	-0.042
9	20	7V Biased	0.709	0.678	-0.031
10	20	7V Biased	0.794	1.077	0.283
11	30	Unbiased	0.691	0.596	-0.095
12	30	Unbiased	0.703	0.768	0.065
13	30	Unbiased	0.697	0.637	-0.06
14	30	Unbiased	0.706	1.099	0.393
15	30	Unbiased	0.65	0.633	-0.017
16	30	7V Biased	0.735	0.846	0.111
17	30	7V Biased	0.687	0.634	-0.053
18	30	7V Biased	0.706	1.121	0.415
19	30	7V Biased	0.772	0.52	-0.252
20	30	7V Biased	0.76	0.765	0.005
21	50	Unbiased	0.744	0.65	-0.094
22	50	Unbiased	0.744	1.049	0.305
23	50	Unbiased	0.631	0.555	-0.076
24	50	Unbiased	0.757	0.746	-0.011
25	50	Unbiased	0.813	0.621	-0.192
26	50	7V Biased	0.75	1.13	0.38
27	50	7V Biased	0.691	0.533	-0.158
28	50	7V Biased	0.716	0.806	0.09
29	50	7V Biased	0.716	0.628	-0.088
30	50	7V Biased	0.81	1.162	0.352
31	0	Correlation	0.819	0.63	-0.189
32	0	Correlation	0.747	0.84	0.093
33	0	Correlation	0.785	0.697	-0.088
34	0	Correlation	0.86	1.08	0.22
35	0	Correlation	0.794	0.611	-0.183

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.747	0.801	0.86	0.041911	0.611	0.7716	1.08	0.19442	-0.189	-0.0294	0.22	0.18006
20	0.586	0.7795	1.152	0.15917	0.555	0.8063	1.25	0.25568	-0.189	0.0268	0.342	0.16951
30	0.65	0.7107	0.772	0.036062	0.52	0.7619	1.121	0.20665	-0.252	0.0512	0.415	0.20983
50	0.631	0.7372	0.813	0.053754	0.533	0.788	1.162	0.24011	-0.192	0.0508	0.38	0.21805

Device Test: 7.18 OVP_ILEAK(OVP_I_1p8V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

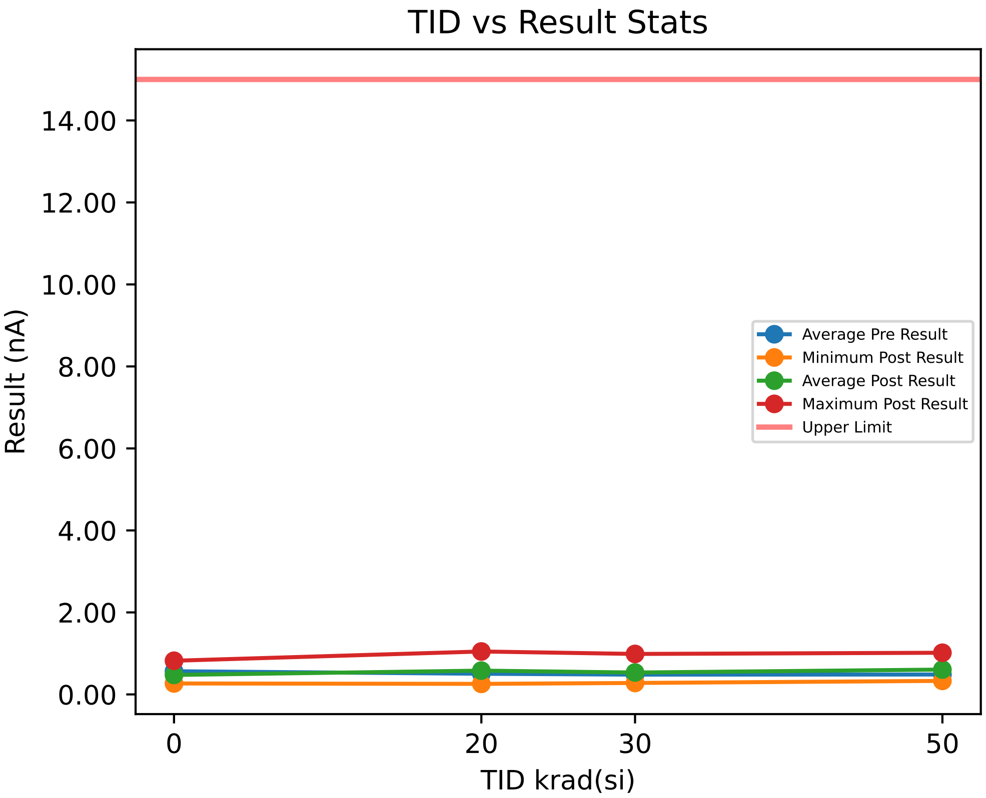
Test Results (Upper Limit = 15.0 (nA))

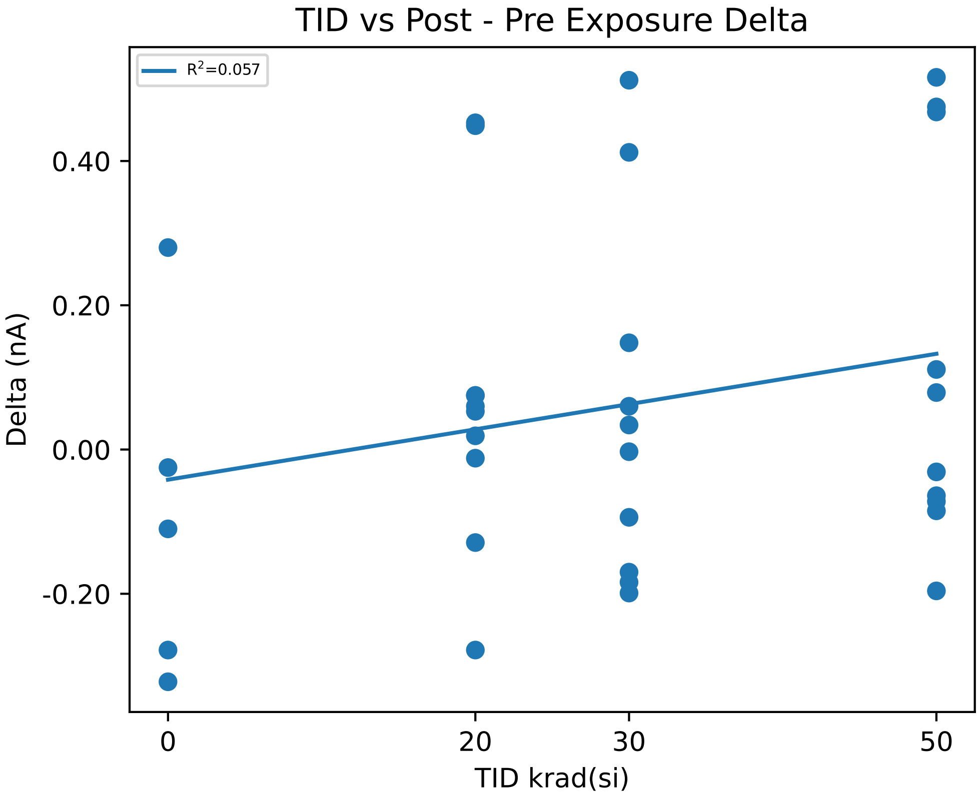
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.504	0.378	-0.126
2	20	Unbiased	1.047	0.877	-0.17
3	20	Unbiased	0.287	0.372	0.085
4	20	Unbiased	0.533	0.53	-0.003
5	20	Unbiased	0.498	0.425	-0.073
6	20	7V Biased	0.494	0.921	0.427
7	20	7V Biased	0.523	0.368	-0.155
8	20	7V Biased	0.548	0.63	0.082
9	20	7V Biased	0.523	0.457	-0.066
10	20	7V Biased	0.526	0.987	0.461
11	30	Unbiased	0.617	0.296	-0.321
12	30	Unbiased	0.454	0.507	0.053
13	30	Unbiased	0.488	0.444	-0.044
14	30	Unbiased	0.419	0.997	0.578
15	30	Unbiased	0.46	0.4	-0.06
16	30	7V Biased	0.454	0.586	0.132
17	30	7V Biased	0.507	0.46	-0.047
18	30	7V Biased	0.469	0.896	0.427
19	30	7V Biased	0.454	0.324	-0.13
20	30	7V Biased	0.491	0.586	0.095
21	50	Unbiased	0.535	0.397	-0.138
22	50	Unbiased	0.482	0.842	0.36
23	50	Unbiased	0.432	0.293	-0.139
24	50	Unbiased	0.601	0.577	-0.024
25	50	Unbiased	0.551	0.425	-0.126
26	50	7V Biased	0.601	0.855	0.254
27	50	7V Biased	0.454	0.416	-0.038
28	50	7V Biased	0.652	0.552	-0.1
29	50	7V Biased	0.491	0.4	-0.091
30	50	7V Biased	0.51	0.852	0.342
31	0	Correlation	0.586	0.375	-0.211
32	0	Correlation	0.551	0.558	0.007
33	0	Correlation	0.642	0.476	-0.166
34	0	Correlation	0.633	0.912	0.279
35	0	Correlation	0.62	0.343	-0.277

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.551	0.6064	0.642	0.037567	0.343	0.5328	0.912	0.22835	-0.277	-0.0736	0.279	0.22339
20	0.287	0.5483	1.047	0.19045	0.368	0.5945	0.987	0.24522	-0.17	0.0462	0.461	0.22754
30	0.419	0.4813	0.617	0.053682	0.296	0.5496	0.997	0.23127	-0.321	0.0683	0.578	0.26388
50	0.432	0.5309	0.652	0.070733	0.293	0.5609	0.855	0.21463	-0.139	0.03	0.36	0.20457

Device Test: 7.19 OVP_ILEAK(OVP_I_1p5V)





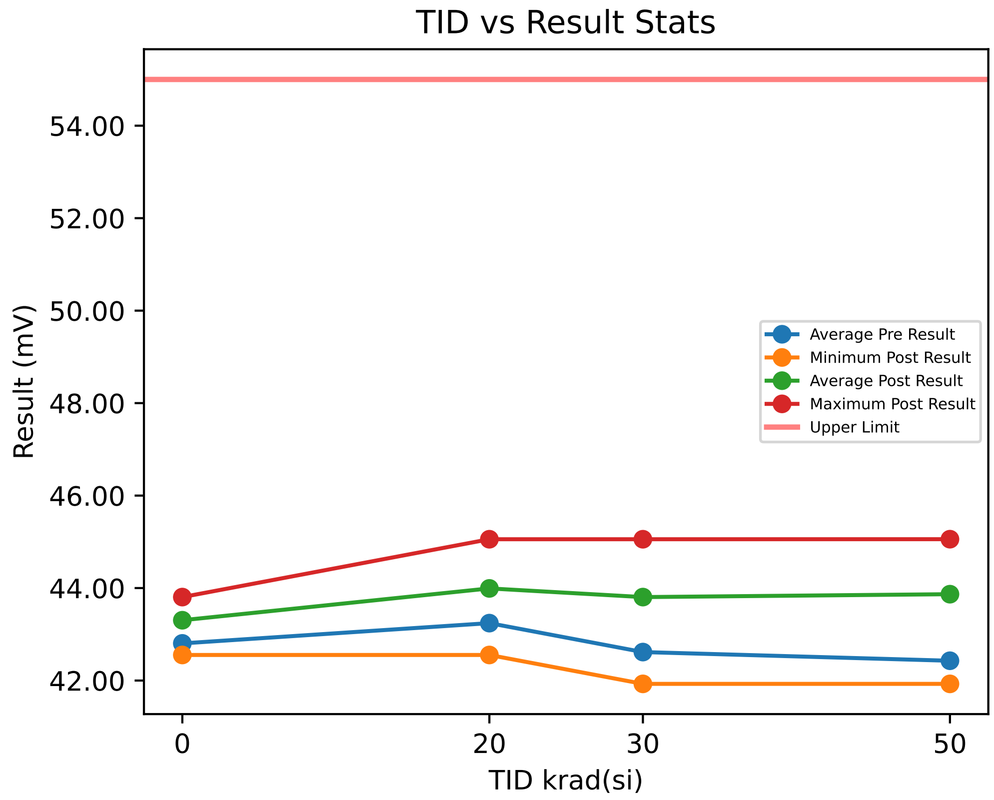
Test Results (Upper Limit = 15.0 (nA))

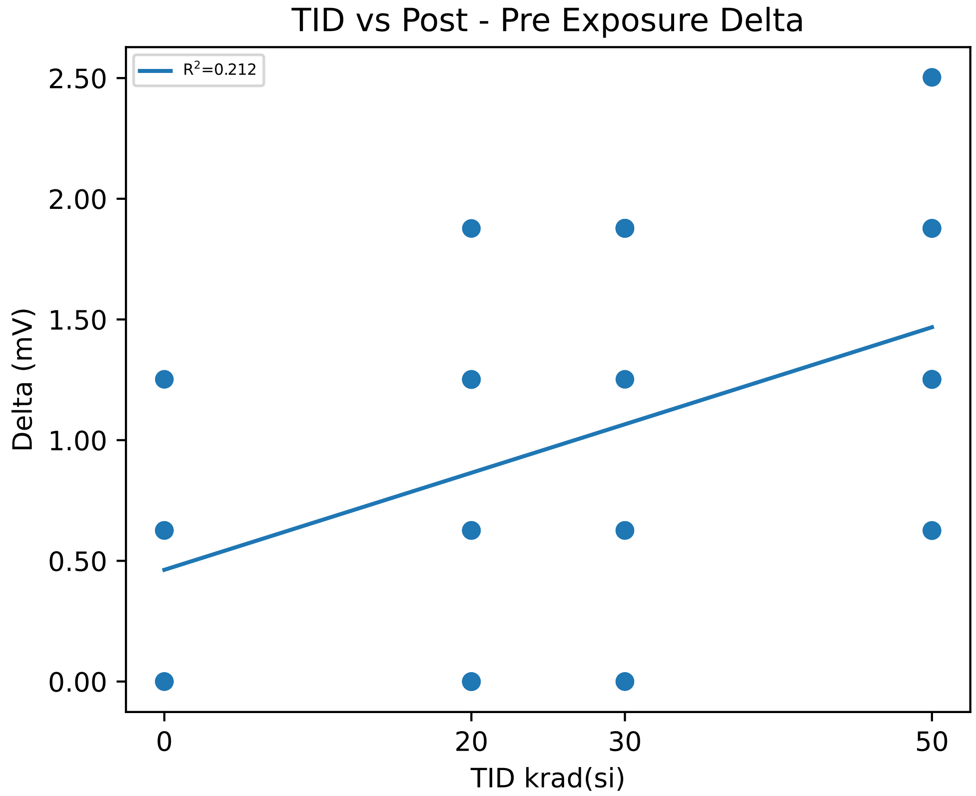
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.356	0.431	0.075
2	20	Unbiased	0.972	1.047	0.075
3	20	Unbiased	0.279	0.339	0.06
4	20	Unbiased	0.507	0.56	0.053
5	20	Unbiased	0.516	0.387	-0.129
6	20	7V Biased	0.529	0.978	0.449
7	20	7V Biased	0.535	0.257	-0.278
8	20	7V Biased	0.441	0.46	0.019
9	20	7V Biased	0.45	0.438	-0.012
10	20	7V Biased	0.45	0.903	0.453
11	30	Unbiased	0.548	0.364	-0.184
12	30	Unbiased	0.428	0.576	0.148
13	30	Unbiased	0.494	0.4	-0.094
14	30	Unbiased	0.469	0.881	0.412
15	30	Unbiased	0.478	0.279	-0.199
16	30	7V Biased	0.494	0.554	0.06
17	30	7V Biased	0.45	0.447	-0.003
18	30	7V Biased	0.475	0.987	0.512
19	30	7V Biased	0.478	0.308	-0.17
20	30	7V Biased	0.507	0.541	0.034
21	50	Unbiased	0.519	0.447	-0.072
22	50	Unbiased	0.5	1.016	0.516
23	50	Unbiased	0.406	0.342	-0.064
24	50	Unbiased	0.434	0.545	0.111
25	50	Unbiased	0.425	0.504	0.079
26	50	7V Biased	0.497	0.972	0.475
27	50	7V Biased	0.526	0.33	-0.196
28	50	7V Biased	0.541	0.51	-0.031
29	50	7V Biased	0.513	0.428	-0.085
30	50	7V Biased	0.491	0.959	0.468
31	0	Correlation	0.554	0.276	-0.278
32	0	Correlation	0.573	0.548	-0.025
33	0	Correlation	0.57	0.46	-0.11
34	0	Correlation	0.541	0.821	0.28
35	0	Correlation	0.589	0.267	-0.322

Test Statistics (nA)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.541	0.5654	0.589	0.018447	0.267	0.4744	0.821	0.22811	-0.322	-0.091	0.28	0.24015
20	0.279	0.5035	0.972	0.18351	0.257	0.58	1.047	0.28629	-0.278	0.0765	0.453	0.22617
30	0.428	0.4821	0.548	0.032419	0.279	0.5337	0.987	0.23531	-0.199	0.0516	0.512	0.24566
50	0.406	0.4852	0.541	0.046671	0.33	0.6053	1.016	0.26933	-0.196	0.1201	0.516	0.2669

Device Test: 7.2 OVP_HYST(OVP_UVLO_HYSTERESIS_1p5V)





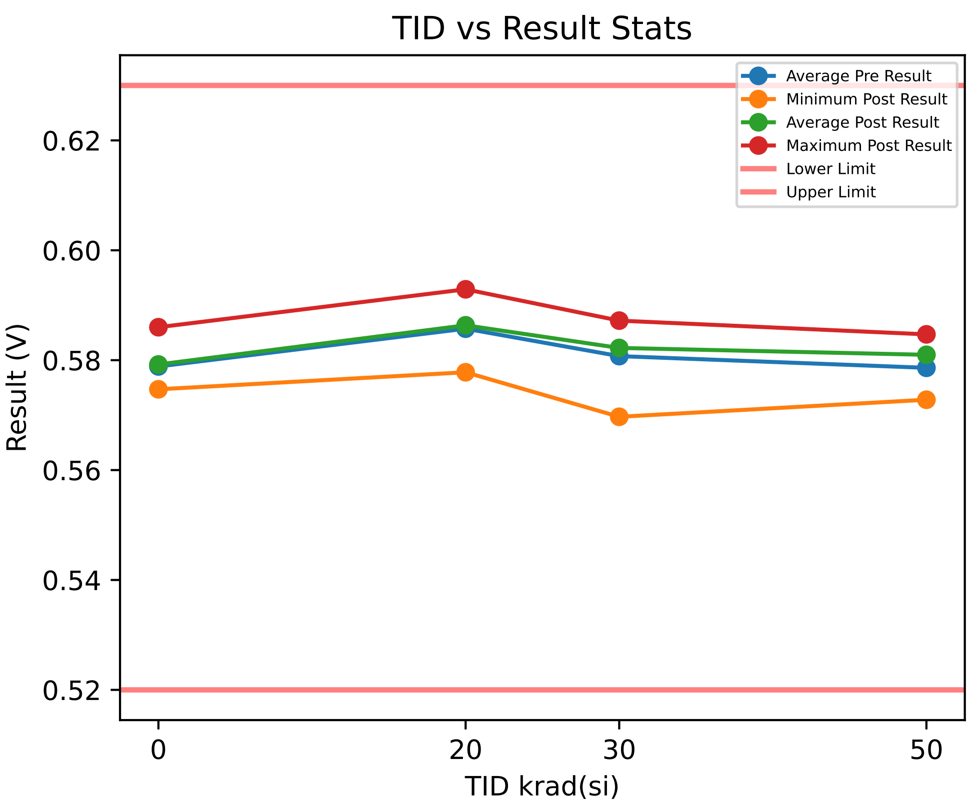
Test Results (Upper Limit = 55.0 (mV))

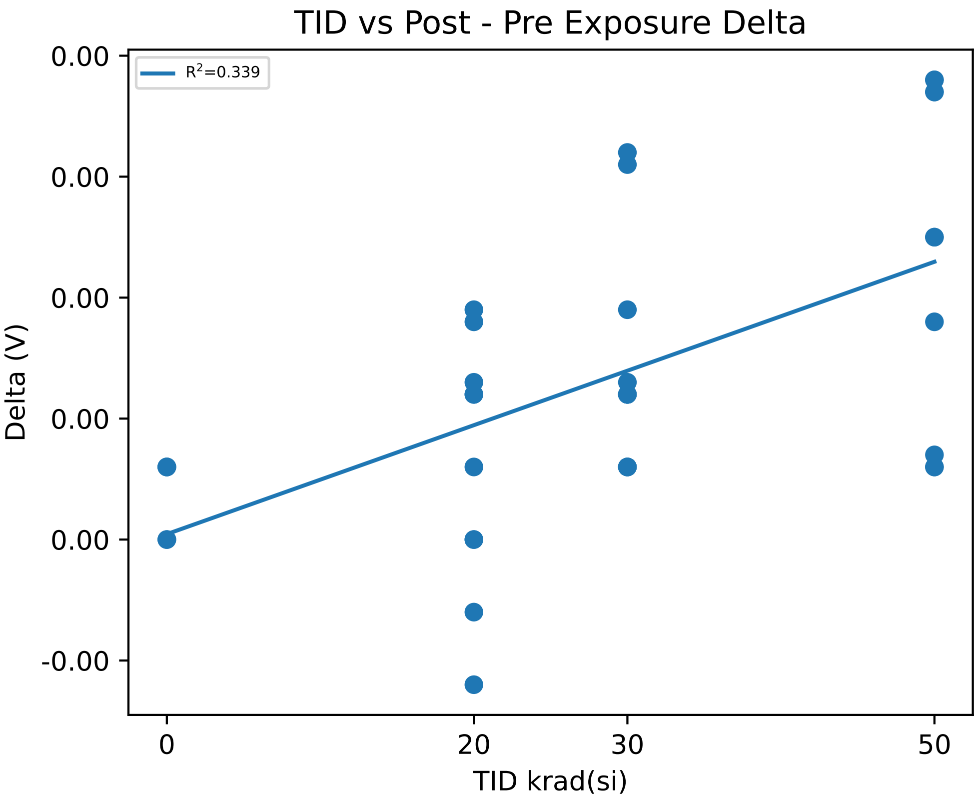
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	42.553	43.179	0.626
2	20	Unbiased	43.805	43.805	0
3	20	Unbiased	43.805	44.431	0.626
4	20	Unbiased	44.43	44.43	0
5	20	Unbiased	42.554	42.553	-0.001
6	20	7V Biased	42.554	44.431	1.877
7	20	7V Biased	43.179	44.43	1.251
8	20	7V Biased	43.805	45.056	1.251
9	20	7V Biased	43.179	43.805	0.626
10	20	7V Biased	42.553	43.805	1.252
11	30	Unbiased	42.553	44.431	1.878
12	30	Unbiased	42.553	44.431	1.878
13	30	Unbiased	43.179	43.805	0.626
14	30	Unbiased	43.179	43.805	0.626
15	30	Unbiased	42.553	43.805	1.252
16	30	7V Biased	41.928	41.928	0
17	30	7V Biased	42.553	42.553	0
18	30	7V Biased	42.553	44.43	1.877
19	30	7V Biased	41.927	43.805	1.878
20	30	7V Biased	43.179	45.056	1.877
21	50	Unbiased	42.553	43.179	0.626
22	50	Unbiased	40.676	41.928	1.252
23	50	Unbiased	41.928	43.179	1.251
24	50	Unbiased	43.179	45.056	1.877
25	50	Unbiased	42.554	43.179	0.625
26	50	7V Biased	42.554	45.057	2.503
27	50	7V Biased	43.179	44.431	1.252
28	50	7V Biased	42.553	44.43	1.877
29	50	7V Biased	42.553	43.805	1.252
30	50	7V Biased	42.553	44.431	1.878
31	0	Correlation	42.553	43.179	0.626
32	0	Correlation	43.179	43.805	0.626
33	0	Correlation	43.179	43.179	0
34	0	Correlation	42.553	42.553	0
35	0	Correlation	42.553	43.805	1.252

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	42.553	42.803	43.179	0.34287	42.553	43.304	43.805	0.52375	0	0.5008	1.252	0.52375
20	42.553	43.242	44.43	0.6885	42.553	43.992	45.056	0.72555	-0.001	0.7508	1.877	0.64629
30	41.927	42.616	43.179	0.46174	41.928	43.805	45.056	0.93274	0	1.1892	1.878	0.80527
50	40.676	42.428	43.179	0.71038	41.928	43.867	45.057	0.99814	0.625	1.4393	2.503	0.5937

Device Test: 7.3 OVP_VTH_Rising(OVP_UVLO_RISING_1p8V)





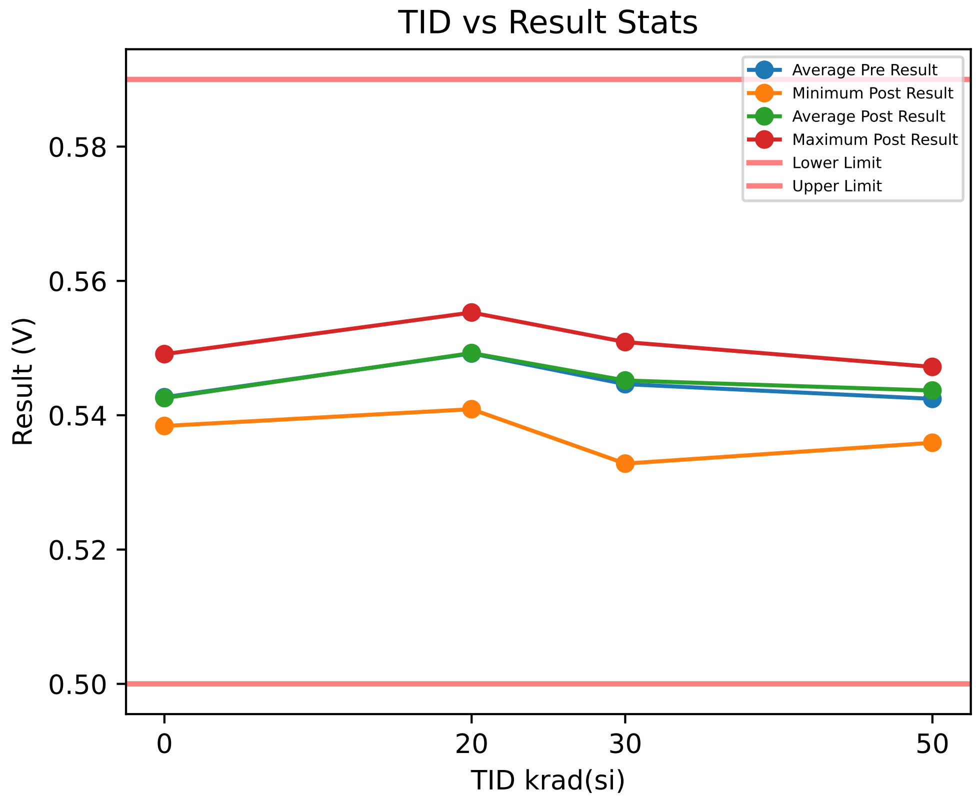
Test Results (Lower Limit = 0.52, Upper Limit = 0.63 (V))

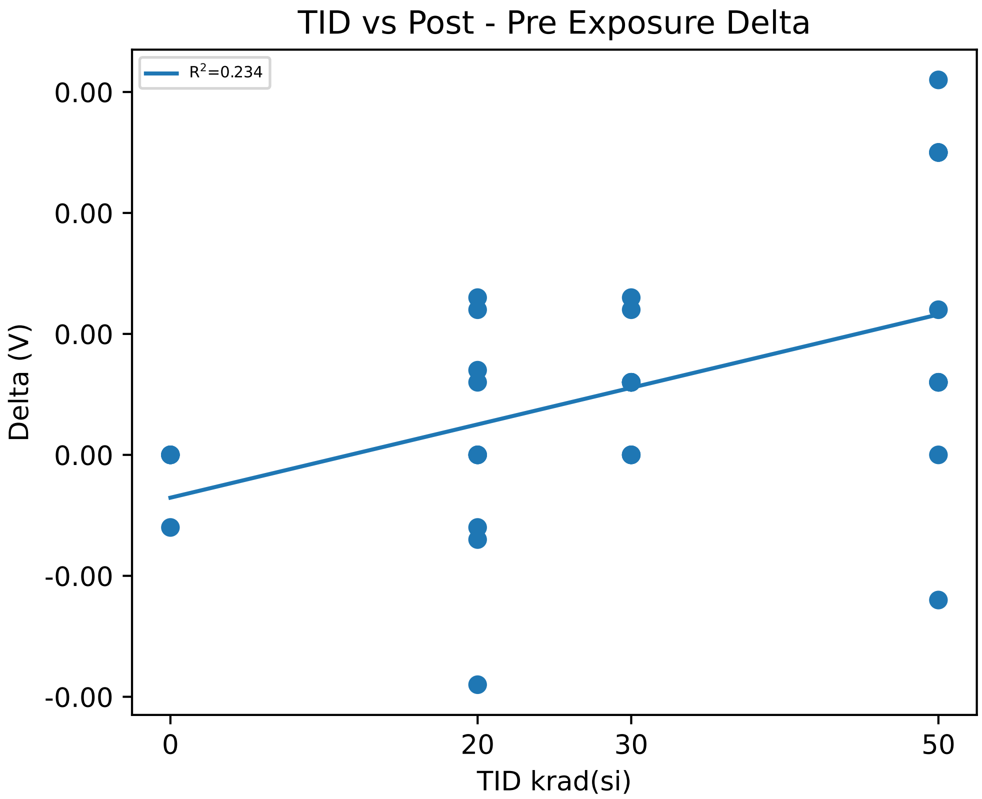
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.5804	0.5816	0.0012
2	20	Unbiased	0.5847	0.586	0.0013
3	20	Unbiased	0.5922	0.591	-0.0012
4	20	Unbiased	0.5841	0.5841	0
5	20	Unbiased	0.5847	0.5847	0
6	20	7V Biased	0.5822	0.5841	0.0019
7	20	7V Biased	0.5935	0.5929	-0.0006
8	20	7V Biased	0.5904	0.5922	0.0018
9	20	7V Biased	0.5879	0.5891	0.0012
10	20	7V Biased	0.5772	0.5778	0.0006
11	30	Unbiased	0.5804	0.5816	0.0012
12	30	Unbiased	0.5854	0.5866	0.0012
13	30	Unbiased	0.5866	0.5872	0.0006
14	30	Unbiased	0.586	0.5866	0.0006
15	30	Unbiased	0.5835	0.5841	0.0006
16	30	7V Biased	0.5678	0.5697	0.0019
17	30	7V Biased	0.576	0.5772	0.0012
18	30	7V Biased	0.5816	0.5829	0.0013
19	30	7V Biased	0.5772	0.5804	0.0032
20	30	7V Biased	0.5829	0.586	0.0031
21	50	Unbiased	0.5785	0.5791	0.0006
22	50	Unbiased	0.5703	0.5728	0.0025
23	50	Unbiased	0.576	0.5766	0.0006
24	50	Unbiased	0.581	0.5835	0.0025
25	50	Unbiased	0.5822	0.5829	0.0007
26	50	7V Biased	0.5829	0.5847	0.0018
27	50	7V Biased	0.5785	0.5822	0.0037
28	50	7V Biased	0.5797	0.5835	0.0038
29	50	7V Biased	0.5766	0.5804	0.0038
30	50	7V Biased	0.5804	0.5841	0.0037
31	0	Correlation	0.5785	0.5791	0.0006
32	0	Correlation	0.5854	0.586	0.0006
33	0	Correlation	0.5753	0.5753	0
34	0	Correlation	0.5747	0.5747	0
35	0	Correlation	0.5804	0.581	0.0006

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5747	0.57886	0.5854	0.0043374	0.5747	0.57922	0.586	0.0046084	0	0.00036	0.0006	0.00032863
20	0.5772	0.58573	0.5935	0.0052405	0.5778	0.58635	0.5929	0.004887	-0.0012	0.00062	0.0019	0.0010401
30	0.5678	0.58074	0.5866	0.0057668	0.5697	0.58223	0.5872	0.0054477	0.0006	0.00149	0.0032	0.00096315
50	0.5703	0.57861	0.5829	0.0036716	0.5728	0.58098	0.5847	0.0038212	0.0006	0.00237	0.0038	0.001376

Device Test: 7.4 OVP_VTH_Falling(OVP_UVLO_FALLING_1p8V)





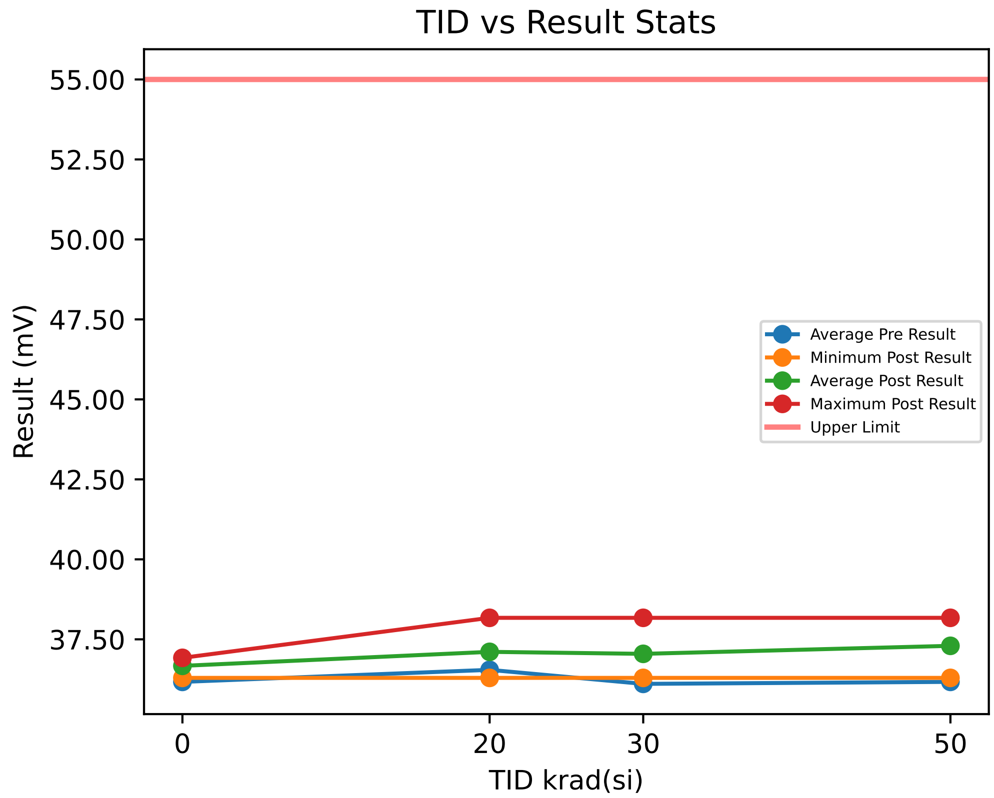
Test Results (Lower Limit = 0.5, Upper Limit = 0.59 (V))

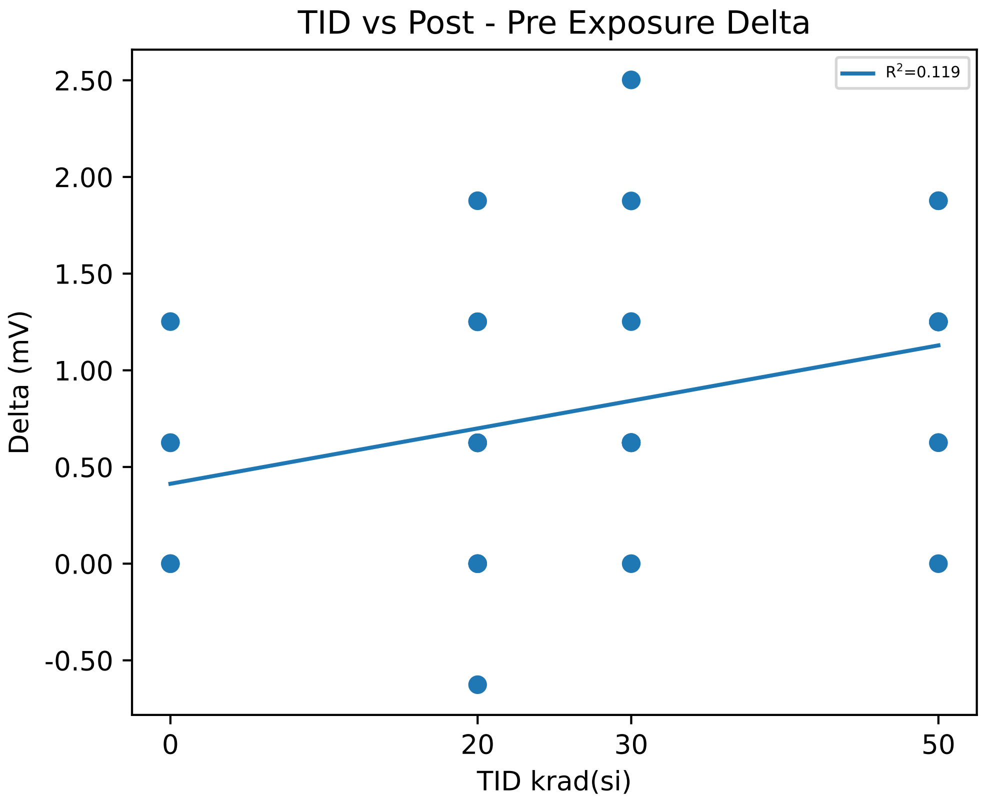
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.5441	0.5453	0.0012
2	20	Unbiased	0.5478	0.5491	0.0013
3	20	Unbiased	0.5547	0.5541	-0.0006
4	20	Unbiased	0.5466	0.5466	0
5	20	Unbiased	0.5491	0.5484	-0.0007
6	20	7V Biased	0.5459	0.5466	0.0007
7	20	7V Biased	0.5572	0.5553	-0.0019
8	20	7V Biased	0.5541	0.5541	0
9	20	7V Biased	0.5516	0.5522	0.0006
10	20	7V Biased	0.5409	0.5409	0
11	30	Unbiased	0.5441	0.5441	0
12	30	Unbiased	0.5491	0.5497	0.0006
13	30	Unbiased	0.5503	0.5509	0.0006
14	30	Unbiased	0.5497	0.5497	0
15	30	Unbiased	0.5472	0.5472	0
16	30	7V Biased	0.5315	0.5328	0.0013
17	30	7V Biased	0.5403	0.5409	0.0006
18	30	7V Biased	0.5453	0.5459	0.0006
19	30	7V Biased	0.5422	0.5428	0.0006
20	30	7V Biased	0.5466	0.5478	0.0012
21	50	Unbiased	0.5422	0.5428	0.0006
22	50	Unbiased	0.5347	0.5359	0.0012
23	50	Unbiased	0.5409	0.5397	-0.0012
24	50	Unbiased	0.5447	0.5453	0.0006
25	50	Unbiased	0.5459	0.5459	0
26	50	7V Biased	0.5466	0.5472	0.0006
27	50	7V Biased	0.5416	0.5447	0.0031
28	50	7V Biased	0.5434	0.5459	0.0025
29	50	7V Biased	0.5403	0.5428	0.0025
30	50	7V Biased	0.5441	0.5466	0.0025
31	0	Correlation	0.5422	0.5422	0
32	0	Correlation	0.5491	0.5491	0
33	0	Correlation	0.539	0.539	0
34	0	Correlation	0.5384	0.5384	0
35	0	Correlation	0.5447	0.5441	-0.0006

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5384	0.54268	0.5491	0.0043985	0.5384	0.54256	0.5491	0.0043374	-0.0006	-0.00012	0	0.00026833
20	0.5409	0.5492	0.5572	0.0051482	0.5409	0.54926	0.5553	0.0046244	-0.0019	6e-05	0.0013	0.00096632
30	0.5315	0.54463	0.5503	0.0056382	0.5328	0.54518	0.5509	0.0054104	0	0.00055	0.0013	0.00046007
50	0.5347	0.54244	0.5466	0.0034268	0.5359	0.54368	0.5472	0.0035333	-0.0012	0.00124	0.0031	0.0013721

Device Test: 7.5 OVP_HYST(OVP_UVLO_HYSTERESIS_1p8V)





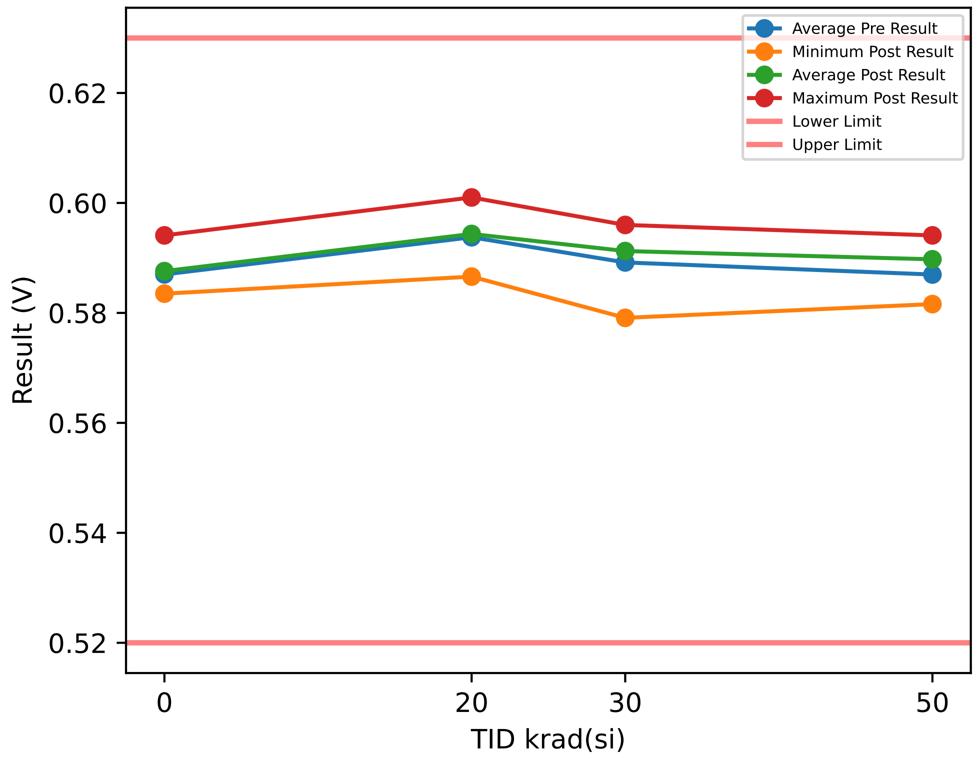
Test Results (Upper Limit = 55.0 (mV))

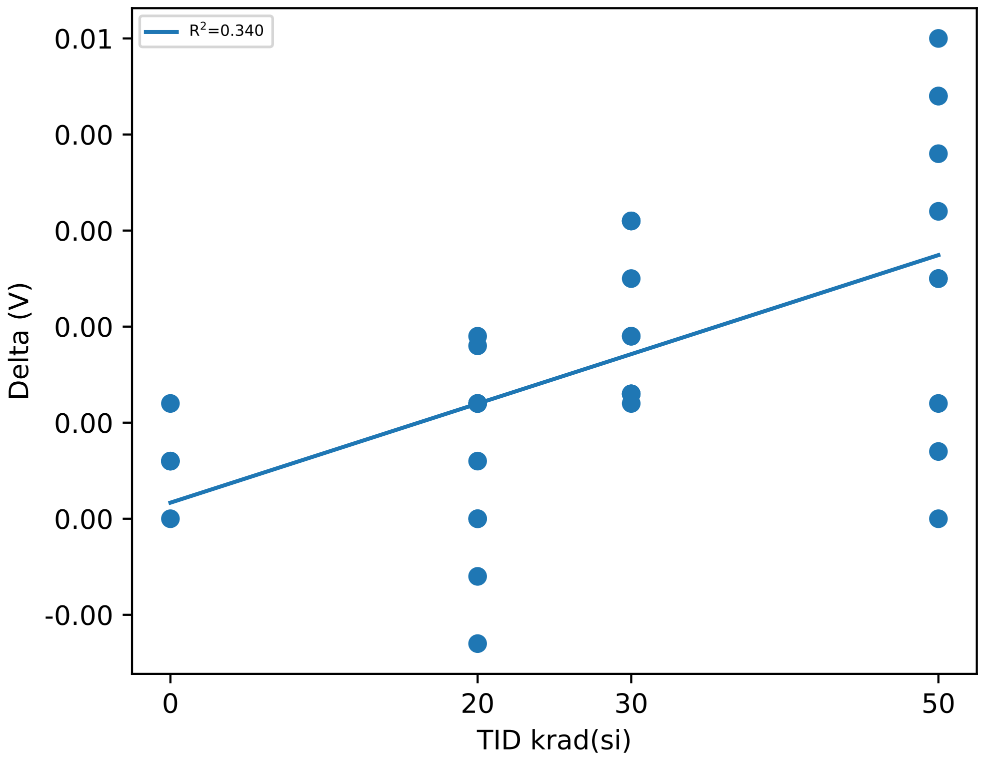
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	36.295	36.295	0
2	20	Unbiased	36.921	36.921	0
3	20	Unbiased	37.547	36.921	-0.626
4	20	Unbiased	37.547	37.547	0
5	20	Unbiased	35.67	36.295	0.625
6	20	7V Biased	36.296	37.547	1.251
7	20	7V Biased	36.296	37.547	1.251
8	20	7V Biased	36.295	38.172	1.877
9	20	7V Biased	36.296	36.921	0.625
10	20	7V Biased	36.296	36.921	0.625
11	30	Unbiased	36.295	37.547	1.252
12	30	Unbiased	36.296	36.921	0.625
13	30	Unbiased	36.295	36.295	0
14	30	Unbiased	36.295	36.921	0.626
15	30	Unbiased	36.295	36.921	0.626
16	30	7V Biased	36.296	36.921	0.625
17	30	7V Biased	35.67	36.296	0.626
18	30	7V Biased	36.295	36.922	0.627
19	30	7V Biased	35.044	37.546	2.502
20	30	7V Biased	36.296	38.172	1.876
21	50	Unbiased	36.295	36.295	0
22	50	Unbiased	35.67	36.921	1.251
23	50	Unbiased	35.044	36.921	1.877
24	50	Unbiased	36.295	38.172	1.877
25	50	Unbiased	36.296	36.922	0.626
26	50	7V Biased	36.296	37.547	1.251
27	50	7V Biased	36.921	37.547	0.626
28	50	7V Biased	36.296	37.547	1.251
29	50	7V Biased	36.296	37.546	1.25
30	50	7V Biased	36.295	37.547	1.252
31	0	Correlation	36.295	36.921	0.626
32	0	Correlation	36.296	36.921	0.625
33	0	Correlation	36.295	36.295	0
34	0	Correlation	36.295	36.295	0
35	0	Correlation	35.669	36.921	1.252

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	35.669	36.17	36.296	0.28007	36.295	36.671	36.921	0.34287	0	0.5006	1.252	0.52369
20	35.67	36.546	37.547	0.60443	36.295	37.109	38.172	0.59368	-0.626	0.5628	1.877	0.74903
30	35.044	36.108	36.296	0.42227	36.295	37.046	38.172	0.57477	0	0.9385	2.502	0.73704
50	35.044	36.17	36.921	0.49354	36.295	37.296	38.172	0.52757	0	1.1261	1.877	0.57484

Device Test: 7.6 OVP_VTH_Rising(OVP_UVLO_RISING_3p3V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

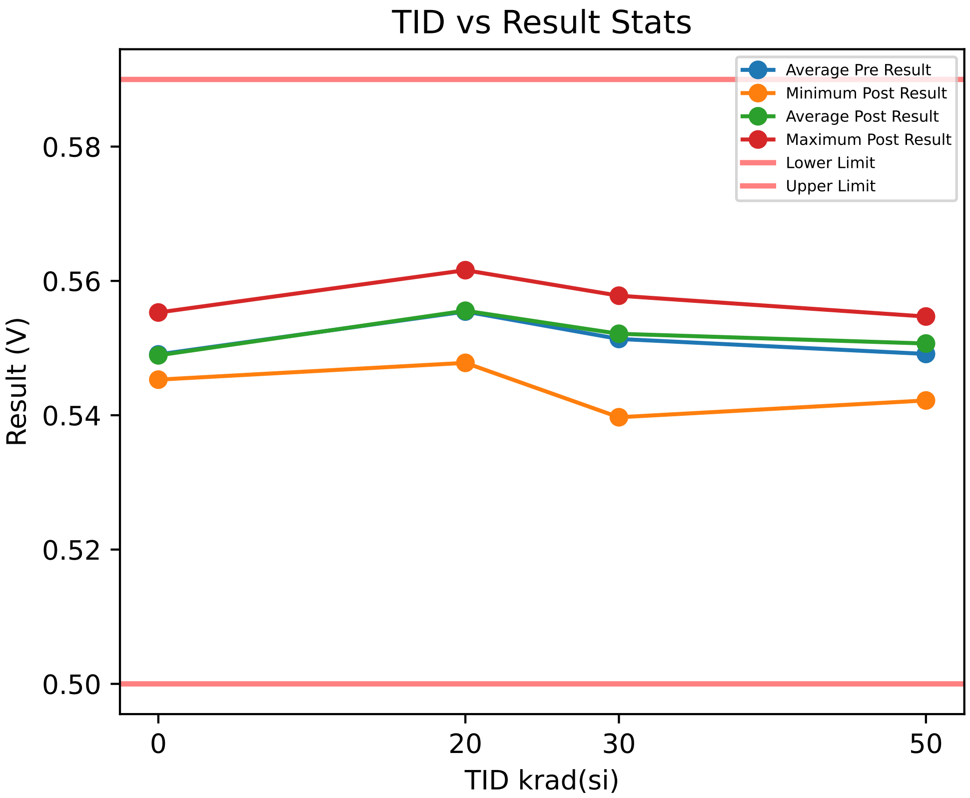
Test Results (Lower Limit = 0.52, Upper Limit = 0.63 (V))

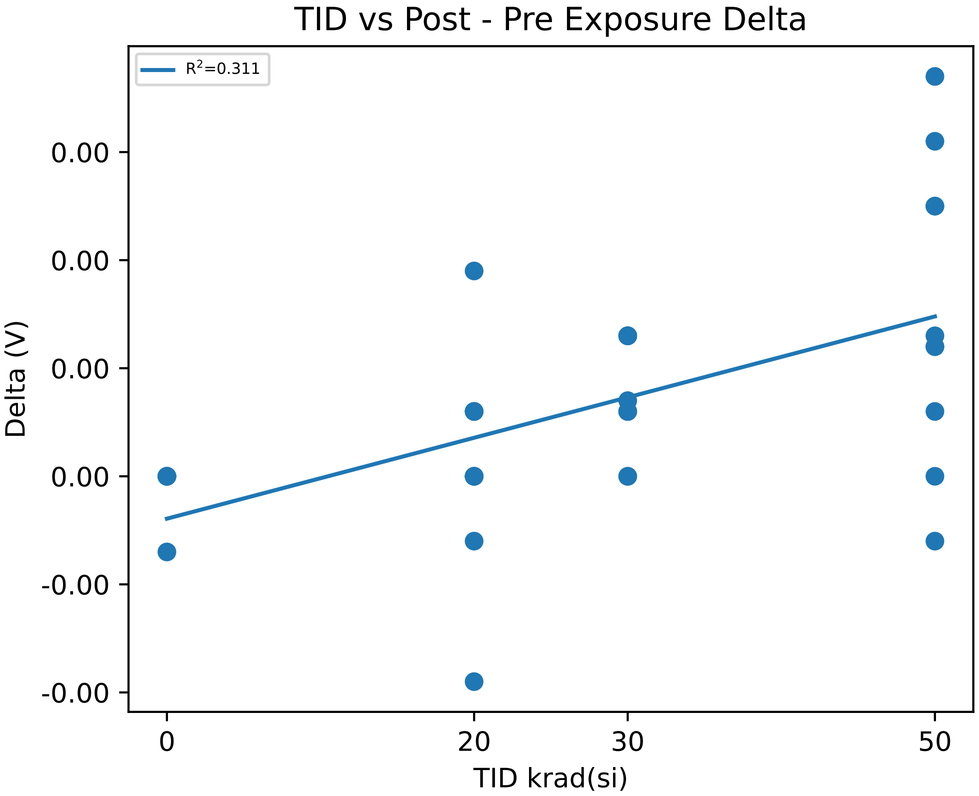
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.5879	0.5891	0.0012
2	20	Unbiased	0.5929	0.5941	0.0012
3	20	Unbiased	0.6004	0.5991	-0.0013
4	20	Unbiased	0.5935	0.5929	-0.0006
5	20	Unbiased	0.5922	0.5922	0
6	20	7V Biased	0.5904	0.5922	0.0018
7	20	7V Biased	0.601	0.601	0
8	20	7V Biased	0.5979	0.5998	0.0019
9	20	7V Biased	0.5954	0.5966	0.0012
10	20	7V Biased	0.586	0.5866	0.0006
11	30	Unbiased	0.5891	0.5904	0.0013
12	30	Unbiased	0.5929	0.5954	0.0025
13	30	Unbiased	0.5947	0.596	0.0013
14	30	Unbiased	0.5947	0.596	0.0013
15	30	Unbiased	0.5929	0.5941	0.0012
16	30	7V Biased	0.576	0.5791	0.0031
17	30	7V Biased	0.5835	0.5854	0.0019
18	30	7V Biased	0.5916	0.5935	0.0019
19	30	7V Biased	0.5854	0.5885	0.0031
20	30	7V Biased	0.591	0.5941	0.0031
21	50	Unbiased	0.5879	0.5891	0.0012
22	50	Unbiased	0.5791	0.5816	0.0025
23	50	Unbiased	0.5854	0.5854	0
24	50	Unbiased	0.5897	0.5929	0.0032
25	50	Unbiased	0.5897	0.5904	0.0007
26	50	7V Biased	0.5916	0.5941	0.0025
27	50	7V Biased	0.5866	0.591	0.0044
28	50	7V Biased	0.5872	0.5916	0.0044
29	50	7V Biased	0.5847	0.5885	0.0038
30	50	7V Biased	0.5879	0.5929	0.005
31	0	Correlation	0.5866	0.5872	0.0006
32	0	Correlation	0.5935	0.5941	0.0006
33	0	Correlation	0.5835	0.5835	0
34	0	Correlation	0.5829	0.5841	0.0012
35	0	Correlation	0.5885	0.5891	0.0006

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5829	0.587	0.5935	0.004293	0.5835	0.5876	0.5941	0.004293	0	0.0006	0.0012	0.00042426
20	0.586	0.59376	0.601	0.0050047	0.5866	0.59436	0.601	0.0047209	-0.0013	0.0006	0.0019	0.001053
30	0.576	0.58918	0.5947	0.0059447	0.5791	0.59125	0.596	0.0055155	0.0012	0.00207	0.0031	0.00081384
50	0.5791	0.58698	0.5916	0.0034611	0.5816	0.58975	0.5941	0.0038225	0	0.00277	0.005	0.001703

Device Test: 7.7 OVP_VTH_Falling(OVP_UVLO_FALLING_3p3V)





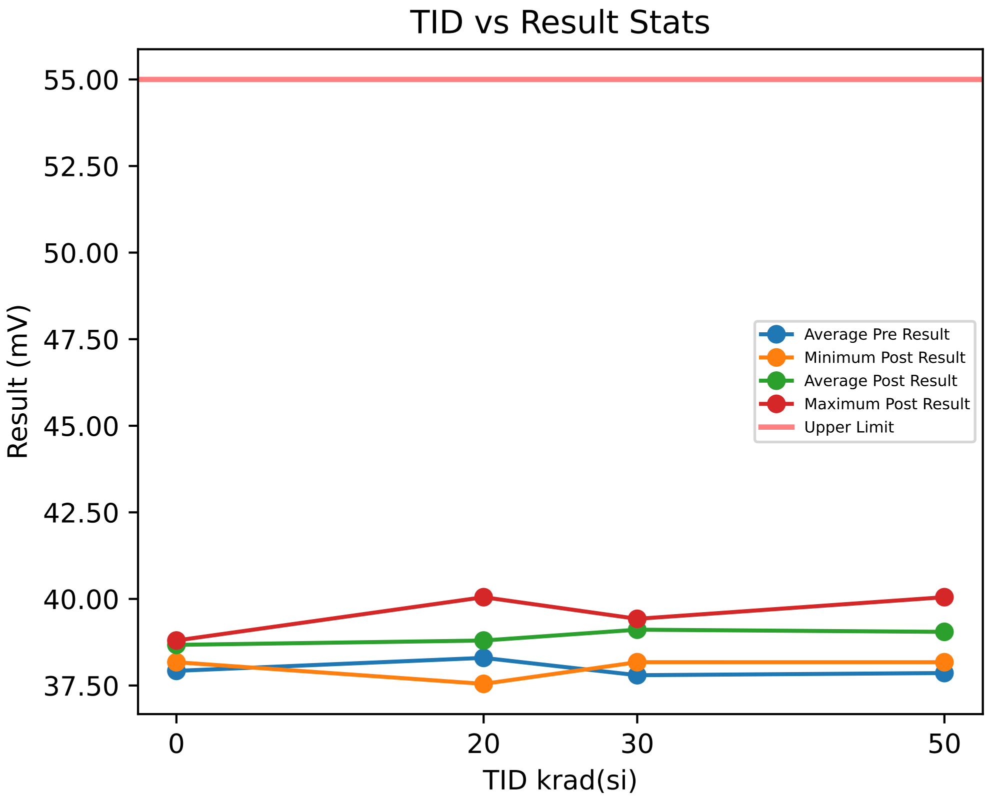
Test Results (Lower Limit = 0.5, Upper Limit = 0.59 (V))

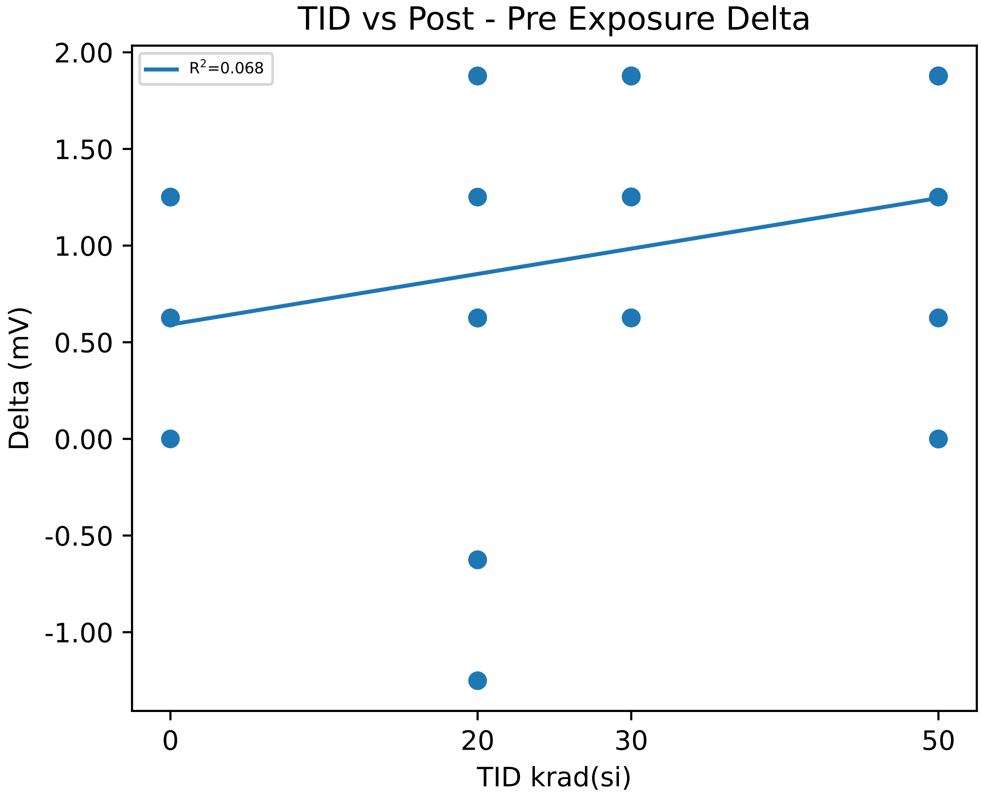
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.5503	0.5509	0.0006
2	20	Unbiased	0.5534	0.5553	0.0019
3	20	Unbiased	0.561	0.561	0
4	20	Unbiased	0.5534	0.5534	0
5	20	Unbiased	0.5553	0.5547	-0.0006
6	20	7V Biased	0.5522	0.5528	0.0006
7	20	7V Biased	0.5635	0.5616	-0.0019
8	20	7V Biased	0.5597	0.5597	0
9	20	7V Biased	0.5578	0.5584	0.0006
10	20	7V Biased	0.5478	0.5478	0
11	30	Unbiased	0.5509	0.5509	0
12	30	Unbiased	0.5553	0.5559	0.0006
13	30	Unbiased	0.5572	0.5578	0.0006
14	30	Unbiased	0.5566	0.5566	0
15	30	Unbiased	0.5547	0.5553	0.0006
16	30	7V Biased	0.5384	0.5397	0.0013
17	30	7V Biased	0.5459	0.5472	0.0013
18	30	7V Biased	0.5534	0.5541	0.0007
19	30	7V Biased	0.5478	0.5491	0.0013
20	30	7V Biased	0.5534	0.5547	0.0013
21	50	Unbiased	0.5497	0.5509	0.0012
22	50	Unbiased	0.5409	0.5422	0.0013
23	50	Unbiased	0.5478	0.5472	-0.0006
24	50	Unbiased	0.5516	0.5528	0.0012
25	50	Unbiased	0.5522	0.5522	0
26	50	7V Biased	0.5541	0.5547	0.0006
27	50	7V Biased	0.5484	0.5509	0.0025
28	50	7V Biased	0.5497	0.5522	0.0025
29	50	7V Biased	0.5466	0.5503	0.0037
30	50	7V Biased	0.5503	0.5534	0.0031
31	0	Correlation	0.5491	0.5484	-0.0007
32	0	Correlation	0.5553	0.5553	0
33	0	Correlation	0.5453	0.5453	0
34	0	Correlation	0.5453	0.5453	0
35	0	Correlation	0.5503	0.5503	0

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5453	0.54906	0.5553	0.0041458	0.5453	0.54892	0.5553	0.004156	-0.0007	-0.00014	0	0.00031305
20	0.5478	0.55544	0.5635	0.0049802	0.5478	0.55556	0.5616	0.0045498	-0.0019	0.00012	0.0019	0.00097274
30	0.5384	0.55136	0.5572	0.0058426	0.5397	0.55213	0.5578	0.0055416	0	0.00077	0.0013	0.00051651
50	0.5409	0.54913	0.5541	0.0036314	0.5422	0.55068	0.5547	0.0036046	-0.0006	0.00155	0.0037	0.001377

Device Test: 7.8 OVP_HYST(OVP_UVLO_HYSTERESIS_3p3V)





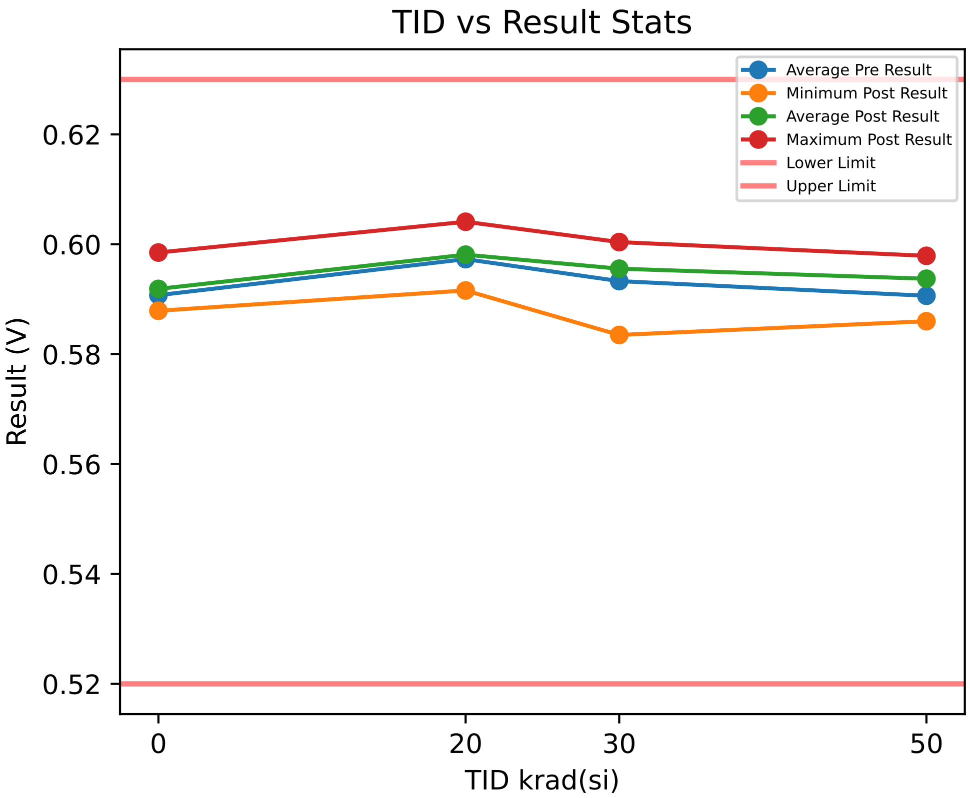
Test Results (Upper Limit = 55.0 (mV))

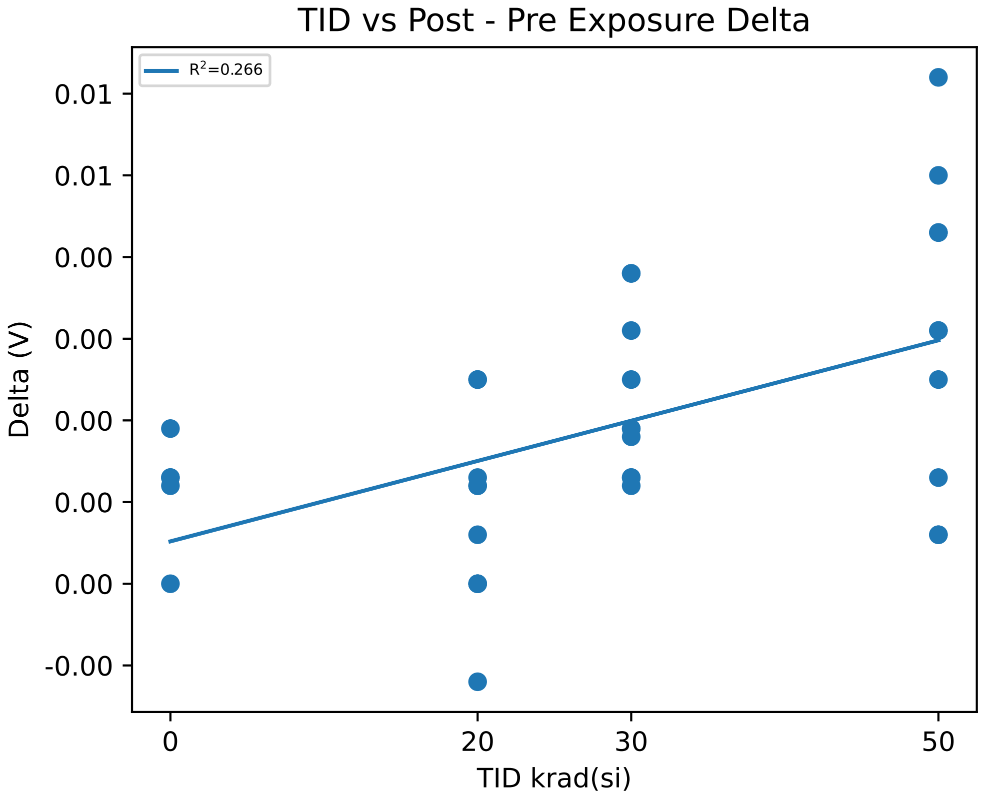
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	37.547	38.172	0.625
2	20	Unbiased	39.424	38.799	-0.625
3	20	Unbiased	39.424	38.173	-1.251
4	20	Unbiased	40.05	39.424	-0.626
5	20	Unbiased	36.921	37.547	0.626
6	20	7V Biased	38.173	39.424	1.251
7	20	7V Biased	37.547	39.424	1.877
8	20	7V Biased	38.172	40.05	1.878
9	20	7V Biased	37.547	38.173	0.626
10	20	7V Biased	38.172	38.798	0.626
11	30	Unbiased	38.172	39.424	1.252
12	30	Unbiased	37.547	39.424	1.877
13	30	Unbiased	37.547	38.173	0.626
14	30	Unbiased	38.172	39.424	1.252
15	30	Unbiased	38.173	38.799	0.626
16	30	7V Biased	37.547	39.424	1.877
17	30	7V Biased	37.547	38.173	0.626
18	30	7V Biased	38.173	39.424	1.251
19	30	7V Biased	37.547	39.425	1.878
20	30	7V Biased	37.547	39.425	1.878
21	50	Unbiased	38.173	38.172	-0.001
22	50	Unbiased	38.173	39.424	1.251
23	50	Unbiased	37.547	38.173	0.626
24	50	Unbiased	38.173	40.05	1.877
25	50	Unbiased	37.547	38.173	0.626
26	50	7V Biased	37.547	39.425	1.878
27	50	7V Biased	38.172	40.05	1.878
28	50	7V Biased	37.547	39.425	1.878
29	50	7V Biased	38.173	38.173	0
30	50	7V Biased	37.547	39.424	1.877
31	0	Correlation	37.547	38.798	1.251
32	0	Correlation	38.173	38.799	0.626
33	0	Correlation	38.172	38.172	0
34	0	Correlation	37.547	38.798	1.251
35	0	Correlation	38.173	38.798	0.625

Test Statistics (mV)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	37.547	37.922	38.173	0.34269	38.172	38.673	38.799	0.28007	0	0.7506	1.251	0.52333
20	36.921	38.298	40.05	1.0133	37.547	38.798	40.05	0.7804	-1.251	0.5007	1.878	1.0552
30	37.547	37.797	38.173	0.32301	38.173	39.111	39.425	0.53167	0.626	1.3143	1.878	0.54791
50	37.547	37.86	38.173	0.32983	38.172	39.049	40.05	0.79157	-0.001	1.189	1.878	0.80543

Device Test: 7.9 OVP_VTH_Rising(OVP_UVLO_RISING_5V)





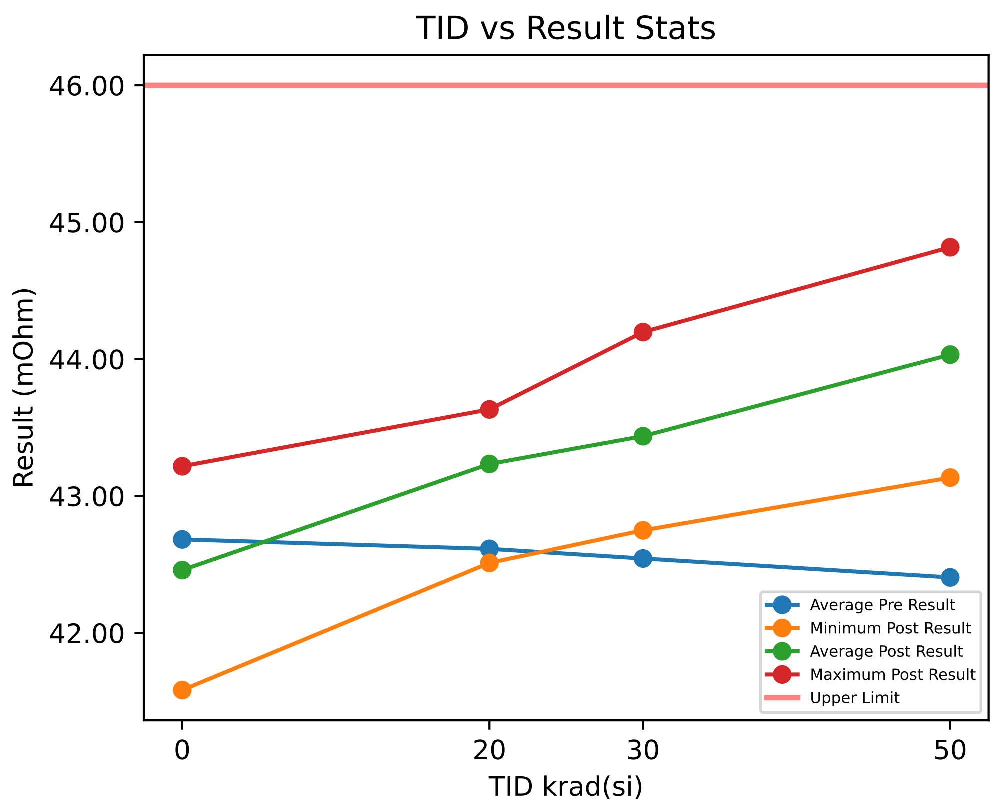
Test Results (Lower Limit = 0.52, Upper Limit = 0.63 (V))

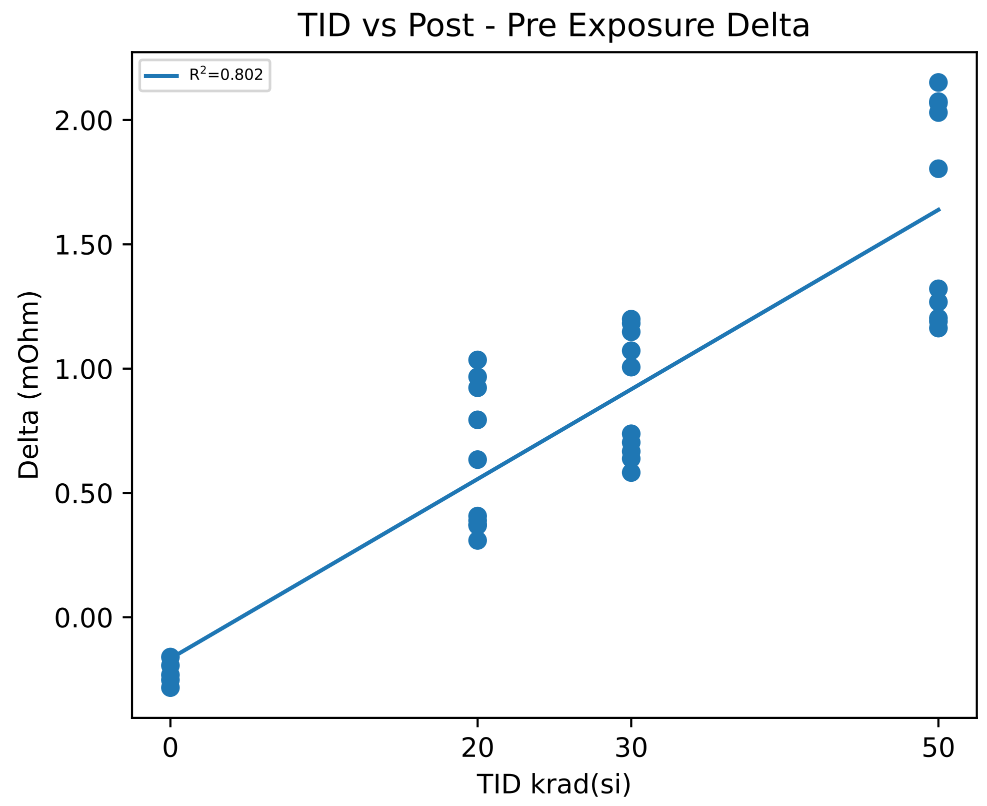
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	0.591	0.5922	0.0012
2	20	Unbiased	0.5966	0.5972	0.0006
3	20	Unbiased	0.6041	0.6029	-0.0012
4	20	Unbiased	0.5972	0.5972	0
5	20	Unbiased	0.596	0.596	0
6	20	7V Biased	0.5935	0.596	0.0025
7	20	7V Biased	0.6041	0.6041	0
8	20	7V Biased	0.601	0.6035	0.0025
9	20	7V Biased	0.5991	0.6004	0.0013
10	20	7V Biased	0.5904	0.5916	0.0012
11	30	Unbiased	0.5929	0.5947	0.0018
12	30	Unbiased	0.5966	0.5991	0.0025
13	30	Unbiased	0.5991	0.6004	0.0013
14	30	Unbiased	0.5991	0.6004	0.0013
15	30	Unbiased	0.5979	0.5991	0.0012
16	30	7V Biased	0.5804	0.5835	0.0031
17	30	7V Biased	0.5866	0.5885	0.0019
18	30	7V Biased	0.5966	0.5985	0.0019
19	30	7V Biased	0.5891	0.5929	0.0038
20	30	7V Biased	0.5947	0.5985	0.0038
21	50	Unbiased	0.5922	0.5935	0.0013
22	50	Unbiased	0.5829	0.586	0.0031
23	50	Unbiased	0.5891	0.5897	0.0006
24	50	Unbiased	0.5935	0.5966	0.0031
25	50	Unbiased	0.5929	0.5935	0.0006
26	50	7V Biased	0.5954	0.5979	0.0025
27	50	7V Biased	0.5904	0.5947	0.0043
28	50	7V Biased	0.591	0.596	0.005
29	50	7V Biased	0.5879	0.5922	0.0043
30	50	7V Biased	0.591	0.5972	0.0062
31	0	Correlation	0.5904	0.5916	0.0012
32	0	Correlation	0.5966	0.5985	0.0019
33	0	Correlation	0.5879	0.5879	0
34	0	Correlation	0.5872	0.5885	0.0013
35	0	Correlation	0.5916	0.5929	0.0013

Test Statistics (V)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5872	0.59074	0.5966	0.0037347	0.5879	0.59188	0.5985	0.0042488	0	0.00114	0.0019	0.00069498
20	0.5904	0.5973	0.6041	0.0048687	0.5916	0.59811	0.6041	0.0044844	-0.0012	0.00081	0.0025	0.0011695
30	0.5804	0.5933	0.5991	0.0061579	0.5835	0.59556	0.6004	0.005699	0.0012	0.00226	0.0038	0.00099688
50	0.5829	0.59063	0.5954	0.0034718	0.586	0.59373	0.5979	0.0036848	0.0006	0.0031	0.0062	0.0018915

Device Test: 8.0 RON_VIN_1P5V_25_Plastic(RdsOn_Vin1p5_6ALoad)





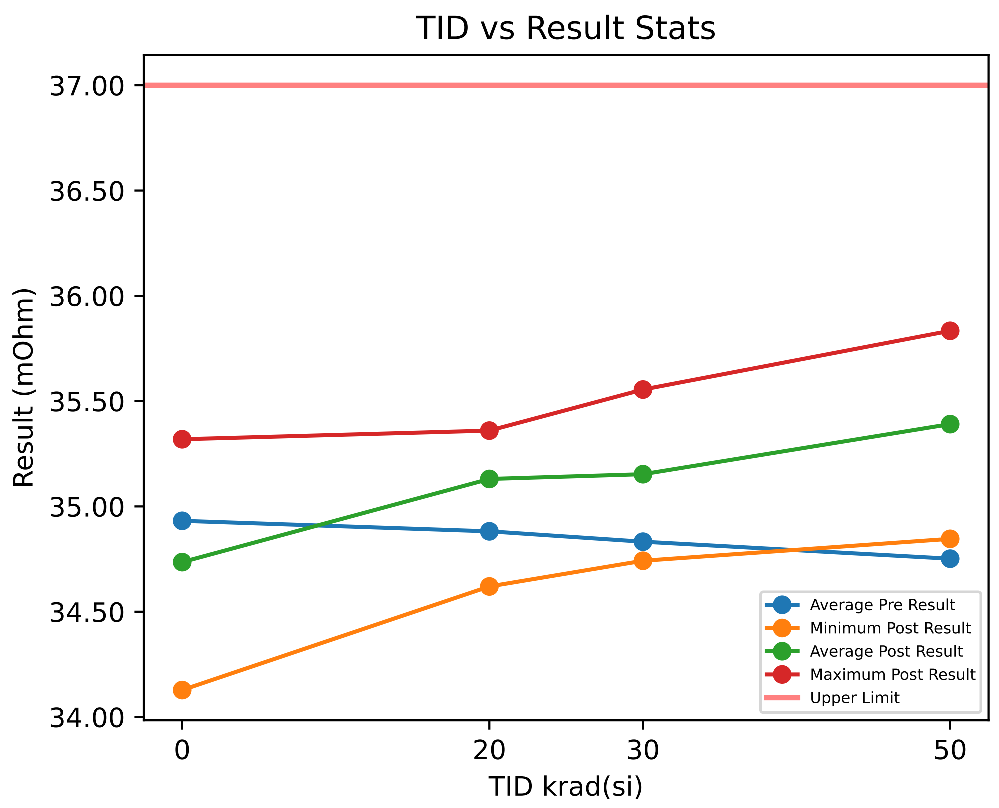
Test Results (Upper Limit = 46.0 (mOhm))

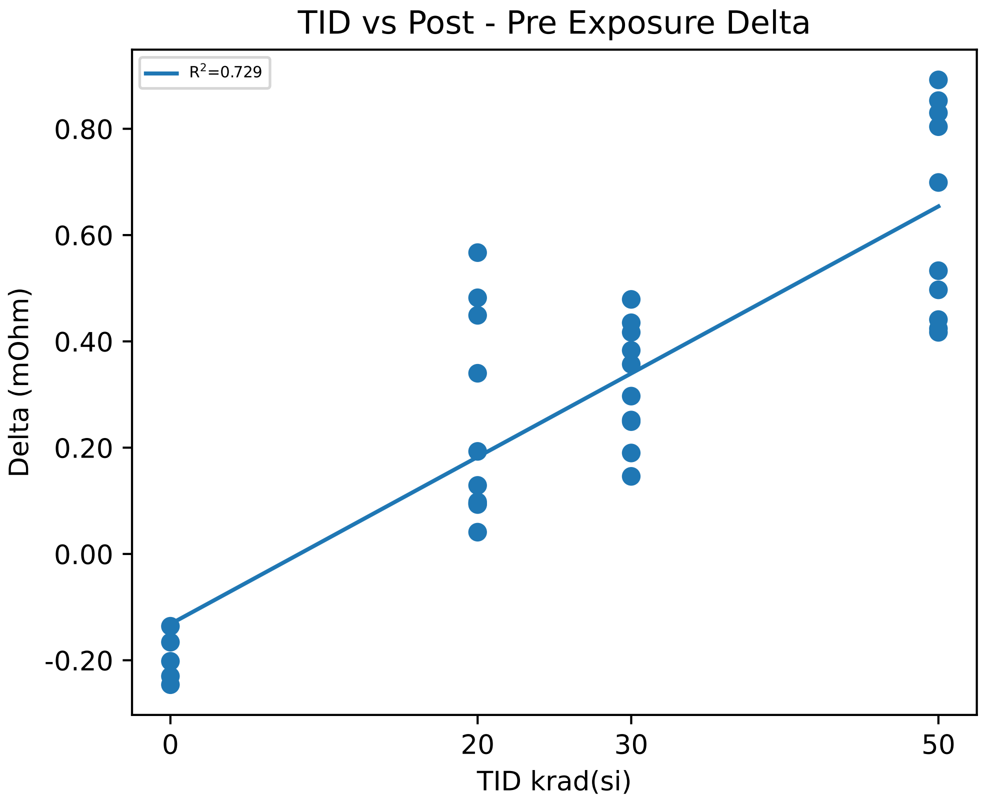
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	42.838	43.632	0.794
2	20	Unbiased	42.452	43.487	1.035
3	20	Unbiased	42.527	43.45	0.923
4	20	Unbiased	42.3	43.267	0.967
5	20	Unbiased	42.696	43.33	0.634
6	20	7V Biased	43.106	43.479	0.373
7	20	7V Biased	42.202	42.511	0.309
8	20	7V Biased	42.904	43.273	0.369
9	20	7V Biased	42.576	42.983	0.407
10	20	7V Biased	42.534	42.923	0.389
11	30	Unbiased	42.796	43.868	1.072
12	30	Unbiased	41.954	42.96	1.006
13	30	Unbiased	42.551	43.75	1.199
14	30	Unbiased	42.625	43.773	1.148
15	30	Unbiased	43.015	44.197	1.182
16	30	7V Biased	42.894	43.597	0.703
17	30	7V Biased	42.16	42.827	0.667
18	30	7V Biased	42.111	42.749	0.638
19	30	7V Biased	42.93	43.512	0.582
20	30	7V Biased	42.395	43.133	0.738
21	50	Unbiased	42.347	44.415	2.068
22	50	Unbiased	42.042	43.846	1.804
23	50	Unbiased	42.176	44.206	2.03
24	50	Unbiased	42.666	44.817	2.151
25	50	Unbiased	42.447	44.521	2.074
26	50	7V Biased	41.971	43.134	1.163
27	50	7V Biased	42.643	43.833	1.19
28	50	7V Biased	42.426	43.747	1.321
29	50	7V Biased	42.294	43.562	1.268
30	50	7V Biased	43.039	44.242	1.203
31	0	Correlation	42.772	42.52	-0.252
32	0	Correlation	43.411	43.217	-0.194
33	0	Correlation	42.616	42.456	-0.16
34	0	Correlation	41.814	41.582	-0.232
35	0	Correlation	42.8	42.517	-0.283

Test Statistics (mOhm)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	41.814	42.683	43.411	0.57255	41.582	42.458	43.217	0.58112	-0.283	-0.2242	-0.16	0.048283
20	42.202	42.614	43.106	0.2775	42.511	43.234	43.632	0.33721	0.309	0.62	1.035	0.28565
30	41.954	42.543	43.015	0.37545	42.749	43.437	44.197	0.49113	0.582	0.8935	1.199	0.24943
50	41.971	42.405	43.039	0.31923	43.134	44.032	44.817	0.50101	1.163	1.6272	2.151	0.43091

Device Test: 8.1 RON_VIN_1P8V_25_Plastic(RdsOn_Vin1p8_6ALoad)





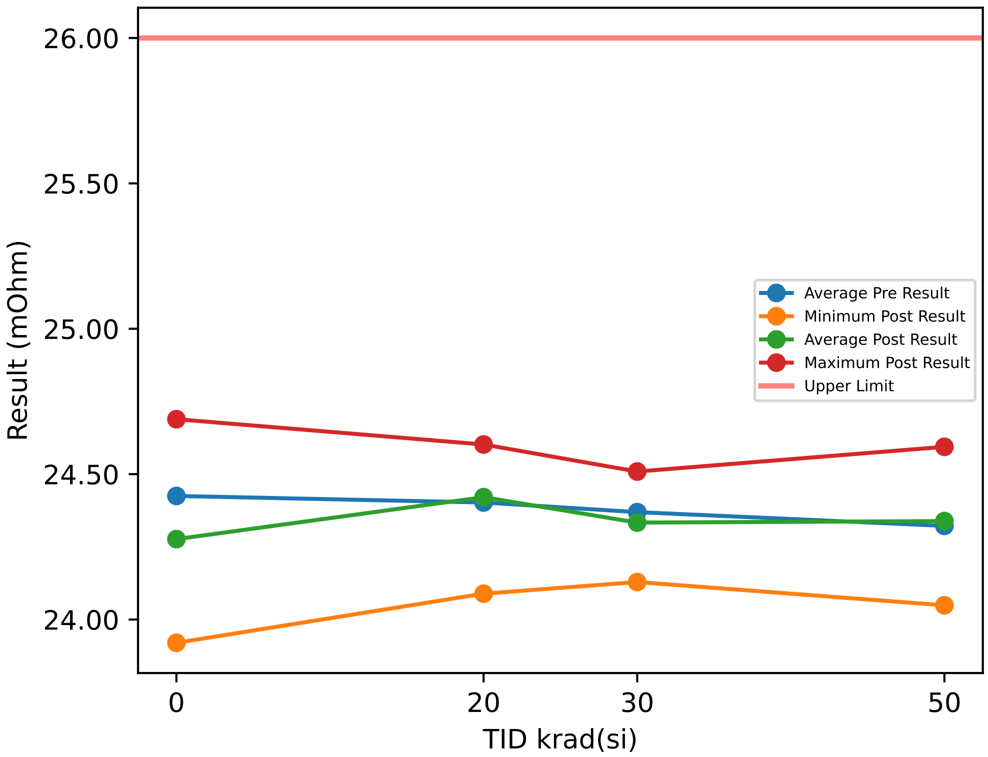
Test Results (Upper Limit = 37.0 (mOhm))

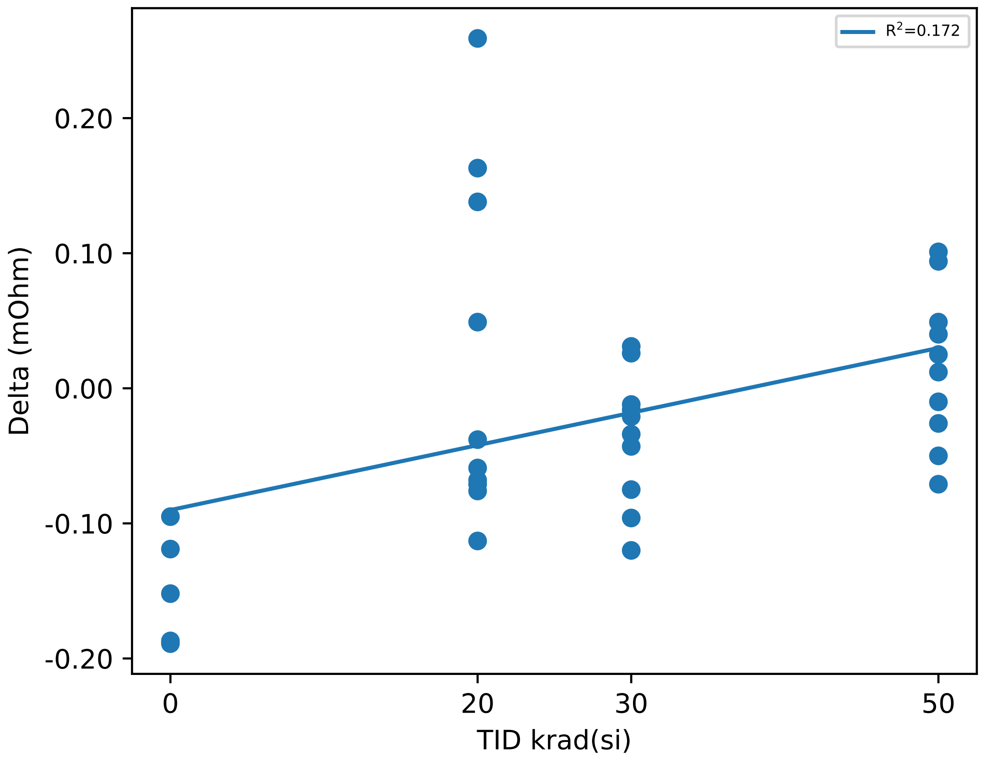
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	35.02	35.36	0.34
2	20	Unbiased	34.68	35.247	0.567
3	20	Unbiased	34.783	35.232	0.449
4	20	Unbiased	34.558	35.04	0.482
5	20	Unbiased	35.018	35.211	0.193
6	20	7V Biased	35.261	35.359	0.098
7	20	7V Biased	34.579	34.62	0.041
8	20	7V Biased	35.16	35.253	0.093
9	20	7V Biased	34.919	35.048	0.129
10	20	7V Biased	34.839	34.934	0.095
11	30	Unbiased	34.947	35.304	0.357
12	30	Unbiased	34.543	34.926	0.383
13	30	Unbiased	34.778	35.257	0.479
14	30	Unbiased	34.914	35.331	0.417
15	30	Unbiased	35.12	35.555	0.435
16	30	7V Biased	35.018	35.27	0.252
17	30	7V Biased	34.564	34.813	0.249
18	30	7V Biased	34.552	34.742	0.19
19	30	7V Biased	35.152	35.298	0.146
20	30	7V Biased	34.737	35.034	0.297
21	50	Unbiased	34.677	35.53	0.853
22	50	Unbiased	34.612	35.311	0.699
23	50	Unbiased	34.572	35.376	0.804
24	50	Unbiased	34.942	35.834	0.892
25	50	Unbiased	34.764	35.594	0.83
26	50	7V Biased	34.422	34.846	0.424
27	50	7V Biased	34.915	35.356	0.441
28	50	7V Biased	34.732	35.265	0.533
29	50	7V Biased	34.644	35.141	0.497
30	50	7V Biased	35.238	35.655	0.417
31	0	Correlation	34.958	34.728	-0.23
32	0	Correlation	35.485	35.319	-0.166
33	0	Correlation	34.916	34.78	-0.136
34	0	Correlation	34.33	34.128	-0.202
35	0	Correlation	34.969	34.723	-0.246

Test Statistics (mOhm)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	34.33	34.932	35.485	0.40942	34.128	34.736	35.319	0.42182	-0.246	-0.196	-0.136	0.045255
20	34.558	34.882	35.261	0.23783	34.62	35.13	35.36	0.22717	0.041	0.2487	0.567	0.19303
30	34.543	34.832	35.152	0.23228	34.742	35.153	35.555	0.26073	0.146	0.3205	0.479	0.11087
50	34.422	34.752	35.238	0.23036	34.846	35.391	35.834	0.28082	0.417	0.639	0.892	0.19528

Device Test: 8.2 RON_VIN_3P3V_25_Plastic(RdsOn_Vin3p3_6ALoad)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

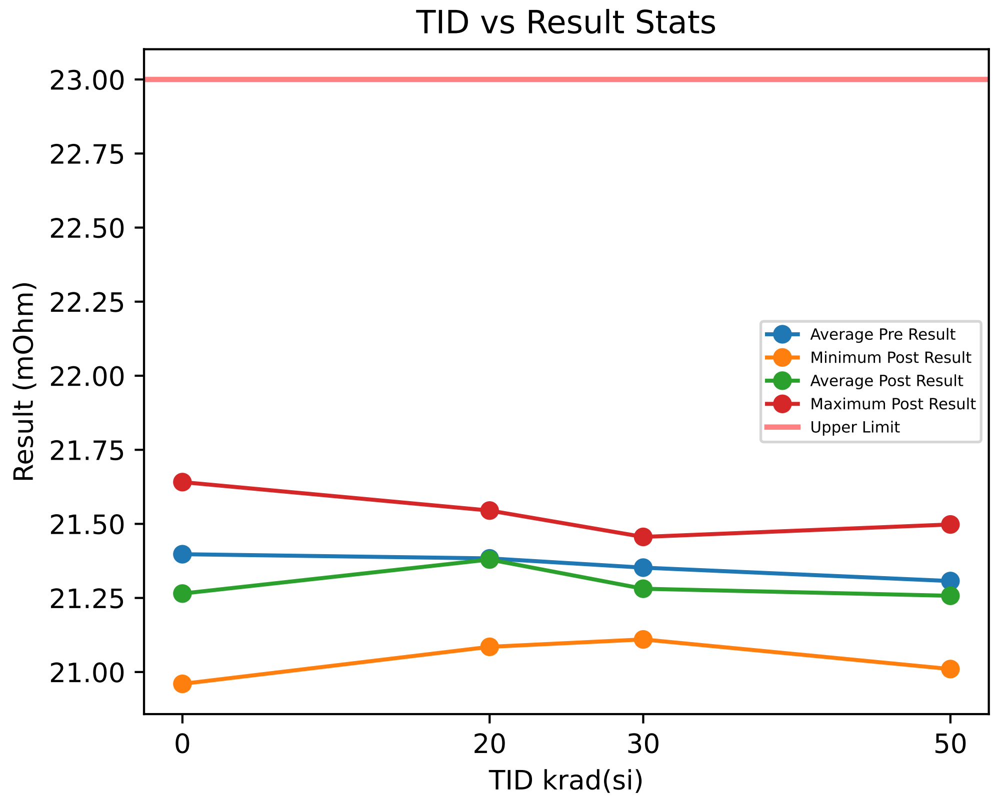
Test Results (Upper Limit = 26.0 (mOhm))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	24.484	24.533	0.049
2	20	Unbiased	24.199	24.458	0.259
3	20	Unbiased	24.3	24.438	0.138
4	20	Unbiased	24.102	24.265	0.163
5	20	Unbiased	24.541	24.47	-0.071
6	20	7V Biased	24.661	24.602	-0.059
7	20	7V Biased	24.202	24.089	-0.113
8	20	7V Biased	24.644	24.576	-0.068
9	20	7V Biased	24.488	24.45	-0.038
10	20	7V Biased	24.404	24.328	-0.076
11	30	Unbiased	24.384	24.309	-0.075
12	30	Unbiased	24.331	24.319	-0.012
13	30	Unbiased	24.271	24.302	0.031
14	30	Unbiased	24.457	24.414	-0.043
15	30	Unbiased	24.479	24.445	-0.034
16	30	7V Biased	24.402	24.381	-0.021
17	30	7V Biased	24.21	24.194	-0.016
18	30	7V Biased	24.225	24.129	-0.096
19	30	7V Biased	24.629	24.509	-0.12
20	30	7V Biased	24.306	24.332	0.026
21	50	Unbiased	24.267	24.361	0.094
22	50	Unbiased	24.374	24.364	-0.01
23	50	Unbiased	24.184	24.209	0.025
24	50	Unbiased	24.436	24.537	0.101
25	50	Unbiased	24.31	24.359	0.049
26	50	7V Biased	24.099	24.049	-0.05
27	50	7V Biased	24.398	24.372	-0.026
28	50	7V Biased	24.277	24.317	0.04
29	50	7V Biased	24.212	24.224	0.012
30	50	7V Biased	24.665	24.594	-0.071
31	0	Correlation	24.405	24.218	-0.187
32	0	Correlation	24.808	24.689	-0.119
33	0	Correlation	24.437	24.342	-0.095
34	0	Correlation	24.072	23.92	-0.152
35	0	Correlation	24.403	24.214	-0.189

Test Statistics (mOhm)

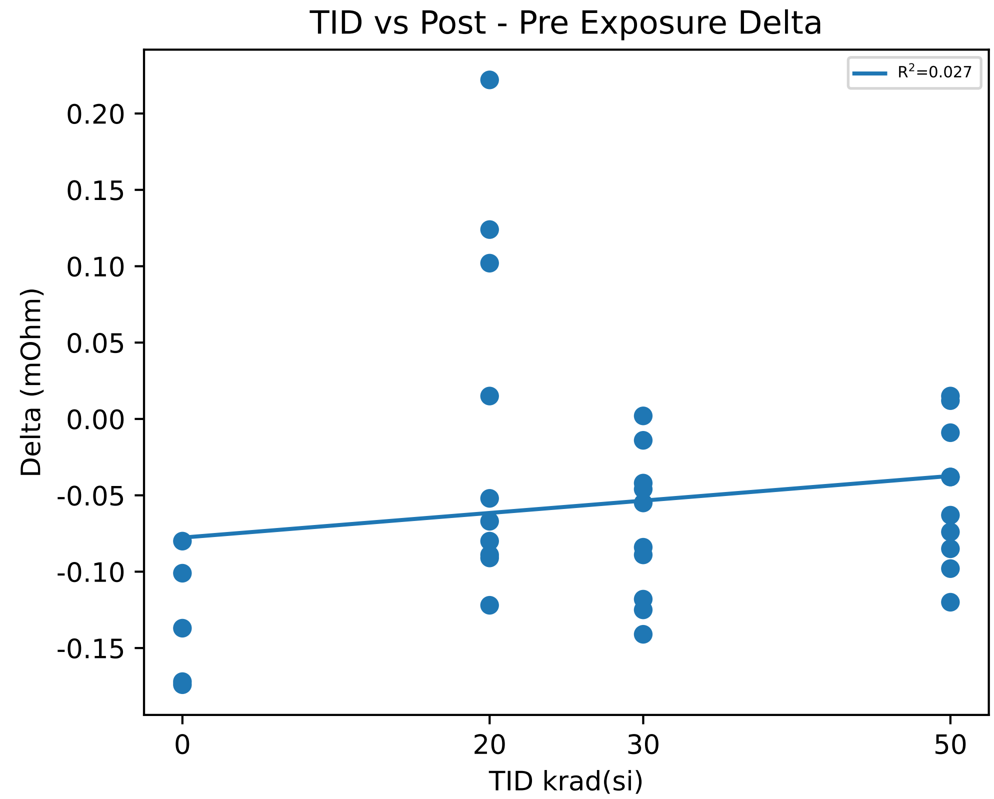
krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	24.072	24.425	24.808	0.26092	23.92	24.277	24.689	0.27788	-0.189	-0.1484	-0.095	0.041434
20	24.102	24.402	24.661	0.19457	24.089	24.421	24.602	0.15543	-0.113	0.0184	0.259	0.12686
30	24.21	24.369	24.629	0.12901	24.129	24.333	24.509	0.11307	-0.12	-0.036	0.031	0.049175
50	24.099	24.322	24.665	0.15818	24.049	24.339	24.594	0.15689	-0.071	0.0164	0.101	0.057188

Device Test: 8.3 RON_VIN_5V_25_Plastic(RdsOn_Vin5p0_6ALoad)


TID vs Result Stats

Test Results (Upper Limit = 23.0 (mOhm))

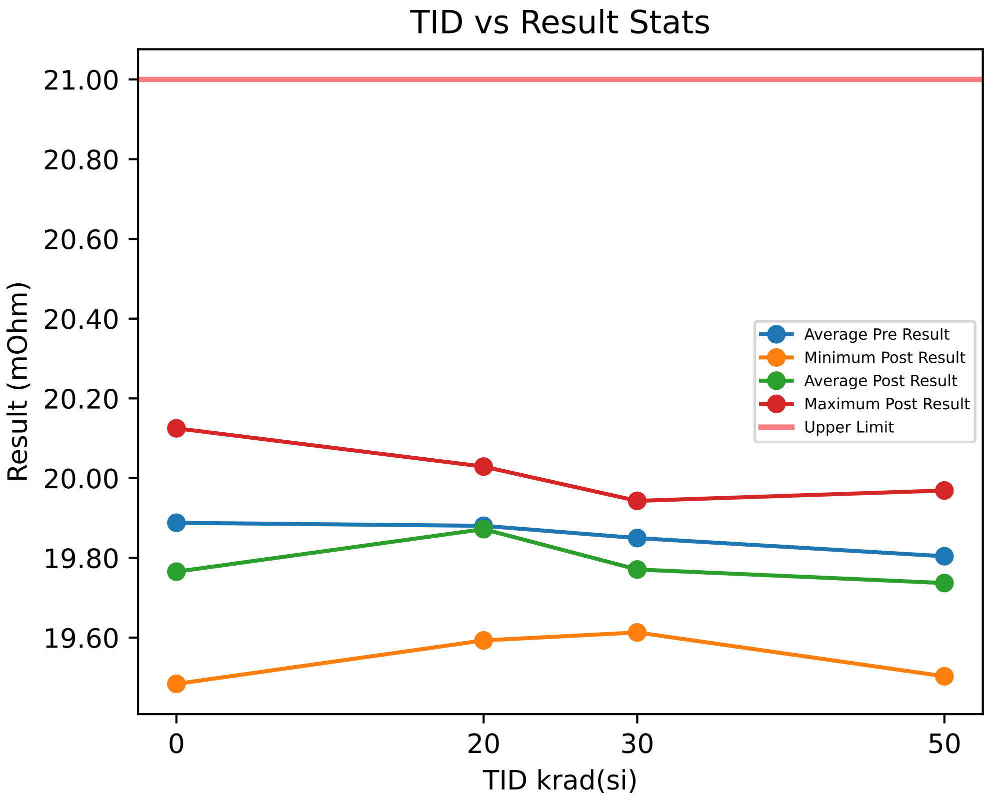
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	21.459	21.474	0.015
2	20	Unbiased	21.19	21.412	0.222
3	20	Unbiased	21.281	21.383	0.102
4	20	Unbiased	21.097	21.221	0.124
5	20	Unbiased	21.51	21.419	-0.091
6	20	7V Biased	21.612	21.545	-0.067
7	20	7V Biased	21.207	21.085	-0.122
8	20	7V Biased	21.61	21.53	-0.08
9	20	7V Biased	21.473	21.421	-0.052
10	20	7V Biased	21.396	21.307	-0.089
11	30	Unbiased	21.355	21.237	-0.118
12	30	Unbiased	21.362	21.307	-0.055
13	30	Unbiased	21.248	21.234	-0.014
14	30	Unbiased	21.442	21.353	-0.089
15	30	Unbiased	21.423	21.339	-0.084
16	30	7V Biased	21.354	21.308	-0.046
17	30	7V Biased	21.216	21.174	-0.042
18	30	7V Biased	21.235	21.11	-0.125
19	30	7V Biased	21.597	21.456	-0.141
20	30	7V Biased	21.291	21.293	0.002
21	50	Unbiased	21.265	21.277	0.012
22	50	Unbiased	21.394	21.309	-0.085
23	50	Unbiased	21.178	21.115	-0.063
24	50	Unbiased	21.402	21.417	0.015
25	50	Unbiased	21.292	21.254	-0.038
26	50	7V Biased	21.108	21.01	-0.098
27	50	7V Biased	21.361	21.287	-0.074
28	50	7V Biased	21.258	21.249	-0.009
29	50	7V Biased	21.195	21.157	-0.038
30	50	7V Biased	21.618	21.498	-0.12
31	0	Correlation	21.372	21.198	-0.174
32	0	Correlation	21.742	21.641	-0.101
33	0	Correlation	21.409	21.329	-0.08
34	0	Correlation	21.097	20.96	-0.137
35	0	Correlation	21.368	21.196	-0.172

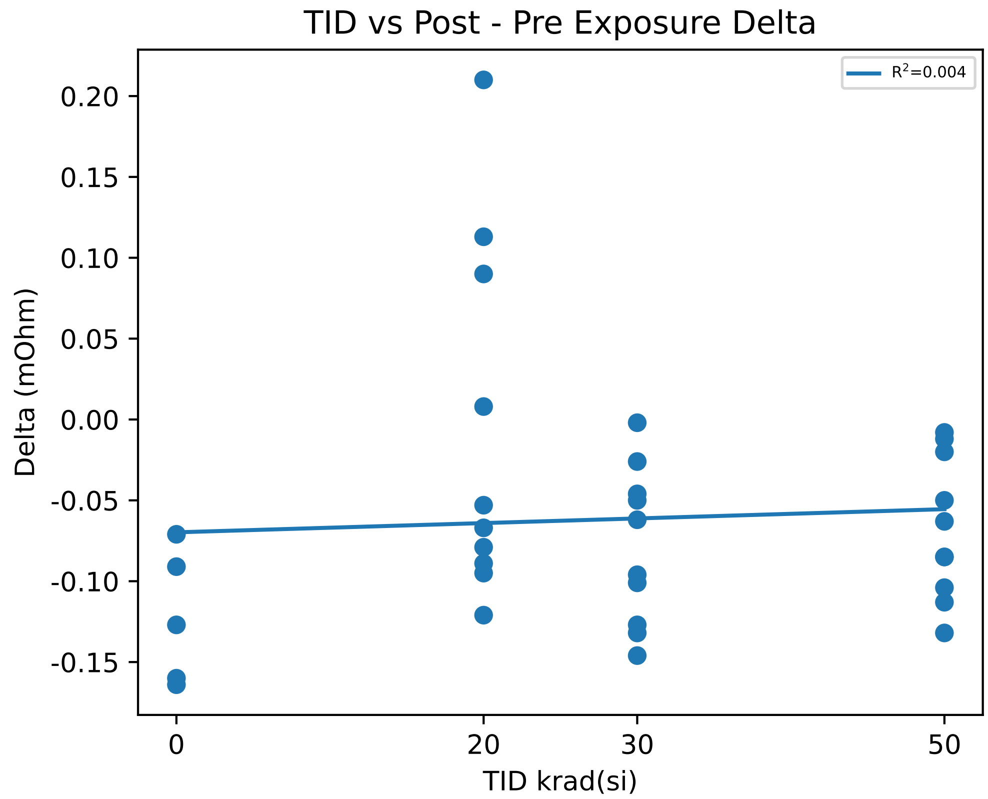

TID vs Post - Pre Exposure Delta

Test Statistics (mOhm)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	21.097	21.398	21.742	0.22947	20.96	21.265	21.641	0.24887	-0.174	-0.1328	-0.08	0.041985
20	21.097	21.384	21.612	0.18091	21.085	21.38	21.545	0.14159	-0.122	-0.0038	0.222	0.11539
30	21.216	21.352	21.597	0.11547	21.11	21.281	21.456	0.0975	-0.141	-0.0712	0.002	0.048094
50	21.108	21.307	21.618	0.14507	21.01	21.257	21.498	0.141	-0.12	-0.0498	0.015	0.046202

Device Test: 8.4 RON_VIN_7V_25_Plastic(RdsOn_Vin7p0_6ALoad)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

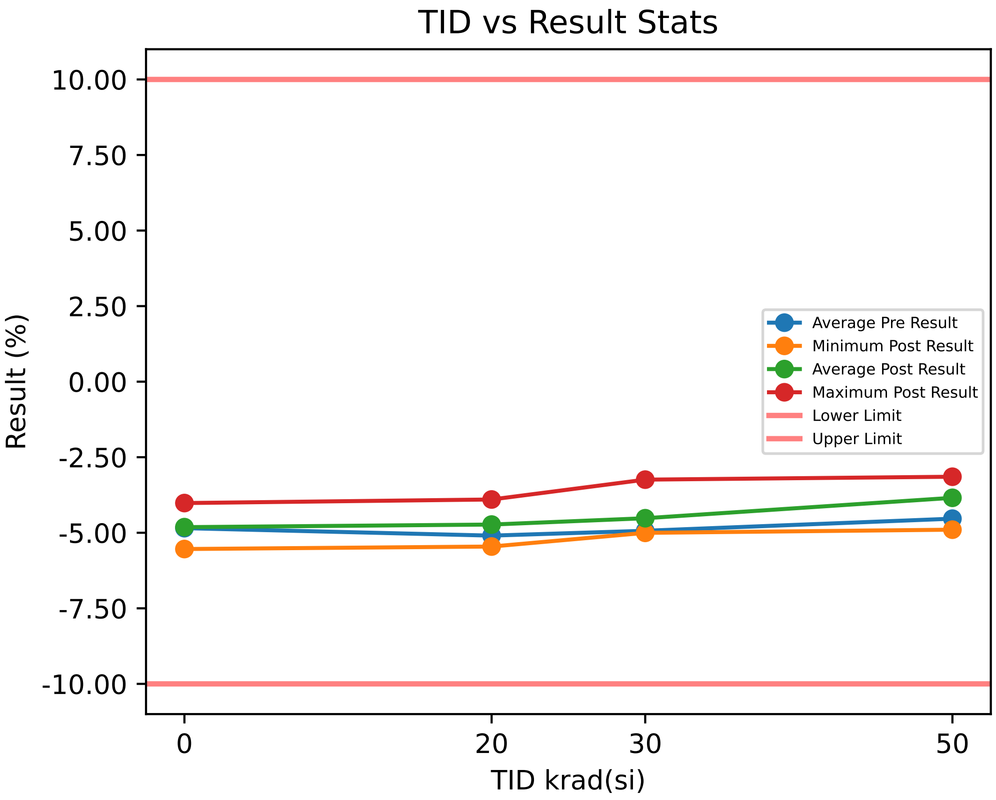
Test Results (Upper Limit = 21.0 (mOhm))

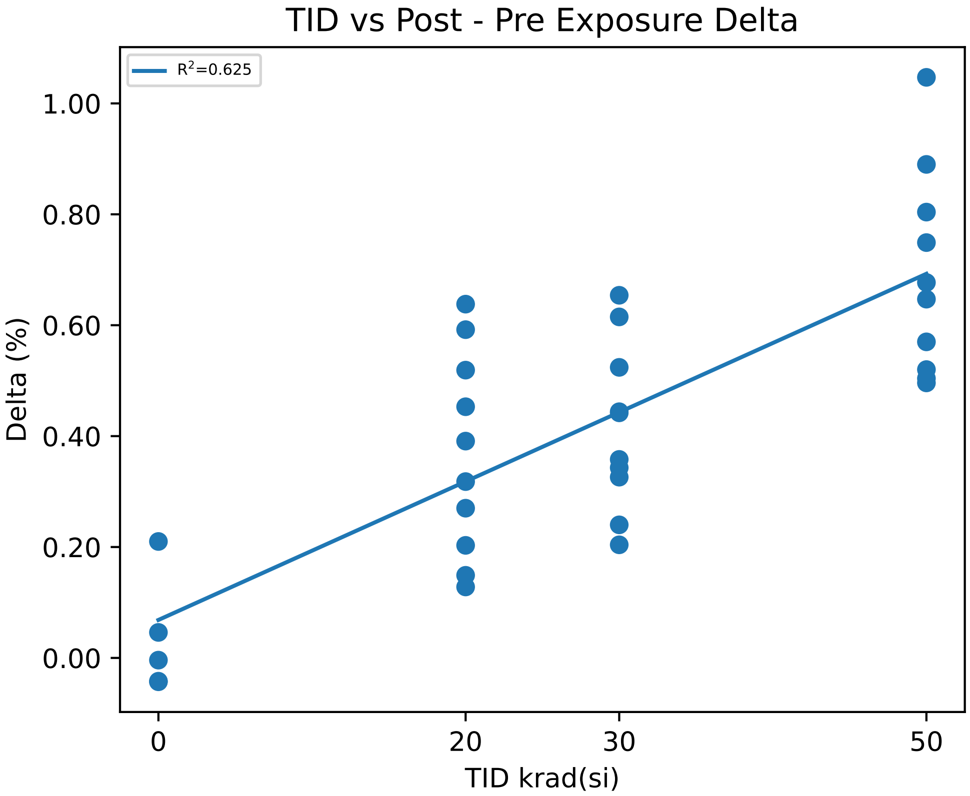
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	19.953	19.961	0.008
2	20	Unbiased	19.693	19.903	0.21
3	20	Unbiased	19.779	19.869	0.09
4	20	Unbiased	19.601	19.714	0.113
5	20	Unbiased	20	19.905	-0.095
6	20	7V Biased	20.096	20.029	-0.067
7	20	7V Biased	19.714	19.593	-0.121
8	20	7V Biased	20.1	20.021	-0.079
9	20	7V Biased	19.971	19.918	-0.053
10	20	7V Biased	19.897	19.808	-0.089
11	30	Unbiased	19.848	19.721	-0.127
12	30	Unbiased	19.877	19.815	-0.062
13	30	Unbiased	19.744	19.718	-0.026
14	30	Unbiased	19.942	19.841	-0.101
15	30	Unbiased	19.902	19.806	-0.096
16	30	7V Biased	19.838	19.788	-0.05
17	30	7V Biased	19.723	19.677	-0.046
18	30	7V Biased	19.745	19.613	-0.132
19	30	7V Biased	20.089	19.943	-0.146
20	30	7V Biased	19.789	19.787	-0.002
21	50	Unbiased	19.77	19.758	-0.012
22	50	Unbiased	19.905	19.801	-0.104
23	50	Unbiased	19.678	19.593	-0.085
24	50	Unbiased	19.889	19.881	-0.008
25	50	Unbiased	19.789	19.726	-0.063
26	50	7V Biased	19.616	19.503	-0.113
27	50	7V Biased	19.847	19.762	-0.085
28	50	7V Biased	19.755	19.735	-0.02
29	50	7V Biased	19.691	19.641	-0.05
30	50	7V Biased	20.101	19.969	-0.132
31	0	Correlation	19.86	19.696	-0.164
32	0	Correlation	20.216	20.125	-0.091
33	0	Correlation	19.899	19.828	-0.071
34	0	Correlation	19.611	19.484	-0.127
35	0	Correlation	19.854	19.694	-0.16

Test Statistics (mOhm)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	19.611	19.888	20.216	0.21586	19.484	19.765	20.125	0.23576	-0.164	-0.1226	-0.071	0.04121
20	19.601	19.88	20.1	0.17446	19.593	19.872	20.029	0.13575	-0.121	-0.0083	0.21	0.11029
30	19.723	19.85	20.089	0.11119	19.613	19.771	19.943	0.092676	-0.146	-0.0788	-0.002	0.048684
50	19.616	19.804	20.101	0.13954	19.503	19.737	19.969	0.13522	-0.132	-0.0672	-0.008	0.043941

Device Test: 9.19 CS_ACCURACY(Accuracy_750mA_6A_7V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

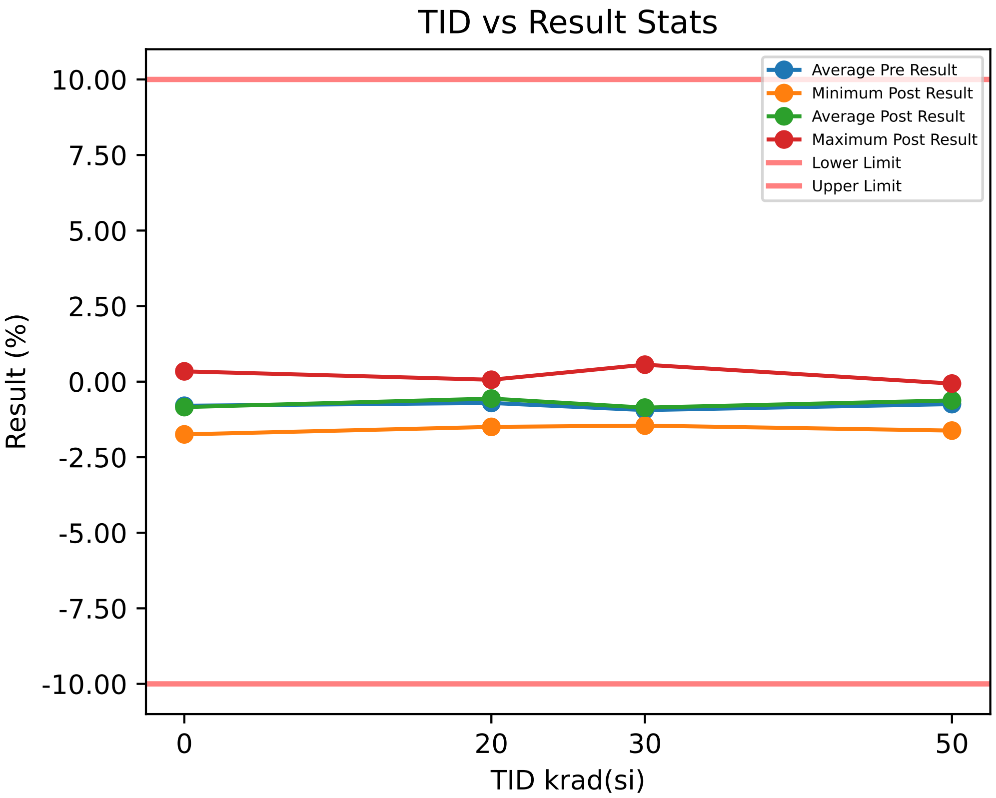
Test Results (Lower Limit = -10.0, Upper Limit = 10.0 (%))

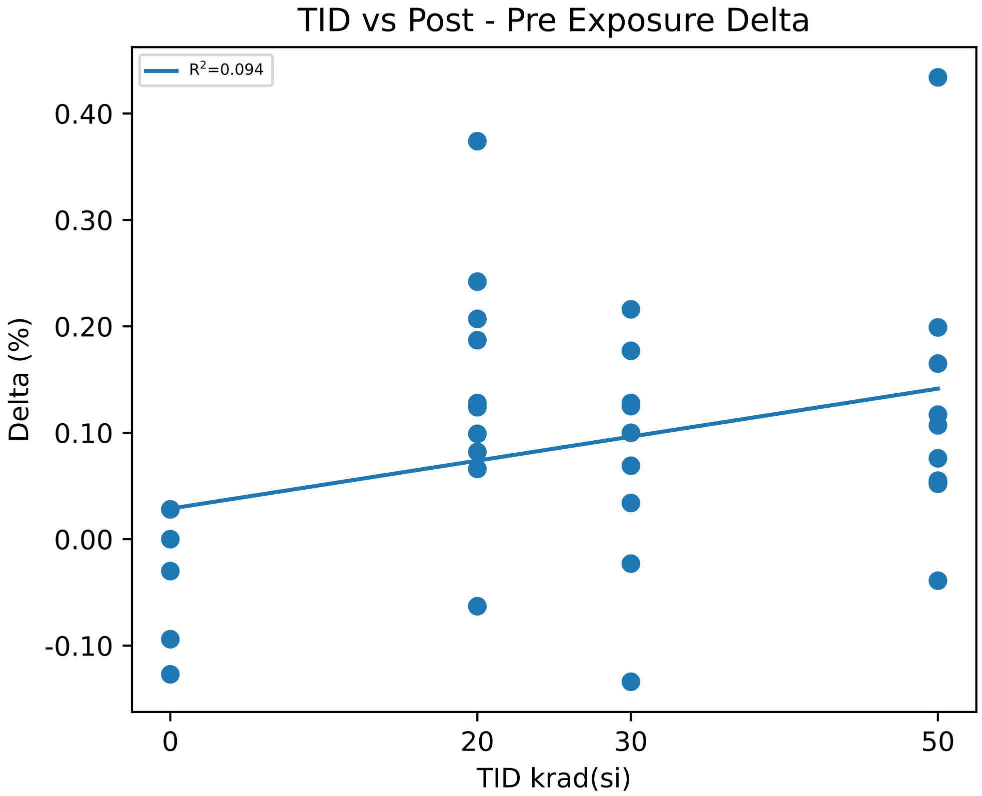
Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	-4.721	-4.518	0.203
2	20	Unbiased	-5.626	-4.988	0.638
3	20	Unbiased	-5.847	-5.456	0.391
4	20	Unbiased	-5.132	-4.54	0.592
5	20	Unbiased	-4.946	-4.676	0.27
6	20	7V Biased	-5.111	-4.793	0.318
7	20	7V Biased	-5.035	-4.907	0.128
8	20	7V Biased	-4.923	-4.404	0.519
9	20	7V Biased	-5.252	-5.103	0.149
10	20	7V Biased	-4.352	-3.899	0.453
11	30	Unbiased	-4.894	-4.654	0.24
12	30	Unbiased	-5.236	-4.893	0.343
13	30	Unbiased	-5.222	-4.698	0.524
14	30	Unbiased	-5.08	-4.636	0.444
15	30	Unbiased	-4.662	-4.304	0.358
16	30	7V Biased	-3.896	-3.242	0.654
17	30	7V Biased	-5.058	-4.616	0.442
18	30	7V Biased	-4.946	-4.62	0.326
19	30	7V Biased	-5.207	-5.003	0.204
20	30	7V Biased	-5.14	-4.525	0.615
21	50	Unbiased	-5.035	-4.465	0.57
22	50	Unbiased	-5.229	-4.733	0.496
23	50	Unbiased	-4.04	-3.363	0.677
24	50	Unbiased	-5.035	-3.988	1.047
25	50	Unbiased	-4.322	-3.573	0.749
26	50	7V Biased	-3.666	-3.146	0.52
27	50	7V Biased	-4.359	-3.855	0.504
28	50	7V Biased	-4.101	-3.211	0.89
29	50	7V Biased	-3.85	-3.203	0.647
30	50	7V Biased	-5.702	-4.898	0.804
31	0	Correlation	-5.095	-5.138	-0.043
32	0	Correlation	-5.103	-4.893	0.21
33	0	Correlation	-4.063	-4.017	0.046
34	0	Correlation	-4.481	-4.485	-0.004
35	0	Correlation	-5.496	-5.538	-0.042

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-5.496	-4.8476	-4.063	0.5694	-5.538	-4.8142	-4.017	0.58712	-0.043	0.0334	0.21	0.1052
20	-5.847	-5.0945	-4.352	0.4244	-5.456	-4.7284	-3.899	0.42802	0.128	0.3661	0.638	0.18211
30	-5.236	-4.9341	-3.896	0.40565	-5.003	-4.5191	-3.242	0.48702	0.204	0.415	0.654	0.14984
50	-5.702	-4.5339	-3.666	0.6731	-4.898	-3.8435	-3.146	0.65923	0.496	0.6904	1.047	0.18302

Device Test: 9.9 CS_ACCURACY(Accuracy_750mA_6A_1p5V)


TID vs Result Stats


TID vs Post - Pre Exposure Delta

Test Results (Lower Limit = -10.0, Upper Limit = 10.0 (%))

Serial #	krad(si)	Exposure Conditions	Pre Result	Post Result	Delta
1	20	Unbiased	-0.139	-0.057	0.082
2	20	Unbiased	-0.987	-0.613	0.374
3	20	Unbiased	-1.03	-0.843	0.187
4	20	Unbiased	-1.195	-0.953	0.242
5	20	Unbiased	-0.272	-0.206	0.066
6	20	7V Biased	-0.656	-0.449	0.207
7	20	7V Biased	-1.434	-1.497	-0.063
8	20	7V Biased	-0.065	0.063	0.128
9	20	7V Biased	-0.632	-0.533	0.099
10	20	7V Biased	-0.639	-0.515	0.124
11	30	Unbiased	-1.063	-1.086	-0.023
12	30	Unbiased	-1.554	-1.454	0.1
13	30	Unbiased	-1.626	-1.41	0.216
14	30	Unbiased	-0.869	-0.743	0.126
15	30	Unbiased	-0.42	-0.295	0.125
16	30	7V Biased	0.434	0.562	0.128
17	30	7V Biased	-1.386	-1.209	0.177
18	30	7V Biased	-1.192	-1.326	-0.134
19	30	7V Biased	-0.435	-0.401	0.034
20	30	7V Biased	-1.296	-1.227	0.069
21	50	Unbiased	-1.674	-1.619	0.055
22	50	Unbiased	-1.313	-1.261	0.052
23	50	Unbiased	-0.304	-0.187	0.117
24	50	Unbiased	-1.216	-0.782	0.434
25	50	Unbiased	-0.575	-0.41	0.165
26	50	7V Biased	-0.533	-0.572	-0.039
27	50	7V Biased	-0.139	-0.063	0.076
28	50	7V Biased	-0.541	-0.488	0.053
29	50	7V Biased	-0.238	-0.131	0.107
30	50	7V Biased	-0.893	-0.694	0.199
31	0	Correlation	-1.088	-1.215	-0.127
32	0	Correlation	-0.607	-0.579	0.028
33	0	Correlation	0.341	0.341	0
34	0	Correlation	-0.917	-1.011	-0.094
35	0	Correlation	-1.715	-1.745	-0.03

Test Statistics (%)

krad(si)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-1.715	-0.7972	0.341	0.75382	-1.745	-0.8418	0.341	0.7829	-0.127	-0.0446	0.028	0.06462
20	-1.434	-0.7049	-0.065	0.4578	-1.497	-0.5603	0.063	0.45909	-0.063	0.1446	0.374	0.11727
30	-1.626	-0.9407	0.434	0.63859	-1.454	-0.8589	0.562	0.64513	-0.134	0.0818	0.216	0.10185
50	-1.674	-0.7426	-0.139	0.51246	-1.619	-0.6207	-0.063	0.49903	-0.039	0.1219	0.434	0.12804

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